

Cardiac Rhythm Disease Management

Product Performance Report

Important Patient Management Information for Physicians





2011 First Edition – Issue 64

lssue 64

This report is available online at www.medtronic.com/CRDMProduct Performance

A Message from the Vice President

Dear Customer,

At Medtronic, product quality and reliability have been and will continue to be a priority. For over 27 years, Medtronic has compiled and produced product performance reports with one primary goal, to provide you with the product information you need to best care for your patients.

Our commitment to you is best expressed in Medtronic's mission: "To strive without reserve for the greatest possible reliability and quality in our products; to be the unsurpassed standard of comparison and to be recognized as a company of dedication, honesty, integrity, and service." To this end, we continually explore new ways to expand, improve, and learn from our product performance systems and measures.

Our quality goals cannot be reached alone. We welcome your collaboration, insight, and recommendations. Please contact our Technical Services Department at 1 (800) 723-4636 with your feedback comments and any questions.

Your participation and assistance in returning explanted products are also critical. Returned products are tested and evaluated so that we can fully measure the performance of our devices. Please refer to the instructions on the next page for assistance in returning products to the Medtronic CRDM Returned Product Analysis Laboratory.

As we constantly strive to exceed your expectations, we thank you for your dedication to improving and saving the lives of those suffering from cardiac rhythm disorders.

With appreciation and warm regards,

Tim Samsel Vice President, Quality and Regulatory Medtronic Cardiac Rhythm Disease Management Medtronic, Inc.

Contact Information

We invite our customers to use these telephone numbers to call with suggestions, inquiries, or specific problems related to our products.

US Technical Services Department

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For questions related to this CRDM Product

Performance Report, please call US Technical Services at the number above, or write to:

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For questions related to returning explanted product or returning product that shows signs of malfunction, please contact:

Outside the United States:

Your Medtronic representative or international technical center at the number above.

Within the United States: Your Medtronic representative or

CRDM Returned Product Analysis Laboratory

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Tim Samsel, Vice President, CRDM Quality and Regulatory

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Introduction

All product performance reports are not created equal. For 27 years, Medtronic has monitored performance via both returned product analysis and multicenter clinical studies.

This Product Performance Report (PPR) presents device survival estimates, advisory summaries, performance notes, and other information pertinent to assessing the performance of Medtronic implantable pulse generators (IPGs), implantable cardioverter defibrillators (ICDs), cardiac resynchronization therapy (CRT) devices, and implantable pacing and defibrillation leads.

This Product Performance Report has been prepared in accordance with International Standard ISO 5841- 2:2000(E).

The survival estimates provided in this report are considered to be representative of worldwide performance.

Survival Estimates

Medtronic, like other companies, monitors CRT, ICD, and IPG device performance using returned product analysis. We also monitor CRT, ICD, and IPG device performance using an active multicenter clinical study.

Returned product analysis is a passive approach to assessing product performance. This approach provides a suitable measure of product performance only when a significant number of explanted products are returned to the manufacturer. Returned product analysis provides a measure of hardware performance, but not necessarily the total clinical performance (e.g., the incidence of complications such as infection, erosion, muscle stimulation, etc. are not estimated).

The survival estimates provided in this report for CRT, ICD, and IPG devices are based on returned product analysis. This approach is suitable because a significant number of explanted generators are returned for analysis.

Lead performance is monitored differently. In contrast to CRT, ICD, and IPG devices, a very small percentage of leads are returned to the manufacturer due to the difficulty of explanting them. For leads, an active clinical study provides more accurate survival estimates compared to estimates based solely on returned product analysis.

Survival estimates for leads are based on clinical observations recorded via Medtronic CRDM's System Longevity Study. This multicenter clinical study is designed to record clinical observations representative of the total clinical experience. Therefore, the lead survival estimates include both lead hardware failure and lead-related medical complications, and do not differentiate a lead hardware failure from other clinical events such as exit block, perforation, dislodgement, or concurrent pulse generator failure. The actuarial life table method is applied to the data collected for CRT, ICD, and IPG devices and leads to provide the survival estimates included in this report. A general introduction to understanding this method of survival analysis is given later in this introduction.

ICD Charge Times

Since May 2000, Medtronic has provided important information on charge time performance of ICDs. The information provided in this report shows how ICD charge time can vary during the time a device is implanted. The information is presented in graphical format showing charge time as a function of implant time. The data for charge times are collected from devices enrolled in the System Longevity Study.

Advisory Summaries

This Product Performance Report includes summaries of all advisories applicable to the performance of the products included in the report. An advisory is added to the report when any product affected by the advisory remains in service and at risk of experiencing the behavior described in the advisory. The advisory will remain in the report until Medtronic estimates no product affected by the advisory remains active, or the risk of experiencing the behavior described in the advisory has passed.

For most advisories, the products subject to the advisory retain essentially the same survival probability as the products of the same model(s) not affected by the advisory. For those advisories where the survival probabilities of the affected and non-affected populations do differ significantly, Medtronic will provide separate survival data for each population. The separate survival data will remain in the report until Medtronic estimates no affected product remains in active service.

Performance Notes

This report concludes with a number of Performance Notes developed by Medtronic to provide additional product performance information relevant to follow-up practice and patient management.

Medtronic urges all physicians to return explanted products and to notify Medtronic when a product is no longer in use, regardless of reason for explant or removal from use.

How You Can Help

Medtronic urges all physicians to return explanted products and to notify Medtronic when a product is no longer in use, regardless of the reason for explant or removal from use. The procedures for returning products vary by geographic location.

Mailer kits with prepaid US postage are available for use within the United States to send CRTs, ICDs, IPGs, and leads to Medtronic's CRDM Returned Product Analysis Lab. These mailers are sized to accommodate the devices and leads from a single patient or clinical event and are designed to meet US postal regulations for mailing biohazard materials.

If the product being returned is located outside the United States, please contact your local Medtronic representative for instructions.

Medtronic also requests the return of explanted products from non-clinical sources, such as funeral homes, and will assume responsibility for storage and disposal of the product once received.

Mailer kits can be obtained by contacting the Returned Product Lab. For information on how to contact the Lab, refer to the Contact Information page of this report.

We continually strive to improve this CRDM Product Performance Report. In keeping with this philosophy, we ask for your suggestions on the content and format of this report, as well as any information you have regarding the performance of Medtronic products. For information on how to comment on this report, see the Contact Information page of this report.

Overview of Survival Analysis

Medtronic uses the Cutler-Ederer actuarial life table method to estimate the length of time over which devices and leads will perform within performance limits established by Medtronic. This probability to perform within performance limits over time is called the *survival probability*.

Devices and leads are followed until an *event* occurs where the device or lead ceases to operate within performance limits. The length of time from implant to the event is recorded for individual devices and leads in the *population sample*. The population sample for CRT, ICD, and IPG devices is made up of patients whose devices are registered as implanted in the United States. For leads, the population sample is the patients enrolled in our multicenter, international prospective System Longevity Study.

For IPGs and ICDs, the events can be normal battery depletion or a device malfunction. For leads, the events are complications as defined in the study protocol.

The actuarial life table method allows Medtronic to account for devices and leads removed from service for reasons unrelated to performance. Devices and leads removed for these reasons are said to be *suspended*. Examples include devices and leads:

- still in service at the time the analysis is performed
- removed to upgrade the device or lead
- no longer in service due to the death of the patient for reasons unrelated to the device or leads
- implanted in patients who are lost to follow-up

For each suspension, the device or lead has performed within performance limits for a period of time, after which its performance is unknown.

An Example

The following example describes the survival analysis method used to establish the survival probability estimates for Medtronic CRDM devices and leads. The example is intended to provide an overview of the analysis process. The definitions of malfunctions and complications, and other details specific to calculating device and lead survival estimates, are provided in the articles *Method for Estimating CRT, ICD, and IPG Device Performance (page 6)* and *Method for Estimating Lead Performance (page 75)*.

Introduction continued

This simple example describes the survival analysis method used to establish the survival probability estimates for Medtronic CRDM devices and leads.

Figure 1

Implant times for devices of 16 patients. Gray bars with an orange X indicate devices removed from service due to an event. Blue bars indicate suspended devices.

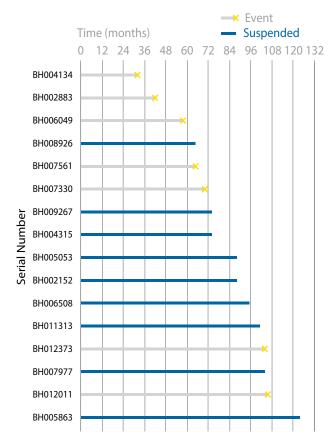


Figure 1 illustrates 16 patients who have implanted devices. The first patient's device (serial number BH004134) operated within performance limits for 32 months. At that time an event occurred. The fourth patient's device (serial number BH008926) did not have an event but is suspended, perhaps because it was still in service at the time of the analysis. This patient had 66 months of implant experience. In this example, Figure 1 shows that seven of the 16 devices suffered events, and nine are suspended.

The first step in the life table method is to divide the implant time into intervals of a specific length. This example will use 12-month intervals. The number of devices entered, suspended, and removed due to an event are counted and summarized, as shown in Table 1. For the first two intervals, all 16 devices survived and none were removed. In the interval (24-36 months), device BH004134 was removed due to an event. Therefore the table entries show that 16 entered the interval, none were suspended, and one was removed due to an event.

For the interval from 36-48 months, only 15 devices entered the interval and one was removed for an event. The remaining intervals are examined and the data entered in columns A, B, and C in like manner. The rest of the columns are filled in using calculations on the data in columns A, B, and C.

The *Effective Sample Size* (D) is the number of devices with full opportunity to experience a qualifying event in the interval. This is computed by subtracting one half the number suspended in the interval from the number that entered the interval. This calculation more accurately reflects the number of devices that could have experienced a qualifying event than simply using the number that entered the interval. Using the number of devices that enter an interval overestimates the sample size because the suspended devices do not complete the interval. Ignoring the suspended devices underestimates the sample size because suspended devices are not credited with their full service time. Using one half the number of suspended devices effectively splits the difference.

The next column in the table is the *Proportion with Event* (E). This is the proportion of devices that had an event in the interval. It is calculated by dividing the *Number of Events* (C) by the *Effective Sample Size* (D). The number can be interpreted as the estimated rate at which events occur in the time interval.

The *Interval Survival Probability* (F) is the estimate of probability of surviving to the end of the interval assuming the device was working at the beginning of the interval. It is calculated as 1 minus the *Proportion with Event* (E). This number can be interpreted as the estimated rate at which events **do not** occur in the time interval.

Introduction continued

The Cumulative Survival Probabilities (G) from the last column of the life table can be plotted versus time intervals in the first column to give a survival curve. Figure 2 shows the survival curve for the data shown in Table 1.

	А	В	с	D	E	F	G
Interval in Months	Number Entered	Number Suspended	Number of Events	Effective Sample Size	Proportion with Event	Interval Survival Probability	Cumulative Survival Probability
0	16	0	0	16	0.000	1.000	1.000
0-12	16	0	0	16	0.000	1.000	1.000
12-24	16	0	0	16	0.000	1.000	1.000
24-36	16	0	1	16	0.063	0.938	0.938
36-48	15	0	1	15	0.067	0.933	0.875
48-60	14	0	1	14	0.071	0.929	0.813
60-72	13	1	2	12.5	0.160	0.840	0.683
72-84	10	2	0	9	0.000	1.000	0.683
84-96	8	3	0	6.5	0.000	1.000	0.683
96-108	5	2	2	4	0.500	0.500	0.341
108-120	1	0	0	1	0.000	1.000	0.341
120-132	1	1	0	0.5	0.000	1.000	0.341

Table 1Life Table for Figure 1

Definitions:

Α	В	C	D	E	F	G
Number Entered	Number Suspended	Number of Events	Effective Sample Size	Proportion with Event	Interval Survival Probability	Cumulative Survival Probability
Number of devices active at the start of the interval	Number of devices removed from service for reasons other than an event	Number of units removed from service due to an event	Number of units with full opportunity to experience a qualifying event in the interval. Computed by subtracting one half the Number Suspended from the Number Entered.	Proportion of devices that had an event in the interval. Computed by dividing the Number of Events by the Effective Sample Size.	The probability of surviving to the end of the interval, assuming the device was working at the beginning of the interval. Computed as 1 minus the Proportion With Event.	The overall probability of surviving to the end of the interval. Computed by multiplying the Interval Survival Probability by the previous interval's Cumulative Survival Probability.

Cumulative Survival Probability (G) is the estimate of the unconditional probability of surviving to the end of the interval. It is computed by multiplying the Interval Survival Probability (F) by the previous interval's Cumulative Survival Probability. The probability of surviving to 132 months in the example is estimated for the table to be 0.341, or 34.1%. The *Cumulative Survival Probabilities* (G) of the life table can be plotted versus time intervals in the first column to give a survival curve. Figure 2 shows the survival curve for the data in Table 1.



Figure 2 Survival Curve for Data Given in Table 1

Confidence Intervals

Since survival curves are based on a sample of the device and lead population, they are only estimates of survival. The larger the effective sample size, the more confident the estimate. A confidence interval can be calculated to assess the confidence in an estimate. In the Product Performance Report, Medtronic provides a 95% confidence interval. This can be interpreted as meaning that 95% of the time, the true survival of the device will fall somewhere in the interval.

Survival Curves in the Product Performance Report

Since the survival estimate can become very imprecise with small effective sample sizes, Medtronic truncates the survival curve when the effective sample size is less than 100 for CRTs, ICDs, and IPGs, and when the number entered is less than 50 for leads. The survival charts in the Product Performance Report show the effective sample size for each year interval where Medtronic has experience. When the effective sample size reaches 100 for CRTs, ICDs, and IPGs or when the number entered reaches 50 for leads, the next data point is added to the survival curve.

Although the report provides tabular data in one-year intervals, the curves are actually computed and plotted using 1-month intervals (for CRT, ICD, and IPG devices) or 3-month intervals (for leads).

A number of references are available for additional information on survival analysis using the Cutler-Ederer life table method.¹

¹ Lee, Elisa T.(2003) Statistical Methods for Survival Data Analysis – 3rd Edition (Wiley Series in Probability and Statistics).

Method for Estimating CRT, ICD, and IPG Device Performance

Medtronic urges all physicians to return explanted products and to notify Medtronic when a product is no longer in use, regardless of reason for explant or removal from use.

The performance of CRT, ICD, and IPG devices is expressed in terms of device survival estimates, where "survival" refers to the function of the device, not the survival of the patient. These survival estimates are intended to illustrate the probability that a device will survive for a given number of years with neither malfunction nor battery depletion.

The survival estimates are determined from the analysis of Medtronic CRDM's United States device registration data and US returned product analysis data. These data are presented graphically and numerically.

Because this analysis is based on returned product analysis, the performance data does not reflect any device-related medical complications such as erosion, infection, muscle stimulation, or muscle inhibition.

Categorization of Depleted and Malfunctioning Devices for Survival Analysis

For survival estimation, every device returned to Medtronic CRDM and analyzed in the CRDM Returned Product Analysis laboratory is assigned to one of three categories. The device 1) is functioning normally, 2) has reached normal battery depletion, or 3) has malfunctioned. This categorization is combined with data from our device registry for the total number of implants and the implant durations to create the survival curves presented on the following pages.

Definition of Malfunction

Medtronic CRDM considers a device as having malfunctioned whenever the analysis shows that any parameter was outside the performance limits established by Medtronic while implanted and in service. To be considered a malfunction or battery depletion, the device must have been returned to Medtronic and analyzed.

Devices damaged after explant, damaged due to failure to heed warnings or contraindications in the labeling, or damaged due to interaction with other implanted devices (including leads) are not considered device malfunctions.

A device subject to a safety advisory is not considered to have malfunctioned unless it has been returned to Medtronic CRDM and found, through analysis, to actually have performed outside the performance limits established by Medtronic. Not all malfunctions expose the patient to a loss of pacing or defibrillation therapy. Some malfunctions included in the following survival estimates may not have been detected at all by the physician or the patient. These malfunctions, however, are included in the survival estimates and provide important feedback to our product development organization.

To provide insight into the nature of malfunctions, each malfunction is categorized as Malfunction with Compromised Therapy Function or Malfunction without Compromised Therapy Function. A summary of these malfunctions is presented for the most recently market-released models.

For this report, Normal Battery Depletion, Malfunction with Compromised Therapy Function, and Malfunction without Compromised Therapy Function are defined as follows:

Normal Battery Depletion – The condition when:

- (a) a device is returned with no associated complaint and the device has reached its elective replacement indicator(s) with implant time that meets or exceeds the nominal (50 percentile) predicted longevity at default (labeled) settings, or
- (b) a device is returned and the device has reached its elective replacement indicator(s) with implant time exceeding 80% of the expected longevity calculated using the available device setting information.

Medtronic CRDM establishes expected longevity by statistically characterizing the power consumed by the device and the power available from the device battery. This characterization is applied to a number of parameter configurations to derive a statistical mean longevity value and standard deviation for each parameter configuration. The statistical mean value minus three standard deviations is used as the expected longevity for determining if a battery depleted normally.

Method for Estimating CRT, ICD, and IPG Device Performance, continued

The Standard Actuarial Method is used to estimate IPG and ICD survival. This product performance report has been prepared in accordance with International Standard ISO 5841-2:2000(E).

For reference purposes, the following pages include estimated longevities for each model. The actual longevity achieved for any device while implanted will depend on the actual programmed parameters and patient factors, and may differ significantly from these estimates.

Malfunction with Compromised Therapy Function

The condition when a device is found to have malfunctioned in a manner that compromised pacing or defibrillation therapy (including complete loss or partial degradation), while implanted and in service, as confirmed by returned product analysis.

Examples: Sudden loss of battery voltage; accelerated current drain such that low battery was not detected before loss of therapy; sudden malfunction during defibrillation therapy resulting in aborted delivery of therapy, intermittent malfunction where therapy is compromised while in the malfunction state.

Malfunction without Compromised Therapy Function

The condition when a device is found to have malfunctioned in a manner that *did not* compromise pacing or defibrillation therapy, while implanted and in service, as confirmed by returned product analysis.

Examples: Error affecting diagnostic functions, telemetry function, data storage; malfunction of a component that causes battery to lose power quickly enough to cause premature battery depletion, but slowly enough that the condition is detected through normal follow-up before therapy is lost; mechanical problems with connector header that do not affect therapy.

Expanded Malfunction Detail

The malfunctions are further divided into categories that identify the subject area of the malfunction. The malfunctions are divided into the following subject areas:

Electrical Component – Findings linked to electrical components such as integrated circuits, resistors, capacitors, diodes, etc.

Electrical Interconnect – Findings linked to the connections between electrical components such as wires, solder joints, wire bonds, etc.

Battery – Findings linked to the battery and its components

Software/Firmware – Findings linked to software or firmware function

Possible Early Battery Depletion – Findings where the actual reported implant time is less than 80% of the expected longevity calculated using the available device setting information with no device malfunction observed. There may not be sufficient device setting information to determine conclusively if battery depletion was normal or premature in the absence of a specific root cause finding. However, returned devices meeting the above criteria are conservatively classified as Possible Early Battery Depletion malfunctions.

Other – Findings related to other components such as insulators, grommets, setscrews, and packaging, and findings where analysis is inconclusive

Returned Product Analysis Process

Analysis of returned product is performed according to written procedures. These procedures determine the minimum analysis required. The analysis required varies depending on the type of device, age of the device, the associated information received with the device, actual experience with models of similar design, and other factors. Additional analysis is performed as necessary to investigate a performance concern from a customer, or to collect specific reliability data.

When a device is returned with a performance concern from a customer, the general analysis process includes a preliminary analysis of the device in its as-received condition, followed by an automated functional test using test equipment equivalent to the equipment used in manufacturing.

When a malfunction is identified, failure analysis is performed to provide the detailed information necessary to investigate possible causes and actions. Medtronic CRDM maintains in-house expertise and performs its failure analysis using facilities it owns and supports. This capability permits detailed failure analysis.

Method for Estimating CRT, ICD, and IPG Device Performance, continued

Medtronic CRDM adjusts all-cause survival estimates to account for underreporting. While this lowers our all-cause survival estimates, we feel it gives a more accurate perspective on real performance.

Statistical Methods for Survival Analysis

Of the several different statistical methods available for survival analysis, the Standard Actuarial Method, with suspensions assumed distributed evenly within the intervals (Cutler-Ederer Method), is used to determine estimates of IPG and ICD survival. This method is commonly used by medical researchers and clinicians.

Implant times are calculated from the implant date to the earlier of the explant date or the cutoff date of the report. From this data an estimate of the probability of device survival is calculated at each monthly interval.

On the following pages, each graph includes a survival curve where events include malfunctions and normal battery depletions. This survival curve is a good representation of the probability a device will survive a period of time without malfunction and without battery depletion. For example, if a device survival probability is 95% after 5 years of service, then the device has a 5% chance of being removed due to battery depletion or malfunction in the first 5 years following implant.

In addition, a second curve is included to show survival excluding normal battery depletion. This curve is a good representation of the probability for a device to survive without malfunction. This curve includes only malfunctions as events and excludes normal battery depletion.

Since the survival estimate can become very imprecise with small effective sample sizes, Medtronic truncates the survival curve when the effective sample size is less than 100 for CRT, ICD, and IPG devices. The survival charts in the Product Performance Report show the effective sample size for each year interval where we have experience. When the effective sample size reaches 100, the next data point is added to the survival curve.

Although the report provides tabular data in one-year intervals, the curves are actually computed and plotted using one-month intervals.

The data in the tables are rounded to the nearest tenth of one percent. Occasionally, a graph may show 100% survival, but have one or more malfunctions or battery depletions. This occurs because, even with the malfunctions or battery depletions, the data rounds to 100%.

The survival curves are statistical estimates. As performance experience accumulates, the estimation improves. Confidence intervals are provided as a way to indicate the degree of certainty of the estimates. Greenwood's formula is used to calculate corresponding 95% confidence intervals for the standard errors, and the complementary log-log method is used to produce the confidence bounds.

Sample Size and How the Population and Population Samples Are Defined

The population sample from which the survival estimates are derived is comprised of the devices registered as implanted in the United States as of the report cutoff date. The number of registered implants, as well as an estimate of the number that remain in active service, is listed for each model. To be included in the population, the device must have been registered with Medtronic's registration system and implanted for at least one day.

This sample based on US implants is considered to be representative of the worldwide population, and therefore the survival estimates shown in this report should be representative of the performance worldwide of these models.

A CRT, ICD, or IPG model or model family will be included in this report when it has accumulated at least 10,000 implant months and will remain in the report as long as at least 500 devices remain active.

Methods Used to Adjust for Underreporting of Malfunction and Battery Depletion

The tables on the following pages show the actual number of malfunctions and battery depletions recorded by the analysis lab for US registered devices. Since not all devices are returned to Medtronic CRDM for analysis, these numbers underestimate the true number of malfunctions and battery depletions. To more accurately estimate the all-cause device survival probabilities, the number of malfunctions and battery depletions used to plot each interval of the all-cause survival curves is adjusted (multiplied) by a factor that is based on an estimate of the magnitude of underreporting. The magnitude of underreporting is estimated by analyzing experience in Medtronic's Device And Registrant Tracking (DART) system.

The DART system is an important element of Medtronic's Quality System. The DART system is designed to meet or exceed the US FDA's device tracking requirements set forth by the Safe Medical Devices Act. In the United States, over 98% of Medtronic's CRT, ICD, and IPG implants become registered in the DART system. continued Because pacemakers do not cure the patient's underlying health problem, when a pacemaker stops functioning (due to either normal battery replacement or malfunction) it is replaced with a new pacemaker. Therefore, the replacement recorded in the DART system is a good indication that the previous pacemaker experienced either battery depletion or malfunction. The fraction of replaced devices that are subsequently returned can be used to estimate the correction factor for the under reporting of the combination of battery depletion and malfunction.

Note that devices of patients who have expired do not factor into the calculation of the correction. It is possible some proportion of these device experienced battery depletion or malfunction. Since these are not counted into the correction factor based on the return rate of replaced devices, a correction factor based only on the return rate of replaced devices may still underestimate the true rate of battery depletion and malfunction. However, devices that are replaced because the patient is receiving a system upgrade or are removed because the patient no longer needs it (e.g., due to heart transplant) do contribute to the calculation of the correction factor and therefore impart an opposite bias.

Also note that this method of calculating the correction factor cannot distinguish between devices that are removed due to malfunction and those due to normal battery depletion. It might seem intuitive that devices that unexpectedly malfunction should be much more likely to be returned to the manufacturer than a device with ordinary normal battery depletion. But this has not been conclusively demonstrated. Therefore, this method only provides a correction factor reflecting the combination of battery depletion and malfunction.

No adjustment for underreporting is applied to the malfunction-free survival curve because a method for estimating malfunction-only underreporting has not been developed.

Adjustments to Registered Implants to Compensate for Unreported Devices Removed from Service

Devices are at times removed from service for reasons other than device malfunction or battery depletion. Examples are devices removed from service due to nondevice related patient mortality and devices removed due to changes in the patient's medical condition. Because an accurate estimate of device survival depends on an accurate estimate of the number of devices in service, it is important not to overstate the number of devices in service.

To ensure the number of devices in service is not overstated, Medtronic addresses this underreporting in two ways. Regular updates obtained from the Social Security Administration about deceased persons is used to update Medtronic's DART data about patients who have died but whose deaths had not been reported to Medtronic. In addition, the patient mortality rate derived from our DART system is monitored and compared to published mortality rates for comparable patient populations. If, during calculation of the survival curves, the patient mortality indicated by the data in DART is significantly different from published rates, an adjustment is applied to correct the difference.

7289 InSync II Marquis

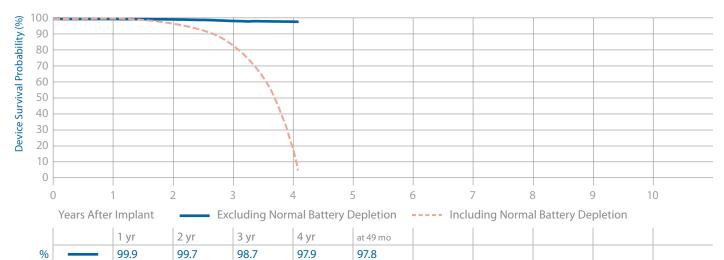
US Market Release	Jul-03
Registered US Implants	28,000
Estimated Active US Implants	100
Normal Battery Depletions (US)	6,470
Advisories: <u>See page 145</u> – 2005 Potential Premature Battery Depletion Due to Battery	Short

Malfunctions (US)
Therapy Function Not Compromised
Electrical Component
Software/Firmware
Possible Early Battery Depletion
Therapy Function Compromised
Battery (9 malfunctions related to advisory)
Electrical Component

Product Characteristics

> 32 10 22

NBD Code	VVED
Serial Number Prefix	PRJ
Max Delivered Energy	30 J
Estimated Longevity	See page 20



4.2

1,000

24,000 Effective Sample Size

99.7

%

96.7

17,000

82.4

12,000

18.3

2,000

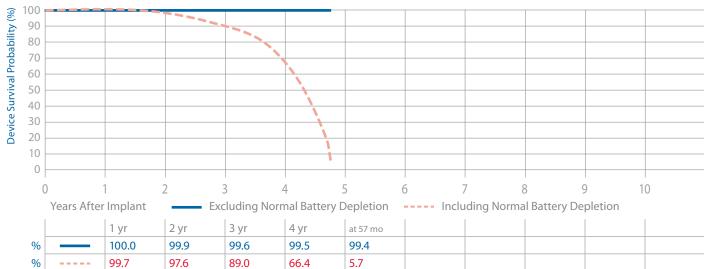
7297 InSync Sentry

US Market Release	Nov-04
Registered US Implants	9,000
Estimated Active US Implants	4
Normal Battery Depletions (US)	2,336
Advisories	None

Malfunctions (US)
Therapy Function Not Compromised
Battery
Electrical Component
Software/Firmware
Possible Early Battery Depletion
Therapy Function Compromised
Electrical Component

Product Characteristics

NBD Code	VVED
Serial Number Prefix	PRK
Max Delivered Energy	35 J
Estimated Longevity	See page 20



300

3,000

7299 InSync Sentry

#

8,000

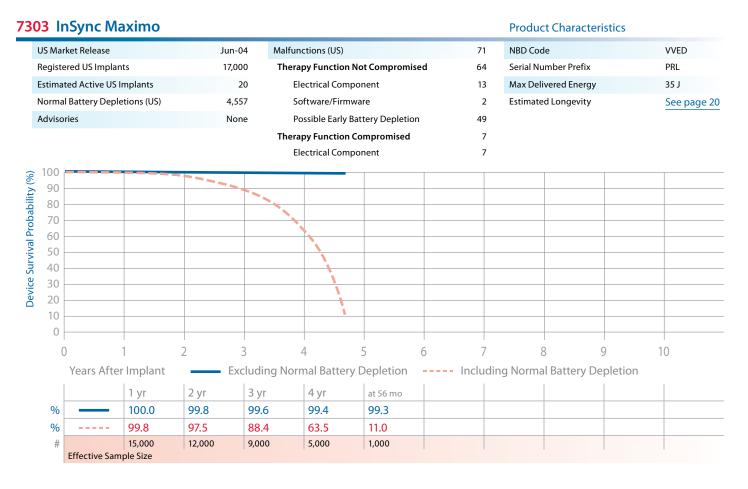
Effective Sample Size

6,000

5,000

7299 I	nSync Se	entry						Product Character	istics	
US Ma	rket Release		Арі	r-05 N	lalfunctions (US)		133	NBD Code	VVE	ED
Regist	ered US Impla	nts	31,	000 -	Therapy Function I	Not Compromised	124	Serial Number Prefix	PR	<
Estima	ated Active US	Implants	3,	000	Electrical Comp	oonent	15	Max Delivered Energy	35.	J
Norm	al Battery Depl	letions (US)	5,	920	Software/Firmv	ware	2	Estimated Longevity	See	e page 20
Adviso	ories		N	one	Possible Early B	attery Depletion	107			1 3
				-	Therapy Function (, ,	9			
					Electrical Comp	-	9			
③ 100										
۲										
08 bilit										
qpado 20										
DI 60										
50 IX										
Device Survival Probability 0 2 0 2 0 2 0 2 0 2 0 2 0 2 0 2 0 2 0 2										
e 30										
01 EV										
<u>م</u> 10										
0										
	0	1	2	3	4	5 6	7	8	9 10	
	Years Afte	er Implant	_	0	Normal Battery		Includin	g Normal Battery De		
		1 yr	2 yr	3 yr	4 yr	at 56 mo				
%		100.0	99.9	99.7	99.4	99.1				
%		99.8	97.7	89.3	63.5	8.5				
#		27,000	22,000	17,000	8,000	1,000				
	Effective San	nple Size								

Source: Medtronic Device Registration and Returned Product Analysis Data as of January 31, 2011

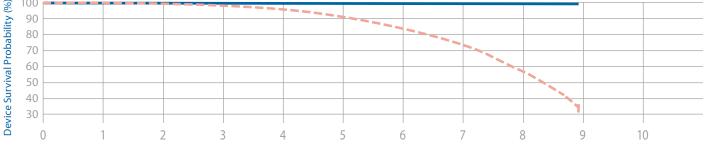


7304 InSync Maximo

'304 li	n <mark>Sync</mark> Ma	aximo							Product Characteris	tics	
US Mai	rket Release		Apr	-05 N	Malfunctions (US)		76		NBD Code		VVED
Registe	Registered US Implants			000	Therapy Function Not Compromised				Serial Number Prefix		PRL
Estima	Estimated Active US Implants			000	Battery				Max Delivered Energy		35 J
Norma	l Battery Deple	etions (US)	3,0	3,000 Electrical Component			8	8	Estimated Longevity		See page 20
Adviso	ories		No	one	Possible Early Ba	ttery Depletion	64				
					Therapy Function C	ompromised	3				
					Electrical Compo	onent	3				
§ 100											
Device Survival Probability (%) 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0											
08 pabi											
70 Floop											
ival 50											
AINS 40											
30 IC											
20 Jevi											
10											
0											
()	1	2	3	4	5 6	5 7		8 9		10
	Years After	r Implant	E>	kcluding	Normal Battery	Depletion	Includ	ding	g Normal Battery Dep	oletion	
		1 yr	2 yr	3 yr	4 yr	at 57 mo					
%		100.0	99.9	99.6	99.2	99.2					
%		99.8	97.8	90.3	66.9	7.0					
#		16,000	13,000	9,000	5,000	400					
	Effective Sam	ple Size									

12 Medtronic CRDM Product Performance Report www.medtronic.com/CRDMProductPerformance

US Market Release	Aug-01	Malfunctions (US)	29	NBD Code	DDDR
Registered US Implants	15,000	Therapy Function Not Compromised	7	Serial Number Prefix	PIN
Estimated Active US Implants	1,000	Electrical Component	4	Estimated Longevity	See page 2
Normal Battery Depletions (US)	1,000	Possible Early Battery Depletion	3		
Advisories	None	Therapy Function Compromised	22		
		Electrical Interconnect	22		



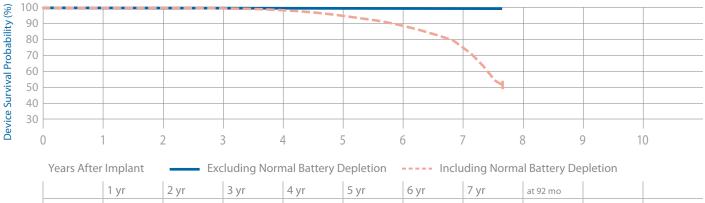
Years After	Implant	Exc	luding Norn	nal Battery D	epletion	Inclu	С
	1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	
	100.0	100.0	99.9	99.8	99.7	99.6	9

Iding Normal Battery Depletion

		1 yr	2 yr	3 yr	4 yr	5 yr	бyr	7 yr	8 yr	at 107 mo	
%		100.0	100.0	99.9	99.8	99.7	99.6	99.6	99.6	99.5	
%		99.9	99.6	98.1	95.8	90.8	83.5	72.9	57.5	33.6	
#		12,000	10,000	8,000	6,000	5,000	4,000	2,000	1,000	100	
	Effective Sample Size										

8042 InSync III

8042 InSync III				Product Characteristics	5
US Market Release	Feb-03	Malfunctions (US)	11	NBD Code	DDDR
Registered US Implants	39,000	Therapy Function Not Compromised	4	Serial Number Prefix	PKF
Estimated Active US Implants	19,000	Electrical Component	3	Estimated Longevity	See page 20
Normal Battery Depletions (US)	758	Possible Early Battery Depletion	1		
Advisories	None	Therapy Function Compromised	7		
		Electrical Component	3		
		Electrical Interconnect	4		



		1 yr	2 yr	3 yr	4 yr	5 yr	бyr	7 yr	at 92 mo	
%		100.0	100.0	100.0	100.0	99.9	99.9	99.9	99.9	
%		99.9	99.8	99.2	97.5	94.3	87.7	74.5	51.2	
#		28,000	20,000	15,000	10,000	7,000	4,000	1,000	100	
	Effective Sample Size									

C154DWK, C164AWK, C174AWK Concerto

US Market Release	May-06
Registered US Implants	81,000
Estimated Active US Implants	48,000
Normal Battery Depletions (US)	2,321
Advisories: <u>See page 139</u> – 2009 Potential Reduced Device Longevity	
Performance Note: <u>See page 150</u> – Anomalies in MOSFET Integrated Circuit Technology	

Malfunctions (US)	256
Therapy Function Not Compromised	230
Electrical Component	13
Electrical Interconnect	1
Software/Firmware	1
Possible Early Battery Depletion	215
Therapy Function Compromised	26
Electrical Component	25
Electrical Interconnect	1

(N) | (A) Product Characteristics

1,219	NBD Code	VVED				
1,211	Serial Number Prefix	PVU, PVT, PVR				
1,208	Max Delivered Energy	35 J				
	Estimated Longevity	See page 20				
3						
8						
7						
1						

100					C154DWł	, C164AWK, C17	4AWK (Non-adv	isory populatior	ı) 98.5%		
90 80											
80											
70											
60			1		C154DWK,	C164AWK, C174	AWK (Advisory p	opulation) 60.8	%		
				-							
50											
40				1							
30				1							
20				1							
10				1							
0				1							
0											
(0 1	1 2	2 3	3 4		5 (5	7	8	9	10

Years After Implant Excluding Normal Battery Depletion ----- Including Normal Battery Depletion Non-Adv 1 yr 2 yr 3 yr 4 yr at 51 mo 100.0 99.8 99.5 99.0 98.5 % % 99.8 97.8 90.6 68.9 59.5 # 69,000 47,000 19,000 1,000 100 Effective Sample Size

	Adv Pop	1 yr	2 yr	3 yr	at 39 mo					
%		99.9	99.4	76.5	60.8					
%		99.7	96.8	44.3	6.4					
#		3,000	3,000	1,000	200					
	Effective Sample Size									

D224TRK Consulta CRT-D

US Market Release	Aug-08	Malfunctions (US)	44	NBD Code	DDED
Registered US Implants	41,000	Therapy Function Not Compromised	43	Serial Number Prefix	PUD
Estimated Active US Implants	35,000	Electrical Component	6	Max Delivered Energy	35 J
Normal Battery Depletions (US)	40	Software/Firmware	1	Estimated Longevity	See page 20
Advisories	None	Possible Early Battery Depletion	36		
		Therapy Function Compromised	1		

Electrical Component

Product Characteristics

1

NBD Code	DDED		
Serial Number Prefix	PUD		
Max Delivered Energy	35 J		
Estimated Longevity	See page 20		

100												
90												
80												
	0	1	2	3	4	5	6	7	8	9	10	
	Years	After Impla	nt	- Excluding	g Normal Bat	ttery Deplet	ion	Including	Normal Batte	ery Depletio	n	

e.									
evio			1 yr	2 yr	at 26 mo				
Õ	%		100.0	99.3	99.1				
	%		99.9	97.2	96.1				
	#		16,000	1,000	400				
		Effective Sam	ole Size						

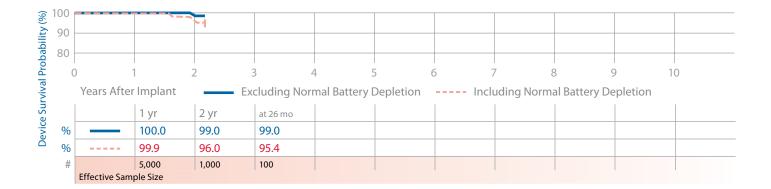
D274TRK Concerto II CRT-D

Effective Sample Size

74TRK Concerto II C	RT-D				Product Chara	cteristics	
US Market Release	Aug-09	Malfunctions (US)		1	NBD Code		DDED
Registered US Implants	19,000	Therapy Function Not	Compromised	0	Serial Number Pref	ix	PUE, PZB
Estimated Active US Implants	17,000	Therapy Function Con	npromised	1	Max Delivered Ene	rgy	35 J
Normal Battery Depletions (US)	2	Electrical Compon	ent	1	Estimated Longevi	ty	See page 20
Advisories	None						
100 90 80 0 1 Years After Implant % 100.0	2 3	4 5	6	7	8	9	10
Years After Implant	Exclud	ling Normal Battery D	epletion	- Includii	ng Normal Batter	y Depletion	
1 yr	at 15 mo						
% 100.0	100.0						
% 99.9	99.9						
# 2,000	100						

D284TRK Maximo II CRT-D

US Market Release	Mar-08	Malfunctions (US)	14	NBD Code	VVED
Registered US Implants	10,000	Therapy Function Not Compromised	14	Serial Number Prefix	PZP
Estimated Active US Implants	8,000	Possible Early Battery Depletion	14	Max Delivered Energy	35 J
Normal Battery Depletions (US)	18	Therapy Function Compromised	0	Estimated Longevity	See page 20
Advisories	None				



Product Characteristics

Device Survival Summary (95% Confidence Interval)

The following table shows CRT device survival estimates with 95% confidence intervals. Estimates are shown both with and without normal battery depletions included.

		10 yr										
		8 yr										
		7 yr										
		6 yr										
		5 yr	97.8 +.2/3 at 49 mo	4.2 +.6/5 at 49 mo	99.4 +.2/2 at 57 mo	5.7 +1.2/-1.0 at 57 mo	99.1 +.2/3 at 56 mo	8.5 +.9/8 at 56 mo	99.3 +.1/2 at 56 mo	11.0 +1.1/-1.0 at 56 mo	99.2 +.2/2 at 57 mo	7.0 +1.2/-1.0 at 57 mo
y (%)		4 yr	97.9 +.2/3	18.3 +.9/8	99.5 +.2/2	66.4 +1.3/-1.4	99.4 +.1/1	63.5 +.8/8	99.4 +.1/2	63.5 +1.0/-1.0	99.2 +.2/2	66.9 +1.0/-1.0
robabilit	. III	3 yr	98.7 +.2/2	82.4 +.6/6	99.6 +.1/2	89.0 +.8/8	99.7 +.1/1	89.3 +.4/4	99.6 +.1/1	88.4 +.6/6	99.6 +.1/1	90.3 +.5/5
Device Survival Probability (%)	Years After Implant	2 yr	99.7 +.1/1	96.7 +.2/3	99.9 +.1/1	97.6 +.3/4	9.99 +.0/1	97.7 +.2/2	99.8 +.1/1	97.5 +.2/3	9.99 +.0/-1	97.8 +.2/3
Device	Years Af	1 yr	9.99 +.0/.+	99.7 +.1/.+	100.0 +.0/1	99.7 +.1/1	100.0 +.0/0	99.8 +.2/1	100.0 +.0/0	99.8 +.1/1	100.0 +.0/0	99.8 +.1/1
			Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion
Malfunctions (US)	alapy Function besimorqu iction Vot besimorqu besimorqu	ru7 5AT Fur	32 + 268 = 300	(9) + 0 = 9 (advisory-related subset)	2 + 36 = 38		<mark>9</mark> + 124 = 133		7 + 64 = 71		3 + 73 = 76	
Malfunctions (US)	npromised stapy bor Not bosimonqu	I9D In In Io Io Io Io Io Io Io	+ 268 =		+ 36		+ 124 =		+ 64 =		+ 73 =	
Malfunctions (US)	oletions (US) srapy Function propy sction Not notronised	Act Imp Dep Dep Dep Dep Dep Dep Dep Dep Dep De	32 + 268 =		2 + 36 =		9 + 124 =		7 + 64 =		3 + 73 =	
Malfunctions (US)	ive US solants rmal Battery pretions (US) mpromised notomised notion Not	US Esti Act Inp Iot Del Del The Cor The Cor	6,470 32 + 268 =		2,336 2 + 36 =		5,920 9 + 124 =		4,557 7 + 64 =		3,000 3 + 73 =	
Malfunctions (US)	Implants ive US solants reapy Function mpromised rotion Not rotion Not rotion Not	Red US Est Del Del Del The Con The Con The Con	100 6,470 32 + 268 =		4 2,336 2 + 36 =		3,000 5,920 9 + 124 =		20 4,557 7 + 64 =		3,000 3,000 3 + 73 =	
Malfunctions (US)	easee jistered implants sinal Battery oletions (US) proponised intromised promised	Red US Est Del Del Del The Con The Con The Con	28,000 100 6,470 32 + 268 =	Advisories: See page 145 - 2005 Potential Premature(9) + 0 = 9Battery Depletion Due to Battery Short(advisory-related subset)	9,000 4 2,336 2 + 36 =		31,000 3,000 5,920 9 + 124 =		17,000 20 4,557 7 + 64 =		19,000 3,000 3,000 3 + 73 =	

					E	Malfunctions (US)	tions (U	2)		Device	Device Survival Probability (%)	robabilit	y (%)					
:		Narket 235e	istered stnslqm	bətem ve US stnsi	yəətfən ləm (SU) snoitəli	rapy Function npromised rapy	rapy ction Not besimorqr	le		Years A	Years After Implant	int						
Model Number	Family	ələЯ V SU	I SN ნəუ	İJDA	Nori		no⊃	stoT		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	10 yr
8040	InSync	Aug-01	15,000	1,000	1,000	22 +	- 2	29	Excluding Normal Battery Depletion	100.0 +.0/0	100.0 +.0/1	99.9 +.0/-1	99.8 +.1/1	99.7 +.1/2	99.6 +.1/2	99.6 +.1/2	99.6 +.1/2	99.5 +.2/3 at 107 mo
									Including Normal Battery Depletion	99.9 +.1/1	99.6 +.1/1	98.1 +.3/3	95.8 +.4/5	90.8 +.7/7	83.5 +.9/-1.0	72.9 +1.3/-1.3	57.5 +1.6/-1.7	33.6 +3.4/-3.4 at 107 mo
8042	InSync III	Feb-03	39,000	19,000	758	+	4	7	Excluding Normal Battery Depletion	100.0 +.0/0	100.0 +.0/0	100.0 +.0/0	100.0 +.0/0	99.9 +.0/1	99.9 +.0/1	99.9 +.1/2	99.9 +.1/2 at 92 mo	
									Including Normal Battery Depletion	9.99 +.0/0	99.8 +.0/1	99.2 +.1/1	97.5 +.3/3	94.3 +.5/5	87.7 +.8/8	74.5 +1.5/-1.5	51.2 +3.5/-3.6 at 92 mo	
C154DWK, C164AWK, C174AWK (Non- advisory population)	Concerto	May-06	81,000	48,000	2,321	- +	230 =	256	Excluding Normal Battery Depletion	100.0 +.0/0	8.99 0/0.+	99.5 +.1/1	99.0 +.2/2	98.5 +.7/-1.5 at 51 mo				
	See page 150 – Performance note on Anomalies in MOSFET Integrated Circuit Technology	Performance uit Technolo	e note on Al gy	nomalies in <i>l</i>	MOSFET				Including Normal Battery Depletion	99.8 +.0/0	97.8 +.1/1	90.6 +.3/3	68.9 +1.3/-1.3	59.5 +3.0/-3.2 at 51 mo				
C154DWK, C164AWK, C174AWK (Advisory population)	Concerto	May-06	4,000	0	205	+ ∞	1,211 =	1,219	Excluding Normal Battery Depletion	99.9 +.1/2	99,4 +.2/4	76.5 +1.8/-1.9	60.8 +2.2/-2.3 at 39 mo					
	Advisories: <u>Se</u> Longevity	See page 139-2009 Potential Reduced Device	– 2009 Pote	ential Reduce	ed Device				Including Normal Battery Depletion	99.7 +.1/3	96.8 +.6/7	44.3 +2.1/-2.2	6.4 +1.4/-1.2 at 39 mo					
	See page 150 – Performance note on Anomalies in MOSFET Integrated Circuit Technology	- Performanc uit Technolo	e note on A qy	nomalies in	MOSFET													

Device Survival Summary continued

	yr						
	10 yr						
	8 yr						
	7 yr						
	6 yr						
	5 yr						
	4 yr						
t	3 yr	99.1 +.3/5 at 26 mo	96.1 +.8/-1.0 at 26 mo			99.0 +.5/-1.0 at 26 mo	95.4 +1.4/-1.9 at 26 mo
Years After Implant	2 yr	99.3 +.2/3	97.2 +.5/7	100.0 +.0/0 at 15 mo	99.9 +.0/1 at 15 mo	99.0 +.5/-1.0	96.0 +1.1/-1.6
Years Aft	1 yr	100.0 +.0/0	99.9 +.0/1	100.0 +.0/0	99.9 +.0/1	100.0 +.0/0	99.9 +.1/1
		Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion
le	ът	44		-		14	
srapy stion Not besimorqn	ung	43 =		Ш О		14 =	
rapy Function psimorqu	Cor	+		+ 		+ 0	
rinal Battery (SU) snoiteld)		40		7		18	
	toA Imp Imp	35,000 40		17,000 2		8,000 18	
ive US Diants mal Battery	US Esti Act Imp	35,000		17,000			
Implants ive US shants radits	Rel Reg Jan Imp Imp			Aug-09 19,000 17,000		8,000	
easee jistered ive US siants siants	Rel Reg Jan Imp Imp	41,000 35,000		19,000 17,000		10,000 8,000	

Reference Chart

The longevity estimates provided are mean values calculated for the parameters given. The actual longevity achieved for any device while implanted will depend on the actual programmed parameters and patient factors, and may differ significantly from these estimates.

0	estimates.				E	stimate	d Longe	vity		F 1	D	
					×**						Replacement ERI)***	End of
Model Number	Family	Connector Style	Volume/ Mass*	Delivered Energy	Charging Frequency	100% Pacing‡	50% Pacing‡	15% Pacing‡	100% Sensing	Battery Voltage	Charge Time	Life (EOL) Battery Voltage
7289	InSync II Marquis	DR+LV true	38 cc 76 g	30 J	Monthly Quarterly Semiannual	3.3 4.2 4.5	3.6 4.9 5.4	4.0 5.5 6.1	4.2 5.8 6.6	≤ 2.62 V	> 16 second charge time	3 months after ERI
7297	InSync Sentry	DR+LV true	40 cc 78 g	35 J	Monthly Quarterly Semiannual	3.3 4.5 5.0	3.7 5.3 6.0	4.1 6.2 7.1	4.3 6.6 7.7	≤ 2.62 V	> 16 second charge time	3 months after ERI
7299	InSync Sentry	DR+LV true	40 cc 78 g	35 J	Monthly Quarterly Semiannual	3.3 4.5 5.0	3.7 5.3 6.0	4.1 6.2 7.1	4.3 6.6 7.7	≤ 2.62 V	> 16 second charge time	3 months after ERI
7303	InSync Maximo	DR+LV true	40 cc 78 g	35 J	Monthly Quarterly Semiannual	3.3 4.5 5.0	3.7 5.3 6.0	4.1 6.2 7.1	4.3 6.6 7.7	≤ 2.62 V	> 16 second charge time	3 months after ERI
7304	InSync Maximo	DR+LV true	40 cc 78 g	35 J	Monthly Quarterly Semiannual	3.3 4.5 5.0	3.7 5.3 6.0	4.1 6.2 7.1	4.3 6.6 7.7	≤ 2.62 V	> 16 second charge time	3 months after ERI

		Estimated Lo	ngevity		
Model Number	Family	Amplitude Setting	500 Lead Ω	1000 Lead Ω	Elective Replacement Time Indicators
8040	InSync	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	11.9 8.9 6.6	13.7 11.4 9.1	**
8042	InSync III	Low 2.5 V (A, RV, LV) Nominal 3.5 V (A, RV, LV) High 5.0 V (A, RV, LV)	8.3 5.9 4.1	9.9 7.8 6.0	**

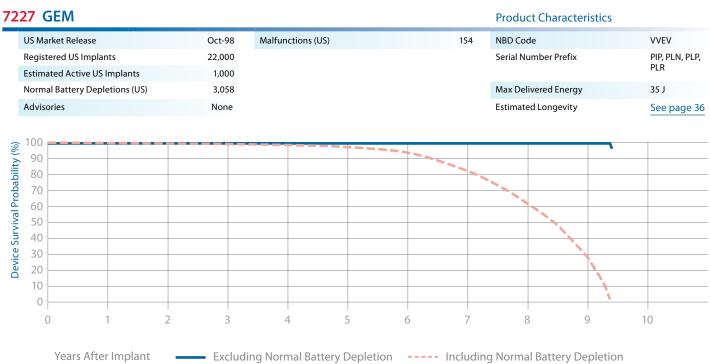
					Es	timated	Longe	vity			mmended	
					*					Replace	ment (RRT)***	-
Model Number	Family	Connector Style	Volume/ Mass*	Delivered Energy	Charging Frequency [*]	100% Pacing‡	50% Pacing‡	15% Pacing‡	100% Sensing	Battery Voltage	Charge Time	End of Service (EOS)
C154DWK, C164AWK, C174AWK	Concerto	DR+LV true	38 cc 68 g	35 J	Monthly Quarterly Semiannual	3.8 5.5 6.3	4.3 6.8 8.0	4.8 8.0 9.8	5.0 8.8 11.0	\leq 2.62 V	_	3 month after RRT or > 16-second charge time
D224TRK	Consulta CRT-D	DR+LV true	38 cc/ 68 g	35 J	Monthly Quarterly Semiannual	3.2 4.4 4.8	3.8 5.5 6.2	4.4 6.8 7.9	4.7 7.5 9.0	≤ 2.63 V	_	3 month after RRT or > 16-second charge time
D274TRK	Concerto II	DR+LV true	38 cc/ 68 g	text	Monthly Quarterly Semiannual	3.2 4.4 4.8	3.8 5.5 6.2	4.4 6.8 7.9	4.7 7.5 9.0	≤ 2.63 V	_	3 month after RRT or > 16-second charge time
D284TRK	Maximo II CRT-D	DR+LV true	38 cc/ 68 g	35 J	Monthly Quarterly Semiannual	3.2 4.4 4.8	3.8 5.5 6.2	4.4 6.8 7.9	4.7 7.5 9.0	≤ 2.63 V	_	3 month after RRT or > 16-second charge time

* Volume and mass differ by connector style.

** A full charge is a full energy therapeutic shock or capacitor reformation.

*** The minimum time between ERI and EOL (or RRT and EOS) is 3 months (100% pacing, two charges per month).

‡ Pacing mode is DDD for CRT models. Parameter settings; lower rate at 60 ppm, sensing rate at 70 bpm, (A, RV, LV) 3.0 V amplitude, 0.4 ms pulse width, and 510-ohm pace load per applicable channel. CRT models with shared biventricular pacing; InSync Marquis 7277 (LV impedance set to 510 ohms), InSync ICD 7272 (RV amplitude set to 4.0 V).

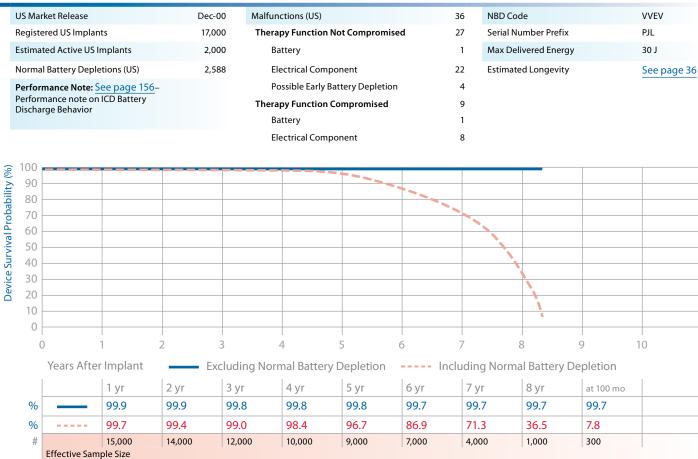


	icuis / liter	inplant	LAC	luung nom	lai Dattery L	repletion		iung Nonna	in Dattery De	pietion	
		1 yr	2 yr	3 yr	4 yr	5 yr	бyr	7 yr	8 yr	9 yr	at 111 mo
%		99.7	99.6	99.5	99.4	99.2	99.2	99.1	99.0	99.0	98.9
%		99.2	98.9	98.5	98.0	97.0	94.0	80.8	60.5	22.8	4.4
#		20,000	17,000	15,000	13,000	11,000	9,000	6,000	4,000	1,000	200
	Effective Same	ple Size									

7230 Marquis VR

Product Characteristics US Market Release Dec-02 Malfunctions (US) 54 NBD Code VVEV **Registered US Implants** 19,000 **Therapy Function Not Compromised** 27 Serial Number Prefix PKD, PLW, PLY Estimated Active US Implants 6,000 **Electrical Component** 12 Normal Battery Depletions (US) 571 Software/Firmware Max Delivered Energy 30 J 1 Possible Early Battery Depletion 13 Estimated Longevity Advisories: See page 145 – 2005 Potential See page 36 Premature Battery Depletion Due to Other 1 **Battery Short Therapy Function Compromised** 27 Battery (18 malfunctions related to advisory) 19 **Electrical Component** 8 100 Device Survival Probability (%) 90 80 70 60 0 2 3 4 5 6 7 8 9 10 ----- Including Normal Battery Depletion Years After Implant Excluding Normal Battery Depletion 2 yr 3 yr 4 yr 5 yr бyr 7 yr at 94 mo 1 yr % 100.0 99.9 99.9 99.8 99.7 99.6 99.4 99.2 % 99.8 99.5 99.1 98.8 98.0 93.7 83.8 70.0 # 17,000 13,000 11,000 10,000 9,000 6,000 3,000 200 **Effective Sample Size**

7231Cx GEM III VR



7232 Maximo VR

US Mai	ket Release		Oct-0	3 Malfun	nctions (US)			51	NBD Code		VVED
	ered US Implar	nts	44,00		apy Function N	lot Compromi	sed	38	Serial Number	Prefix	PRN
	ted Active US I		24,00		lectrical Comp			18	Max Delivered	Energy	35 J
	l Battery Deple	•	64		ossible Early Ba		on	19	Estimated Long		See page 36
					ther	, , , , , , , , , , , , , , , , , , , ,		1			<u>bee page b</u>
		e 145–2005 Pote epletion Due to	ntial		apy Function C	ompromised		13			
	/ Short				lectrical Comp			11			
					lectrical Interco			1			
				Po	ossible Early Ba	attery Depletic	on	1			
100											
90											
80											
70											
()	1 2	3	}	4	5	6	7	8	9	10
	Years Afte	r Implant			mal Battery	Depletion	-	cludin	g Normal Bati	-	
					1		1		5		
		-	2 yr	3 yr	4 yr	5 yr	6 yr	7 y			
%		100.0	99.9	99.9	99.9	99.8	99.8	99.	.8		
%		99.9	99.7	99.4	99.1	97.3	88.3	78	.9		
#		39,000	35,000	30,000	23,000	14,000	3,000	100)		
	Effective Sam	ple Size									

22 Medtronic CRDM Product Performance Report www.medtronic.com/CRDMProductPerformance **Product Characteristics**

Product Characteristics



7,000

5,000

4,000

7274 Marquis DR

13,000

Effective Sample Size

12,000

10,000

9,000

#

%

#

Effective Sample Size

Product Characteristics

1,000

200

	Mar-02	Malfun	ctions (US)			188	NBD Co	de		VVED
	48,000	Thera	py Function N	ot Compromise	ed	82	Serial N	umber Prefix		PKC
s	3,000	Ba	attery (3 malfur	nctions related to	advisory)	5	Max De	livered Energy		30 J
JS)	6,511	El	ectrical Compo	onent		26	Estimat	ed Longevity		See page
	ıl	Po	ossible Early Ba	ttery Depletion		51				
Due to		Thera	py Function Co	ompromised		106				
		Ba	ttery (73 malfu	nctions related t	o advisory)	79				
		Ele	ectrical Compo	nent		27				
	3		1	5 (5			8	9	10
	s JS) • 2005 Potentia • Due to • • • • • • • • • • • • • • • • • • •	s 3,000 JS) 6,511 2005 Potential	s 3,000 Ba JS) 6,511 El 2005 Potential Due to Thera Ba	s 3,000 Battery (3 malfur JS) 6,511 Electrical Compo 2005 Potential Due to Therapy Function Co Battery (73 malfur	s 3,000 Battery (3 malfunctions related to JS) 6,511 Electrical Component 2005 Potential Due to Therapy Function Compromised Battery (73 malfunctions related to Electrical Component	s 3,000 Battery (3 malfunctions related to advisory) JS) 6,511 Electrical Component 2005 Potential Due to Therapy Function Compromised Battery (73 malfunctions related to advisory) Electrical Component	s 3,000 Battery (3 malfunctions related to advisory) 5 JS) 6,511 Electrical Component 26 2005 Potential Due to Therapy Function Compromised 106 Battery (73 malfunctions related to advisory) 79 Electrical Component 27	s 3,000 Battery (3 malfunctions related to advisory) 5 Max De JS) 6,511 Electrical Component 26 Estimat 2005 Potential Due to Therapy Function Compromised 106 Battery (73 malfunctions related to advisory) 79 Electrical Component 27	s 3,000 Battery (3 malfunctions related to advisory) 5 Max Delivered Energy JS) 6,511 Electrical Component 26 Estimated Longevity 2005 Potential Possible Early Battery Depletion 51 51 Due to Therapy Function Compromised 106 Battery (73 malfunctions related to advisory) 79 Electrical Component 27	s 3,000 Battery (3 malfunctions related to advisory) 5 Max Delivered Energy J5) 6,511 Electrical Component 26 Estimated Longevity 2005 Potential Due to Possible Early Battery Depletion 51 51 Therapy Function Compromised Battery (73 malfunctions related to advisory) 106 54 Electrical Component 27 27

90.2

18,000

64.7

10,000

5.6

1,000

0

Source: Medtronic Device Registration and Returned Product Analysis Data as of January 31, 2011

99.4

34,000

98.4

26,000

96.8

22,000

99.7

42,000

7275 GEM III DR

Product Characteristics

JS Market Release	Nov-00	Malfunctions (US)	39	NBD Code	VVED
Registered US Implants	20,000	Therapy Function Not Compromised	28	Serial Number Prefix	PJM
Estimated Active US Implants	400	Battery	1	Max Delivered Energy	30 J
Normal Battery Depletions (US)	4,250	Electrical Component	9	Estimated Longevity	See page 3
Performance Note: <u>See page 156</u> –		Software/Firmware	1		
Performance note on ICD Battery Discharge Behavior		Possible Early Battery Depletion	17		
Discharge benavior		Therapy Function Compromised	11		
		Battery	2		
		Electrical Component	8		
100		Electrical Interconnect	1		
100					
90					
80					
70					
60					
50					
40					
30					
20					
10					
0					
0 1 2	3	4 5 6	7	8 9	10

				_	-				
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr		
%		99.9	99.9	99.8	99.8	99.7	99.7		
%		99.6	99.0	96.9	90.2	64.6	8.4		
#		18,000	15,000	13,000	10,000	5,000	400		
	Effective Sam	ple Size							

7278 Maximo DR

IS Ma	irket Release		Oct-	03 Malf	unctions (US)			45	NBD Code	VVED
egist	ered US Implant	S	38,0	00				37	Serial Number Prefix	PRM
stima	ated Active US In	nplants	14,0	00	Electrical Comp	onent		16	Max Delivered Energy	35 J
lorm	al Battery Deple	tions (US)	2,9	23	Possible Early Ba	attery Depletion	n	21	Estimated Longevity	See page
dvis	ories: See page	<mark>. 145 –</mark> 2005 P	otential	The	erapy Function C	ompromised		8		
rema	ature Battery Dej y Short	pletion Due to	•		Electrical Compo	onent		7		
atter	y short				Possible Early Ba	attery Depletior	n	1		
100										
90										
80										
70										
60										
50										
40										
30								_		
20										
10							<u> </u>	_		
0										
	0 1		2	3	4	5	6	7	8 9	10
	Years After	Implant	— Fx	cludina Na	ormal Battery	Depletion	Inc	ludin	g Normal Battery Depletic	n
			I		1		1			
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr		0 mo	
%		100.0	99.9	99.9	99.9	99.8	99.8	99.		
%		99.9	99.6	99.1	97.4	88.4	55.6	11.		
#	Effective Samp	34,000	29,000	25,000	20,000	13,000	3,000	100		

24 Medtronic CRDM Product Performance Report www.medtronic.com/CRDMProductPerformance Source: Medtronic Device Registration and Returned Product Analysis Data as of January 31, 2011

Product Characteristics

7288 Intrinsic

Product Characteristics

 \Box

JS Market Rele	ease	Aug	g-04 N	Aalfunctions (US)			57	NBD Code		VVED
Registered US	Implants	31	,000	Therapy Function	Not Comprom	ised	50	Serial Number	r Prefix	PUB
Estimated Acti	ve US Implants	14	,000	Battery			2	Max Delivered	l Energy	35 J
Normal Batter	y Depletions (U	5) 1	,897	Electrical Comp	onent		17	Estimated Lor	ngevity	See page 3
Advisories		N	lone	Software/Firm	ware		1			
				Possible Early B	attery Depleti	on	30			
				Therapy Function	Compromised		7			
				Electrical Comp	onent		7			
100										
90 80										
70										
60										
50										
40						1				
30										
0	1	2	3	4	5	6	7	8	9	10
Years	After Impla	nt <u> </u> E	Excluding	Normal Battery	Depletion		ncludir	ig Normal Bat	ttery Depleti	on
	1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	at	73 mo		
% —	- 100.0	99.9	99.9	99.8	99.8	99.7	99	.7		
%	99.9	99.6	99.1	98.0	88.3	52.0	43	.5		
#	28,000	26,000	23,000	19,000	12,000	1,000	30)		
Effecti	ve Sample Size									

7290Cx Onyx

Product Characteristics

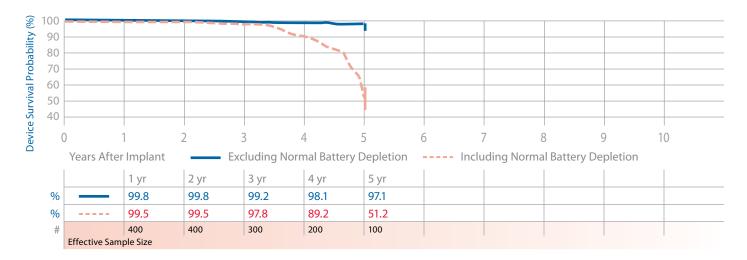
JS Market Release	Mar-04	Malfunctions (US)		5	Ν	BD Code		VVEV
Registered US Implants	1,000	Therapy Function	Not Compromise	e d 4	Se	erial Number Prefix	(PRP
Estimated Active US Implants	500	Electrical Com	ponent	3	M	ax Delivered Energ	ау	30 J
Normal Battery Depletions (US)	51	Possible Early	Battery Depletion	1	Es	timated Longevity	/	See page 3
Advisories	None	Therapy Function	Compromised	1				
		Electrical Com	ponent	1				
100 90 90 80 70 90			~`,					
60	3			6 7		8	9	10
Years After Implant	-	4 ing Normal Batter r 4 yr			ding N	o lormal Battery	-	10
i yi	_ yı _ J y	yi	5 yı	at 021110				

% - -#

Tears Arter	Implant	LAG	liuunig Non	nai battery L	repletion	incluui	ing normai	
	1 yr	2 yr	3 yr	4 yr	5 yr	at 69 mo		
	99.9	99.5	99.5	99.4	99.4	99.4		
	99.8	98.8	98.0	96.5	91.1	74.5		
	1,000	1,000	1,000	1,000	400	100		
Effective Sam	ple Size							

D153ATG, D153DRG EnTrust

US Market Release DDED, VVED Jun-05 Malfunctions (US) 8 NBD Code **Registered US Implants** 500 **Therapy Function Not Compromised** 7 Serial Number Prefix PNR 7 30 J Estimated Active US Implants Possible Early Battery Depletion Max Delivered Energy 100 Normal Battery Depletions (US) 97 **Therapy Function Compromised** Estimated Longevity 1 See page 37 Advisories None **Electrical Component** 1



D154ATG, D154DRG EnTrust

JS Market Release		Jun-	05 Mal	functions (US)			82	NBD Code	e		DDED, VV
Registered US Imp	ants	28,0	00 Th	erapy Function	Not Compromi	sed	73	Serial Nu	mber Prefix		PNR
Estimated Active L	S Implants	17,0	00	Electrical Comp	ponent		18	Max Deliv	vered Energ	y	35 J
Normal Battery De	pletions (US)	4	53	Software/Firm	ware		2	Estimated	d Longevity		See page
Advisories		No	ne	Possible Early B	Battery Depletic	'n	53				
			Th	erapy Function	Compromised		9				
				Electrical Comp	oonent		9				
100											
	1	2	3	4	5	6	7	8	}	9	10
90 80 0	1 ter Implant				5		7 cludir		Battery [
90 80 0	1 ter Implant			4	5		7 cludir				
90 80 0		Ex	cluding N	4 lormal Battery	5 7 Depletion	In	7 cludir				
90 80 0 Years Af	1 yr	Ex 2 yr	cluding N 3 yr	4 lormal Battery 4 yr	5 7 Depletion 5 yr	at 64 mo	7 cludir				

Product Characteristics

Product Characteristics

D154AWG, D164AWG Virtuoso DR

US Market Release	May-06
Registered US Implants	72,000
Estimated Active US Implants	56,000
Normal Battery Depletions (US)	134
Advisories: <u>See page 139</u> – 2009 Potential Reduced Device Longevity	
D (N) Common 150	

Performance Note: See page 150-Anomalies in MOSFET Integrated Circuit Technology

Product Characteristics

(N) (A)

64

41

10

1

30

23

23

1,542	NBD Code	VVED
1,537	Serial Number Prefix	PVV, PUL
1,537	Max Delivered Energy	35 J
	Estimated Longevity	See page 37
5		
5		

90 -			_			WG (Non-adviso	, population) 33				
30 -											
70 -											
50 -					154AWG, D164	AWG (Advisory po	opulation) 55.1%				
50 -											
40											
30 -				<u> </u>							
20											
10				1							
0	Years After		1	3 Excluding No		1	6 Inc	7 7 uding Nor	8 mal Batter	9 9 Ty Depletion	10
%								,		-	
%	Years After Non-Adv	1 yr 100.0	2 yr 99.9	Excluding No 3 yr 99.9	rmal Battery 4 yr 99.7	y Depletion at 52 mo 99.7		,		-	
0 % #	Years After Non-Adv	1 yr 100.0 99.9 65,000	2 yr 99.9 99.7	Excluding No 3 yr 99.9 99.3	rmal Battery 4 yr 99.7 98.4	y Depletion at 52 mo 99.7 97.8		,		-	
% % #	Years After Non-Adv	1 yr 100.0 99.9 65,000	2 yr 99.9 99.7	Excluding No 3 yr 99.9 99.3	rmal Battery 4 yr 99.7 98.4	y Depletion at 52 mo 99.7 97.8		,		-	
% #	Years After Non-Adv	1 yr 100.0 99.9 65,000	2 yr 99.9 99.7	Excluding No 3 yr 99.9 99.3	rmal Battery 4 yr 99.7 98.4	y Depletion at 52 mo 99.7 97.8		,		-	
% #	Years After Non-Adv	1 yr 100.0 99.9 65,000 ple Size	2 yr 99.9 99.7 49,000	Excluding No 3 yr 99.9 99.3 23,000	rmal Battery 4 yr 99.7 98.4 2,000	y Depletion at 52 mo 99.7 97.8		,		-	
0 % #	Years After Non-Adv	1 yr 100.0 99.9 65,000 ple Size 1 yr	2 yr 99.9 99.7 49,000	Excluding No 3 yr 99.9 99.3 23,000 3 yr	rmal Battery 4 yr 99.7 98.4 2,000 at 46 mo	y Depletion at 52 mo 99.7 97.8		,		-	

Malfunctions (US)

Therapy Function Not Compromised

Possible Early Battery Depletion

Electrical Component

Electrical Interconnect

Therapy Function Compromised

Electrical Component

US Market Release		Jun-	05	Malfunctions (US)		4	14	NBD Code		VVEV
Registered US Implar	nts	14,0	00	Therapy Function	n Not Comprom	ised 3	36	Serial Number P	refix	PNT
Estimated Active US	Implants	9,0	00	Battery			2	Max Delivered E	inergy	35 J
Normal Battery Deple	etions (US)		47	Electrical Com	nponent		13	Estimated Long	evity	See page
Advisories		No	ne	Possible Early	Battery Depleti	on 2	21			
				Therapy Function	n Compromised	I	8			
				Electrical Com	nponent		8			
100										
100					_					
100										
80	1	2	2		5	6	7		0	10
100 90 80 0	1	2	3	4	5	6	7	8	9	10
100 90 80 0 Years Afte	1 r Implant	_	-	4 J Normal Batter	-	-	7 udir	8 Normal Batte	-	
100 90 80 0 Years Afte	1 r Implant 1 yr	_	-		-	-	7 udir	_	-	
100 90 80 0 Years Afte		E>	cluding	Normal Batter	ry Depletion	Incl	7 udir	_	-	
90 90 0 Years Afte	1 yr	Ex 2 yr	cluding 3 yr	y Normal Batter 4 yr	ry Depletion	at 63 mo	7 udir	_	-	

D154VWC, D164VWC Virtuoso VR

IS Mar	rket Release		May-0	5 Malfun	ctions (US)		21	NBD Code		VVEV
Registered US Implants 33,0				D Thera	py Function Not Compror	mised	10	Serial Number Pre	PUN, PUP	
stimated Active US Implants 26,00				D Ele	ectrical Component		5	Max Delivered En	35 J	
lormal Battery Depletions (US)				2 Ele	ectrical Interconnect		1	Estimated Longev	See page	
	ories: See page			Pc	ossible Early Battery Deple	tion	4			
	ial Reduced Dev			Thera	py Function Compromise	d	11			
Anon	mance Note: Se nalies in MOSFE		ircuit	Ele	ectrical Component		11			
echno	ology	-								
100										
100 90 80										
90) 1		2 3	3	4 5	6	7	8	9	10
90 80) 1 Years After	Implant	Exc	luding Norr	mal Battery Depletion	-	1	8 g Normal Batter	-	
90 80 0		Implant 1 yr	Exc	luding Norr 3 yr	mal Battery Depletion	-	1	_	-	
90 80 0		Implant 1 yr 100.0	2 yr 99.9	luding Norr 3 yr 99.9	mal Battery Depletion 4 yr 99.9	-	1	_	-	
90 80 0		Implant 1 yr	Exc	luding Norr 3 yr	mal Battery Depletion	-	1	_	-	

Product Characteristics

JS Mai	ket Release		Aug	g-08 N	Malfunctions (US)			8	NBD Code	NBD Code			
Registe	ered US Implan	ts			herapy Func	erapy Function Not Compromised			Serial Number	PUG			
stima	ted Active US li	nplants	29	.000	Electrical Component			2	Max Delivered	35 J			
Vorma	l Battery Deple	tions (US)	24		Possible Early Battery Depletion				Estimated Long	Estimated Longevity			
Adviso	ries		None Therapy Function Compromised Electrical Component					4	4 3				
								3					
					Software/I	Firmware		1					
100			_										
90													
80													
()	1	2	3	4	5	б	7	8	9	10		
	Years After	Implant	E	Excluding	Normal Bat	tery Depleti	on	Includi	ng Normal Bat	tery Depletion	n		
		1 yr	2 yr	at 26 mo)								
			000	99.9									
%		100.0	99.9	55.5									
% %		100.0 99.8	99.9 99.4	99.4									

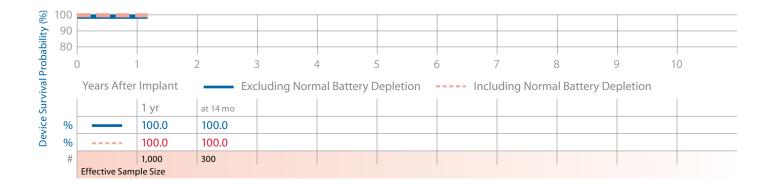
D224VRC Secura VR

US Market Release		Aug	g-08 Malfunctions (US)			3	NBD Code		VVEV		
Registered US Implants Estimated Active US Implants			12,	000	Therapy Function Not Compromised Possible Early Battery Depletion				Serial Number P	PUX	
			11,	000					Max Delivered E	35 J	
Norma	al Battery Deple	etions (US)		5	Therapy Function Compromised				Estimated Long	See page	
Adviso	ories		Ν	one	Electrical Component			1			
				Software/Firmware				1			
100 90			_								
100 90 80			-								
90 80	0	1	2	3	4	5	6	7	8	9	10
90 80		1 Implant	E		4 Normal Bat			Ι	8 g Normal Batte	-	
90 80	0	1			Normal Bat			Ι	-	-	
90 80	0	1 Implant	E	xcluding	Normal Bat			Ι	-	-	
90 80 (0	1 1 1 yr	E 2 yr	at 26 m	Normal Bat			Ι	-	-	

Product Characteristics

<u>0</u>

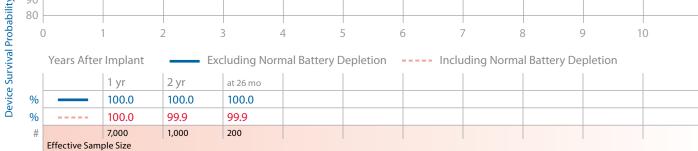
274DRG Virtuoso II DR				Product Characteristics	
US Market Release	Aug-09	Malfunctions (US)	0	NBD Code	VVED
Registered US Implants	13,000	Therapy Function Not Compromised	0	Serial Number Prefix	PZT
Estimated Active US Implants	12,000	Therapy Function Compromised	0	Max Delivered Energy	35 J
Normal Battery Depletions (US)	0			Estimated Longevity	See page 37
Advisories	None				



D274VRC Virtuoso II VR

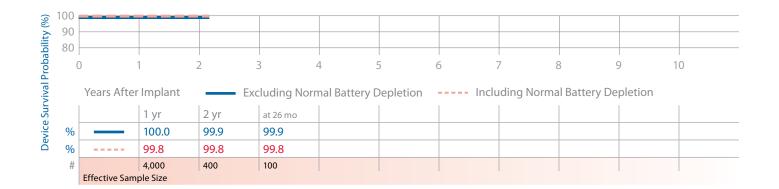
74VRC	Virtuos	o II VR								Produc	t Character	istics	
US Marke	JS Market Release Aug-09					Malfunctions (US)					NBD Code		
Registere	egistered US Implants 5,000				Therapy Function Not Compromised					Serial Number Prefix			PUY, PZH
Estimated	timated Active US Implants 5,000				Therapy Function Compromised				0	Max Deli	vered Energy		35 J
Normal B	Normal Battery Depletions (US)			0						Estimate	d Longevity		See page 37
Advisorie	s		Non	e									
90 80 0 Y	1 /ears After Im		—— Exc	3 Sluding	4 Norm	al Battery I	5 Depletion	6 Inc	7 Iudin	۶ g Norma	Battery De	9 Pletion	10
	1	yr	at 14 mo						_				
%	10	0.00	100.0										
%	10	0.0	100.0										
#		000	100										
Ef	ffective Sample	Size											

84DRG Maximo II DR				Product Characteristics	
US Market Release	Mar-08	Malfunctions (US)	1	NBD Code	VVED
Registered US Implants	13,000	Therapy Function Not Compromised	0	Serial Number Prefix	PUG
Estimated Active US Implants	12,000	Therapy Function Compromised	1	Max Delivered Energy	35 J
Normal Battery Depletions (US)	2	Electrical Component	1	Estimated Longevity	See page 3
Advisories	None				
100					
90					



D284VRC Maximo II VR

D284VRC Maximo II VR				Product Characteristics	
US Market Release	Mar-08	Malfunctions (US)	3	NBD Code	VVEV
Registered US Implants	8,000	Therapy Function Not Compromised	0	Serial Number Prefix	PZN
Estimated Active US Implants	7,000	Therapy Function Compromised	3	Max Delivered Energy	35 J
Normal Battery Depletions (US)	4	Electrical Component	2	Estimated Longevity	See page 37
Advisories	None	Software/Firmware	1		



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Survival Summary (95% Confidence Interval)	
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The following table shows ICD device survival estimates with 95% confidence intervals. Estimates are shown both with and without normal battery depletions included.

			Malfunctions (US)		Device S	Device Survival Probability (%)	obability	(%)					
jistered implants ive US strad pletions (US) pletions (US) pletions (US)	stants rmal Battery pletions (US) crapy Function grapy baironised	erapy.	toN noitor bəsimorqm		Years Aft	Years After Implant	t	-				-	
Est Act Inn No De De	oN ⊳dT oN		ıny		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	10 yr
Oct-98 22,000 1,000 3,058 —		I	- 154	t Excluding Normal Battery Depletion	99.7 +.1/1	99.6 +.1/1	99.5 +.1/1	99.4 +.1/1	99.2 +.1/1	99.2 +.1/1	99.1 +.1/2	99.0 +.2/2	98.9 +.2/2 at 111 mo
				Including Normal Battery Depletion	99.2 +.1/1	98.9 +.1/2	98.5 +.2/2	98.0 +.2/2	97.0 +.3/3	94.0 +.4/4	80.8 +.8/8	60.5 +1.1/-1.1	4.4 +1.0/8 at 111 mo
Dec-02 19,000 6,000 571 27 +	571 27		27 = 54	Excluding Normal Battery Depletion	100.0 +.0/0	99.9 +.0/1	99.9 +.0/1	99.8 +.1/1	99.7 +.1/1	99.6 +.1/1	99.4 +.2/2	99.2 +.2/3 at 94 mo	
Advisories: <u>See page 145</u> – 2005 Potential Premature Battery (18) + Depletion Due to Battery Short (advisor)		(18) + (advisor)	(18) + (0) (18) (advisory-related subset)) Including Normal Battery Depletion	99.8 +.1/1	99.5 +.1/1	99.1 +.1/2	98.8 +.2/2	98.0 +.2/3	93.7 +.5/5	83.8 +1.0/-1.0	70.0 +2.4/-2.6 at 94 mo	
Dec-00 17,000 2,000 2,588 9 +	2,588 9		27 = 36	Excluding Normal Battery Depletion	99.9 +.0/1	99.9 +.0/1	99.8 +.1/1	99.8 +.1/1	99.8 +.1/1	99.7 +.1/1	99.7 +.1/1	99.7 +.1/1	99.7 +.1/1 at 100 mo
See page 156 – Performance note on ICD Battery Discharge Behavior	ttery			Including Normal Battery Depletion	99.7 +.1/1	99.4 +.1/1	99.0 +.2/2	98.4 +.2/2	96.7 +.3/4	86.9 +.7/7	71.3 +1.0/-1.1	36.5 +1.4/-1.4	7.8 +1.3/-1.2 at 100 mo
Oct-03 44,000 24,000 645 13 +	645 13		38 = 51	Excluding Normal Battery Depletion	100.0 +.0/0	9.99 +.0/0	9.99 /0.+	9.99 0/0.+	99.8 +.0/1	99.8 +.0/1	99.8 +.1/1		
Advisories: <u>See page 145</u> – 2005 Potential Premature Battery (0) + Depletion <u>Due to Battery</u> Short (advisory)	(0) (advi	(0) + (advisory-	+ (0) = (0) sory-related subset)	Including Normal Battery Depletion	9.66 0/0.+	99.7 +.0/1	99.4 +.1/1	99.1 +.1/1	97.3 +.2/2	88.3 +.7/8	78.9 +2.2/-2.4		
Oct-98 15,000 300 2,067 —		1	- 100) Excluding Normal Battery Depletion	9.99 1/0.+	99.8 +.1/1	99.7 +.1/1	99.5 +.1/2	99.3 +.1/2	99.1 +.2/2	99.0 +.2/2	98.8 +.2/3	98.8 +.2/3 at 104 mo
				Including Normal Battery Depletion	99.6 +.1/1	99.4 +.1/1	98.7 +.2/2	97.7 +.3/3	95.3 +.4/5	88.9 +.7/7	74.7 +1.1/-1.1	40.2 +1.5/-1.5	9.3 +1.4/-1.3 at 104 mo
Mar-02 48,000 3,000 6,511 106 +	6,511 106		82 = 188	3 Excluding Normal Battery Depletion	100.0 +.0/0	9.99 +.0/0	99.8 +.0/1	99.6 +.1/1	99.4 +.1/1	99.3 +.1/1	99.2 +.1/1		
Advisories: <u>See page 145</u> – 2005 Potential Premature Battery (73) + Depletion <u>Due to Battery</u> Short (advisory-	(73) (advi	(73) + (advisory-	+ (3) = (76) sory-related subset)) Including Normal Battery Depletion	7.99.7 1/0.+	99.4 +.1/1	98.4 +.1/1	96.8 +.2/2	90.2 +.4/4	64.7 +.7/7	5.6 +.7/7		

continued

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Malfunctions
continued
Device Survival Summary

Device Survival Probability (%)

		5		5		Malfunctions			ר שטואסת		ODADIILY	(70)					
e: Medtronic C		təxhatkət əssə	jistered stnslqml	bətemi VU əvi stnalo	rnal Battery snoitaic	riapy Function mpromised iction Not pormised	le		Years Aft	Years After Implant	÷						
	Family		I SN ɓəy	†2Å		an JoJ	toT		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr 8	8 yr	10 yr
7275	GEM III DR	Nov-00	20,000	400	4,250	11 + 28 =	39	Excluding Normal Battery Depletion	9.99 /0.+	99.9 +.0/1	99.8 +.1/1	99.8 +.1/1	99.7 +.1/1	99.7 +.1/1			
tration	<u>See page 156</u> – Performance note on ICD Battery Discharge Behavior	– Performanc Iavior	e note on lC	CD Battery				Including Normal Battery Depletion	99.6 +.1/1	99.0 +.1/2	96.9 +.3/3	90.2 +.5/5	64.6 +1.0/-1.0	8.4 +1.0/9			
1278	Maximo DR	Oct-03	38,000	14,000	2,923	<mark>8</mark> + 37 =	45	Excluding Normal Battery Depletion	100.0 +.0/0	9.99 /0.+	9.99 /0.+	99.9 +.0/1	99.8 +.0/1	99.8 +.0/1	99.8 +.0/1 at 80 mo		
urp od Di	Advisories: <u>See page 145</u> – 2005 Potential Premature Battery Depletion <u>Due to Battery</u> Short	<u>ee page 145 –</u> e to Battery Sh	2005 Poten hort	tial Premature		(0) + (0) = (0) (advisory-related subset)	(0) bset)	Including Normal Battery Depletion	9.99 0/0.+	99.6 +.1/1	99.1 +.1/1	97.4 +.2/2	88.4 +.5/5	55.6 +1.1/-1.1	11.1 +2.4/-2.1 at 80 mo		
7288	Intrinsic	Aug-04	31,000	14,000	1,897	7 + 50 =	57	Excluding Normal Battery Depletion	100.0 +.0/0	9.99 /0.+	9.99 0/0.+	99.8 +.0/1	99.8 +.1/1	99.7 +.1/1	99.7 +.1/1 at 73 mo		
nalucia								Including Normal Battery Depletion	9.99 0/0.+	99.6 +.1/1	99.1 +.1/1	98.0 +.2/2	88.3 +.5/5	52.0 +1.9/-1.9	43.5 +2.6/-2.6 at 73 mo		
7290Cx	Onyx	Mar-04	1,000	500	51	+ + =	S	Excluding Normal Battery Depletion	99.9 +.1/7	99.5 +.3/8	99.5 +.3/8	99.4 +.4/9	99.4 +.4/9	99.4 +.4/9 at 69 mo			
								Including Normal Battery Depletion	99.8 +.2/7	98.8 +.5/-1.0	98.0 +.8/-1.2	96.5 +1.1/-1.6	91.1 +2.1/-2.7	74.5 +4.8/-5.7 at 69 mo			
D153ATG, D153DRG	EnTrust DR	Jun-05	500	100	26	1 + 7 =	ω	Excluding Normal Battery Depletion	99.8 +.2/-1.4	99.8 +.2/-1.4	99.2 +.5/-1.7	98.1 +1.0/-2.3	97.1 +1.5/-2.9				
								Including Normal Battery Depletion	99.5 +.3/-1.4	99.5 +.3/-1.4	97.8 +1.1/-2.2	89.2 +3.1/-4.2	51.2 +6.9/-7.3				
D154ATG, D154DRG	EnTrust DR	Jun-05	28,000	17,000	453	<mark>9</mark> + 73 =	82	Excluding Normal Battery Depletion	100.0 +.0/0	9.99 /0.+	99.8 +.0/1	99.7 +.1/1	99.5 +.1/1	99.5 +.1/1 at 64 mo			
Madt								Including Normal Battery Depletion	9.99 1/0.+	99.7 1/1.+	99.1 +.1/1	97.6 +.2/2	89.7 +.7/8	85.7 +1.3/-1.4 at 64 mo			
D154AWG (Non-advisory population)	Virtuoso DR	May-06	72,000	56,000	134	23 + 41 =	64	Excluding Normal Battery Depletion	100.0 +.0/0	9.99 0/0.+	9.99 0/0.+	99.7 1/1.+	99.7 +.1/1 at 52 mo				
M Drodu								Including Normal Battery Depletion	9.99 0/0.+	99.7 +.0/0	99.3 +.1/1	98.4 +.2/3	97.8 +.6/8 at 52 mo				

ICD Implantable Cardioverter Defibrillators, continued

Source: Medtronic Device Registration and Returned Product Analysis Data as of January 31, 2011

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Device Survival Summary continued

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	www.medtronic.com/CRDMProductPerformance

continued

Family Virtuoso DR May-06 4,000 US Implan Registere Registere US Marke Estimated Controso DR May-06 4,000 100 Active US Estimated Povice Longevity	Active US Constructions Constructions Constructions Constructions	۰ Therapy Function + Therapy 50 Compromised 50 Compromised	= 1,542 Total	Excluding Normal Battery Depletion Including Normal Battery Depletion	Years Af 1 yr +.0/0 99.9	Years After Implant 1 yr 2 yr 3 100.0 99.9 99 40.2 99.6 88 1,1/-2 14	nt 3 yr 90.4 +1.0/-1.1 +1.3/-1.4	4 yr 55.1 +1.9/-1.9 at 46 mo at 46 mo at 46 mo	5 yr	6 yr	7 yr	8 yr
See page 150 – Performance note on Anomalies in MOSFET Integrated Circuit Technology EnTrust VR Jun-05 14,000 9,000	omalies in 9,000 47	39 + 8	= 44	Excluding Normal Battery Depletion Including	9.99 1/0.+	99.9 +.0/1	99.8 +.1/1 99.2	99.7 1:-/1:+ 98.7	99.4 +.2/3	99.4 +.2/3 at 63 mo 97.0		
Virtuoso VR May-06 33,000 26,000 Advisories: See page 139 – 2009 Potential Reduced Device Longevity	26,000 32	11 + 10	= 21	Normal Battery Depletion Excluding Normal Battery Depletion Including Normal Battery Depletion	1.0.1 100.0 +.0/0 +.0/0 +.0/0	1/1.+ 0/0.+ 7.99 7.29	/+ 9.99 1/0.+ 9.96 1/1.+	99.9 +.0/-1 +.0/-1 +.1/-1	o/c.+	+.o./8 at 63 mo		
See page 150 – Performance note on Anomalies in MOSFET Integrated Circuit Technology Secura DR Aug-08 32,000 29,000	omalies in 29,000 24	4 + 4	∞	Excluding Normal Battery	100.0 +.0/0	99.9 +.1/-2	99.9 +1/2					
				Depletion Including Normal Battery Depletion	99.8 +.1/1	99.4 +.2/3	at 26 mo 99.4 +.2/3 at 26 mo					
12,000 11,	11,000 5	- +	ς, Π	Excluding Normal Battery Depletion	100.0 +.0/1	100.0 +.0/1	100.0 +.0/1 at 26 mo					
				Including Normal Battery Depletion	99.9 +.0/1	99.5 +.3/7	99.5 +.3/7 at 76m0					

		8 yr								
		7 yr								
		6 yr								
		5 yr								
(%)		4 yr								
obability	t	3 yr					100.0 +.0/0 at 26 mo	99.9 +.0/1 at 26 mo	99.9 +.0/1 at 26 mo	99.8 +.1/2 at 26 mo
Device Survival Probability (%)	Years After Implant	2 yr	100.0 +.0/0 at 14 mo	100.0 +.0/0 at 14 mo	100.0 +.0/0 at 14 mo	100.0 +.0/0 at 14 mo	100.0 +.0/0	99.9 +.0/1	99.9 +.0/1	99.8 +.1/2
Device S	Years Afr	1 yr	100.0 +.0/0	100.0 +.0/0	100.0 +.0/0	100.0 +.0/0	100.0 +.0/0	100.0 +.0/1	100.0 +.0/1	99.8 +.1/1
			Excluding Normal Battery Depletion	Including Normal Battery Depletion						
	le	тоt	0		0		-		m	
ions	ıction Not npromised	ru7 ToD	0 = 0		0 = 0		0 = 1		0 =	
Malfunctions	npromised	Cor The Fur Cor	II		II		II		П	
Malfunctions	npromised srapy detion Not bezimorqn	I9D ID ID ID ID ID ID ID ID ID ID ID ID ID	 0 +		= 0 +		= 0		 0 +	
Malfunctions	oletions prapy Function propy stron Not notron Sot	Act Imp Noi Dep The Coi Fur Fur	 0 + 0		 0 + 0		- -		 0 + m	
Malfunctions	ive US plants plants pletions pletions promised notion Not notion Sed	US Esti Imp Imp Imp Imp Imp Imp Imp Imp Imp Imp	 0 + 0 0		= 0 + 0		2 1 + 0 =		4 3 4 0 =	
Malfunctions	Implants ive US solatts plants plattons plations plations plations plation promised notion Not notion sed	Rel Rec US Esti Rod Moi Del Del The Coi The Coi	Aug-09 13,000 12,000 0 + 0 =		Aug-09 5,000 5,000 0 + 0 =		12,000 2 1 + 0 =		7,000 4 3 + 0 =	
Malfunctions	easee jistered mplants sitepy Function plants srapy mpromised mpromised mpromised	Rel Rec US Esti Rod Moi Del Del The Coi The Coi	13,000 12,000 0 + 0 =		5,000 5,000 0 + 0 =		13,000 12,000 2 1 + 0 =		8,000 7,000 4 3 + 0 =	

Source: Medtronic Device Registration and Returned Product Analysis Data as of January 31, 2011

Device Survival Summary continued

Reference Chart

The longevity estimates provided are mean values calculated for the parameters given. The actual longevity achieved for any device while implanted will depend on the actual programmed parameters and patient factors, and may differ significantly from these estimates.

					E	stimate	d Longe	vity		Elective	Replacement	
					در بر						ERI)***	End of Life
Model Number	Family	Connector Style	Volume/ Mass*	Delivered Energy	Charging Frequency**	100% Pacing‡	50% Pacing‡	15% Pacing‡	100% Sensing	Battery Voltage	Charge Time	Life (EOL) Battery Voltage
7227	GEM	B, Cx, D, E	49 cc* 90 g	35 J	Monthly Quarterly Semiannual	5.3 7.7 8.8	5.7 8.5 10.0	6.0 9.3 11.0	6.1 9.6 11.5	≤ 2.55 V	—	$\leq 2.40 V^{\S}$
7230	Marquis VR	B, Cx, E	36 cc 75 g	30 J	Monthly Quarterly Semiannual	4.9 7.3 8.5	5.2 8.0 9.3	5.4 8.5 10.0	5.5 8.7 10.4	≤ 2.62 V	> 16-second charge time	3 months after ERI
7231Cx	GEM III VR	Cx	39 cc 77 g	30 J	Monthly Quarterly Semiannual	4.3 6.0 6.6	4.7 6.8 7.5	5.0 7.4 8.5	5.2 7.8 8.9	≤ 2.55 V	_	≤ 2.40 V
7232	Maximo VR	B, Cx, E	39 cc 76 g	35 J	Monthly Quarterly Semiannual	4.4 7.0 8.2	4.7 7.5 9.0	4.8 8.0 9.7	4.9 8.3 10.0	≤ 2.62 V	> 16-second charge time	3 months after ERI
7271	GEM DR	DR	62 cc 115 g	35 J	Monthly Quarterly Semiannual	6.0 7.4 7.9	6.9 8.4 9.0	7.5 9.3 10.0	7.8 9.8 10.6	≤ 4.91 V	_	≤ 4.57 V [§]
7274	Marquis DR	DR+LV	36 cc 75 g	30 J	Monthly Quarterly Semiannual	4.0 5.6 6.2	4.4 6.4 7.2	4.8 7.1 8.1	4.9 7.5 8.6	≤ 2.62 V	> 16-second charge time	3 months after ERI
7275	GEM III DR	DR	39.5 cc 78 g	30 J	Monthly Quarterly Semiannual	3.3 4.2 4.5	3.8 5.0 5.5	4.3 5.8 6.5	4.4 6.3 7.0	≤ 2.55 V	—	≤ 2.40 V
7278	Maximo DR	DR	39 cc 77 g	35 J	Monthly Quarterly Semiannual	3.7 5.3 6.0	4.1 6.1 7.0	4.3 6.8 8.0	4.5 7.1 8.5	≤ 2.62 V	> 16-second charge time	3 months after ERI
7288	Intrinsic	DR	38 cc 76 g	35 J	Monthly Quarterly Semiannual	3.7 5.4 6.1	4.1 6.1 7.0	4.3 6.8 8.0	4.5 7.1 8.5	≤ 2.62 V	> 16-second charge time	3 months after ERI
7290Cx	Onyx	Сх	39 cc 77 g	30 J	Monthly Quarterly Semiannual	3.8 5.0 5.4	4.1 5.6 6.1	4.3 6.2 6.7	4.5 6.4 7.0	≤ 2.55 V	> 16-second charge time	≤ 2.40 V

* Volume and mass differ by connector style.

 ** A full charge is a full energy the rapeutic shock or capacitor reformation.

*** The minimum time between ERI and EOL is 3 months (100% pacing, two charges per month).

‡ Pacing mode is VVI for single chamber models and DDD for dual chamber and CRT models. Parameter settings; lower rate at 60 ppm, sensing rate at 70 bpm, (A, RV, LV) 3.0 V amplitude, 0.4 ms pulse width, and 510-ohm pace load per applicable channel. CRT models with shared biventricular pacing; InSync Marquis 7277 (LV impedance set to 510 ohms), InSync ICD 7272 (RV amplitude set to 4.0 V).

§ For Model 7271 and 7227 devices, if charge time exceeds 30 seconds, the device is at EOL. Immediate replacement is recommended. If three consecutive charge cycles exceed 30 seconds, the "charge circuit inactive" indicator is tripped and all therapies except emergency VVI pacing are disabled.

continued

Reference Chart continued

						stimate	d Longe	vity		Repl	nmended acement RT)***	
Model Number	Family	Connector Style	Volume/ Mass*	Delivered Energy	Charging Frequency**	100% Pacing‡	50% Pacing‡	15% Pacing‡	100% Sensing	Battery Voltage	Charge Time	End of Service (EOS)
D153ATG, D153DRG	EnTrust	DR	33 cc 63 g	30 J	Monthly Quarterly Semiannual	3.5 4.8 5.3	3.8 5.4 6.1	4.1 6.0 6.9	4.2 6.3 7.2	≤ 2.61 V	_	3 months after RRT or > 16-second charge time
D154ATG, D154DRG	EnTrust	DR	35 cc 68 g	35 J	Monthly Quarterly Semiannual	3.8 5.5 6.1	4.2 6.1 7.0	4.4 6.8 7.9	4.6 7.0 8.3	≤ 2.61 V	_	3 months after RRT or > 16-second charge time
D154AWG, D164AWG	Virtuoso	DR	37 cc 68 g	35 J	Monthly Quarterly Semiannual	4.1 6.3 7.3	4.5 7.3 8.7	4.8 8.3 10.1	5.0 8.8 11.0	≤ 2.62 V	_	3 months after RRT or > 16-second charge time
D154VRC	EnTrust	Cx	35 cc 68 g	35 J	Monthly Quarterly Semiannual	4.8 7.5 9.0	5.0 8.3 10.0	5.2 8.8 10.7	5.3 9.0 11.0	≤ 2.61 V	_	3 months after RRT or > 16-second charge time
D154VWC, D164VWC	Virtuoso	Cx	37 cc 68 g	35 J	Monthly Quarterly Semiannual	4.8 8.1 10.0	5.1 9.0 11.2	5.3 9.6 12.3	5.4 10.0 12.9	≤ 2.62 V	_	3 months after RRT or > 16-second charge time
D224DRG	Secura DR	DR	37 cc 68 g	35 J	Monthly Quarterly Semiannual	3.60 5.07 5.70	4.08 6.05 7.00	4.50 7.00 8.27	4.67 7.50 9.00	≤ 2.63 V	_	3 months after RRT or > 16-second charge time
D224VRC	Secura VR	Cx	37 cc 68 g	35 J	Monthly Quarterly Semiannual	4.33 6.67 7.76	4.67 7.45 8.85	4.92 8.05 9.79	5.00 8.41 10.25	≤ 2.63 V	_	3 months after RRT or > 19-second charge time
D274DRG	Virtuoso II DR	DR	37 cc 68 g	35 J	Monthly Quarterly Semiannual	3.6 5.0 5.7	4.0 6.0 7.0	4.5 7.0 8.3	4.7 7.5 9.0	≤ 2.63 V	_	3 months after RRT or > 16-second charge time
D274VRC	Virtuoso II VR	Cx	37 cc 68 g	35 J	Monthly Quarterly Semiannual	4.3 6.7 7.8	4.7 7.5 8.9	4.9 8.0 9.8	5.0 8.4 10.3	≤ 2.63 V	_	3 months after RRT or > 19-second charge time
D284DRG	Maximo II DR	DR	37 cc 68 g	35 J	Monthly Quarterly Semiannual	3.60 5.07 5.70	4.08 6.05 7.00	4.50 7.00 8.27	4.67 7.50 9.00	≤ 2.63 V	_	3 months after RRT or > 16-second charge time
D284VRC	Maximo II VR	Cx	37 cc 68 g	35 J	Monthly Quarterly Semiannual	4.33 6.67 7.76	4.67 7.45 8.85	4.92 8.05 9.79	5.00 8.41 10.25	≤ 2.63 V	_	3 months after RRT or > 19-second charge time

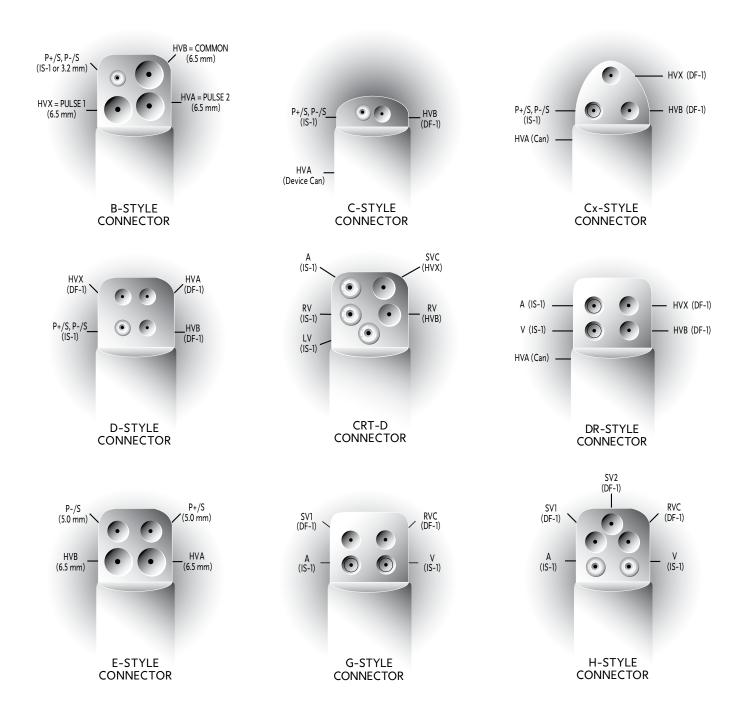
* Volume and mass differ by connector style.

** A full charge is a full energy therapeutic shock or capacitor reformation.

*** The minimum time between RRT and EOS is 3 months (100% pacing, two charges per month).

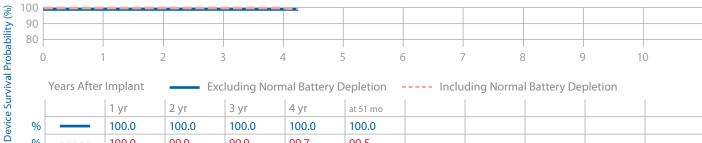
[‡] Pacing mode is VVI for single chamber models and DDD for dual chamber models. Parameter settings; lower rate at 60 ppm, sensing rate at 70 bpm, (A, RV, LV) 3.0 V amplitude, 0.4 ms pulse width, and 510-ohm pace load per applicable channel.

ICD Connector Styles



Adapta DR ADDR01, ADDR03, ADDR06, ADD01

				DDDR, DDD
Registered US Implants 232,000	Therapy Function Not Compromised	23	Serial Number Prefix	PWB, PWD,
Estimated Active US Implants 189,000	Electrical Component	23		PWC, PWF, NWB, NWC,
Normal Battery Depletions (US) 54	Therapy Function Compromised	13		NWD
Performance Note: <u>See page 148</u> – Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI	Electrical Component	13	Estimated Longevity	See page 73



a a			Tyr	2 yr	3 yr	4 yr	at 51 mo			
evic	%		100.0	100.0	100.0	100.0	100.0			
Ω	%		100.0	99.9	99.9	99.7	99.5			
	#		160,000	96,000	44,000	5,000	200			
		Effective Sam	ple Size							

Adapta DR ADDRL1

S Mar	ket Release		Jul-06	5 Malfun	ctions (US)			3	NBG Coo	le		DDDR
egiste	ered US Implant	ts	35,000) Thera	py Function No	ot Compromise	d	2	Serial Nu	ımber Prefix		PWE, NWE
stimat	ted Active US In	mplants	30,000) El	ectrical Compo	nent		2				
lormal	l Battery Deple	tions (US)	3	3 Therapy Function Compromised				1	Estimated Longevity			See page 7
erforn	nance Note: <u>Seo</u> nance note on [akers with Meas		up ERI	El	ectrical Intercor	nnect		1				
100 🗖												
90												
90 80 0	1	2	. 3		4 5	5 (5	7	8	3	9	10
80	Years After				4 5 mal Battery [4 yr		-	7 ludin		3 Il Battery De	-	10
80		Implant	——— Exc	luding Norr	mal Battery [-	7 ludin			-	10
80 - 0		Implant 1 yr	Exc	luding Norr 3 yr	mal Battery [4 yr		-	7 ludin			-	10

Product Characteristics

3	NBG Code	DDDR
2	Serial Number Prefix	PWE, NWE
2		
1	Estimated Longevity	See page 73
1		

Adapta DR ADDRS1				Product Characterist	ics
US Market Release	Jul-06	Malfunctions (US)	2	NBG Code	SSIR
Registered US Implants	22,000	Therapy Function Not Compromised	1	Serial Number Prefix	PWA
Estimated Active US Implants	17,000	Electrical Component	1		
Normal Battery Depletions (US)	22	Therapy Function Compromised	1	Estimated Longevity	See page 73
Performance Note: See page 148 – Performance note on Dual Chamber Pacemakers with Measurement Lock-up Ef		Electrical Component	1		
00 00 100 00 1 2					
	3	4 5 6	7	8 9	10

Irviva		Years After	Implant	E>	Excluding Normal Battery Depletion Including Normal Battery Depletion								
e Su			1 yr	2 yr	3 yr	4 yr	at 49 mo						
evic	%		100.0	100.0	100.0	100.0	100.0						
Δ	%		100.0	99.8	99.7	97.7	97.7						
	#		14,000	8,000	4,000	400	200						
		Effective Sam	ple Size										

Adapta SR ADSR01, ADSR03, ADSR06

·										
JS Market Release		Jul-	06 Ma	alfunctions (US)			2	NBG Code		SSIR
Registered US Implants		43,0	00 T	herapy Function	Not Compromi	sed	0	Serial Number	Prefix	NWN, NWM,
Estimated Active US Imp	plants	32,0	00 T	herapy Function	Compromised		2		NWP	
Normal Battery Depletic	ons (US)		18	Electrical Component			1	Estimated Long	See page 73	
Advisories		No	ne	Electrical Interc	connect		1			
90 80										
80 0 1 Vears After In %	1 yr 100.0	Ex 2 yr 100.0	3 yr 100.0	4 Normal Battery 4 yr 100.0	at 50 mo	6	7 Includir	8 ng Normal Bat	9 tery Deplet	10 ion
80 1 Vears After In %	1 yr	Ex 2 yr	cluding 1 3 yr	Normal Battery	/ Depletion at 50 mo		7 Includir			

01						Produc	t Character	ristics	
	Jul-06 M	alfunctions (US)			0	NBG Cod	le		VDO
	1,000 T	herapy Function N	ot Compromise	d	0	Serial Number Prefix		PWG, NWG	
s	1,000 T	herapy Function C	ompromised		0	Estimate	d Longevity		See page 7
JS)	0								
148 – namber ent Lock-up ERI									
2	3	4	5	6	7	8	3	9	10
ant2 yr	Excluding	Normal Battery	Depletion	Incl	udin	g Norma	l Battery De	epletion	
.0 100.0	100.0	100.0							
.0 100.0	100.0	100.0							
400	200	100							

AT500 AT501, 7253

-		-									
IS Mar	ket Release		Mar-	03 M	lalfunctions (US)			10	NBG Code		DDDRP
egiste	ered US Implan	nts	11,0	00 1	Therapy Function N	ot Compromis	ed	5	Serial Number Prefix		IJF
stimat	ted Active US I	mplants	5	00	Electrical Compo	nent		2	Estimated Longevity	,	See page 7
lormal	Battery Deple	etions (US)	2,0	44	Possible Early Ba	ttery Depletior	I	3			
		ee page 154		1	Therapy Function Co	ompromised		5			
erforn ystem	nance note on Follow-Up Pro	AT500 Pacing otocol			Electrical Compo	nent		3			
					Electrical Interco	nnect		1			
					Possible Early Ba	ttery Depletion		1			
100											
90											
80											
70											
60											
50							•				
40											
30											
20											
10											
0						-					
0)	1	2	3	4	5	6	7	8	9	10
	Years After	r Implant	Ex	cluding	Normal Battery	Depletion	Ir	cluding	g Normal Battery	Depletion	
		1 yr	2 yr	3 yr	4 yr	5 yr	бyr	at 7	78 mo		
%		100.0	100.0	100.0	99.9	99.9	99.9	99	.9		
%		99.9	99.8	99.4	97.3	82.2	42.5	4.1			
#		10,000	9,000	8,000	7,000	5,000	1,000	100)		
	Effective Sam	nple Size									

Pulse DR E1DR01, E1DR03, E	1DR06				Product Characte	ristics	
JS Market Release	Dec-03	Malfunctions (US)		1	NBG Code		DDDR
Registered US Implants	7,000	Therapy Function N	ot Compromised	1	Serial Number Prefix		PRA
Estimated Active US Implants	3,000	Electrical Compo	onent	1	Estimated Longevity		See page
Normal Battery Depletions (US)	180	Therapy Function Co	ompromised	0			
Performance note on Dual Chamber Pacemakers with Measurement Lock-up	ERI		++				
90							
80				•			

	Years After	r Implant	E	Excluding Normal Battery Depletion Including Normal Battery Depletion									
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	at 82 mo					
%		100.0	100.0	100.0	100.0	100.0	100.0	100.0					
%		100.0	100.0	99.8	99.1	98.2	96.4	84.6					
#		6,000	6,000	5,000	4,000	4,000	3,000	300					
	Effective Sam	ple Size											

EnPulse DR E1DR21

US Market Release	Dec-03	Malfunctions (US)	0	NBG Code	DDDR
Registered US Implants	2,000	Therapy Function Not Compromised	0	Serial Number Prefix	PPT
Estimated Active US Implants	mated Active US Implants 100		0	Estimated Longevity	See page 73
Normal Battery Depletions (US)	250				
Performance Note: <u>See page 148</u> – Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI					
90					

() ()												
(%) A	90											
bility	30											
bab	70											
Pro	50											
_	50							<u>``</u>				
ž	40											
S	30							Ч				
vice							-					0
De	()	I .	2 :	3 4	4 .		о	/ 8	5) 1	0
		Years After	Implant	Exc	cluding Norn	nal Battery D	epletion	Inclu	iding Norma	l Battery De	pletion	

		1 yr	2 yr	3 yr	4 yr	5 yr	бyr	at 78 mo		
%		100.0	100.0	100.0	100.0	100.0	100.0	100.0		
%		99.9	99.6	98.9	96.4	91.9	60.3	32.7		
#		2,000	1,000	1,000	1,000	1,000	400	100		
	Effective Sam	ole Size								

Product Characteristics

42 Medtronic CRDM Product Performance Report www.medtronic.com/CRDMProductPerformance

EnPulse 2 DR E2DR01, E2DR03, E2DR06

US Market Release	Feb-04	Malfunctions (US)	20	NBG Code	DDDR
Registered US Implants	101,000	Therapy Function Not Compromised	16	Serial Number Prefix	PNB, PNC, PN
Estimated Active US Implants	55,000	Electrical Component	14		
Normal Battery Depletions (US)	659	Possible Early Battery Depletion	2	Estimated Longevity	See page 73
Performance Note: See page 148 –		Therapy Function Compromised	4		
Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI		Battery	1		
rucentalers with medsalentent book up en		Electrical Component	2		
		Electrical Interconnect	1		
- 100					
£ 90					

Product Characteristics

Product Characteristics

%)	90											
lity												
abi	80											
qo		0	1	2	3	4	5	6	7	8) 1	0
al Pi				_								
٧i		Years After	r Implant	E>	cluding Nor	mal Battery	Depletion	Incl	uding Norma	al Battery De	pletion	

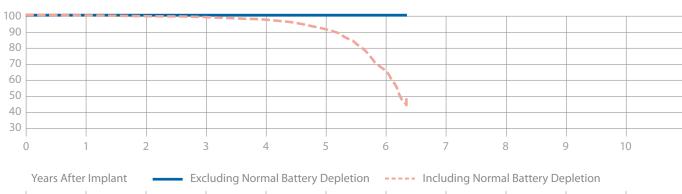
≦											
e Su			1 yr	2 yr	3 yr	4 yr	5 yr	бyr	at 80 mo		
evice	%		100.0	100.0	100.0	100.0	100.0	100.0	100.0		
ă	%		100.0	99.9	99.8	99.5	98.7	96.7	90.9		
	#		91,000	81,000	73,000	64,000	38,000	12,000	200		
		Effective Sam	ole Size								

EnPulse 2 DR E2DR21

US Market Release	Feb-04	Malfunctions (US)	1	NBG Code	DDDR
Registered US Implants	12,000	Therapy Function Not Compromised	0	Serial Number Prefix	PMU
Estimated Active US Implants	5,000	Therapy Function Compromised	1	Estimated Longevity	See page 73
Normal Battery Depletions (US)	586	Electrical Component	1		
Performance Note: See page 148 – Performance note on Dual Chamber					

Pacemakers with Measurement Lock-up ERI





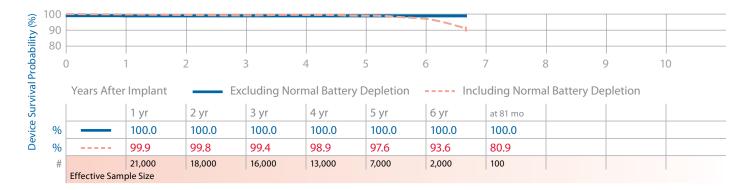
		1 yr	2 yr	3 yr	4 yr	5 yr	бyr	at 76 mo		L
%		100.0	100.0	100.0	100.0	100.0	100.0	100.0		
%		99.9	99.6	99.2	97.6	91.3	65.3	44.5		
#		11,000	9,000	8,000	7,000	4,000	1,000	100		
	Effective Sam	ple Size								

ruise 2	DR E2DR31, E2	2DR33						Product Cha	racteristi	CS	
JS Market R	Release	Fe	b-04	Malfunctions (US)			0	NBG Code			DDDR
Registered L	US Implants	1	,000	Therapy Function	Not Compromise	d	0	Serial Number P	refix		PNL
Estimated A	Active US Implants		300	Therapy Function	Compromised		0	Estimated Long	evity		See page 7
Normal Batt	tery Depletions (US)		1								
Performance	e Note: <u>See page 148</u> e note on Dual Chamb with Measurement Lo	ber									
100											
90											
100											
90	1	2	3	4	5 6	6	7	8	9		0
90 80 0	1 ars After Implant	_	-	4 g Normal Batter	_	-	7 uding	8 Normal Batte	-		0
90 80 0	1 ars After Implant 1 yr	_	-		_	-	7 uding	-	-		0
90 80 0			Excludin	g Normal Batter 4 yr	y Depletion	Inclu	7 uding	-	-		0
90 90 80 0 Yea	1 yr	2 yr	Excludin	g Normal Batter 4 yr 0 100.0	y Depletion 5 yr	at 64 mo	7 uding	-	-		10

EnPulse 2 SR E2SR01, E2SR03, E2SR06

Effective Sample Size

US Market Release	Dec-03	Malfunctions (US)	4	NBG Code	SSIR
Registered US Implants	25,000	Therapy Function Not Compromised	3	Serial Number Prefix	PMW, PMY,
Estimated Active US Implants	11,000	Electrical Component	2		PNA
Normal Battery Depletions (US)	257	Possible Early Battery Depletion	1	Estimated Longevity	See page 7
Advisories	None	Therapy Function Compromised	1		
		Other	1		



JS Mar	rket Release		Dec	-03 N	Malfunctions (US)			0	NBG Code		VDD
Registe	ered US Implan	ts	1,	000	Therapy Function	n Not Compromi	sed	0	Serial Number P	refix	PMV
stima	ated Active US I	mplants		300	Therapy Function	n Compromised		0	Estimated Longe	evity	See page 7
lorma	al Battery Deple	tions (US)		20							
Perforr	mance Note: <u>Se</u> mance note on nakers with Mea	Dual Chamber	-up ERI								
100 90 80	0	1	2	3	4	5	6	7	8	9	10
90 80	0 Years After	1 Implant			4 Normal Batter			7	8 g Normal Batte	-	
90 80	-	1 Implant 1 yr						7 :ludin		-	
90 80	-		_ — E	xcluding	Normal Batter	ry Depletion	Inc	7 :ludin		-	
90 80 (-	1 yr	2 yr	xcluding 3 yr	Normal Batter 4 yr 100.0	ry Depletion 5 yr	at 66 mo	7 :ludin		-	

EnRhythm DR P1501DR

EnRhy	thm DR	P1501DR							Product Ch	aracteristic	S
US M	arket Release		May-05	Malfu	nctions (US)			114	NBG Code		DDDRP
Regis	tered US Implan	its	103,000	Ther	apy Function	Not Comprom	nised	77	Serial Number	Prefix	PNP
Estim	ated Active US I	mplants	72,000		Battery			48	Estimated Lon	igevity	See page 73
Norm	al Battery Deple	etions (US)	75		(33 malfunct Electrical Co	<i>ions related to c</i> omponent	advisory)	11			
	risories: See page 138 – 2010 Low Battery age Displayed at Device Interrogation formance Note: <u>See page 150</u> – malies in MOSFET Integrated			Possible Early Battery Depletion			letion	18			
			Ther	Therapy Function Compromised			37				
		T Integrated		Electrical Co	omponent		34				
	uit Technology				Electrical In	terconnect		2			
ity (%) 06 (%)					Possible Ear	ly Battery Dep	letion	1			
Device Survival Probability (%)	0 Years After		2 3	uding Nor	4 rmal Batter	5 y Depletion	6	7 ncludin	8 Ig Normal Bat	9 ttery Deplet	10 tion
ie St		1 yr	2 yr	3 yr	4 yr	5 yr	at 67 mo				
% evic		100.0	100.0	99.9	99.8	99.7	99.6				
□ %	% 100.0 99.9			99.8	99.5	98.9	97.8				
#				47,000	32,000	8,000	100				
	Effective Sample Size										

Kappa 400 DR KDR401, KDR403

DDD/RO **US Market Release** Jan-98 Malfunctions (US) 23 NBG Code PER, PET **Registered US Implants** 47,000 **Therapy Function Not Compromised** 13 Serial Number Prefix 9 Estimated Active US Implants 2,000 Estimated Longevity **Electrical Component** See page 73 Normal Battery Depletions (US) 7,035 **Electrical Interconnect** 1 Advisories None Possible Early Battery Depletion 2 Other 1 **Therapy Function Compromised** 10 **Electrical Component** 7 Electrical Interconnect 3 100 Device Survival Probability (%) 90 80 70 60 50 40 30 20 10 0 2 3 5 7 0 1 4 6 8 9 Excluding Normal Battery Depletion Years After Implant ----- Including Normal Battery Depletion

		1 yr	2 yr	3 yr	4 yr	5 yr	бyr	7 yr	8 yr	at 101 mo
%		100.0	100.0	100.0	100.0	99.9	99.9	99.9	99.9	99.9
%		99.9	99.9	99.7	99.5	98.9	96.8	86.1	46.9	6.5
#		42,000	38,000	34,000	30,000	27,000	22,000	16,000	5,000	1,000
	Effective Sam	ole Size								

Kappa 400 SR KSR401, KSR403

10 0 0

Product Characteristics

Product Characteristics

ippa 400 Sh KSR401, KSR40	15			Product Characteristics	
US Market Release	Feb-98	Malfunctions (US)	5	NBG Code	SSI/R
Registered US Implants	15,000	Therapy Function Not Compromised	4	Serial Number Prefix	PEU, PGD
Estimated Active US Implants	1,000	Electrical Component	3	Estimated Longevity	See page 7
Normal Battery Depletions (US)	1,290	Possible Early Battery Depletion	1		
Advisories	None	Therapy Function Compromised	1		
		Electrical Interconnect	1		
100					
80 70					
70					
60					
50 40					
40					
30					
20					

Years After Implant

2

3

4

6

7

5

Excluding Normal Battery Depletion
 Including Normal Battery Depletion

9

10

8

		1 yr	2 yr	3 yr	4 yr	5 yr	бyr	7 yr	8 yr	9 yr	at 110 mo
%		100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0
%		99.9	99.8	99.6	99.1	98.5	96.9	90.4	64.3	20.7	9.4
#		13,000	11,000	10,000	9,000	7,000	6,000	4,000	2,000	300	100
	Effective Sample Size										

1

Kappa 600 DR KDR601, KDR603, KDR606

	_						
	US Ma	rket Release		Jan-99	Malfunctions (US)		
	Regist	ered US Implant	s	24,000	Therapy Function	n Not Compromise	ed
	Estima	ted Active US In	nplants	2	Electrical Cor	nponent	
	Norma	l Battery Deple	tions (US)	3,495	Therapy Function	n Compromised	
	Fractu – 2009 Perfori	red Power Supp		so page 140	Electrical Con Electrical Inte (34 malfunctio		ory)
			urement Lock-up	o ERI			
%	100						1 m m m
ž	90						
bili	80						
Device Survival Probability (%)	70						
Pre	60						
iva	50						
un.	40						
e	30						
evi	20						
	20 10						
	10						

Product Characteristics

39

34

NBG Code	DDD/RO
Serial Number Prefix	PHF, PHH, PHG
Estimated Longevity	See page 73

00 90										
80										
70										
60							· · · ·			
50										
40										
30										
20										
10		 						1		
0								· · · · ·		
0			1		1		1			
(0	2 3	3 4	4 !	5 6)	/ 8	3 .) 1	0

Years After Implant _____ Excluding Normal Battery Depletion _---- Including Normal Battery Depletion

		1 yr	2 yr	3 yr	4 yr	5 yr	бyr	7 yr	8 yr	at 106 mo
%		100.0	100.0	100.0	99.9	99.9	99.9	99.8	99.7	99.6
%		99.9	99.9	99.8	99.5	98.8	96.8	87.6	57.0	7.3
#		21,000	19,000	17,000	15,000	13,000	12,000	9,000	4,000	300
	Effective Sam	ple Size								

Mar-01

14,000

100

2,087

Kappa 600 DR KDR651, KDR653

US Market Release

Interconnect Wires

Registered US Implants

Estimated Active US Implants

Normal Battery Depletions (US)

Performance Note: See page 148 –

Advisories: See page 146 – 2002 Potential Fractured Power Supply Wires; See also page 140 – 2009 Potential Separation of

Product Characteristics

Malfunctions (US)	33	NBG Code		DDD/RO
Therapy Function Not Compromised	2	Serial Number Prefix		PLJ, PLK
Electrical Component	1	Estimated Longevity	,	See page 73
Possible Early Battery Depletion	1			
Therapy Function Compromised	31			
Electrical Component	1			
Electrical Interconnect (22 malfunctions related to advisory)	30			
		×.		

Device Survival Probability (%)

0											
0											
)											
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)								<u> </u>			
)								<u> </u>			
)								- N			
								1			
)									<u>i</u>		
)											
)											
	1	2	2	4	- -	6	-	8		9	10

3 yr 4 yr 7 yr 8 yr 1 yr 2 yr 5 yr бyr at 101 mo % 100.0 100.0 100.0 100.0 100.0 99.9 99.7 99.5 99.4 % 99.9 99.9 99.8 99.4 98.1 94.7 80.3 40.7 6.0 11,000 10,000 7,000 5,000 2,000 200 # 13,000 9,000 8,000 **Effective Sample Size**

Карра 700 D КD701, КD703, КD706

	US Mar	ket Release		Jan-	99 Ma	functions (US)			0	NBG Cod	de	ſ	DD
	Registe	ered US Implant	ts	3	00 Tł	erapy Function N	ot Compromise	d	0	Serial Nu	umber Prefix	F	PH
	Estimat	ted Active US Ir	nplants		40 Tł	erapy Function Co	ompromised		0	Estimate	ed Longevity	9	Se
	Norma	l Battery Deple	tions (US)		17							-	
	Fractur page 1	ries: <u>See page</u> ed Power Supp 1 <u>40</u> – 2009 Pote nnect Wires	oly Wires; See a	lso									
	Perforn Pacema	nance Note: <u>Se</u> nance note on I akers with Meas	Dual Chamber	up ERI									
(%)	100						+			N 1			
ility	90												_
robab	80 08)	1	2	3	4	5 (5	7	1	8	9 10)
Device Survival Probability (%)		Years After	Implant	E×	cluding N	ormal Battery	Depletion	Inclu	uding	g Norma	al Battery De	pletion	
ie Sl			1 yr	2 yr	3 yr	4 yr	5 yr	бyr	7 yr		at 93 mo		
evio	%		100.0	100.0	100.0	100.0	100.0	100.0	100	.0	100.0		
Δ	%		100.0	100.0	100.0	99.0	97.8	95.3	93.9	9	88.9		
	#		300	200	200	200	200	100	100		100		

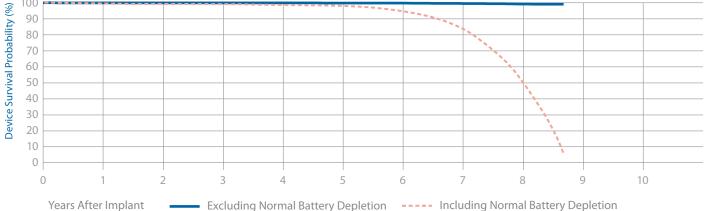
Effective Sample Size

Product Characteristics

DDD PHK See page 74

Kappa 700 DR KDR701, KDR703, KDR706

US Market Release	Feb-99	Malfunctions (US)	478	NBG Code	DDD/RO
Registered US Implants	192,000	Therapy Function Not Compromised	31	Serial Number Prefix	PGU, PGY,
Estimated Active US Implants	21,000	Battery	1		PGW
Normal Battery Depletions (US)	25,384	Electrical Component	24	Estimated Longevity	See page 74
Advisories: See page 146 – 2002 Poter	ntial	Electrical Interconnect	1		
Fractured Power Supply Wires; See also	_	Possible Early Battery Depletion	3		
page 140 – 2009 Potential Separation of Interconnect Wires	of	Other	2		
Performance Note: See page 148 –		Therapy Function Compromised	447		
Performance note on Dual Chamber Pacemakers with Measurement Lock-up E	RI	Electrical Component	15		
racemakers with measurement Lock-up L	iu	Electrical Interconnect (348 malfunctions related to advisory)	431		
		Possible Early Battery Depletion	1		
100					



		I						5		I
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	at 104 mo
%		100.0	100.0	99.9	99.9	99.9	99.8	99.7	99.5	99.3
%		99.9	99.8	99.6	99.1	98.0	95.1	83.9	50.7	5.0
#		173,000	156,000	139,000	123,000	105,000	85,000	58,000	22,000	2,000
	Effective Sam	ole Size								

Kappa 700 DR KDR721

US Market Release	Feb-99	Malfunctions (US)
Registered US Implants	10,000	Therapy Function Not Compromised
Estimated Active US Implants	0	Electrical Component
Normal Battery Depletions (US)	1,314	Therapy Function Compromised
Advisories: See page 146– 2002 Potential Fractured Power Supply Wires; See also		Electrical Interconnect (4 malfunctions related to advisory)

page 140 – 2009 Potential Separation of Interconnect Wires

Performance Note: See page 148 -Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI

Product Characteristics

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4

NBG Code	DDD/RO
Serial Number Prefix	PGR
Estimated Longevity	See page 74
	<u>bee page / i</u>

90						
80						
70						
60	 				 	
50						
40						
30						
20				 N		
10				-!		
0						1

Excluding Normal Battery Depletion ----- Including Normal Battery Depletion Years After Implant

				-	-						
		1 yr	2 yr	3 yr	4 yr	5 yr	бyr	7 yr	at 85 mo		
%		100.0	100.0	100.0	100.0	99.9	99.9	99.9	99.9		
%		99.9	99.6	98.8	96.6	90.8	68.2	19.7	13.7		
#		8,000	7,000	6,000	5,000	4,000	2,000	300	200		
	Effective Sample Size										

Kappa 700 SR KSR701, KSR703, KSR706

NBG Code US Market Release Feb-99 Malfunctions (US) 28 SSI/R **Registered US Implants** 55,000 **Therapy Function Not Compromised** 3 Serial Number Prefix PHT, PHW, PHU Estimated Active US Implants 5,000 **Electrical Component** 2 Normal Battery Depletions (US) 4,193 Possible Early Battery Depletion 1 Estimated Longevity See page 74 Advisories: See page 140 – 2009 Potential Separation of Interconnect Wires **Therapy Function Compromised** 25 **Electrical Component** 4 Electrical Interconnect 21 100 Device Survival Probability (%) 90 80 70 60 50 40 30 20 10 0 2 3 4 5 6 8 9 10 Years After Implant Excluding Normal Battery Depletion ----- Including Normal Battery Depletion 3 yr 4 yr 5 yr бyr 7 yr 8 yr 9 yr 1 yr 2 yr at 110 mo % 100.0 100.0 100.0 100.0 100.0 100.0 99.9 99.8 99.8 99.8 % 99.9 99.7 99.4 98.6 97.0 93.4 56.7 83.2 17.6 8.4 # 46,000 39,000 33,000 28,000 22,000 17,000 11,000 5,000 1,000 200 **Effective Sample Size**

Карра 700 VDD куррлот

S Mar	rket Release			Jan-99	Malfund	tions (US)			4	NBG Cod	le		VDD/RO
egiste	ered US Implar	nts		2,000	Therap	y Function N	lot Compromise	ed	0	Serial Nu	ımber Prefix		PHP
tima	ted Active US I	Implants		20	Therap	y Function C	ompromised		4	Estimate	d Longevity		See page
Normal Battery Depletions (US)		ery Depletions (US) 1/			167 Electrical Interconnect				4				
actur age terco erforr erforr	red Power Sup 140 – 2009 Pot onnect Wires mance Note: Se mance note on	tential Separati ee page 148 – Dual Chamber asurement Lock	also on of		(4 r.	nalfunctions r	elated to advisor	y)					
00											1		
90									_				
80									_				
70													
60													
50										<u> </u>			
40										<u>`\</u>			
30													
(ן ר	1	2	3	2	1	5	6	7		3	9	10
%	Years Afte	r Implant 1 yr 99.9 99.7	2 yr 99.9 99.7		9	nal Battery 4 yr 99.8 98.9	Depletion 5 yr 99.8 98.5	-	ludir 7 1 99	ng Norma yr 9.6	al Battery Do at 94 mo 99.6 39.7	-	
% #													
#	Effective Sam	1,000	1,000	1,00	0	1,000	1,000	1,000	40	0	100		

52 Medtronic CRDM Product Performance Report www.medtronic.com/CRDMProductPerformance **Product Characteristics**

Kappa 800 DR KDR801, KDR803

US Market Release	Jan-02
Registered US Implants	4,000
Estimated Active US Implants	1,000
Normal Battery Depletions (US)	349

Malfunctions (US) **Therapy Function Not Compromised Therapy Function Compromised** Electrical Interconnect

Product Characteristics

3

0

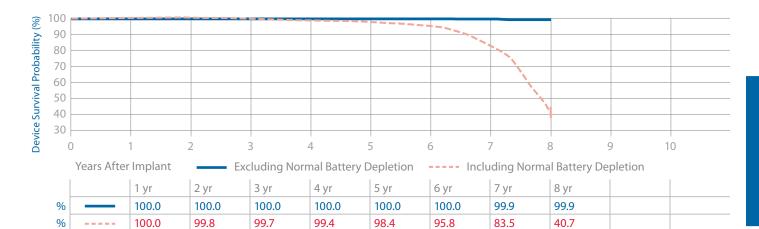
3

3

NBG Code	DDD/RO
Serial Number Prefix	PKW, PKY
Estimated Longevity	See page 74

Performance Note: See page 148 -Performance note on Dual Chamber

Pacemakers with Measurement Lock-up ERI



2,000

2,000

1,000

28,000

5,000

100

Product Characteristics

Kappa 900 DR	KDR901, KDR903,	KDR906
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4,000

Effective Sample Size

#

#

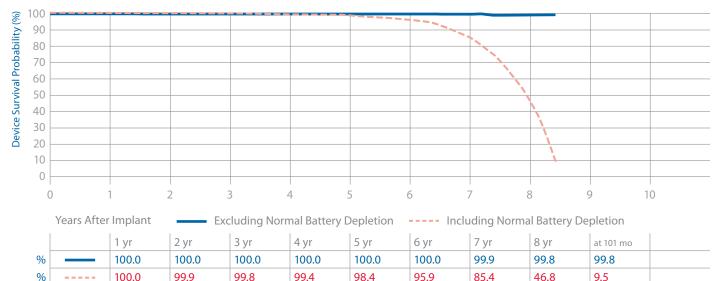
6

3,000

3,000

3,000

US Market Release	Jan-02	Malfunctions (US)	66	NBG Code	DDD/RO
Registered US Implants	125,000	Therapy Function Not Compromised	15	Serial Number Prefix	PKM, PKN, PKP
Estimated Active US Implants	40,000	Electrical Component	14		
Normal Battery Depletions (US)	7,689	Electrical Interconnect	1	Estimated Longevity	See page 74
Performance Note: See page 148 –		Therapy Function Compromised	51		
Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI		Electrical Component	9		
racemakers with measurement Lock-up Eki		Electrical Interconnect	42		



65,000

49,000

Source: Medtronic Device Registration and Returned Product Analysis Data as of January 31, 2011

101,000

91,000

80,000

113,000

Effective Sample Size

300

Kappa 900 SR KSR901, KSR903, KSR906

US Market Release Jan-02 Malfunctions (US) 16 NBG Code VVEV **Registered US Implants** 37,000 **Therapy Function Not Compromised** 8 Serial Number Prefix PLF, PLG, PLH Estimated Active US Implants 10,000 **Electrical Component** 7 Normal Battery Depletions (US) Estimated Longevity 1,391 Possible Early Battery Depletion See page 74 1 **Therapy Function Compromised** See page 140 – 2009 Potential 8 Separation of Interconnect Wires Electrical Interconnect 8 100 Device Survival Probability (%) 90 80 70 60 50 40 30 20 0 2 3 4 5 6 7 8 9 10 Years After Implant **Excluding Normal Battery Depletion** ----- Including Normal Battery Depletion 1 yr 2 yr 3 yr 4 yr 5 yr бyr 7 yr 8 yr at 101 mo 100.0 100.0 100.0 100.0 100.0 99.9 99.9 99.8 99.8 % % 99.9 99.7 99.5 98.8 97.3 94.3 83.4 49.2 26.7 # 30,000 26.000 22.000 19.000 13,000 9,000 5,000 1.000 100

Kappa 900 VDD KVDD901

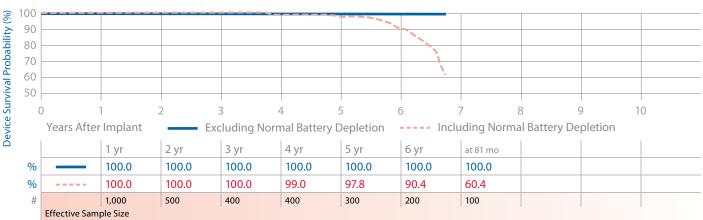
Effective Sample Size

US Market Release	Jan-02	Malfunctions (US)	0	NBG Code	VDD
Registered US Implants	1,000	Therapy Function Not Compromised	0	Serial Number Prefix	PLE
Estimated Active US Implants	50	Therapy Function Compromised	0	Estimated Longevity	See page 74
Normal Battery Depletions (US)	73				

See page 140 – 2009 Potential Separation of Interconnect Wires

Performance Note: See page 148 -Performance note on Dual Chamber

Pacemakers with Measurement Lock-up ERI



Product Characteristics

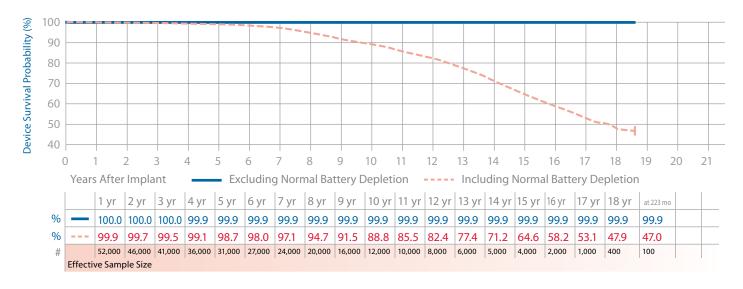


Kappa 920 DR KDR921 **Product Characteristics US Market Release** Jan-02 Malfunctions (US) 4 NBG Code VVEV **Registered US Implants** 16,000 **Therapy Function Not Compromised** 1 Serial Number Prefix PLF, PLG, PLH Estimated Active US Implants 1,000 **Electrical Component** 1 Normal Battery Depletions (US) 2,312 **Therapy Function Compromised** 3 Estimated Longevity See page 74 See page 140 – 2009 Potential Electrical Interconnect 3 Separation of Interconnect Wires Performance Note: See page 148 -Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI 100 Device Survival Probability (%) 90 80 70 60 50 40 30 20 10 0 2 5 3 6 7 8 9 10 4

	Years After Implant		Exc	luding Norm	al Battery D	epletion -	Including Normal Battery Depletion				
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	at 82 mo			
%		100.0	100.0	100.0	100.0	100.0	99.9	99.9			
%		99.9	99.7	99.2	97.1	89.8	58.7	7.4			
#		14,000	12,000	11,000	9,000	7,000	3,000	200			
	Effective Sam	ple Size									

Legend II 8424, 8426, 8427

US Market Release	Nov-91	Malfunctions (US)	34	NBG Code	SSIRO
Registered US Implants	58,000			Serial Number Prefix	2P, 2T, 2U
Estimated Active US Implants	2,000			Estimated Longevity	See page 74
Normal Battery Depletions (US)	2513				
Advisories	None				



Medtronic CRDM Product Performance Report 55 www.medtronic.com/CRDMProductPerformance

Minix/Minix ST 8340, 8341, 8341M, 8342, 8330, 8331, 8331M

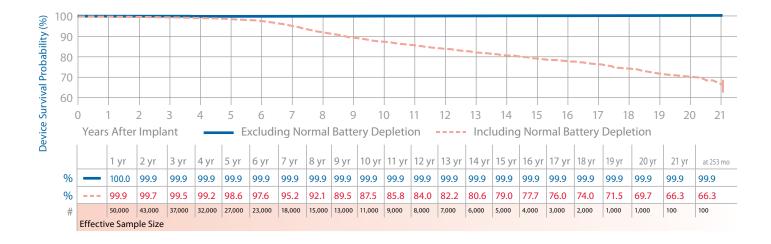
US Market Release	Dec-89
Registered US Implants	58,000
Estimated Active US Implants	3,000
Normal Battery Depletions (US)	1,702
Advisories: See page 147- 1991 P	otential Delayed

Product Characteristics

Product Characteristics

50	NBG Code	SSIRO
	Serial Number Prefix	2P, 2T, 2U
	Estimated Longevity	See page 74

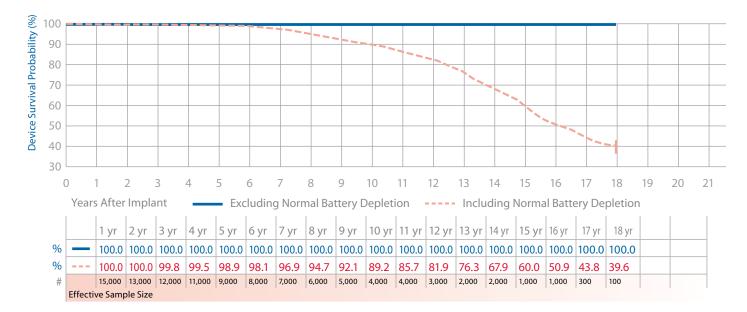
Advisories: See page 147– 1991 Potential Delayed Restoration of Permanent Settings

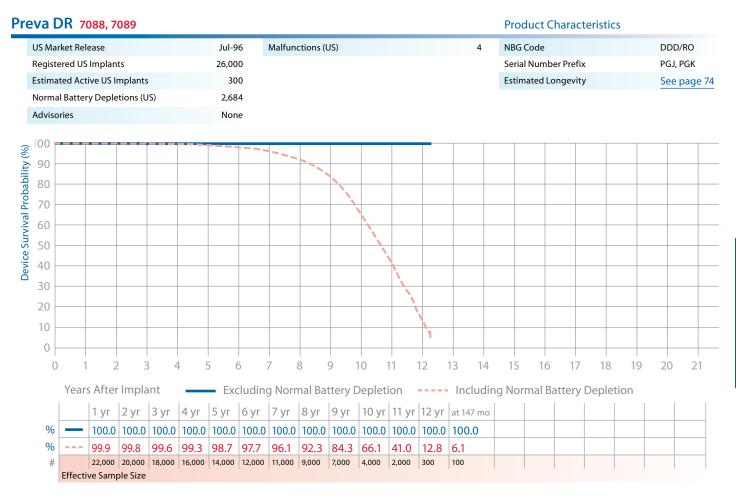


Malfunctions (US)

Minuet 7107, 7108

US Market Release	Mar-92	Malfunctions (US)	4	NBG Code	DDDCO
Registered US Implants	17,000			Serial Number Prefix	1Z1, 2G1
Estimated Active US Implants	1,000			Estimated Longevity	See page 74
Normal Battery Depletions (US)	922				
Advisories	None				



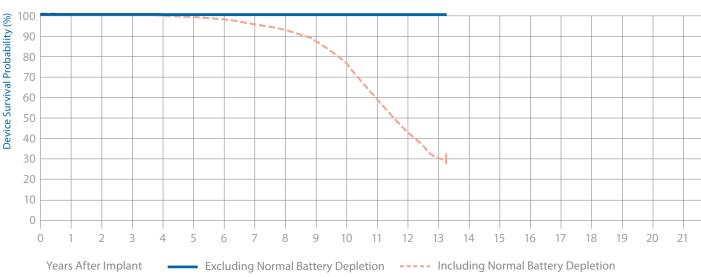


DG

IPG Implantable Pulse Generators, continued

Preva SR 8088, 8089

Product Characteristics Malfunctions (US) SSI/R US Market Release Jul-96 1 NBG Code **Registered US Implants** 18,000 Serial Number Prefix PGL, PGM Estimated Active US Implants 1,000 Estimated Longevity See page 74 Normal Battery Depletions (US) 1,006 Advisories None

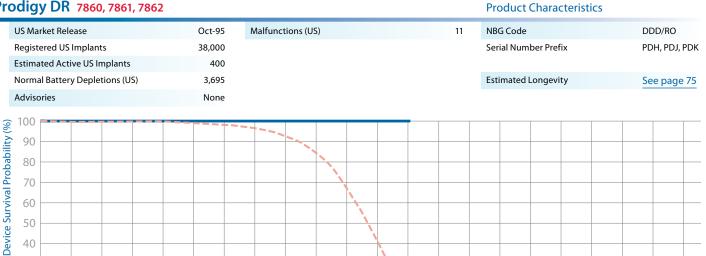


		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	11 yr	12 yr	13 yr	at 159 mo				
%		100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0				
%		99.9	99.8	99.4	99.0	98.2	97.2	94.8	91.9	86.9	74.7	58.3	42.2	29.2	28.7				
#		15,000	12,000	11,000	9,000	8,000	6,000	5,000	4,000	3,000	2,000	1,000	1,000	200	100				
	Effecti	ve Samp	ole Size																

Prevail S 8085, 8086

Pr	evail	S 80	85, 80	86													Produc	t Cha	racte	eristic	S			
	US Ma	rket Rele	ease				Oct-9	5	Malfun	ctions (l	JS)				1	1	NBG Coc	le				SS		
	Regist	ered US	Implant	ts			4,00	0									Serial Nu	ımber f	Prefix			PG	L, PGM	
	Estima	ted Acti	ive US Ir	nplants			40	0									Estimate	d Long	jevity			Se	e page	74
	Norma	l Batter	y Deple	tions (U	S)		4	8																
	Adviso	ories					Non	e																
(%	100			_	_				_		_	_	_			1								
Device Survival Probability (%)	90										+	·			<u> </u>									
lide	80													[[]	1-1									
rob	00																							
/al P	70																							
irviv	() 1		2 3	3 4	4	5	6	7	8	9 .	10 1	11	12	13 1	14	15	16	17	18	19	20	21	
e SL		Year	After	Impla	nt		- Exc	luding	n Norn	nal Bat	tterv [)enleti	ion		Inclu	Idina	Norma	l Ratt	erv [Denlet	ion			
evio									-						1	1	1					I.	1	
			1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	11 yr	12 yr	13 yr	at 164	no		_					
	%		100.0	100.0	100.0	100.0	99.9	99.9	99.9	99.9	99.9	99.9	99.9	99.9	99.9	99.9			_					
	%		99.8	99.8	99.7	99.7	99.0	98.8	98.0	97.1	95.3	93.2	89.8	89.0	87.3	86.5	;							
	#			3,000	2,000	2,000	1,000	1,000	1,000	1,000	1,000	1,000	500	400	200	100								
		Effectiv	ve Samp	Die Size																				





Years After Implant Excluding Normal Battery Depletion ----- Including Normal Battery Depletion -

		1 yr	2 yr	3 yr	4 yr	5 yr	бyr	7 yr	8 yr	9 yr	10 yr	11 yr	12 yr					
%	—	100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0					
%		99.9	99.8	99.7	99.3	98.7	97.9	96.3	92.3	84.4	67.9	41.5	4.3					
#		33,000	30,000	27,000	24,000	21,000	19,000	16,000	13,000	10,000	6,000	2,000	100					
	Effective Sample Size																	

Prodiav SR 8158, 8160, 8161, 8162

Pro	odig	y SR	8158,	, 8160,	, 8161,	8162											Prod	uct Ch	naract	eristi	CS		
	US Ma	rket Rele	ease				Oct-9	5	Malfun	ctions (l	JS)					4	NBG C	ode				SS	I/R
	Regist	ered US	Implant	ts			22,00	0									Serial I	Numbe	r Prefix				M, PED, PEE,
	Estima	ted Acti	ive US Ir	mplants			1,00	0														PE	:F
	Norma	l Batter	y Deple	tions (U	S)		1,21	5									Estima	ted Lor	ngevity			Se	ee page 75
	Adviso	ries					Non	e															
(%	100																-1						
Device Survival Probability (%)	90																						
lide	80																						
Prob											<u> </u>												
val F	70																						
urvi	60																						
ce S	50																		_	_			
Devi	40																		_	_			
	30																		_	_			
	20														1				_				
	() 1	2	2 3	4	- 5	5 6	5 7	' 8	9) 10	ہ 11 0	1 12	2 13	14 3 14	1	15	16	17	18	19	20	21
		Years	s After	Impla	nt		Exc	luding	g Norn	nal Ba	ttery [Deplet	ion		Inclu	Iding	g Norn	nal Ba	ttery	Deple	etion		
			1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	11 yr	12 yr	13 yr	at 161 n	10						
	%		100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.	0						
	%		99.8	99.6	99.2	98.6	97.7	96.5	94.7	91.5	86.0	73.9	59.7	44.7	31.5	27.9							
	#			16,000	14,000	12,000	10,000	8,000	7,000	5,000	4,000	3,000	2,000	1,000	200	100							
		Effectiv	ve Samp	ole Size																			

Source: Medtronic Device Registration and Returned Product Analysis Data as of January 31, 2011

Sensia DR SEDR01, SED01

US Market Release	Jul-06	Malfunctions (US)	7	NBG Code	DDD, DDDR
Registered US Implants	84,000	Therapy Function Not Compromised	5	Serial Number Prefix	PWL, PWK,
Estimated Active US Implants	67,000	Electrical Component	5		NWL
Normal Battery Depletions (US)	27	Therapy Function Compromised	2	Estimated Longevity	See page 75
Performance Note: <u>See page 148</u> – Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI		Electrical Component	2		

100 Device Survival Probability (%) 90 80 5 9 0 2 3 4 6 7 8 10 Years After Implant **Excluding Normal Battery Depletion** ----- Including Normal Battery Depletion 1 yr 2 yr 3 yr 4 yr at 50 mo 100.0 % 100.0 100.0 100.0 100.0 % 100.0 99.8 99.7 99.4 100.0 # 34,000 1,000 200 58,000 15,000 Effective Sample Size

Sensia SR SESR01, SES01

Product Characteristics

US Market Release	Jul-06	Malfunctions (U	S)		2	NBG Code		SSIR, SSI
Registered US Implants	55,000	Therapy Funct	ion Not Compr	omised	1	Serial Number Prefi	ix	PWR, PWS,
Estimated Active US Implants	40,000	Electrical C	omponent		1			NWR
Normal Battery Depletions (US)	23	Therapy Funct	ion Compromi	sed	1	Estimated Longevit	ty	See page 7
Advisories	None	Electrical Ir	nterconnect		1			
90								
80								
0 1	2 3	4	5	6	7	8	9	10
Years After Implant	Exclud	ing Normal Bat	tery Depletio	on	Including	Normal Battery	Depletion	

Su			Ι.	L _	1 -	Ι.		1	1	
<u>e</u>			1 yr	2 yr	3 yr	4 yr	at 49 mo			
ev	%		100.0	100.0	100.0	100.0	100.0			
	%		100.0	99.9	99.8	99.4	99.4			
	#		35,000	19,000	8,000	1,000	300			
		Effective Sam	ple Size							

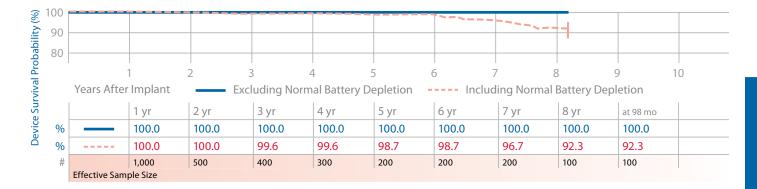
gma 100 S SS103, SS106				Product Characteristics
US Market Release	Aug-99	Malfunctions (US)	0	NBG Code
Registered US Implants	1,000	Therapy Function Not Compromised	0	Serial Number Prefix
Estimated Active US Implants	100	Therapy Function Compromised	0	Estimated Longevity

Estimated Active US Implants	100
Normal Battery Depletions (US)	16

SSI PJG, PJH Estimated Longevity See page 75

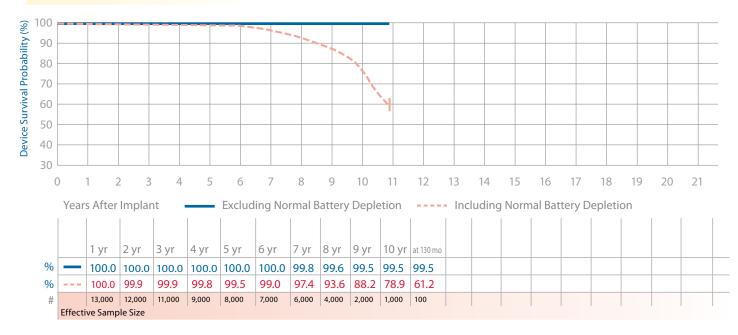
Product Characteristics

Separation of Interconnect Wires



Sigma 200 DR SDR203

Malfunctions (US)	29	NBG Code	DDD/RO
Therapy Function Not Compromised	1	Serial Number Prefix	PJD
Electrical Component	1	Estimated Longevity	See page 75
Therapy Function Compromised	28		
Electrical Component	1		
Electrical Interconnect (19 malfunctions related to advisory)	27		
	Therapy Function Not Compromised Electrical Component Therapy Function Compromised Electrical Component Electrical Interconnect	Therapy Function Not Compromised1Electrical Component1Therapy Function Compromised28Electrical Component1Electrical Interconnect27	Therapy Function Not Compromised 1 Serial Number Prefix Electrical Component 1 Estimated Longevity Therapy Function Compromised 28 Electrical Component 1 Electrical Interconnect 27



Sigma 200 SR SSR203

US Market Release	Sep-99
Registered US Implants	12,000
Estimated Active US Implants	2,000
Normal Battery Depletions (US)	177

99 Malfunctions (US) 00 **Therapy Function Not Compromised** 00 **Therapy Function Compromised**

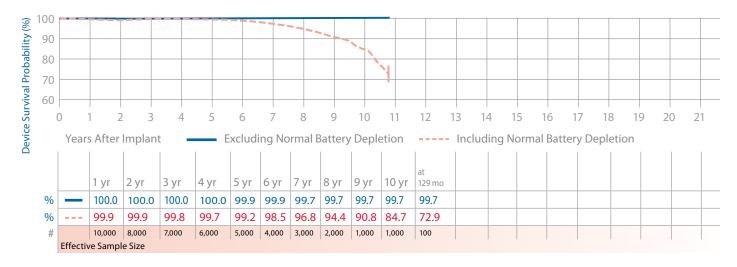
> **Electrical Interconnect** (12 malfunctions related to advisory)

Product Characteristics

13

13	NBG Code	SSI/R
0	Serial Number Prefix	PJG
13	Estimated Longevity	See page 75

Advisories: See page 144 – 2005 Potential Separation of Interconnect Wires; See also page 140 – 2009 Potential Separation of Interconnect Wires



Sigma 300 DR SDR303, SDR306

Product Characteristics Aug-99 US Market Release Malfunctions (US) 190 NBG Code DDD/RO **Registered US Implants** 107,000 **Therapy Function Not Compromised** Serial Number Prefix PJD, PJE 6 **Estimated Active US Implants** 38,000 **Electrical Component** 5 **Estimated Longevity** See page 75 Normal Battery Depletions (US) 1,517 Possible Early Battery Depletion 1 Advisories: See page 144 – 2005 Potential **Therapy Function Compromised** 184 Separation of Interconnect Wires; See also Electrical Component 8 page 140 – 2009 Potential Separation of Interconnect Wires Electrical Interconnect 176 (107 malfunctions related to advisory) 100 Device Survival Probability (%) 90 80 70 60 5 8 0 2 3 6 9 10 11 12 13 15 17 18 19 21 14 16 20 Years After Implant **Excluding Normal Battery Depletion** ----- Including Normal Battery Depletion 9 yr 1 yr 2 yr 3 yr 4 yr 5 yr 6 yr 7 yr 8 yr 10 yr 11 yr % 100.0 100.0 100.0 99.9 99.9 99.9 99.7 99.5 99.5 99.5 99.5 % 99.9 99.9 99.8 99.6 99.3 98.8 97.7 94.8 89.7 81.4 62.4 73,000 62,000 50,000 39,000 28,000 18,000 10,000 4,000 200

92,000 82,000 **Effective Sample Size**

Sigma 300 SR SSR303, SSR306

-					
US Market Release	Sep-99	Malfunctions (US)	39	NBG Code	SSI/R
Registered US Implants	54,000	Therapy Function Not Compromised	1	Serial Number Prefix	PJG, PJH
Estimated Active US Implants	14,000	Electrical Component	1	Estimated Longevity	See page 75
Normal Battery Depletions (US)	559	Therapy Function Compromised	38		
Advisories: See page 144 – 2005 Poter	itial	Electrical Component	3		
Separation of Interconnect Wires; See al page 140 – 2009 Potential Separation o Interconnect Wires		Electrical Interconnect (24 malfunctions related to advisory)	35		

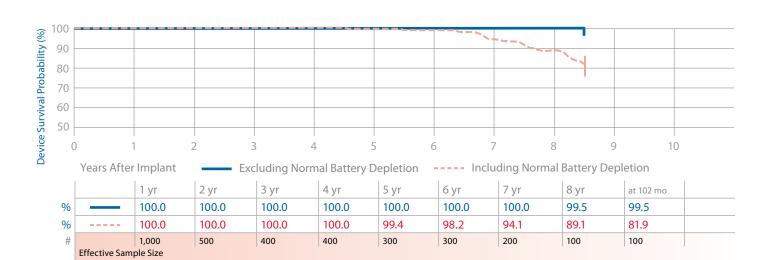
Product Characteristics

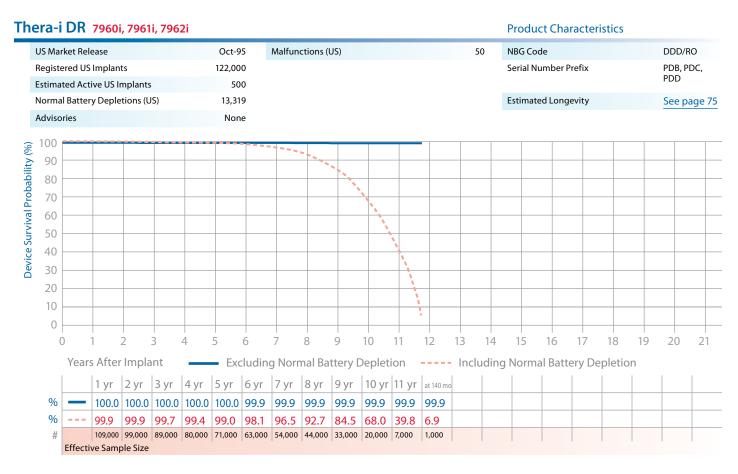
Product Characteristics

100 Device Survival Probability (%) 90 80 70 60 0 2 3 4 5 6 7 8 9 13 14 15 16 19 20 10 11 12 17 18 21 Years After Implant **Excluding Normal Battery Depletion** ----- Including Normal Battery Depletion at 2 yr 7 yr 9 yr 1 yr 3 yr 4 yr 5 yr бyr 8 yr 10 yr 130 mo % 100.0 100.0 100.0 100.0 100.0 99.9 99.8 99.7 99.7 99.7 99.7 99.5 % 99.9 99.9 99.7 99.2 98.5 97.1 94.4 89.8 82.2 66.3 # 43,000 36,000 30,000 24,000 18,000 14,000 9,000 6,000 3,000 1,000 100 **Effective Sample Size**

Sigma 300 VDD svDD303

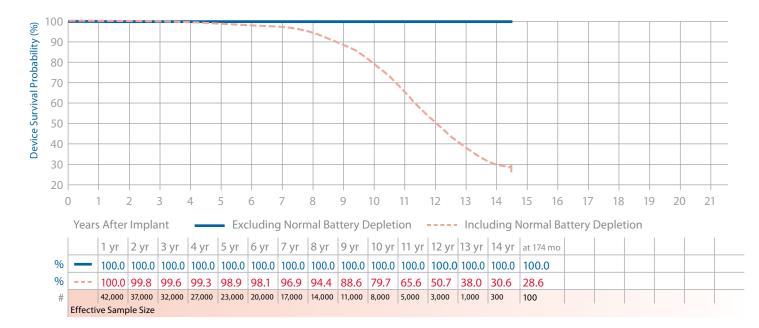
US Market Release Sep-99 Malfunctions (US) 1 NBG Code VDDD **Registered US Implants** 1,000 **Therapy Function Not Compromised** 0 Serial Number Prefix PJD Estimated Active US Implants Estimated Longevity 100 **Therapy Function Compromised** 1 See page 75 Normal Battery Depletions (US) 35 **Electrical Interconnect** 1 Advisories: See page 144 – 2005 Potential (1 malfunction related to advisory) Separation of Interconnect Wires

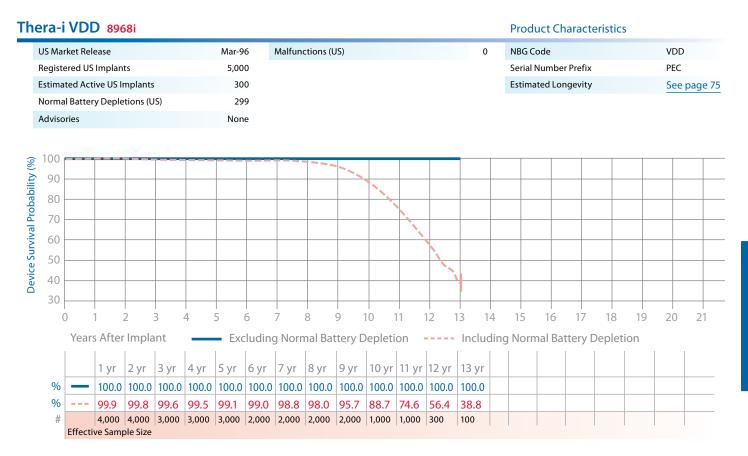




Thera-i SR 8960i, 8961i, 8962i

US Market Release	Oct-95 Ma	alfunctions (US)	7	NBG Code	SSIR
Registered US Implants	50,000			Serial Number Prefix	PDU, PDV,
Estimated Active US Implants	2,000				PDW
Normal Battery Depletions (US)	2,730			Estimated Longevity	See page 75
Advisories	None				





Versa DR VEDR01

US Market Release	Jul-06	Malfunctions	; (US)	6		NBG Code		DDDR
Registered US Implants	69,000	Therapy Fu	nction Not Compromise	d 4		Serial Number Prefi	x	PWH, NWH
Estimated Active US Implants	55,000	Electrica	al Component	4		Estimated Longevit	.y	See page 75
Normal Battery Depletions (US)	21	Therapy Fu	nction Compromised	2				
Performance Note: <u>See page 148</u> – Performance note on Dual Chamber Pacemakers with Measurement Lock-up	ERI	Electrica	al Component	2				
100								
90								
					7			10
	3 Exclue	4 ding Normal B	5 Sattery Depletion	6 Inclu	7 ding	8 Normal Battery	9 Depletion	10
	Exclue		1	-	7 ding	0	-	10
	Exclue 2 yr 3	ding Normal B	1	-	7 ding	0	-	10
90 90 80 0 1 2 Years After Implant 1 % 100.0 1	Exclue 2 yr 3 100.0 1	ding Normal B	r at 50 mo 0.0 100.0	-	7 ding	0	-	10

Source: Medtronic Device Registration and Returned Product Analysis Data as of January 31, 2011

Effective Sample Size

95%	letoT	36		m		7		7		0	
nfidence Interval) l estimates with 9 Malfunctions (US)	Compromised	П		Ш		Ш		Ш		Ш	
e Int ates	Therapy Function Not	23		5		-		0		0	
enc fun	Compromised	+		+		+		+		+	
nfid al es Mal	Therapy Function	13		-		-		7		0	
(95% Cc ce surviv	Vormal Battery Depletions (US)	54	Chamber	m	Chamber	22	Chamber	18		0	Chamber
nmary .IPG devi	bətemitz∃ Active US stnslqml	189,000	ote on Dual (.ock-up ERI	30,000	ote on Dual (-ock-up ERI	17,000	ote on Dual (_ock-up ERI	32,000		1,000	ote on Dual (.ock-up ERI
Device Survival Summary (95% Confidence Interval) The following table shows IPG device survival estimates with 95% included.	Registered 2U arisidaris	232,000	<u>See page 148</u> – Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI	35,000	<u>See page 148</u> – Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI	22,000	<u>See page 148</u> – Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI	43,000		1,000	<u>See page 148</u> – Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI
Survi wing tab	US Market Release	Jul-06	i j	Jul-06		Jul-06	<u>148</u> – Perf rs with Mea	Jul-06		Jul-06	148 – Perf rs with Me
Device The follov included.	Mumber Model	ADDR01, ADDR03, ADDR06,	See page 148 Pacemakers w	ADDRL1	<u>See page 148</u> – Pacemakers with	ADDRS1	See page Pacemake	ADSR01, ADSR03, ADSR06		ADVDD01 Jul-06	<u>See page 148</u> – Pacemakers with
	VlimeT	Adapta DR		Adapta DR		Adapta DR		Adapta SR		Adapta VDD	
бб Medtronic С	RDM Product Perf	ormance	Report			1			Source:	Medtro	nic Devi
	tronic.com/CRDI				e						

IPG Implantable Pulse Generators, continued

	included.					included. Malfunctions	nction	IS (US)			Device	Surviv	al Proba	Device Survival Probability (%)	()							
	lel Iber	larket ase	istered stnslqm	bəter ve US stnsi	nal Battery (SU) znoitel	rapy Function promised	rapy ction Not	ı ı		<u> </u>	Years A	Years After Implant	plant									
	nuN nuN	ələA V SU		itoA			unj		etoT		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	10 yr	12 yr	14 yr	16 yr
Adapta DR	ADDR01, ADDR03, ADDR06,	Jul-06	232,000	189,000	54		. 23	с П	36 No	Excluding Normal Battery Depletion	100.0 +.0/0	100.0 +.0/0	100.0 +.0/0	100.0 +.0/0	100.0 +.0/0 at 51 mo							
	<mark>See page 1</mark> Pacemaker	<u>48</u> – Perfo 's with Mea	ormance no surement L	<u>See page 148</u> – Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI	hamber				No	Including Normal Battery Depletion	100.0 +.0/0	9.99 +.0/-,0	9.99 +.0/0	99.7 +.1/.+	99.5 +.2/2 at 51 mo							
Adapta DR	ADDRL1	Jul-06	35,000	30,000	m	+	5		No	Excluding Normal Battery Depletion	100.0 +.0/0	100.0 +.0/0	100.0 +.0/0	100.0 +.0/0								
	<u>See page 1</u> Pacemaker	<u>48</u> – Perfo s with Mea	ormance no surement L	<u>See page 148</u> – Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI	hamber				No	Including Normal Battery Depletion	100.0 +.0/0	100.0 +.0/0	100.0 +.0/0	99.3 +.4/8								
Adapta DR	ADDRS1	Jul-06	22,000	17,000	22	+	.		2 Noi	Excluding Normal Battery Depletion	100.0 +.0/0	100.0 +.0/0	100.0 +.0/0	100.0 +.0/0	100.0 +.0/0 at 49 mo							
	<u>See page 1</u> Pacemaker	<u>48</u> – Perfo 's with Mea	ormance no surement L	<u>See page 148</u> – Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI	hamber				Ň	Including Normal Battery Depletion	100.0 +.0/0	99.8 +.1/1	99.7 +.1/2	97.7 +.9/-1.5	97.7 +.9/-1.5 at 49 mo							
Adapta SR	ADSR01, ADSR03, ADSR06	Jul-06	43,000	32,000	18	+	0		2 Noi	Excluding Normal Battery Depletion	100.0 +.0/0	100.0 +.0/0	100.0 +.0/1	100.0 +.0/1	100.0 +.0/1 at 50 mo							
									No	Including Normal Battery Depletion	100.0 +.0/0	100.0 +.0/0	99.8 +.1/1	99.5 +.2/3	99.5 +.2/3 at 50 mo							
Adapta VDD	ADVDD01	Jul-06	1,000	1,000	0	+	0	"	0 0	Excluding Normal Battery Depletion	100.0 +.0/0	100.0 +.0/0	100.0 +.0/0	100.0 +.0/0 at 39 mo								
	<mark>See page 1</mark> Pacemaker	<u>48</u> – Perfc s with Mea	ormance nc surement L	<u>See page 148</u> – Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI	hamber				No	Including Normal Battery Depletion	100.0 +.0/0	100.0 +.0/0	100.0 +.0/0	100.0 +.0/0 at 39 mo								
AT500	AT501, 7253	Mar-03	11,000	500	2,044	ب +	Ŀ O		10 No	Excluding Normal Battery Depletion	100.0 +.0/1	100.0 +.0/1	100.0 +.0/1	99.9 +.1/1	99.9 +.1/1	99.9 +.1/1	99.9 +.1/1 at 78 mo					
	<u>See page 1</u> System Fol	<mark>54</mark> – Perfoi low-Up Pro	rmance not otocol	See page 154 – Performance note on AT500 Pacing System Follow-Up Protocol	acing				No	Including Normal Battery Depletion	99.9 +.0/1	99.8 +.1/1	99.4 +.1/2	97.3 +.3/4	82.2 +.9/-1.0	42.5 +1.5/-1.5	4.1 +1.3/-1.1 at 78 mo					
EnPulse DR	E1DR01, E1DR03, E1DR06	Dec-03	7,000	3,000	180	+ 0	-	II	1 Noi	Excluding Normal Battery Depletion	100.0 +.0/0	100.0 +.0/0	100.0 +.0/1	100.0 +.0/1	100.0 +.0/1	100.0 +.0/1	100.0 +.0/1 at 82 mo					
	<mark>See page 1</mark> Pacemaker	<u>48</u> – Perfc s with Mea	ormance nc surement L	<u>See page 148</u> – Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI	hamber				No	Including Normal Battery Depletion	100.0 +.0/0	100.0 +.0/0	99.8 +.1/2	99.1 +.2/3	98.2 +.4/4	96.4 +.5/6	84.6 +2.1/-2.3 at 82 mo					
EnPulse DR	E1DR21	Dec-03	2,000	100	250	+	0		0 0	Excluding Normal Battery Depletion	100.0 +.0/0	100.0 +.0/0	100.0 +.0/0	100.0 +.0/0	100.0 +.0/0	100.0 +.0/0	100.0 +.0/0 at 78 mo					
	<u>See page 1</u> Pacemaker	48 – Perfo s with Mea	ormance no surement L	See page 148 – Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI	hamber				No	Including Normal Battery	99.9 +.1/4	99.6 +.2/5	98.9 +.4/7	96.4 +.9/-1.2	91.9 +1.4/-1.7	60.3 +3.3/-3.5	32.7 +4.4/-4.4					

Bit Bit State Sta						E	ואומוומווררוסו			E				1111					
3 3 3 4 5 7 5 7 5 7 5 7 5 7 5 7 5 7 5 7 5 7 5 7 5 7 5 7 1	۷lir			listered anglants	SU 9vi		npromised	ction Not besimorqu	le		Years A	ufter Imp	Jant						
Difficult Total and the state of the state	ns7			SU Səß	†2A		Cor	ru7 Cor	тоt		1 yr	2 yr	yr		 		 	 	16 yr
Exercise of endingeneration of the second of the	EnPulse 2 DR	E2DR01, E2DR03, E2DR06		101,000	55,000	659	+									00.0 .0/0 t 80 mo			
DR1 Feb dia 2000 1 1 0 0000<		<mark>See page</mark> Pacemake	- 148 – Perf ers with Mea	ormance nc asurement L	ote on Dual Cl Lock-up ERI	hamber										0.9 1.4/-1.6 t 80 mo			
Component of the function of the functin of the function of the function of the function of the functi	EnPulse 2 DR	E2DR21	Feb-04	12,000	5,000	586	+									00.0 .0/1 t 76 mo			
CR081 Fold 100 301 100 300		<mark>See page</mark> Pacemake	- 148 – Perf ers with Mea	ormance nc asurement L	ote on Dual Cl <u>-</u> ock-up ERI	hamber										14.5 3.8/-3.9 t 76 mo			
Separe IS - Performance on Dari form Separe IS - Information of the second	EnPulse 2 DR	E2DR31, E2DR33		1,000	300	-	+								 00.0 .0/0 t 64 mo				
		See page Pacemake	148 – Perf ers with Mea	ormance nc asurement L	ote on Dual Cf _ock-up ERI	hamber							_		00.0 .0/0 t 64 mo				
Problem <	EnPulse 2 SR	E2SR01, E2SR03, E2SR06	Dec-03	25,000	11,000	257	+									00.0 .0/0 t 81 mo			
EVDD1 Lot 20 $1 - 0$ $0 - 1$ <																0.9 3.7/-4.4 t 81 mo			
See page 143 - Performance note on Dual Chamber \cdot </td <td>EnPulse 2 VDD</td> <td>E2VDD01</td> <td></td> <td>1,000</td> <td>300</td> <td>20</td> <td>+</td> <td></td> <td></td> <th></th> <td>100.0 +.0/0</td> <td></td> <td></td> <td></td> <td>00.0 .0/0 t 66 mo</td> <td></td> <td></td> <td></td> <td></td>	EnPulse 2 VDD	E2VDD01		1,000	300	20	+				100.0 +.0/0				00.0 .0/0 t 66 mo				
Piotone Naves		<mark>See page</mark> Pacemake	- 148 – Perf ers with Mea	ormance nc asurement L	ote on Dual Cl Lock-up ERI	hamber)4.7 .2.7/-5.5 t 66 mo				
Advisories: Seepage 138 - 2010 Low Battery tologate $(0) + (33) = 33$ tologateIncluding topped to topped topped to topped topped $(0,0) + (0,0$	EnRhythm DR	P1501DR		103,000	72,000	75	+								99.6 .1/1 t 67 mo				
Geepge 150 - Performance note on anomalies in MOSFET Integrated Circuit Technology IO I IO		Advisorie Voltage D	ss: <u>See page</u> Visplayed at	<u>e 138</u> – 2010 Device Inte) Low Battery errogation		(0) + () (advisory-r		_)7.8 4/5 t 67 mo				
KDR401 Jan-98 47,000 7,035 10 + 13 = 23 Kextuating Depletion 100.0 100.0 100.0 99.9 99.9 99.9 99.9 99.9 99.9 99.9 99.9 99.9 99.9 99.9 99.9 99.9 99.9 90.0 1.00.0 <th1.00.0< th=""> <th1.00.0< th=""> <th1.00< td=""><td></td><td>See page MOSFET I₁</td><td>150 – Perfc ntegrated (</td><td>ormance no Circuit Techı</td><td>ite on anoma. nology</td><td>lies in</td><td></td><td></td><td></td><th></th><td></td><td></td><td></td><td></td><td> </td><td></td><td></td><td></td><td></td></th1.00<></th1.00.0<></th1.00.0<>		See page MOSFET I ₁	150 – Perfc ntegrated (ormance no Circuit Techı	ite on anoma. nology	lies in									 				
See page 148 - Performance note on Dual Chamber Including 99.9 99.9 99.7 99.5 98.6 86.1 46.9 Pacemakers with Measurement Lock-up ERI Nomal Battery +0/-0 +0/-1 +1/-1 +1/-1 +2/-2 +5/-5 +5/-	Kappa 400 DR	KDR401, KDR403		47,000	2,000	7,035	+								 		 99.9 0/0 it 101 mo		
KSR401,Feb-9815,0001,2901+4=5Excluding 10.0100.0100.0100.0100.0100.0100.0100.0KSR403PopletionP0.0P0.0P0.0P0.0P0.0P0.0P0.0P0.0P0.0P0.0P0.0KSR403P0.0P0.0P0.0P0.0P0.0P0.0P0.0P0.0P0.0P0.0P0.0P0.0KSR403P0.0P0.0P0.0P0.0P0.0P0.0P0.0P0.0P0.0P0.0P0.0KSR403P0.0P0.0P0.0P0.0P0.0P0.0P0.0P0.0P0.0P0.0P0.0KSR403P0.0P0.0P0.0P0.0P0.0P0.0P0.0P0.0P0.0P0.0P0.0P0.0KSR403P0.0P0.0P0.0P0.0P0.0P0.0P0.0P0.0P0.0P0.0P0.0KSR403P0.0P0.0P0.0P0.0P0.0P0.0P0.0P0.0P0.0P0.0P0.0KSR403P0.0P0.0P0.0P0.0P0.0P0.0P0.0P0.0P0.0P0.0P0.0P0.0KSR403P0.0P0.0P0.0P0.0P0.0P0.0P0.0P0.0P0.0P0.0P0.0KSR404P0.0P0.0P0.0P0.0P0.0P0.0P0.0P0.0P0.0P0.0P0.0KSR404P0.0P0.0P0.0P0.0		<mark>See page</mark> Pacemake	- 148 – Perf ers with Mea	ormance nc asurement L	ote on Dual Cl <u>'</u> ock-up ERI	hamber											5.5 8/8 it 101 mo		
Including Normal Battery Depletion 99.9 +0/-1 99.8 +1/-1 99.5 +1/-1 96.9 +2/-3 96.9 +4/-4 64.3 +1/5/16	Kappa 400 SR			15,000	1,000	1,290	+										00.0 0/1 it 110 mo		
	continued																9.4 -2.0/-1.8 it 110 mo	 	

Source: Medtronic Device Registration and Returned Product Analysis Data as of January 31, 2011

Medtronic CRDM Product Performance Report 67 www.medtronic.com/CRDMProductPerformance

Ddl

Device Survival Probability (%)

Malfunctions (US)

Device Survival Summary continued

IPG Implantable Pulse Generators, continued

						Malfunctions (US)		Device	Device Survival Probability (%)	al Probał	bility (%)								
λļiu	nber	tease Asse	istered stnslqm	bətem VU 9v stnsl	mal Battery (2U) znoiteld	rapy Function npromised ction Not opy npromised		Years	Years After Implant	olant									
mea		eleß		Acti		un∃ ∍dT no⊃		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	10 yr	12 yr	14 yr	16 yr
Kappa 600 DR	KDR601, KDR603, KDR606	Jan-99	24,000	5	3,495	36 + 3 = 39	Excluding Normal Battery Depletion	100.0 +.0/0	100.0 +.0/0	100.0 +.0/0	9.99 +.0/0	99.9 +.0/-1	99.9 +.0/1	99.8 +.1/1	99.7 +.1/1	99.6 +.1/2 at 106 mo			
	Advisories: <u>See page</u> 146–2002 Potential Fractured Power Supply Wires; <u>See also page</u> 140 – 2009 Potential Separation of Interconnect Wires	See page 1 ly Wires; <u>Se</u> paration of	46– 2002 se also pac Interconr	Potential Fra <u>je 140</u> – 200 rect Wires	actured)9	(34) + (0) = (34) (advisory-related subset)	Including Normal Battery Depletion	9.99 +.0/-,0	99.9 +.0/-,1	99.8 +.0/1	99.5 +.1/1	98.8 +.2/2	96.8 +.3/3	87.6 +.6/6	57.0 +1.1/-1.1	7.3 +1.1/-1.0 at 106 mo			
	See page 148 – Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI	8 – Perfori with Measu	mance no: urement L	te on Dual C ock-up ERl	hamber														
Kappa 600 DR	KDR651, I KDR653	Mar-01	14,000	100	2,087	31 + 2 = 33	Excluding Normal Battery Depletion	100.0 +.0/0	100.0 +.0/0	100.0 +.0/0	100.0 +.0/1	100.0 +.0/1	9.99 +.0/-,1	99.7 +.1/2	99.5 +.2/2	99.4 +.2/3 at 101 mo			
	Advisories: <u>See page</u> 146 – 2002 Potential Fractured Power Supply Wires; <u>See also page</u> 140 – 2009 Potential Separation of Interconnect Wires	See page 1 ly Wires; <u>Se</u> paration of	<u>46 – 2002</u> <u>se also pag</u> Interconr	Potential Fr je 140 – 200 rect Wires	actured 19	 (22) + (0) = (22) (advisory-related subset)) Normal Battery Depletion	99.9 +.0/-+	99.9 +.0/-,1	99.8 +.1/1	99.4 +.1/2	98.1 +.3/3	94.7 +.5/5	80.3 +.9/-1.0	40.7 +1.5/-1.5	6.0 +1.3/-1.1 at 101 mo			
	See page 148 – Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI	8 – Perfori with Measu	mance no: urement L	te on Dual C ock-up ERl	hamber														
Kappa 700 D	KD701, KD703, KD706	Jan-99	300	40	17	0 0 + 0	Excluding Normal Battery Depletion	100.0 +.0/0	100.0 +.0/0	100.0 +.0/0	100.0 +.0/0	100.0 +.0/0	100.0 +.0/0	100.0 +.0/0	100.0 +.0/0 at 93 mo				
	Advisories: <u>See page</u> 146–2002 Potential Fractured Power Supply Wires; <u>See also page</u> 140 – 2009 Potential Separation of Interconnect Wires	See page 1. ly Wires; Se paration of	46– 2002 se also pac Interconr	Potential Fra <u>je 140</u> – 200 rect Wires	actured)9	(0) + (0) = (0) (advisory-related subset)	Normal Battery Depletion	100.0 +.0/0	100.0 +.0/0	100.0 +.0/0	99.0 +.8/-3.1	97.8 +1.4/-3.5	95.3 +2.3/-4.5	93.9 +2.8/-4.9	88.9 +4.2/-6.5 at 93 mo				
	See page 148 - Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI	8 – Perfori with Measu	mance no: urement L	te on Dual C ock-up ERl	hamber														
Kappa 700 DR	KDR701, F KDR703, KDR706	Feb-99	192,000	21,000	25,384	447 + 31 = 478	Excluding Normal Battery Depletion	100.0 +.0/0	100.0 +.0/0	6.66 0/0.+	9.99 +.0/0	0:-/0:+	9.68 0/0.+	99.7 0/0.+	99.5 +.1/1	99.3 +.1/1 at 104 mo			
	Advisories: <u>See page</u> <u>146</u> – 2002 Potential Fractured Power Supply <u>Wires; See also page</u> <u>140</u> – 2009 Potential Separation of Interconnect Wires	See page 1 ly Wires; Se paration of	46 – 2002 se also paci Interconr	Potential Fr ge 140 – 200 rect Wires	actured 19	(348) + (0) = (348) (advisory-related subset)) Including Normal Battery Depletion	9.99 +.0/-,0	99.8 +.0/0	9.66 +.0/-,0	99.1 +.0/1	98.0 +.1/1	95.1 +.1/1	83.9 +.3/3	50.7 +.4/4	5.0 +.4/4 at 104 mo			
	See page 148 - Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI	8 – Perfori with Measu	mance no: urement L	te on Dual C ock-up ERl	hamber														
Kappa 700 DR	KDR721	Feb-99	10,000	0	1,314	4 + 1 = 5	Excluding Normal Battery Depletion	100.0 +.0/1	100.0 +.0/1	100.0 +.0/1	100.0 +.0/1	99.9 +.0/1	9.99 1/0.+	9.99 1/0.+	99.9 +.0/1 at 85 mo				
	Advisories: <u>See page</u> 146–2002 Potential Fractured Power Supply Wires; <u>See also page</u> 140 – 2009 Potential Separation of Interconnect Wires	See page 1 ly Wires; Se paration of	46- 2002 se also pac Interconr	Potential Fra ge 140 – 200 rect Wires	actured)9	(4) + (0) = (4) (advisory-related subset)	Including Normal Battery Depletion	99.9 +.0/-,1	99.6 +.1/2	98.8 +.2/3	96.6 +.4/5	90.8 +.7/8	68.2 +1.4/-1.5	19.7 +2.0/-1.9	13.7 +2.0/-1.9 at 85 mo				
	See page 148 - Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI	8 – Perfor with Measu	mance no	te on Dual C ock-up ERI	hamber														

Device Survival Summary continued

IPG Imp

Device Survival Probability (%)

Malfunctions

1	16 yr			.,											
	14 yr														
	12 yr														
	10 yr	99.8 +.1/1 at 110 mo	8.4 +1.1/-1.0 at 110 mo						99.8 +.1/1 at 101 mo	9.5 +1.2/-1.1 at 101 mo	99.8 +.1/2 at 101 mo	26.7 +3.1/-3.1 at 101 mo			
	8 yr	99.8 +.1/1	56.7 +.9/9	99.6 +.2/7 at 94 mo	39.7 +4.9/-4.9 at 94 mo		99.9 +.1/3	40.7 +4.1/-4.2	99.8 +.0/1	46.8 +.8/8	99.8 +.1/2	49.2 +1.9/-1.9			
	7 yr	99.9 +.0/1	83.2 +.6/6	99.6 +.2/7	69.9 +3.4/-3.7		99.9 +.1/3	83.5 +1.6/-1.7	9.99 9/0.+	85.4 +.3/3	99.9 +.0/1	83.4 +.8/8		100.0 +.0/0 at 81 mo	60.4 +6.5/-7.2 at 81 mo
	6 yr	100.0 +.0/0	93.4 +.3/3	99.6 +.2/7	94.1 +1.4/-1.7		100.0 +.0/3	95.8 +.7/9	100.0 +.0/0	95.9 +.2/2	99.9 +.0/1	94.3 +.4/4		100.0 +.0/0	90.4 +2.8/-3.9
	5 yr	100.0 +.0/0	97.0 +.2/2	99.8 +.1/5	98.5 +.6/9		100.0 +.0/0	98.4 +.4/5	100.0 +.0/0	98.4 +.1/1	100.0 +.0/0	97.3 +.2/2		100.0 +.0/0	97.8 +1.1/-2.1
	4 yr	100.0 +.0/0	98.6 +.1/1	99.8 +.1/5	98.9 +.5/8		100.0 +.0/0	99.4 +.2/3	100.0 +.0/0	99.4 +.0/1	100.0 +.0/0	98.8 +.1/2		100.0 +.0/0	99.0 +.6/-1.7
plant	3 yr	100.0 +.0/0	99.4 +.1/1	99.9 +.1/4	99.4 +.3/6		100.0 +.0/0	99.7 +.2/3	100.0 +.0/0	99.8 +.0/0	100.0 +.0/0	99.5 +.1/1		100.0 +.0/0	100.0 +.0/0
Years After Implant	2 yr	100.0 +.0/0	99.7 +.0/-	99.9 +.1/4	99.7 +.2/4		100.0 +.0/0	99.8 +.1/2	100.0 +.0/0	0/0.+	100.0 +.0/0	99.7 +.1/1		100.0 +.0/0	100.0 +.0/0
Years	1 yr	100.0 +.0/0	0:-/0:+	99.9 +.1/4	99.7 +.2/4		100.0 +.0/0	100.0 +.0/1	100.0 +.0/0	100.0 +.0/0	100.0 +.0/0	0:-/0:+		100.0 +.0/0	100.0 +.0/0
		Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion		Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion		Excluding Normal Battery Depletion	Including Normal Battery Depletion
le	toT	28	(0)	4	(4)		m		99		16			0	
ction Not npromised		"	=	"	=		"		ی ۱۱		"			"	
rapy	әчт	κ +	(0) +	0 +	(0) +		0 +		+		∞ +			0 +	
rapy Function promised		25	(0)	4	(4)		m		51		œ			0	
mal Battery Jetions		4,193	aration	167	ed ential	Ŀ	349	Ŀ	7,689	ū	1,391	connect	Ŀ	73	connect
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stnslqm	150	55,000	009 Pote		otentia e 140 – J	e on Dua ock-up El		e on Dua ock-up El	125,000	e on Dua ock-up El	37,000	eparatio	e on Dua ock-up El		eparatio
istered			<u>140</u> – 20	9 2,000	– 2002 F Ilso pag :t Wires	nce not ment Lc	2 4,000	nce not ment Lc		nce not ment Lc		ential Se	nce not ment Lc	1,000	ential Se
Narket Sase		Feb-99	Advisories: <u>See also page 140</u> – 2009 Potential Separation of Interconnect Wires	Jan-99	Advisories: <u>See page 146</u> – 2002 Potential Fractured Power Supply Wires; <u>See also page 140</u> – 2009 Potential Separation of Interconnect Wires	<u>See page 148</u> – Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI	Jan-02	<u>See page 148</u> – Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI	Jan-02	<u>See page 148</u> – Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI	, Jan-02	See page 140 – 2009 Potential Separation of Interconnect Wires	<u>See page 148</u> – Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI	Jan-02	See page 140 – 2009 Potential Separation of Interconnect Wires
		KSR701, KSR703, KSR706	Advisories: <u>See also pa</u> of Interconnect Wires	10	ies: <u>See</u> upply <u>M</u> ion of In	le 148 – kers witł		le 148 – kers with		le 148 – kers witł	KSR901, KSR903, KSR906	ge 140 .	le 148 – kers witł	10	ge 140 -
nber del	ooM nuN	KSR701, KSR703,	Advisor of Interc	KVDD701	Advisor Power S Separati	See pag Pacemal	KDR801, KDR803	See pag Pacemal	KDR901, KDR903, KDR906	<u>See pag</u> Pacema	KSR901 KSR906	See pa Wires	See pag Pacemal	KVDD901	See pa Wires
		Kappa 700 SR		Kappa 700 VDD			Kappa 800 DR		Kappa 900 DR		Kappa 900 SR			Kappa 900 VDD	

Source: Medtronic Device Registration and Returned Product Analysis Data as of January 31, 2011

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IPG Implantable Pulse Generators, continued

J.	Implantab	ie P	uise G	enerat	lors, co												
		16 yr				99.9 +.0/0 at 223 mo	47.0 +1.8/-1.8 at 223 mo	99.9 +.0/1 at 253 mo	66.3 +2.3/-2.5 at 253 mo	100.0 +.0/1 at 216 mo	39.6 +2.8/-2.8 at 216 mo						
		14 yr				9.99 /0.+	71.2 +.9/9	9.99 0/0.+	80.6 +.7/7	100.0 +.0/1	67.9 +1.5/-1.6	100.0 +.0/1 at 147 mo	6.1 +1.2/-1.1 at 147 mo	100.0 +.0/1 at 159 mo	28.7 +2.6/-2.5 at 159 mo	99.9 +.1/4 at 164 mo	86.5 +2.6/-3.2 at 164 mo
		12 yr				0/0.+	82.4 +.6/6	9.9 0/0.+	84.0 +.6/6	100.0 +.0/1	81.9 +1.0/-1.1	100.0 +.0/1	12.8 +1.3/-1.2	100.0 +.0/1	42.2 +2.0/-2.0	99.9 +.1/4	89.0 +2.1/-2.6
		10 yr				0/0.+	88.8 +.4/4	6:66 0/0.+	87.5 +.5/5	100.0 +.0/1	89.2 +.7/8	100.0 +.0/1	66.1 +1.0/-1.1	100.0 +.0/1	74.7 +1.3/-1.4	99.9 +.1/4	93.2 +1.5/-1.9
		8 yr				0/0.+	94.7 +.3/3	9.99 -/0.+	92.1 +.4/4	100.0 +.0/1	94.7 +.5/5	100.0 +.0/0	92.3 +.5/5	100.0 +.0/1	91.9 +.7/7	99.9 +.1/4	97.1 +.8/-1.2
		7 yr	99.9 +.0/1 at 82 mo	7.4 +1.5/-1.3 at 82 mo		9.99 0/0.+	97.1 +.2/2	9.99 0/0.+	95.2 +.3/3	100.0 +.0/1	96.9 +.3/4	100.0 +.0/0	96.1 +.3/3	100.0 +.0/1	94.8 +.5/5	99.9 +.1/4	98.0 +.6/9
		6 yr	99.9 +.0/1	58.7 +1.2/-1.3		9.99 0/0.+	98.0 +.1/2	9:99 0/0.+	97.6 +.2/2	100.0 +.0/1	98.1 +.2/3	100.0 +.0/0	97.7 +.2/3	100.0 +.0/1	97.2 +.3/4	99.9 +.1/4	98.8 +.4/7
(%		5 yr	100.0 +.0/1	89.8 +.6/6		9.99 0/0.+	98.7 1/1.+	9.99 0/0.+	98.6 +.1/1	100.0 +.0/1	98.9 +.2/2	100.0 +.0/0	98.7 +.2/2	100.0 +.0/1	98.2 +.2/3	99.9 +.1/4	99.0 +.4/6
Device Survival Probability (%)		4 yr	100.0 +.0/1	97.1 +.3/3		0:-/0:+	99.1 +.1/.+	9.9 0/0.+	99.2 +.1/1	100.0 +.0/1	99.5 +.1/1	100.0 +.0/0	99.3 +.1/1	100.0 +.0/1	99.0 +.2/2	100.0 +.0/0	99.7 +.1/3
/al Prob	nplant	3 yr	100.0 +.0/1	99.2 +.1/2		100.0 +.0/0	99.5 +.1/1	9.99 0/0.+	99.5 +.1/1	100.0 +.0/0	99.8 +.1/1	100.0 +.0/0	99.6 +.1/1	100.0 +.0/0	99.4 +.1/2	100.0 +.0/0	99.7 +.1/3
ce Surviv	Years After Implant	2 yr	100.0 +.0/0	99.7 1/1.+		100.0 +.0/0	99.7 +.0/-+	9.9 0/0.+	99.7 +.0/-1	100.0 +.0/0	100.0 +.0/0	100.0 +.0/0	99.8 +.0/1	100.0 +.0/0	99.8 +.1/1	100.0 +.0/0	99.8 +.1/2
Devid	Years	1 yr	100.0 +.0/0	9.99 1/0.+		100.0 +.0/0	9.99 0/0.+	100.0 +.0/0	0/0.+	100.0 +.0/0	100.0 +.0/0	100.0 +.0/0	9.99 0/0.+	100.0 +.0/0	99.9 +.0/1	100.0 +.0/0	99.8 +.1/2
			Excluding Normal Battery Depletion	Including Normal Battery Depletion		Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion
	le	toT	4			34		50	I	4		4		-		-	
Malfunctions	rapy ction Not psimorqn	unj	" 			I		I	I	I		I		I		I	
Malfu	rapy Function rapy Function		m			1		1	I								
	mal Battery rnoise		2,312		amber	2,513		1,702	layed	922		2,684		1,006		48	
	bətem VU əvi stnslı	ł5A	1,000	baration of	on Dual Chi k-up ERI	2,000		3,000	– 1991 Potential Delayed ettings	1,000		300		1,000		400	
	istered anglasts		16,000	otential Sep	ance note ement Loc	58,000		58,000		17,000		26,000		18,000		4,000	
	texket Base	eles NSU	Jan-02	<mark>0 – 2009 P(</mark> <u>M</u> ires	 Perform ith Measur 	Nov-91		Dec-89	ee page 1. Permanen	Mar-92		Jul-96		Jul-96		Oct-95	
	nber del	nuN nuN	KDR921	<u>See page 140</u> – 2009 Potential Separation of Interconnect Wires	See page 148 - Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI	8424, 8426, 8427		8330, 8331, 8331M, 8340, 8341, 8341M, 8342	Advisories: <u>See page 147</u> – 1991 F Restoration of Permanent Settings	7107, 7108		7088, 7089		8088, 8089		8085, 8086	
	Δın	ne7	Kappa 920 DR			Legend II		Minix/ Minix ST		Minuet		Preva DR		Preva SR		Prevail S	

Device Survival Summary continued

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aDevice Survival Probability (%)	Years After Implant	1 yr 2 yr 3 yr 4 yr 5 yr 6 yr 7 yr 8 yr 10 yr 12 yr 14 yr 16 yr	Excluding 100:0	Including 99.9 99.8 99.7 99.3 98.7 97.9 96.3 92.3 67.9 4.3 Normal Battery +.0/0 +.0/1 +.1/1 +	Excluding Normal Battery 100.0 100	Including 99.6 99.2 98.6 97.7 96.5 94.7 91.5 73.9 44.7 27.9 Normal Battery +1/-1 +1/-1 +2/-2 +2/-3 +3/-4 +4/-5 +6/-6 +1.2/-1.9 +2/5/2.6 Depletion Depletion 1	Excluding 100.0	Including 100.0 100.0 99.8 99.7 99.4 Normal Battery +.0/0 +.0/0 +.0/1 +.1/1 +.3/6 Depletion at50 mo at50 mo at50 mo at50 mo	Excluding 100.0	Including 100.0 99.9 99.4 99.4 Normal Battery +.0/0 +.1/1 +.3/4 +.3/4 Depletion at 49 mo at 49 mo at 49 mo	Excluding Normal Battery Depletion 100.0	Including Normal Battery 100.0 90.6 98.7 98.7 96.7 92.3 92.3 Normal Battery +.0/0 +.3/-1.3 +.3/-1.3 +.3/-1.3 +.3/-1.3.4 +.3.2/-5.4 +.3.2/-5.4 Depletion Pepletion Pepletion Perlocities Perlocities Perlocities Perlocities Perlocities	Excluding all Battery 100.0 100.0 100.0 100.0 100.0 100.0 99.8 99.6 99.5 99.5 Pepletion +.0/0 +.0/0 +.0/0 +.0/1 +.0/1 +.1/2 +.2/2 +.2/2 Depletion 0/0 +.0/0 +.0/1 +.0/1 +.1/1 +.1/2 +.2/2 +.2/2	$ \begin{array}{ c c c c c c c c c c c c c c c c c c c$	Excluding all Battery Depletion 100.0 +0/-0 100.0 +.0/-0 100.0 +.0/-1 100.0 +.0/-1 100.0 +.0/-1 99.7 +.1/2 99.7 +.1/3 99.7 +.1/3 99.7 +.1/3 Depletion 100.0 100.0 99.9 99.9 99.7 99.7 99.7 99.7	Including 99.9 99.9 99.8 99.7 99.2 98.5 96.8 94.4 84.7 72.9 Normal Battery +.0/-1 +.1/1 +.1/2 +.2/3 +.3/4 +.5/6 +.1/19 +.3/6/-4.0 Depletion Depletion 1 1.1/1 +.1/2 +.2/3 +.3/4 +.5/6 +.1/19 +.3/6/-4.0	Excluding all Battery 100.0 100.0 99.9 99.9 99.9 99.7 99.5 99.5 99.5 Pall Battery +.0/0 +.0/0 +.0/0 +.0/0 +.0/0 +.0/1 +.1/1 +.1/1 +.1/1 Depletion 0/0 +.0/0 +.0/0 +.0/0 +.0/1 +.1/1 +.1/1 1.1/2.1	Including 99.9 99.9 99.9 99.8 97.7 94.8 81.4 62.4 Normal Battery +.0/0 +.0/0 +.0/0 +.1/1 +.1/1 +.3/3 +.3/3 +.3/3.2 Denolation Denolation
(%)		5 yr	100.0 +.0/0	98.7 +.1/1	100.0 +.0/0	97.7 +.2/3	100.0 +.0/0 at 50 mo	99.4 +.3/6 at 50 mo	100.0 +.0/0 at 49 mo	99.4 +.3/4 at 49 mo	100.0 +.0/0		100.0 +.0/1	99.5 +.1/2	99.9 1/0.+	99.2 +.2/3	9.99 0:-/0:+	99.3 +.1/1
bability		4 yr	100.0 +.0/0	99.3 +.1/1	100.0 +.0/0	98.6 +.2/2	100.0 +.0/0	99.7 +.1/1	100.0 +.0/0	99.4 +.3/4	100.0 +.0/0		100.0 +.0/0	99.8 +.1/.1	100.0 +.0/1	99.7 +.1/2	0/0.+	99.6 +.0/0
ival Pro	nplant	3 yr	100.0 +.0/0	99.7 1/1.+	100.0 +.0/0	99.2 +.1/1	100.0 +.0/0	99.8 +.0/1	100.0 +.0/0	99.8 +.1/1	100.0 +.0/0	99.6 +.3/-1.3	100.0 +.0/0	999 +.0/-1	100.0 +.0/0	99.8 +.1/.+	100.0 +.0/0	99.8 +.0/0
ice Surv	After In	2 yr	100.0 +.0/0	99.8 +.0/-1	100.0 +.0/0	99.6 +.1/1	100.0 +.0/0	100.0 +.0/0	100.0 +.0/0	9.99 -/0.+	100.0 +.0/0	100.0 +.0/0	100.0 +.0/0	9.99 1/0.+	100.0 +.0/0	99.9 +.1/1	100.0 +.0/0	9.99 +.0/0
aDev	Years	1 yr					100.0 +.0/0											
			xcluding I Battery epletion	ncluding al Battery Depletion	xcluding Il Battery epletion	າcluding l Battery epletion	kcluding I Battery epletion	icluding Battery epletion	ccluding Battery epletion	ncluding Il Battery epletion	kcluding Battery epletion	icluding Battery epletion	cluding Battery pletion	cluding Battery Pletion	luding 3attery oletion	cluding Battery epletion	cluding Battery pletion	cluding Battery
			Norma D	Norma	Norma D	Norma D	Normal D	Normal D	Normal D	Norma D	Normal D	Ir Normal D	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	In Normal De	Excluding Normal Battery Depletion	In Normal
	le	itoT	11 Norma D	Norma	4 Norma D	Norma D	7 Norm	Normal	2	Norma D	0	(0) ubset)	29	(19) ubset)	13	-	190	5
nctions	yqsy toti outo besimorqn Ia	uoj		Norma		Norma D	5 = 7 Norm	Normal D	1 = 2	Norma D	0 = 0	= (0) subset)	1 = 29	= (19) d subset)	0 = 13	= (12) d subset)	6 = 190	= (107)
alfunction	upromised	no) nui adT no)		Norma		D D	= 7 Norm	Normal D	= 2	Norma	0	= (0) ed subset)	= 29	= (19) :ed subset)	= 13	= (12) :ed subset)	= 190	= (107)
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alfunction	sletions rrapy Function npromised rotion Not npromised	Acti qml Jod Dep The Con The tu The		Norm	4	Norma D	2 + 5 = 7 Norm	Chamber	1 + 1 = 2	L Contraction of the second se	0 0 +	(0) + (0) = (0) (advisory-related subset)	28 + 1 = 29	ation (19) + (0) = (19) (advisory-related subset)	13 + 0 = 13	(12) + (0) = (12) (advisory-related subset)	184 + 6 = 190	(107) + (0) = (107)
alfunction	ive US shants mal Battery shetions mpromised retion Not npromised	USI Esti Imp Imp Dep Dep Con The Con	3,695 — — 11	Norm	1,215 — 4		27 2 + 5 = 7 Norm	Chamber	23 1 + 1 = 2		16 0 + 0 = 0	(0) + (0) = (0) (advisory-related subset)	396 28 + 1 = 29	ation (19) + (0) = (19) (advisory-related subset)	177 13 + 0 = 13	(12) + (0) = (12) (advisory-related subset)	38,000 1,517 184 + 6 = 190	(107) + (0) = (107)
alfunction	Implants mated ive US mal Battery pletions npromised npromised npromised	Reld Reg LS1 Nor Dep Dep The Con The Con	400 3,695 — — 11	Norm	1,000 1,215 4		67,000 27 2 + 5 = 7 Norm	Chamber	40,000 23 1 + 1 = 2		100 16 0 + 0 = 0	(0) + (0) = (0) (advisory-related subset)	4,000 396 28 + 1 = 29	ation (19) + (0) = (19) (advisory-related subset)	2,000 177 13 + 0 = 13	(12) + (0) = (12) (advisory-related subset)	1,517 184 + 6 = 190	(107) + (0) = (107)
	mber Market jistered inplants mal Battery market mpromised mpromised mpromised mpromised mpromised mpromised mpromised	USI Reld Reg Dep Inp Dep Inp Dep Inp Dep Inp Con The Con	38,000 400 3,695 — — 11	Norm	22,000 1,000 1,215 4		84,000 67,000 27 2 + 5 = 7 Norm	See page 148 - Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI D	55,000 40,000 23 1 + 1 = 2		1,000 100 16 0 + 0 = 0	= (0) subset)	16,000 4,000 <u>396</u> 28 + 1 = 29	= (19) d subset)	12,000 2,000 177 13 + 0 = 13	= (12) d subset)	38,000 1,517 184 + 6 = 190	= (107)

Source: Medtronic Device Registration and Returned Product Analysis Data as of January 31, 2011

IPG Implantable Pulse Generators, continued

Πηριαπιασ	16 yr		enerato					100.0 +.0/0 at 174 mo	28.6 +1.9/-1.9 at 174 mo				
	14 yr 10							100.0 10 +.0/0 +.C	30.6 28 +1.6/-1.6 +1 at	100.0 +.0/0 at 156 mo	38.8 +4.2/-4.2 at 156 mo		
	12 yr	99.7 +.1/1 at 130 mo	66.3 +3.3/-3.6 at 130 mo			99.9 +.0/0 at 140 mo	6.9 +.6/6 at 140 mo	100.0 1+.0/0	50.7 3 +1.1/-1.1 +	100.0 1 +.0/0 +	56.4 3 +3.1/-3.2 4 a		
	10 yr	99.7 +.1/1	82.2 +1.3/-1.3	99.5 +.4/-3.0 at 102 mo	81.9 +5.0/-6.5 at 102 mo	6.99 0/0.+	68.0 +.5/5	100.0 +.0/0	79.7 +.7/7	100.0 +.0/0	88.7 +1.4/-1.6		
	8 yr	99.7 +.1/-1	94.4 +.4/5	99.5 +.4/-3.0	89.1 +3.4/-4.8	0/0.+	92.7 +.2/2	100.0 +.0/0	94.4 +.3/3	100.0 +.0/0	98.0 +.5/6		
	7 yr	99.8 +.1/1	97.1 +.3/3	100.0 +.0/0	94.1 +2.3/-3.6	9.99 +.0/0	96.5 +.1/1	100.0 +.0/0	96.9 +.2/2	100.0 +.0/0	98.8 +.3/5		
	6 yr	99.9 +.0/1	98.5 +.2/2	100.0 +.0/0	98.2 +1.0/-2.2	0/0.+	98.1 +.1/1	100.0 +.0/0	98.1 +.2/2	100.0 +.0/0	99.0 +.3/4		
	5 yr	100.0 +.0/0	99.2 +.1/1	100.0 +.0/0	99.4 +.4/-1.6	100.0 +.0/0	99.0 +.1/-,1	100.0 +.0/0	98.9 1/1.+	100.0 +.0/0	99.1 +.3/4	100.0 +.0/0 at 50 mo	99.7 +.1/1 at 50 mo
	4 yr	100.0 +.0/0	99.5 +.1/1	100.0 +.0/0	100.0 +.0/0	100.0 +.0/0	99.4 +.0/-1	100.0 +.0/0	99.3 +.1/1	100.0 +.0/0	99.5 +.2/3	100.0 +.0/0	99.7 +.1/1
nplant	3 yr	100.0 +.0/0	99.7 +.0/-1	100.0 +.0/0	100.0 +.0/0	100.0 +.0/0	99.7 +.0/-/	100.0 +.0/0	99.6 +.1/1	100.0 +.0/0	99.6 +.2/3	100.0 +.0/0	99.8 +.0/1
Years After Implant	2 yr	100.0 +.0/0	9.99 +.0/0	100.0 +.0/0	100.0 +.0/0	100.0 +.0/0	9.99 +.0/0	100.0 +.0/0	99.8 +.0/0	100.0 +.0/0	99.8 +.1/2	100.0 +.0/0	9.99 +.0/0
Years	1 yr	100.0 +.0/0	9.99 0/0.+	100.0 +.0/0	100.0 +.0/0	100.0 +.0/0	9.99 +.0/0	100.0 +.0/0	100.0 +.0/0	100.0 +.0/0	99.9 +.1/1	100.0 +.0/0	100.0 +.0/0
		Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion
IJ	stoT	39	(24) subset)	-		50		~		0		9	
rapy ction Vot besimorqr	noJ nuJ 9dT	" 	(24) + (0) = (24) (advisory-related subset)	" 0		I		I		I		4	
rapy Function besimorq		+ 38	(24) + (advisor	+		I		1		1		+	
nal Battery letions		559	aration 19	35	aration	13,319		2,730		299		21	amber
bətem SU əv stnsi	itoA	14,000	otential Sepa <u>ge 140</u> – 200 ect Wires	100	otential Sepa	500		2,000		300		55,000	e on Dual Cha ck-up ERI
istered stnslqm	I SN ნəუ	54,000	14- 2005 Provine 2	1,000	14- 2005 P	122,000		50,000		5,000		69,000	mance not irement Lo
Aarket sase	ələЯ V SU	Sep-99	Advisories: See page 144– 2005 Potential Separation of Interconnect Wires; See also page 140 – 2009 Potential Separation of Interconnect Wires	Sep-99	Advisories: <u>See page 144</u> – 2005 Potential Separation of Interconnect Wires	Oct-95		Oct-95		Mar-96		Jul-06	<u>See page 148</u> – Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI
lel tel	unN ooW	SSR303, SSR306	Advisories of Intercon Potential S	SVDD303	Advisories of Intercon	7960i, 7961i, 7962i		8960i, 8961i, 8962i		8968i		VEDR01	<u>See page 1</u> Pacemaker
ג ון nic CRDM Pro	mea	Sigma 300 SR		Sigma 300 VDD		Thera-i DR		Thera-i SR		e: Medt		Versa DR	

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Device Survival Summary continued

Device Survival Probability (%)

Malfunctions

Reference Chart

The longevity estimates provided are mean values calculated for the parameters given. The longevity estimates shown here assume a lower rate of 60 ppm, 100% pacing, and pulse width of 0.4 ms unless noted otherwise. The actual longevity achieved for any device while implanted will depend on the actual programmed parameters and patient factors, and may differ significantly from these estimates. The elective replacement time is indicated via telemetry indication, and rate and mode change to 65 ppm and VVI respectively (VOO/65 with magnet), unless noted otherwise.

		Estimated I	ongevity		
Family	Model Number	Amplitude Setting	500 Lead Ω	1000 Lead Ω	Elective Replacement Indicators
Adapta DR	ADDR01, ADDR03, ADDR06, ADD01	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.4 6.0 4.5	8.2 7.3 6.0	**
Adapta DR	ADDRS1	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	5.5 4.3 3.2	6.1 5.4 4.4	**
Adapta DR	ADDRL1	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	9.1 7.4 5.4	10.1 9.0 7.3	**
Adapta SR	ADSR01, ADSR03, ADSR06	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	7.3 6.4 5.0	7.8 7.4 6.2	**
Adapta VDD	ADVDD01	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	6.2 5.5 4.4	6.5 6.2 5.4	**
AT500	AT501, 7253	Low 2.0 V (A, RV) Nominal 3.0 V (A, RV) High 5.0 V (A, RV)	7.7 5.8 3.7	8.3 7.0 5.2	Telemetry indication. Pacing mode and rate (magnet and non-magnet) as programmed.
EnPulse DR	E1DR01, E1DR03, E1DR06	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.5 6.2 4.4	8.5 7.6 5.9	**
EnPulse DR	E1DR21	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	5.4 4.3 3.0	6.0 5.4 4.2	**
EnPulse 2 DR	E2DR01, E2DR03, E2DR06	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.5 6.2 4.4	8.5 7.6 5.9	**
EnPulse 2 DR	E2DR21	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	5.4 4.3 3.0	6.0 5.4 4.2	**
EnPulse 2 DR	E2DR31, E2DR33	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	9.0 7.4 5.2	10.1 9.1 7.1	**
EnPulse 2 SR	E2SR01, E2SR03, E2SR06	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.2 6.3 4.8	7.7 7.3 6.1	**
EnPulse 2 VDD	E2VDD01	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	6.1 5.5 4.3	6.5 6.2 5.4	**
EnRhythm DR	P1501DR	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	10.6 8.0 5.4	12.3 10.3 7.8	**
Kappa 400 DR	KDR401, KDR403	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.8 6.4 5.1	8.5 7.5 6.5	**
Kappa 400 SR	KSR401, KSR403	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	7.9 6.9 5.8	8.4 7.7 7.0	**
Kappa 600 DR	KDR601, KDR603, KDR606	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.7 6.3 4.4	8.6 7.7 6.0	**
Kappa 600 DR	KDR651, KDR653	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.7 6.3 4.4	8.6 7.7 6.0	**

**Telemetry indication. Rate and mode change to 65 ppm and VVI respectively (VOO/65 with magnet).

Reference Chart continued

		Estimated Long	gevity		
Family	Model Number	Amplitude Setting	500 Lead Ω	1000 Lead Ω	Elective Replacement Indicators
Kappa 700 D	KD701, KD703, KD706	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.7 6.3 4.4	8.6 7.7 6.0	**
Kappa 700 DR	KDR701, KDR703, KDR706	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.7 6.3 4.4	8.6 7.7 6.0	**
Kappa 700 DR	KDR721	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	5.5 4.4 3.0	6.1 5.5 4.2	**
Kappa 700 SR	KSR701, KSR703, KSR706	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	7.4 6.5 4.9	7.9 7.5 6.2	**
Kappa 700 VDD	KVDD701	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	6.2 5.6 4.4	6.6 6.3 5.3	**
Kappa 800 DR	KDR801, KDR803	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.7 6.3 4.4	8.6 7.7 6.0	**
Kappa 900 DR	KDR901, KDR903, KDR906	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.7 6.3 4.4	8.6 7.7 6.0	**
Kappa 920 DR	KDR921	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	5.5 4.4 3.0	6.1 5.5 4.3	**
Kappa 900 SR	KSR901, KSR903, KSR906	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	7.3 6.4 4.9	7.9 7.4 6.1	**
Kappa 900 VDD	KVDD901	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	6.2 5.6 4.4	6.6 6.3 5.4	**
Legend II	8424, 8426, 8427	Low 2.5 V, 0.36 ms (RV) Nominal 3.3 V, 0.36 ms (RV) High 5.0 V, 0.36 ms (RV)	12.9 9.4 7.8	14.5 11.8 10.5	If programmed to non-rate responsive mode (e.g., VVI), rate decrease of 10% from programmed rate. Telemetry indication. If programmed to rate responsive mode (e.g., VVIR), rate change to 65 ppm and mode change to VVI. Telemetry indication.
Minix	8340, 8341, 8341M, 8342	Low 2.5 V (RV) Nominal 3.3 V (RV) High 5.0 V (RV)	14.9 10.2 7.9	17.3 13.6 11.3	Telemetry indication. Rate decrease of 10% from programmed rate.
Minix ST	8330, 8331, 8331M	Low 2.5 V (RV) Nominal 5.0 V (RV) High 8.0 V (RV)	14.9 7.9 4.0	17.3 11.4 7.0	Telemetry indication. Rate decrease of 10% from programmed rate.
Minuet	7107, 7108	Low 2.5 V, 0.36 ms (A, RV) Nominal 4.0 V, 0.36 ms (A, RV) High 5.0 V, 0.36 ms (A, RV)	12.5 7.7 4.7	15.6 10.9 7.6	**
Preva DR	7088, 7089	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	9.9 7.4 5.4	11.3 9.4 7.5	**
Preva SR	8088, 8089	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	9.8 8.0 6.4	10.7 9.5 8.1	**
Prevail S	8085, 8086	Low 2.5 V, 0.42 ms (RV) Nominal 3.3 V, 0.42 ms (RV) High 5.0 V, 0.42 ms (RV)	16.4 10.8 8.6	19.4 14.4 12.4	Telemetry indication. Rate decrease of 10% from programmed rate.

**Telemetry indication. Rate and mode change to 65 ppm and VVI respectively (VOO/65 with magnet).

Reference Chart continued

		Estimated I	ongevity		
Family	Model Number	Amplitude Setting	500 Lead Ω	1000 Lead Ω	Elective Replacement Indicators
Prodigy DR	7860, 7861, 7862	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	9.9 7.4 5.4	11.3 9.4 7.5	**
Prodigy SR	8158, 8160, 8161, 8162	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	9.8 8.0 6.4	10.7 9.5 8.1	**
Sensia DR	SEDR01, SED01	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.5 6.1 4.5	8.3 7.4 6.0	**
Sensia SR	SESR01, SES01	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	7.3 6.4 5.0	7.8 7.4 6.2	**
Sigma 100 S	SS103, SS106	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	10.1 8.2 6.4	11.1 9.8 8.4	**
Sigma 200 DR	SDR203	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	10.1 7.5 5.5	11.7 9.6 7.8	**
Sigma 200 SR	SSR203	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	10.1 8.2 6.4	11.1 9.8 8.4	**
Sigma 300 DR	SDR303, SDR306	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	10.1 7.5 5.5	11.7 9.6 7.8	**
Sigma 300 SR	SSR303, SSR306	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	10.1 8.2 6.4	11.1 9.8 8.4	**
Sigma 300 VDD	SVDD303	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	8.9 7.3 5.8	9.7 8.6 7.4	**
Thera-i DR	7960i, 7961i, 7962i	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	9.9 7.4 5.4	11.3 9.4 7.5	**
Thera-i SR	8960i, 8961i, 8962i	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	9.8 8.0 6.4	10.7 9.5 8.1	**
Thera-i VDD	8968i	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	11.5 9.6 7.7	12.4 11.1 9.7	**
Versa DR	VEDR01	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.5 6.1 4.5	8.3 7.4 6.0	**

Ddl

 ** Telemetry indication. Rate and mode change to 65 ppm and VVI respectively (VOO/65 with magnet).

Method for Estimating Lead Performance

Medtronic CRDM has tracked lead survival for over 27 years with its multicenter, global chronic lead studies.

Leads Performance Analysis

Implanted leads operate in the challenging biochemical environment of the human body and the body's response to foreign objects. Implanted leads are also subject to mechanical stresses associated with heart motion, body motion, and patient anatomy.

In this environment, pacemaker and defibrillation leads cannot be expected to last forever. While IPGs and ICDs have a battery that will deplete after a predictable length of time, a lead's longevity cannot be predicted, nor are there simple indicators that a lead is approaching the end of its service life. Therefore, regular monitoring while implanted, and evaluation of lead integrity upon IPG or ICD replacement, is necessary to determine if a lead may be approaching the end of its service life.

Returned Product Analysis Shortfalls

All leads and lead segments returned to Medtronic are analyzed to determine whether or not they meet performance limits established by Medtronic. Although returned product analyses are valuable for gaining insight into lead failure mechanisms, this data cannot be used by itself for determining the survival probability of leads because only a small fraction of leads are explanted and returned for analysis. Additionally, those leads that are returned cannot be assumed to be statistically representative of the performance of the total population for a given lead model. Partial or total lead extraction can result in significant damage to a lead, making a definitive analysis of a suspected failure and its cause impossible. Thus, lead survival probabilities are more appropriately determined through a clinical surveillance study. Although returned product analysis results are presented in this report, Medtronic tracks lead survival through its System Longevity Study.

System Longevity Study (SLS)

The SLS is a prospective, non-randomized multicenter, global study designed to monitor the performance of market-released cardiac therapy products. Medtronic has been monitoring the performance of its cardiac therapy products with a multicenter study for 27 years and has evaluated the performance of more than 75,000 leads, with data reported from 14 countries on four continents.

The primary purpose of the SLS is to evaluate and publish the long-term reliability and performance of Medtronic market-released cardiac therapy products by analyzing product survival probabilities. Productrelated adverse events, indicating the status of the product, are collected to measure survival probabilities. The data gathered in this study may also be used to support the design and development of investigational plans for new cardiac therapy products. The SLS is designed to continue indefinitely, encompassing new products as they become commercially available.

Eligible products for study enrollment include all Medtronic market-released cardiac therapy products. Medtronic may limit overall enrollment of any product when the number of enrollments provides an adequate number to effectively assess product survivability. Medtronic reserves the right to close enrollment of a product at a site level in order to ensure all participating sites have an equal opportunity to enroll.

To ensure a sufficiently large and representative source of data, participating clinical centers must meet specific selection criteria. In addition, centers are selected to be representative of the range of clinical environments in which Medtronic conducts business.

Investigators enroll qualified subjects with specific Medtronic market-released cardiac therapy products and follow these subjects from their implant date until they can no longer be followed (e.g., death and lost to follow-up). Using a Clinical Investigation Plan, each center monitors and reports on the performance of specific Medtronic market-released cardiac therapy products (e.g., product-related adverse events, replacements and abandonments) and subject status (e.g., subject death and subject withdrawal from the study). Subjects will be followed by their respective center in accordance with the center's established practices for routine follow-up.

Patients are eligible for enrollment in the study if:

- 1. They are within 6 months post-implant of a Medtronic market-released lead connected to a market-released CRT, ICD, or IPG device, and the lead is used for a pacing, sensing, or defibrillation application, or
- 2. They participated in a qualifying study of a marketreleased Medtronic cardiac therapy product; complete implant and follow-up data are available; and the data is appropriately and legally released for use in the study.

The Standard Actuarial Method is used to determine estimates of lead survival.

The SLS protocol requires regular follow-up reporting on all leads actively followed in the study. The follow-up schedule for this study is based on utilizing routine, scheduled office/clinic visits and unscheduled office/ clinic visits prompted by symptoms or complaints. Data collected at each follow-up includes routine clinical electrical data, any system modifications, and any lead or generator adverse events.

Each study center must inform Medtronic whenever a lead complication has occurred or when a patient is no longer participating in the study. Under the study protocol, each lead is assumed to be normally active unless a lead-related complication is confirmed, the lead is abandoned or explanted, the patient is no longer available for follow-up, or more than 24 months have passed since last follow-up. The data analyses assume that the patient is still part of the study and no lead complications had occurred as of the report cutoff date unless specifically reported by the center.

Medtronic evaluates center compliance with study protocol through clinical monitoring at each study site. Additionally, study center personnel must be trained in the study procedures prior to participating, and they must adhere to the policies and procedures of their local ethics boards.

Lead Complications

All adverse events are critically evaluated by a Medtronic technical review committee and the investigator is asked to assess the relationship of the adverse event to the presence or performance of the implanted system, generator and/or lead(s).

The SLS complication criteria are defined below. These criteria do not, however, enable a lead integrity or "hardware" failure to be conclusively differentiated from other clinical events such as an undetected lead dislodgement, exit block, or concurrent pulse generator failure manifested as a sensing or capture problem.

A lead-related complication is considered to have occurred if at least one of the following clinical observations is reported and at least one of the following clinical actions is made 30 days or more after the implant.

Clinical Observations

- Failure to capture
- Failure to sense/undersensing
- Oversensing
- Abnormal pacing impedance (based on lead model, but normal range is typically 200-3,000 ohms)
- Abnormal defibrillation impedance (based on lead model, but normal range is typically 20-200 ohms)
- Insulation breach, observed visually, that has degraded system performance
- Conductor fracture, observed visually or radiographically
- Extracardiac stimulation
- Cardiac perforation
- Lead dislodgement

Clinical Actions

- Lead surgically abandoned/capped
- Lead electrically abandoned/capped
- Lead explanted
- Lead replaced
- Polarity reprogrammed (i.e., bipolar to unipolar; unipolar to bipolar)
- Lead use continued based on medical judgment despite a known clinical performance issue
- Other lead-related surgery performed (e.g., lead mechanical alteration or unsuccessful repositioning)

Note: Successful lead repositioning is not a qualifying action.

Data Analysis Methods

The performance of leads is expressed in terms of lead survival estimates, where "survival" refers to the function of the lead, not the survival of the patient. These survival estimates are intended to illustrate the probability that a lead will survive for a given number of years without a lead-related complication.

The survival estimates are determined from the analysis of the data collected through the SLS. These data are presented graphically and numerically.

Survival times are calculated from the implant date to the earlier of the complication date, out-of-service date (for example, subject leaves the study, the lead is no longer being used, or no data has been reported within a specified time interval), or the cutoff date of the report. If a lead experiences more than one complication, the first is used to calculate survival time; although all complications associated with a lead are in the tables in this report.

Of the several different statistical methods available for survival analysis, the Standard Actuarial Method, with suspensions assumed distributed across the intervals (Cutler-Ederer Method), is used to determine estimates of lead survival. This method is commonly used by medical researchers and clinicians.

On the following pages, each graph includes a survival curve where events include qualifying lead-related complications. This survival estimate is a good representation of the probability a lead will survive a period of time without a lead-related complication. For example, if a survival probability is 95% after 5 years of service, then the lead has a 5% chance of experiencing a lead-related complication in the first 5 years following implant.

Since the survival estimate can become very imprecise with small effective sample sizes, Medtronic truncates the survival curve when the number of leads entering an interval is less than 50 leads. When the number of leads entering an interval reaches 50, the next data point is added to the survival curve. Although the report provides tabular data in 1-year intervals, the curves are actually computed and plotted using 3-month intervals.

The data in the tables is rounded to the nearest tenth of one percent. Occasionally, a graph may show 100% survival, but have one or more complications. This occurs because even with the complications, the data rounds to 100%.

The survival curves are statistical estimates. As performance experience accumulates, the estimation improves. Confidence intervals are provided as a way to indicate the degree of certainty of the estimates. Greenwood's formula is used to calculate corresponding 95% confidence intervals for the standard errors, and the complementary log-log method is used to produce the confidence bounds.

Medtronic urges all physicians to return explanted products and to notify Medtronic when a product is no longer in use, regardless of reason for explant or removal from use.

Sample Size and How the Population and Population Samples Are Defined

The population sample from which the survival estimates are derived is comprised of the patients successfully enrolled in the SLS as of the report cutoff date. The number of enrolled implants is listed for each model.

This sample based on SLS enrollments is considered to be representative of the worldwide population, including data from 14 countries on four continents, and therefore the survival estimates shown in this report should be representative of the performance worldwide of these models.

In general, a model or model family will be included in this report when more than 100 leads have been enrolled and no fewer than 50 leads followed for at least 6 months. Models will remain in the report for at least 20 years as long as Medtronic estimates at least 500 leads remain active in the United States, based on estimated US implants.

Medtronic, at its discretion, may stop providing updated performance information on lead models that received original US market-release approval 20 or more years ago. These models may be removed from this report at that time.

Returned Product Analysis Results

Every lead or lead portion returned to Medtronic receives an analysis. Although the returned product analysis data is not used to generate the survival estimates, the data provides valuable insight into the causes of lead malfunction.

For reporting returned product analysis results, Medtronic CRDM considers a lead as having malfunctioned whenever the analysis shows that any parameter was outside the performance limits established by Medtronic while implanted and in service. To be considered a malfunction for returned product analysis reporting, the lead must have been returned to Medtronic and analyzed.

The results of the analysis is presented in four categories. The lead reporting categories are:

• Conductor Fracture: Conductor malfunction with complete or intermittent loss of continuity that could interrupt current flow (e.g., fractured conductors), including those associated with clavicle flex fatigue or crush damage.

- Insulation Breach: A malfunction of the insulation allowing inappropriate entry of body fluids or inappropriate current flow between the conductors, or between the conductor and the body. Examples include cuts, tears, depressions, abrasions, and material degradation.
- Crimps/Welds/Bonds: Any malfunction in a conductor or lead body associated with a point of connection.
- Other: Malfunctions of specific lead mechanical attributes, such as sensors, connectors, seal rings, or malfunction modes not included in the three categories above.

A lead subject to a safety advisory is not considered to have malfunctioned unless it has been returned to Medtronic CRDM and found, through analysis, to actually have performed outside the performance limits established by Medtronic.

For leads designed for either ventricular or atrial use, the numbers listed in the Returned Product Analysis tables include both.

The numbers of malfunctions listed in the Returned Product Analysis tables are the actual numbers confirmed in the returned product analysis from the United States. The numbers of complications listed in the complications tables are the actual numbers observed in the SLS centers around the world.

US Reports of Acute Lead Observations (Occurring within First Month of Service)

In the first weeks following lead implantation, physiologic responses and lead performance can vary until longterm lead stability is attained. Acute (defined as the first month after implant) lead performance may be subject to a number of factors, including patient-specific anatomy,

clinical conditions and/or varying implant conditions/ techniques. After a period of time, the implant and the lead performance stabilizes. It is for this reason that the System Longevity Study results, which are intended to measure long-term performance, do not include complications that occur within the first 30 days after implant.

Information about the clinical experience in the first month of service is included in this report. The source for this information is Medtronic's complaint handling system database. The information is summarized in tables titled "US Reports of Acute Lead Observations." To be included in this summary of observations, a lead must first be successfully implanted and registered in Medtronic's Device and Registrant Tracking system.

Each Event Report received by Medtronic's complaint handling system is assigned one or more Reason for Report codes based on the information received. The Reason for Report codes have been grouped into Acute Lead Observation categories. The categories used for this product performance report are drawn from the "FDA Guidance for Submission of Research and Marketing Applications for Permanent Pacemaker Leads and for Pacemaker Lead Adapter 510(k) Submissions." The categories are:

- 1. Cardiac Perforation
- 2. Conductor Fracture
- 3. Lead Dislodgement
- 4. Failure to Capture
- 5. Oversensing
- 6. Failure to Sense
- 7. Insulation Breach
- 8. Impedance Abnormal
- 9. Extracardiac Stimulation
- 10. Unspecified

Although multiple observations are possible for any given lead, only one observation is reported per lead. The observation reported is the observation highest on the list. For example, if an Event Report includes observations for both Lead Dislodgement and Failure to Sense, Lead Dislodgement is reported.

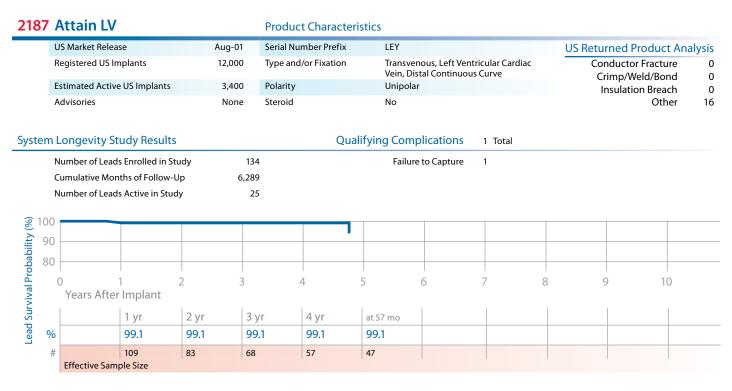
The lead event reported to Medtronic may or may not have involved clinical action or product returned to Medtronic. The lead may have remained implanted and in service.

Estimated Number of Implanted and Active Leads in the United States

In addition to providing the number of leads enrolled in the SLS, this report also provides the number of leads registered as implanted and the number remaining active in the United States based on the status recorded in the Medtronic Device and Registrant Tracking system.

Some lead models do not have a survival curve presented in this report. These lead models do not have a survival curve because they have insufficient sample size in the System Longevity Study. Returned Product Analysis results for these models are included here for reference and comparison.

Left-Heart Leads



2188 Attain CS

Data as of January 31, 2011

Product Characteristics

US Market Release	Aug-01	Serial Number Prefix	LEB	US Returned Product Anal	lysis
Registered US Implants	1,800	Type and/or Fixation	Transvenous, Coronary Sinus/ Cardiac Vein, Canted	Conductor Fracture Crimp/Weld/Bond	1
Estimated Active US Implants	400	Polarity	Bipolar	Insulation Breach	0
Advisories	None	Steroid	No	Other	0

Syst	em L	ongevity Stu	dy Results			Qualifyin	g Complicatio	ons 1 Tot	al			
	N	umber of Leads	Enrolled in Study	, 1 <u>5</u>	5	Extra	a Cardiac Stimula	tion 1				
	C	umulative Montl	ns of Follow-Up	460)							
	N	umber of Leads	Active in Study	()							
	100											
ty (%	90	Survival estin	nate not availab	le due to insuffic	ient sample size	2						
bilit												
oba	80											
al Pr		0	1 :	2 3	4		5 6		7 8	8 9	9 10	
Lead Survival Probability (%)		Years After I	mplant									
ad Si												
Lea	%											
	#											
		Effective Samp	e Size									

Source: Medtronic Device Registration and Returned Product Analysis

55	Attain O	1 VV		FIC	oduct Charact	ensues					
	US Market Rele	ease	Ma	y-02 Ser	al Number Prefix	BAA			US Returned	Product Ana	alysis
	Registered US	Implants	100	,800 Тур	e and/or Fixation		venous, Left Ven I Double Curve	tricular Cardiac Vein,		tor Fracture Weld/Bond	38
	Estimated Acti	ve US Implant	s 43	,500 Pol	arity	Unip	olar			tion Breach	2
	Advisories		Ν	lone Ste	roid	Yes				Other	72
stem	Longevity S	Study Resul	ts		Q	ualifying Co	mplications	38 Total			
	Number of Lea	ds Enrolled in	Study	675		Lead	Dislodgement	15	Unspecified C	linical Failure	3
	Cumulative Mo	onths of Follow	v-Up	28,309		Fai	ure to Capture	12	Extra Cardia	c Stimulation	7
	Number of Lea	nds Active in St	udy	179		Conc	luctor Fracture	1			
10	0 -										
10											
9	0										
8	0										
	0	1	2	3	4	5	6	7 8	9	10	
	Years Afte	er Implant	_	0		5		,	-		
10 9 8		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr			
9	6	95.9	94.9	94.2	94.2	94.2	93.1	93.1			
	#	547	428	346	264	185	117	52			
	Effective Sa	mole Size							'	1	

4194	Attain OT	W		Produ	ict Character	istics						
	US Market Releas	se	Aug-04	Serial N	lumber Prefix	LFG				US Retur	ned Produc	t Analysis
	Registered US Im	plants	96,300	Type ar	nd/or Fixation		ous, Left Ver ein, Distal De		ve		ductor Fractu	
	Estimated Active	US Implants	64,500	Polarity	/	Bipolar					imp/Weld/Boi Isulation Brea	
	Advisories		None	Steroid		Yes					Oth	
Syster	m Longevity St	udy Results			Qua	lifying Comp	lications	13 Tota	I			
	Number of Leads		-	034		Lead Disl	odgement	7			ied Clinical Fail	
	Cumulative Mon	ths of Follow-U	p 24,	852		Failure	to Capture	2		Extra C	ardiac Stimulat	ion 2
	Number of Leads	s Active in Stud	у	779		Insula	ation (ESC)	1				
• 10												
%) (%	00					-						
bilit	90											
oba	80											
al Pro	0	1	2 3		4	5	6	7	8	ç) 1	0
Lead Survival Probability (%)	Years After	Implant										
ead		1 yr	2 yr	3 yr	4 yr	5 yr						
Ľ.	%	99.2	98.5	98.5	98.0	97.3						
	#	650	389	230	136	45						

Effective Sample Size

	U	IS Market Releas	se	Aug-08	B Serial N	lumber Prefix	AAD			US Retur	ned Product Ar	nalysi
	Re	egistered US Im	plants	10,200) Type ar	nd/or Fixation		nous, Left Ver ble Lobe Fixa	ntricular Cardiac Vein, Ition	Conductor Fractur Crimp/Weld/Bone		
	Es	stimated Active	US Implants	8,800	D Polarity	/	Unipolar				sulation Breach	
	Ad	dvisories		None	e Steroid		Yes				Other	2
vste	em L	ongevity St	udy Results			Qualif	fying Comp	olications	4 Total			
	N	lumber of Leads	Enrolled in Stu	Jdy	654		Lead Dis	lodgement	1			
	Cu	umulative Mon	ths of Follow-U	lp 10),682		Conduct	tor Fracture	1			
	N	lumber of Leads	A	.,	501							
	INI		s Active in Stud	у	591	ł	Extra Cardiac S	Stimulation	2			
5		Id hiber of Leads	S Active in Stud	y	591		Extra Cardiac !	Stimulation	2			
1011 (100		Active in Stud	y	591		Extra Cardiac S	Stimulation	2			
	100 90			y			Extra Cardiac :		2			
(a) (100 90 80								2			
	100 90 80			2	3	4	Extra Cardiac :	6	2	8	9	10
	100 90 80		1						2	8	9	10
	100 90 80	0	1						2	8	9	10
	100 90 80	0	1 Implant	2	3	4			2	8	9	10

4196 Attain Ability

Product Characteristics

	US Market Release		May-09	Serial Number Prefix	PVI		US Returned Product Ar	alysis
	Registered US Imp	lants	26,600	Type and/or Fixation	Transvenous, Left Vent Preformed Body, Doub		Conductor Fracture	
	Estimated Active U	IS Implants	23,900	Polarity	Bipolar		Crimp/Weld/Bond Insulation Breach	(
	Advisories		None	Steroid	Yes		Other	1
tem	n Longevity Stud	dy Results		Qual	fying Complications	2 Total		
	Number of Leads E	nrolled in Study	1,228		Lead Dislodgement	1		
	Cumulative Month	s of Follow-Up	11,774		Extra Cardiac Stimulation	1		
	Number of Leads A	Active in Study	1,138					
10								
10	10							
9	90							
	30	1 2		4	5 6	7	8 9	10
	0	1 2	2.3	4	5 6	7	8 9	10
	30		2.3	4	5 6	7	8 9	10
	0		2. 3 at 18 mo	4	5 6	7	8 9	10
	0 Vears After Ir	mplant		4	5 6	7	8 9	10
8	0 Vears After Ir	mplant 1 yr	at 18 mo	4	56	7	8 9	10

Lead Survival Summary (95% Confidence Interval)

		ease	ъ	n Study		onths of study	1	Survival		lity (%)						
Model Number	Family	US Market Release	Leads Enrolled	Leads Active in Study	Qualifying Complications	Cumulative Months of Follow-Up in Study	Years A 1 yr	fter Imp	lant 3 yr	4 yr	5 yr	бyr	7 yr	8 yr	9 yr	10 yr
2187	Attain LV	Aug-01	134	25	1	6,289	99.1 +0.8/-5.1	99.1 +0.8/-5.1	99.1 +0.8/-5.1	99.1 +0.8/-5.1	99.1 +0.8/-5.1 at 57 mo					
2188	Attain CS	Aug-01	15	0	1	460	100.0 at 0 mo									
4193	Attain OTW	May-02	675	179	38	28,309	95.9 +1.3/-1.8	94.9 +1.5/-2	94.2 +1.7/-2.2	94.2 +1.7/-2.2	94.2 +1.7/-2.2	93.1 +2.1/-2.9	93.1 +2.1/-2.9			
4194	Attain OTW	Aug-04	1,034	779	13	24,852	99.2 +0.4/-0.9	98.5 +0.7/-1.3	98.5 +0.7/-1.3	98.0 +1/-1.8	97.3 +1.4/-2.8					
4195	Attain StarFix	Aug-08	654	591	4	10,682	99.4 +0.4/-1.3	99.4 +0.4/-1.3	98.2 +1.3/-5.3	98.2 +1.3/-5.3						
4196	Attain Ability	May-09	1,228	1,138	2	11,774	99.8 +0.2/-0.6	99.8 +0.2/-0.6 at 18 mo								

Source: System Longevity Study Data as of January 31, 2011

US Returned Product Analysis Summary

Model Number	Family	US Market Release	Estimated US Implants	Estimated US Active	Conductor Fracture	Crimp/Weld/ Bond	Insulation Breach	Other
2187	Attain LV	Aug-01	12,000	3,400	0	0	0	16
2188	Attain CS	Aug-01	1,800	400	1	0	0	0
4193	Attain OTW	May-02	100,800	43,500	38	0	2	72
4194	Attain OTW	Aug-04	96,300	64,500	5	0	31	17
4195	Attain StarFix	Aug-08	10,200	8,800	1	0	1	21
4196	Attain Ability	May-09	26,600	23,900	0	0	2	14

Source: Returned Product Analysis Data as of January 31, 2011

US Reports of Acute Lead Observations

Model Number	Family	Estimated US Implants	Cardiac Perforation	Conductor Fracture	Lead Dislodgement	Failure to Capture	Oversensing	Failure to Sense		Impedance Abnormal	Extracardiac Stimulation	Unspecified
2187	Attain LV	12,000	1	0	8	4	0	1	0	0	1	0
2188	Attain CS	1,800	0	0	2	0	0	0	0	0	0	0
4193	Attain OTW	100,800	1	1	50	14	0	0	0	2	18	0
4194	Attain OTW	96,300	1	2	80	22	2	0	0	3	16	3
4195	Attain StarFix	10,200	0	0	17	9	0	0	0	1	11	0
4196	Attain Ability	26,600	1	1	56	17	0	0	2	7	26	1

Report Cutoff Date: January 31, 2011

Reference Chart

Model Number	Family	Туре	Insulation	Conductor Material	Tip Electrode	Connector Type
2187	Attain LV	Transvenous Cardiac Vein Preformed Body	Polyurethane (55D)	MP35N	Platinized Platinum	IS-1 UNI
2188	Attain CS	Transvenous Cardiac Vein Preformed Body	Polyurethane (55D)	MP35N	Platinized Platinum	IS-1 BI
4193	Attain OTW	Transvenous Cardiac Vein Preformed Body	Polyurethane (55D)	MP35N	Platinized Platinum	IS-1 UNI
4194	Attain OTW	Transvenous Cardiac Vein Preformed Body	Polyurethane (55D)/ Silicone (4719)	MP35N	Platinum Alloy	IS-1 BI
4195	Attain StarFix	Transvenous Cardiac Vein Deployable Lobes	Polyurethane (55D)	MP35N	Platinum Alloy	IS-1 Uni
4196	Attain Ability	Transvenous Cardiac Vein Preformed Body	Polyurethane (55D), SI polyimide	Ag core – MP35N	Tapered, Annualar, Titanium nitride	IS-1 BI

Defibrillation Leads

6721, 6921 Epicardial Patch

Product Characteristics

	US Market Rele	ase	F	eb-93	Serial Number Prefix	ТВН, ТВ	G, TBB, TAD, T	AC, or TAB	US R	eturned Produ	ct Analy	/sis
	Registered US	Implants		8,600	Type and/or Fixation	Epicard	ial Defib Patch	n, Suture		Conductor Fra		7
	Estimated Acti	ive US Implants		1,400	Polarity	Defib E	lectrode only		Crimp/Weld Insulation F			1
	Advisories			None	Steroid	No					oreach Other	1
ystem	n Longevity S	Study Result	s		Qua	lifying Com	plications	51 Total				
	Number of Lea	ads Enrolled in S	itudy	407		Failur	e to Capture	8	I	mpedance Out of	Range	
	Cumulative Mo	onths of Follow-	-Up	20,011		Conduc	ctor Fracture	21		Overs	ensing	1
	Number of Lea	ads Active in Stu	ıdy	7	Insu	lation (not furt	her defined)	2				
10												
10												
9	0											
8	80											
7	/0											
7	0	1	2	3	4	5	6	7	8	9	10	
7	1	1 r Implant	2	3	4	5	6	7	8	9	10	
9 8 7	0	1 r Implant 1 yr	2 2 yr	3 3 yr		5 5 yr	6 6 yr	7 7 7 yr	8 8 yr	9 at 99 mo	10	
	0		_		4 yr	-		1			10	
9	0 Years Afte	1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	at 99 mo		

6930 Sprint Fidelis

Product Characteristics

US Market Release	5ep-04	Serial Number Prefix	LFK	US Returned Product Analysis
Registered US Implants	400	Type and/or Fixation	Transvenous, Vent, Defib and Pace/Sense, Tines	Conductor Fracture 3 Crimp/Weld/Bond 0
Estimated Active US Implants	200	Polarity	True Bipolar/One Coil	Insulation Breach 0
Advisories See page 142 – 2007 Potential Conduct		Steroid	Yes	Other 0
Wire Fracture	JI			

System Longevity Study Results

Qualifying Complications 0 Total

Number of Leads Enrolled in Study	4
Cumulative Months of Follow-Up	12
Number of Leads Active in Study	2

	Survival estimation	ate not availabl	e due to insuffi	cient sample size	2						
80 -											
0		⊿	2	3 4	1	5 (6	/ 8	5	9 1	0
0	Years After	Implant	2	3 4	1	5 (6	/ 2	3 9	9	0
0	Years After	Implant	2	3 4			6	/ 2	5 5	9 1	0
0	Years After	Implant		3 4		5 (6	/ 2	3 5	9 1	0
	Years After	Implant	2	3 4			b		3		
%	Years After	Implant									

_	Sprint Fid	CIIS		Product Chara	reteristies					
	US Market Releas	e	Sep-04	Serial Number Pre	efix LF	L		US Returned F	Product An	alysi
	Registered US Im	plants	8,100	Type and/or Fixat		ansvenous, Vent, D crew-in	efib and Pace/Sense,	Conducto Crimp/M	r Fracture /eld/Bond	363
	Estimated Active	US Implants	4,800	Polarity	Tr	ue Bipolar/One Coi			on Breach	C
	Advisories			Steroid	Ye	25			Other	2
	See page 142 – Wire Fracture	2007 Potential C	onductor							
sten	n Longevity Stu	udy Results			Qualifying	Complications	16 Total			
	Number of Leads	Enrolled in Stud	y 294	ł	L€	ad Dislodgement	2	Impedance O	ut of Range	3
	Cumulative Mont	hs of Follow-Up	10,456	5		Failure to Capture	3	C	versensing	3
	Number of Leads	Active in Study	189)	C	onductor Fracture	3		OTH	1
						Failure to Sense	1			
10	0									
10	0									
9	Ŭ									
9	Ŭ									
9	0	2	3	4	5	6	7 8	9	10	
9	0		3	4	5	6	7 8	9	10	
9	0 1	Implant	3 2 yr 3		5	6	7 8	9	10	
8	0 1	Implant 1 yr	-	yr 4 yr	5	6	7 8	9	10	

6932 Sprint

Product Characteristics

JJZ Sprint	1100			
US Market Release	Aug-96 Seria	al Number Prefix TC	A	US Returned Product Analysis
Registered US Implants	15,000 Туре		ansvenous, Vent, Defib and Pa nes	ace/Sense, Conductor Fracture 20 Crimp/Weld/Bond 0
Estimated Active US Implants	5,000 Polar	rity Tr	ue Bipolar/One Coil	Insulation Breach 22
Advisories	None Stero	oid Ye	S	Other 9
ystem Longevity Study Results		Qualifying (Complications 10 Tota	al
Number of Leads Enrolled in Study	411		Failure to Capture 2	Extra Cardiac Stimulation 1
Cumulative Months of Follow-Up	23,850		Failure to Sense 2	Oversensing 4
Number of Leads Active in Study	60	Impeda	nce Out of Range 1	
2 100				
90				
80				
0 1 2 3 4	5 6 7	8 9 10 1	1 12 13 14	15 16 17 18 19 20 21
Years After Implant				
100 90 90 90 80 0 1 2 3 4 Years After Implant 1 yr 2 yr 3 yr 4 y	r 5yr 6yr 7	yr 8yr 9yr 10yr	at 126 mo	
% 99.2 98.3 98.3 98.		7.7 96.8 96.8 96.8	96.8	
# 355 277 230 191	152 125 10	05 92 78 59	49	
Effective Sample Size				

l	JS Mark	et Relea	se			Dec-93	3 9	Serial Nu	mber Pr	efix	T/	AT, TBU,	or TAF				US Re	eturne	d Proc	luct An	alysis
F	Register	ed US In	nplants			16,100	ר כ	Гуре and	/or Fixa	tion	Tr	ansven	ous CS or S	VC Defib						racture	16
E	stimate	ed Activ	e US Imj	olants		2,700	D F	Polarity			0	ne Defi	o Coil						•	d/Bond	(
A	dvisor	ies				None	e 9	Steroid			N	0						inst	liation	Breach Other	32 16
em l	Longe	evity St	udy R	esults						Quali	fying	Comp	lications	56 To	otal						
١	lumbei	r of Lead	s Enroll	ed in Stu	ıdy		966				L	ead Disl	odgement	1			Im	pedanc	e Out of	Range	4
C	Cumula	tive Mor	nths of F	ollow-U	р	49	9,814					Failure	to Capture	8			Unsp	pecified	Clinical	Failure	4
١	lumbei	r of Lead	s Active	in Stud	у		25				С	onduct	or Fracture	19			Ext	tra Card	iac Stim	ulation	5
												Failu	re to Sense	1					Overs	ensing	12
										Insula	ation (no	ot furth	er defined)	2							
100																					
90												-									
80												-									
	0	1	2	3 4	4 !	5 (б	7	8	9 1	0	11 ·	12 13	14	15	16	17	18	19	20	21
	Years	After	Implai	nt																	
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	11 yr	at 135 mo								
		00.4	97.5	97.2	96.6	95.0	94.4		92.7	91.3	90.2	90.2	90.2								
%		98.4	21.5	11.2																	

6935 Sprint Quattro Secure

Product Characteristics

1922	Sprint Quattro Secure		Product Characteristics	S		
	US Market Release	Nov-08	Serial Number Prefix	TAU	US Returned Product Analys	is
	Registered US Implants	16,800	Type and/or Fixation	Transvenous, Vent, Defib and Pace/Sense, Screw-in	Conductor Fracture Crimp/Weld/Bond	5
	Estimated Active US Implants	15,700	Polarity	True Bipolar/One Coil	Insulation Breach	0
	Advisories	None	Steroid	Yes	Other	22
	Performance Note: See page 149 -					

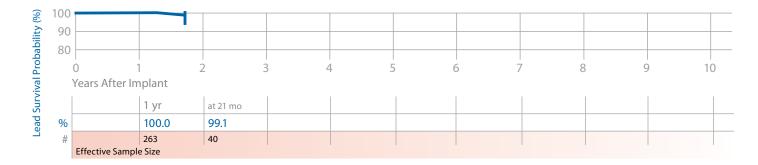
Helix Retraction

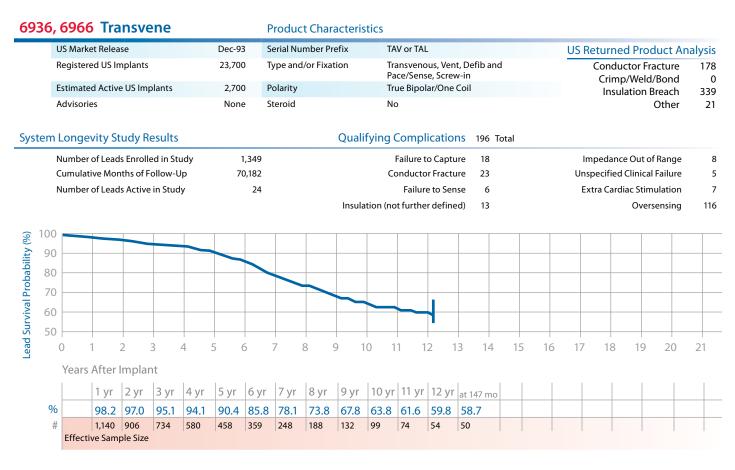
Henx netraction

System Longevity Study Results

Qualifying Complications 1 Total

Number of Leads Enrolled in Study	773	Conductor Fracture 1
Cumulative Months of Follow-Up	8,465	
Number of Leads Active in Study	735	

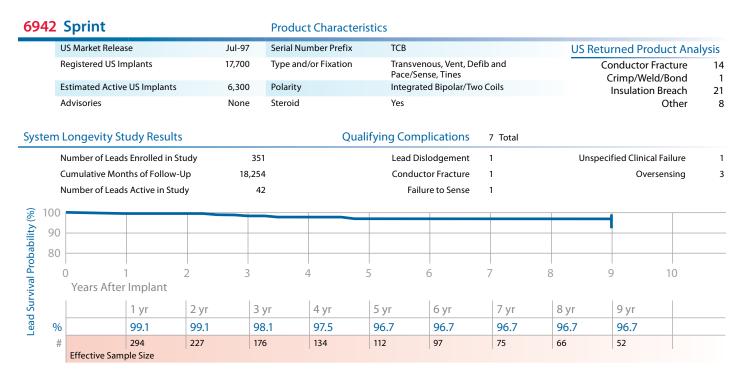




6939, 6999 Sub-Q Patch **Product Characteristics** US Market Release Dec-93 Serial Number Prefix TBA or TAP **US Returned Product Analysis Registered US Implants** 3,600 Type and/or Fixation Subcutaneous Defib Patch, Suture **Conductor Fracture** 28 Estimated Active US Implants Crimp/Weld/Bond 0 300 Polarity Defib Electrode Only **Insulation Breach** 5 Advisories None Steroid No Other 1 System Longevity Study Results **Qualifying Complications** 47 Total Number of Leads Enrolled in Study 384 Failure to Capture 11 Impedance Out of Range 2 Cumulative Months of Follow-Up 18,141 **Conductor Fracture** 12 **Unspecified Clinical Failure** 2 Number of Leads Active in Study Extra Cardiac Stimulation 2 Failure to Sense 1 5 Insulation (not further defined) 4 Oversensing 10 Lead Survival Probability (%) 90 80 9 2 3 4 5 6 7 8 10 Years After Implant 4 yr 2 yr 3 yr 5 yr 6 yr 7 yr 1 yr at 93 mo % 96.0 94.1 93.7 93.7 91.5 88.3 86.0 86.0 116 # 311 249 193 146 82 60 50

Leads

Effective Sample Size of Lead Group Overall



-	Sprint				Product C	haracteris	lics						
	US Market Re	lease		Oct-97	Serial Numb	er Prefix	TCE			ι	JS Returned	d Product Ana	lysis
	Registered U	5 Implants		20,800	Type and/or	Fixation		ious, Vent, De 1se, Screw-in	efib and			uctor Fracture p/Weld/Bond	56 1
	Estimated Ac	tive US Impl	ants	7,500	Polarity		True Bipo	olar/One Coil				lation Breach	23
	Advisories			None	Steroid		Yes					Other	11
sten	m Longevity Study Results Number of Leads Enrolled in Study		sults			Qualif	ying Comp	lications	82 Total				
	Number of Le	ads Enrolle	d in Study	1,311			Lead Dis	lodgement	1	Ins	ulation (not fu	rther defined)	1
	Cumulative N	lonths of Fo	llow-Up	76,043	5		Failure	to Capture	11		Impedance	Out of Range	7
	Number of Le	ads Active i	n Study	284	Ļ		Conduct	or Fracture	17		Unspecified (Clinical Failure	3
							Failu	re to Sense	6			Oversensing	35
												Other	1
10	0												
9	0												
8	0												
	0	1	2	3	4	5		6	7	8	9	10	
		ter Implai	nt										
	Years Af			1	4	5 yr	бyr	7 yr	8 yr	9 yr	10 yr	at 123 mo	
10 9 8	Years Af	1 yr	2 yr	3 yr	4 yr	Jyi	O yr			-).		011251110	
%	Years Af	1 yr 98.7	2 yr 97.7	3 yr 96.5	4 yr 95.5	93.7	92.1	91.5	91.2	90.2	90.2	90.2	

			D	. 0.0	Control Nierro	h D (°	TDC						
	US Market Rel			c-00	Serial Num		TDC				US Retur	ned Product	Analysis
	Registered US	Implants	37,	700	Type and/o	or Fixation		svenous, Vent, De e/Sense, Tines	fib and			ductor Fracture	
	Estimated Act	ive US Implants	21,	200	Polarity		True	Bipolar/Two Coils	;			sulation Breach	
	Advisories		Ν	one	Steroid		Yes					Othe	r 10
vsten	n Longevity	Study Results	5			Qua	alifying Co	omplications	5 Total				
	Number of Le	ads Enrolled in S	tudy	362				Failure to Sense	1				
	Cumulative M	onths of Follow-	Up	11,578			Impedan	ce Out of Range	1				
	Number of Le	ads Active in Stu	dy	224			Unspecified	l Clinical Failure	1				
								Oversensing	2				
8 10 10 10 10 10 10 10 10 10 10 10 10 10	-												
8													
0	0	1	2	3	4		5	6	 7	8	9	10	
	Years Aft	er Implant											
5		1 yr	2 yr	3 уі	r 4	l yr	5 yr	бyr	at 78 mo				
ģ	%	100.0	100.0	99.	1 9	97.0	94.4	94.4	94.4				
	#	229	134	101	7	'8	61	56	50				

	Sprir									~											
	US Marke					Sep-97		erial Nur			TDA						US Re	eturne	ed Proc	duct Ar	alysis
F	Registere	ed US Im	plants			42,800) Ty	/pe and,	/or Fixat	ion		svenous, e/Sense, S		fib and					uctor Fr p/Weld		107
E	Estimate	d Active	US Imp	lants		15,100	P	olarity			Inte	grated Bip	olar/Tw	o Coils					lation E		31
ŀ	Advisorie	25				None	s St	teroid			Yes									Other	15
tem	Longe	vity St	udy Re	sults						Qualif	ying Co	omplica	tions	36 To	otal						
1	Number	of Leads	5 Enrolle	d in Stu	ıdy	1	,154				Fa	ilure to Ca	apture	2			Unsp	pecified	l Clinical	Failure	1
C	Cumulati	ve Mon	ths of Fo	ollow-U	р	63	,334				Con	ductor Fr	acture	6			Ex	tra Carc	liac Stim	ulation	1
1	Number	of Leads	Active	in Study	y		164					Failure to	Sense	4					Over	sensing	17
1	Number	of Leads	Active	in Study	ý		164			I		Failure to ce Out of		4 5					Over	sensing	17
1	Number	of Leads	Active	in Study	y		164			I									Over	sensing	17
۱ 100	Number	of Leads	S Active	in Study	y		164			1									Over	sensing	17
	Number	of Leads	Active	in Study	y		164			1									Over	sensing	17
100 90	Number	of Leads	Active	in Study	y		164												Over	sensing	17
100 90 80	Number	of Leads	Active	in Study		5 6		7 8	3 9		mpedan				15	16	17	18	Over:	sensing	21
100 90 80	0		2 3	3 2		5 6		7 8	3 9		mpedan	ce Out of	Range	5	15	16	17	18			
100 90 80	0		Active	3 2		5 6		7 8	3 9		mpedan	ce Out of	Range	5	15	16	17	18			
100 90 80	0		2 3 Impla	3 2 nt	4 5	5 6		7 E	8 yr		mpedan	ce Out of	Range	5	15	16	17	18			
100 90 80	0 f	After	2 3 Impla	3 2 nt			5			9 yr	mpedan 11 10 yr 1 1	ce Out of 12	Range	5	15	16	17	18			

	US Market Release	Nov-01	Serial Number Prefix	TDG		US Retur	ned Product Ar	nalysi
	Registered US Implants	303,100	Type and/or Fixation	Transvenous, Vent, De Pace/Sense, Screw-in	efib and		iductor Fracture imp/Weld/Bond	21
	Estimated Active US Implants	217,100	Polarity	True Bipolar/Two Coil	s		sulation Breach	1
	Advisories	None	Steroid	Yes			Other	14
	Performance Note: See page 14 Helix Retraction	<u> 19</u> -						
en	n Longevity Study Results		Qual	ifying Complications	28 Total			
	Number of Leads Enrolled in Study	2,698		Lead Dislodgement	3	Impeda	ance Out of Range	
	Cumulative Months of Follow-Up	93,822	!	Failure to Capture	1	Unspecifi	ied Clinical Failure	
	Number of Leads Active in Study	1,618	ł	Conductor Fracture	4		Oversensing	
				Failure to Sense	2			
			Insul	Failure to Sense ation (not further defined)	2 2			
10			Insul			-		
9	0		Insul			-1		
	0		Insul					
9	0	3				8 9	10	
9	0	3		ation (not further defined)		8 9	10	
9	0 0 0 1 2 Years After Implant	3 yr 3	4	ation (not further defined)			10 at 99 mo	
9	0 0 0 1 2 Years After Implant 1 yr 2	_	4 /r 4 yr	ation (not further defined)	2	8 yr		

6948 Sprint Fidelis

Product Characteristics

US Market Release	Sep-04	Serial Number Prefix	LFH	US Returned Product Ana	alysis
Registered US Implants	10,400	Type and/or Fixation	Transvenous, Vent, Defib and Pace/Sense, Tines	Conductor Fracture Crimp/Weld/Bond	80
Estimated Active US Implants	6,300	Polarity	True Bipolar/Two Coils	Insulation Breach	1
Advisories		Steroid	Yes	Other	6
See page 142 – 2007 Potential Co	nductor				

Qualifying Complications

0 Total

See page 142 – 2007 Potential Conductor Wire Fracture

System Longevity Study Results

Number of Leads Enrolled in Study	30
Cumulative Months of Follow-Up	1,237
Number of Leads Active in Study	19

100 90	Survival estim	ate not availabl	e due to insuffi	cient sample size	e					
90										
80										
C	0 1	2)	3 4	- 5	6	7	8	9	1
0	0 1 Years After In	2 nplant		3 4	5	6) 7 	8	9	
%	0 1 Years After In	2 nplant		3 4	5	6)	/ 8	9	1

	-	delis	-							
	US Market Relea		Sep		erial Number Prefix	LFJ			US Returned Product A	nalysi
	Registered US I	mplants	186,	800 T	ype and/or Fixation	Trans Screw		fib and Pace/Sense,	Conductor Fracture Crimp/Weld/Bond	408
	Estimated Activ	e US Implants	105,	300 P	olarity	True E	Bipolar/Two Coil	S	Insulation Breach	
	Advisories See page 142 Wire Fracture	– 2007 Potentia	al Conductor	S	teroid	Yes			Other	6
tem	n Longevity S	tudy Results	5		Qua	alifying Co	mplications	44 Total		
	Number of Lead	ds Enrolled in St	tudy	795		Lead	Dislodgement	1	Insulation (not further defined)	
	Cumulative Mo	nths of Follow-I	Up	32,621		Fail	ure to Capture	2	Impedance Out of Range	
	Number of Lead	ds Active in Stud	dy	424		Cond	uctor Fracture	18	Oversensing	1
						F	ailure to Sense	2	Other	
100 90 80		1	2	3	4	5	6	7 8	9 10	
	Years Afte		~	5		5	0	/ 0	9 10	
		1 yr	2 yr	3 yr	4 yr	5 yr	at 66 mo			
0	6	98.8	96.9	94.9	93.8	92.5	91.3			
7						112	50			

996 5	Sub-Q Lead		Product Charact	teristics			
U	JS Market Release	Jun-01	Serial Number Prefix	C TCR		US Returned Product An	alysis
R	legistered US Implants	3,100	Type and/or Fixation	n Subcutaneous De	efib Coil, Suture	Conductor Fracture	7
Es	stimated Active US Implants	1,900	Polarity	One Defib Coil		Crimp/Weld/Bond Insulation Breach	C
A	dvisories	None	Steroid	No		Other	C
stem L	Longevity Study Results		Q	ualifying Complicatio	ns 1 Total		
N	lumber of Leads Enrolled in Study	28	3	Conductor Fract	ure 1		
C	Cumulative Months of Follow-Up	777	,				
N	lumber of Leads Active in Study	18	3				
100 90 80	Survival estimate not available du	ue to insufficie	ent sample size				
90							
80							
	0 1 2	3	4	5 6	7	8 9	10
	Years After Implant						
%							
#							
	Effective Sample Size						

Leads

		əssələ	pə	۲put2 ni ع		sdînoM virês	Device :	survival F	Device Survival Probability (%)	ty (%)									
ımber odel	λlim	אפרket R	lloın∃ sba	əvitɔA ɛbɕ pirifying	oiteoilqm	əvitelum 1U-wollo7	Years Al	lqn											
NN W	1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1 1	sn [ъŢ	r	^۲ כס		— F					6 yr	7 yr	8 yr	10 yr	12 yr	14 yr	16 yr	18 yr
6721, 6921	Epicardial Patch	Feb-93	407	~	51	20,011	96.5 +1.5/-2.4	95.0 +1.8/-2.8	92.3 +2.5/-3.5	91.3 +2.7/-3.8	88.7 +3.4/-4.7	81.6 +5.1/-6.6	79.6 +5.5/-7.2	79.6 +5.5/-7.2	79.6 +5.5/-7.2 at 99 mo				
6930	Sprint Fidelis	Sep-04	4	2	0	127	100.0 at 0 mo												
	Advisories: See page 142 – 2007 Potential Conductor Wire Fracture	007 Potentia	al Conduct	or Wire Frac	ture														
6931	Sprint Fidelis	Sep-04	294	189	16	10,456	98.2 +1.1/-2.5	95.8 +1.9/-3.2	93.7 +2.5/-3.9	93.7 +2.5/-3.9									
	Advisories: See page 142 – 2007 Potential Conductor Wire Fracture	007 Potentia	al Conduct	or Wire Frac	ture														
6932	Sprint	96-96	411	60	10	23,850	99.2 +0.5/-1.7	98.3 +0.9/-2.1	98.3 +0.9/-2.1	98.3 +0.9/-2.1	97.7 +1.3/-2.5	97.7 +1.3/-2.5	97.7 +1.3/-2.5	96.8 +1.7/-3.9	96.8 +1.7/-3.9	96.8 +1.7/-3.9 at 126 mo			
6933, 6937, 6937A, 6963	svc/cs	Dec-93	966	25	56 4	49,814	98.4 +0.7/-1	97.5 +0.9/-1.3	97.2 +0.9/-1.4	96.6 +1.1/-1.6	95.0 +1.6/-2.1	94.4 +1.7/-2.3	93.2 +2/-2.8	92.7 +2.2/-3.1	90.2 +3.2/-4.7	90.2 +3.2/-4.7 at 135 mo			
6935	Sprint Quattro Secure Nov-08 773 735 1 See page 149 – Performance note on Helix Retraction 6935 and 6947	Nov-08 e note on Hel	773 lix Retractio	735 on 6935 and	1 16947	8,465	100.0	99.1 +0.8/-5.6 at 21 mo											
6936, 6966	Transvene	Dec-93	1,349	24	196	70,182	98.2 +0.6/-1	97.0 +0.8/-1.2	95.1 +1.2/-1.5	94.1 +1.3/-1.7	90.4 +1.9/-2.3	85.8 +2.5/-3	78.1 +3.5/-3.9	73.8 +3.9/-4.4	63.8 +5.1/-5.7	59.8 +5.8/-6.4	58.7 +6.1/-6.7 at 147 mo		
6939, 6999	Sub-Q Patch	Dec-93	384	7	47	18,141	96.0 +1.6/-2.7	94.1 +2/-3.2	93.7 +2.1/-3.3	93.7 +2.1/-3.3	91.5 +2.9/-4.4	88.3 +3.8/-5.5	86.0 +4.6/-6.5	86.0 +4.6/-6.5 at 93 mo					
6942	Sprint	Jul-97	351	42	7	18,254	99.1 +0.6/-1.9	99.1 +0.6/-1.9	98.1 +1.1/-2.8	97.5 +1.4/-3.2	96.7 +1.8/-3.8	96.7 +1.8/-3.8	96.7 +1.8/-3.8	96.7 +1.8/-3.8	96.7 +1.8/-3.8 at 108 mo				
6943	Sprint	Oct-97	1,311	284	82 7	76,043	98.7 +0.5/-0.9	97.7 +0.7/-1.1	96.5 +0.9/-1.3	95.5 +1.1/-1.4	93.7 +1.4/-1.8	92.1 +1.7/-2	91.5 +1.8/-2.3	91.2 +1.8/-2.3	90.2 +2.2/-2.8	90.2 +2.2/-2.8 at 123 mo			
6944	Sprint Quattro	Dec-00	362	224	ŝ	11,578	100.0	100.0	99.1 +0.8/-5.5	97.0 +2/-6.1	94.4 +3.2/-7.6	94.4 +3.2/-7.6	94.4 +3.2/-7.6 at 78 mo						
6945	Sprint	Sep-97	1,154	164	36 6	63,334	99.4 +0.4/-0.6	98.7 +0.5/-1	98.3 +0.6/-1.1	97.7 +0.8/-1.3	96.8 +1.1/-1.6	96.1 +1.3/-1.9	95.5 +1.4/-2.1	94.3 +1.8/-2.6	93.2 +2.2/-3.1	93.2 +2.2/-3.1 at 129 mo			
6947	Sprint Quattro Secure Nov-01 2,698 1,618 28 See page 149 – Performance note on Helix Retraction 6935 and 6947	Nov-01 e note on He	2,698 Iix Retracti	1,618 ion 6935 and		93,822	99.5 +0.2/-0.3	99.4 +0.2/-0.5	99.1 +0.3/-0.7	98.7 +0.5/-0.8	98.4 +0.6/-1	98.0 +0.7/-1.2	97.3 +1.1/-1.7	97.3 +1.1/-1.7	96.1 +2/-3.7 at 99 mo				
6948	Sprint Fidelis	Sep-04	30	19	0	1,237	100 .0 at 0 mo												
	Advisories: See page 142 – 2	– 2007 Potential Conductor Wire Fracture	al Conduct	or Wire Frac	ture														
6949	Sprint Fidelis	Sep-04	795	424	,	32,621	98.8 +0.6/-1.1	96.9 +1.1/-1.5	94.9 +1.4/-2	93.8 +1.7/-2.2	92.5 +2/-2.7	91.3 +2.7/-3.8 at 66 mo							
	Advisories: See page 142 – 2007 Potential Conductor Wire Fracture	2007 Potentia	al Conduct	or Wire Frac	ture														

www.medtronic.com/CRDMProductPerformance

US Returned Product Analysis Summary

Model Number	Family	US Market Release	Estimated US Implants	Estimated US Active	Conductor Fracture	Crimp/Weld/ Bond	Insulation Breach	Other
6721, 6921	Epicardial Patch	Feb-93	8,600	1,400	70	1	10	1
6930	Sprint Fidelis	Sep-04	400	200	3	0	0	0
6931	Sprint Fidelis	Sep-04	8,100	4,800	363	0	0	2
6932	Sprint	Aug-96	15,000	5,000	20	0	22	9
6933, 6937, 6937A, 6963	SVC/CS	Dec-93	16,100	2,700	168	0	32	16
6935	Sprint Quattro Secure	Nov-08	16,800	15,700	5	0	0	22
6936, 6966	Transvene	Dec-93	23,700	2,700	178	0	339	21
6939, 6999	Sub-Q Patch	Dec-93	3,600	300	28	0	5	1
6942	Sprint	Jul-97	17,700	6,300	14	1	21	8
6943	Sprint	Oct-97	20,800	7,500	56	1	23	11
6944	Sprint Quattro	Dec-00	37,700	21,200	56	2	2	10
6945	Sprint	Sep-97	42,800	15,100	107	3	31	15
6947	Sprint Quattro Secure	Nov-01	303,100	217,100	212	4	14	143
6948	Sprint Fidelis	Sep-04	10,400	6,300	80	0	1	6
6949	Sprint Fidelis	Sep-04	186,800	105,300	4,081	3	9	69
6996	Sub-Q Lead	Jun-01	3,100	1,900	7	0	0	0

US Reports of Acute Lead Observations

Model Number	Family	Estimated US Implants	Cardiac Perforation	Conductor Fracture	Lead Dislodgement	Failure to Capture	Oversensing	Failure to Sense		Impedance Abnormal	Extracardiac Stimulation	Unspecified
6721, 6921	Epicardial Patch	8,600	1	1	0	0	1	0	2	4	0	4
6931	Sprint Fidelis	8,100	1	2	1	1	3	1	0	0	0	1
6932	Sprint	15,000	0	0	5	2	0	2	0	1	0	1
6933, 6937, 6937A, 6963	SVC/CS	16,100	0	0	2	1	1	0	2	1	0	4
6935	Sprint Quattro Secure	16,800	4	3	7	10	10	2	1	7	1	0
6936, 6966	Transvene	23,700	7	2	1	6	4	5	1	1	0	5
6939, 6999	Sub-Q Patch	3,600	0	0	0	0	0	0	0	1	0	1
6942	Sprint	17,700	1	1	2	4	1	0	0	2	0	1
6943	Sprint	20,800	1	0	0	3	1	1	1	3	0	0
6944	Sprint Quattro	37,700	1	1	9	10	8	2	0	7	0	7
6945	Sprint	42,800	0	1	4	6	8	2	2	1	1	3
6947	Sprint Quattro Secure	303,100	15	17	69	43	86	26	3	43	1	14
6948	Sprint Fidelis	10,400	0	1	7	7	1	0	0	1	0	0
6949	Sprint Fidelis	186,800	9	35	28	33	29	23	6	23	0	14
6996	SubQ	3,100	0	0	1	0	1	0	0	1	0	1

Report Cutoff Date: January 31, 2011

Reference Chart

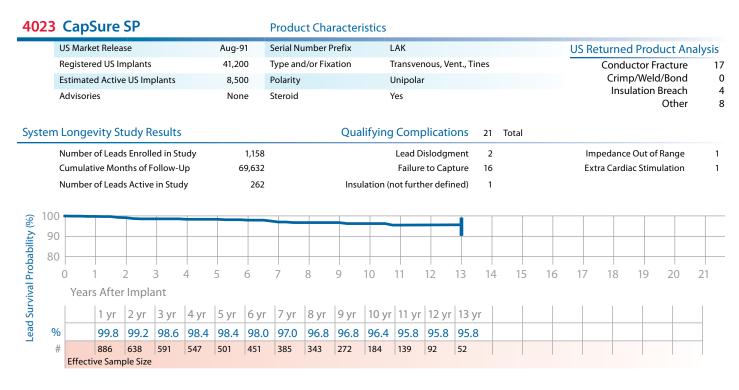
			Pin Conf	iguration	_		
Model Number	Family	Туре	Pace/Sense	High Voltage	Lead Body Diameter	Insulation, Lead Body	Fixation, Steroid
6721	Epicardial Patch	Epi Patch	—	DF-1	S, M, L	Silicone, Single Lumen	Suture
6921	Epicardial Patch	Epi Patch	_	6.5 mm	S, M, L	Silicone, Single Lumen	Suture
6930	Sprint Fidelis	Endo RV True Bipolar Sensing	IS-1	DF-1	6.6 Fr	Silicone with Polyurethane Overlay, Multilumen	Passive, Steroid
6931	Sprint Fidelis	Endo RV True Bipolar Sensing	IS-1	DF-1	6.6 Fr	Silicone with Polyurethane Overlay, Multilumen	Active, Steroid
6932	Sprint	Endo RV True Bipolar Sensing	IS-1	DF-1	7.8 Fr	Silicone, Multilumen	Passive, Steroid
6933	SVC/CS	Endo SVC/CS Coil	_	DF-1	7 Fr	Silicone, Single Lumen	Passive
6934S	Transvene	Endo RV True Bipolar Sensing	IS-1	DF-1	12 Fr	Silicone, Coaxial	Passive, Steroid
6935	Sprint Quattro Secure	Endo RV True Bipolar Sensing	IS-1	DF-1	8.2 Fr	Silicone with Polyurethane Overlay, Multilumen	Active, Steroid
6936	Transvene	Endo RV True Bipolar Sensing	IS-1	DF-1	10 Fr	Polyurethane, Coaxial	Active
6937	SVC/CS	Endo SVC Coil	_	DF-1	5.5 Fr	Silicone, Single Lumen	Passive
6937A	SVC/CS	Endo SVC Coil	_	DF-1	7.5 Fr	Silicone with Polyurethane Overlay, Single Lumen	Passive
6939	Sub-Q Patch	SQ Patch	_	DF-1	One Size	Silicone, Single Lumen	Suture
6942	Sprint	Endo RV/SVC Integrated Bipolar Sensing	IS-1	2 DF-1	7.8 Fr	Silicone, Multilumen	Passive, Steroid
6943	Sprint	Endo RV True Bipolar Sensing	IS-1	DF-1	7.8 Fr	Silicone, Multilumen	Active, Steroid
6944	Sprint Quattro	Endo RV/SVC True Bipolar Sensing	IS-1	2 DF-1	8.2 Fr	Silicone with Polyurethane Overlay, Multilumen	Passive, Steroid
6945	Sprint	Endo RV/SVC Integrated Bipolar Sensing	IS-1	2 DF-1	7.8 Fr	Silicone, Multilumen	Active, Steroid
6947	Sprint Quattro Secure	Endo RV/SVC True Bipolar Sensing	IS-1	2 DF-1	8.2 Fr	Silicone with Polyurethane Overlay, Multilumen	Active, Steroid
6948	Sprint Fidelis	Endo RV/SVC True Bipolar Sensing	IS-1	2 DF-1	6.6 Fr	Silicone with Polyurethane Overlay, Multilumen	Passive, Steroid
6949	Sprint Fidelis	Endo RV/SVC True Bipolar Sensing	IS-1	2 DF-1	6.6 Fr	Silicone with Polyurethane Overlay, Multilumen	Active, Steroid
6963	SVC/CS	Endo SVC/CS Coil	_	6.5 mm	7 Fr	Silicone, Single Lumen	Passive
6966	Transvene	Endo RV True Bipolar Sensing	3.2 mm L.P.	6.5 mm	10 Fr	Polyurethane, Coaxial	Active
6996	Sub-Q Lead	SQ Coil	_	DF-1	7.5 Fr	Silicone, Single Lumen	Passive
6999	Sub-Q Patch	SQ Patch	_	6.5 mm	One Size	Silicone, Single Lumen	Suture

Pacing Leads

3830 SelectSecure **Product Characteristics** US Market Release Aug-05 Serial Number Prefix LFF **US Returned Product Analysis Registered US Implants** 18,800 Type and/or Fixation Transvenous, V or A, Screw-in **Conductor Fracture** 2 Crimp/Weld/Bond 0 Estimated Active US Implants 15,500 Polarity Bipolar Insulation Breach 6 Advisories Steroid None Yes Other 5 **Atrial Placement** System Longevity Study Results **Qualifying Complications** 1 Total Number of Leads Enrolled in Study 596 Failure to Sense 1 Cumulative Months of Follow-Up 12,367 Number of Leads Active in Study 500 Lead Survival Probability (%) 100 90 80 0 2 3 4 5 6 8 9 10 7 Years After Implant 1 yr 2 yr 3 yr 4 yr 5 yr 99.8 % 99.8 99.8 99.8 99.8 # 271 142 101 64 48 Effective Sample Size

Ventricular Placement

tem L	ongevity St	udy Results			Q	ualifying Co	mplications	2 Tota	al		
С	lumber of Lead umulative Mon	ths of Follow-U	Jp	374 9,721		Impedanc	e Out of Range	2			
N	lumber of Lead	s Active in Stuc	ly	281							
100						_					
90											
80											
(0	1	2	3	4	5	6	7	8	9	10
	Years After	Implant									
		1 yr	2 yr	3 yr	4 yr	5 yr					
%		100.0	100.0	100.0	100.0	100.0					
#		202	123	92	66	50					
	Effective Sam	ple Size									

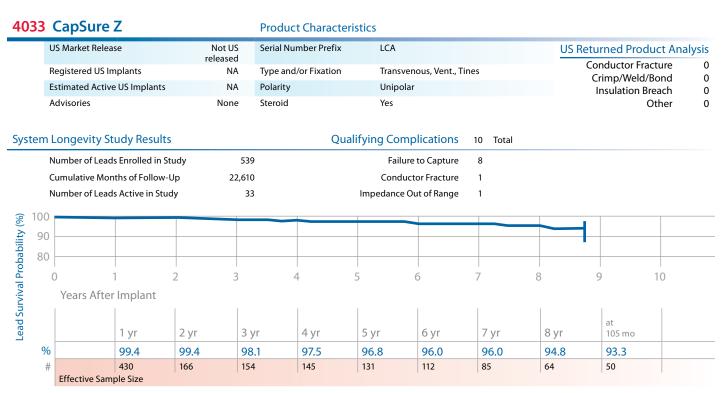


4024 CapSure SP

Product Characteristics

	US Market Release	Oct-91	Serial Number Pr	efix LAJ		US Returned Product Ana	lysis
	Registered US Implants	222,300	Type and/or Fixat	tion Transvenous, Vent., Tin	les		
	Estimated Active US Implants	48,500	Polarity	Bipolar		Conductor Fracture	28
	Advisories	None	Steroid	Yes		Crimp/Weld/Bond Insulation Breach Other	0 148 41
Syster	m Longevity Study Results			Qualifying Complications	4 Total		
	Number of Leads Enrolled in Study	1,21	5	Failure to Capture	3		
	Cumulative Months of Follow-Up	30,182	2	Insulation (not further defined)	1		
	Number of Leads Active in Study	19	9				





4067 CapSureFix

Product Characteristics

stered US Implants nated Active US Implants sories gevity Study Result ber of Leads Enrolled in St ulative Months of Follow ber of Leads Active in St	Non ts Study r-Up 1	00 Polar	bid	Unipo Yes lifying Con Failu	enous, V or A, S lar nplications ure to Capture Out of Range	crew-in 8 Total 6 1			r Fracture /eld/Bond on Breach Other	1 C C 1
sories gevity Study Result ber of Leads Enrolled in ulative Months of Follow	Non ts Study r-Up 1	ne Sterc 171 10,425	bid	Yes lifying Con Failu	nplications ire to Capture	6			on Breach	
gevity Study Result ber of Leads Enrolled in ulative Months of Follow	ts Study '-Up 1	171 10,425		lifying Con Failu	ire to Capture	6		Insulatio		
ber of Leads Enrolled in Sulative Months of Follow	Study r-Up 1	10,425	Qua	Failu	ire to Capture	6				
ulative Months of Follow	r-Up 1	10,425			-					
	•			Impedance	Out of Range	1				
ber of Leads Active in St	udy	48								
					Oversensing	1				
1	2	3	4	5	6	7	8	9	10	
ears After Implant										
						at				
1 yr	2 yr	3 yr	4 yr	5 yr	бyr	78 mo				
98.1	98.1	98.1	98.1	98.1	98.1	98.1				
130	98	90	82	77	65	50				
	1 yr 98.1	1 yr 2 yr 98.1 98.1 130 98	ars After Implant 1 yr 2 yr 3 yr 98.1 98.1 98.1 130 98 90	ars After Implant 1 yr 2 yr 3 yr 4 yr 98.1 98.1 98.1 98.1 130 98 90 82	ars After Implant 1 yr 2 yr 3 yr 4 yr 5 yr 98.1 98.1 98.1 98.1 98.1 130 98 90 82 77	ars After Implant 1 yr 2 yr 3 yr 4 yr 5 yr 6 yr 98.1 98.1 98.1 98.1 98.1 98.1 130 98 90 82 77 65	ars After Implant 1 yr 2 yr 3 yr 4 yr 5 yr 6 yr $\frac{at}{78 \text{ mo}}$ 98.1 98.1 98.1 98.1 98.1 98.1 98.1 98.1 130 98 90 82 77 65 50	ars After Implant 1 yr 2 yr 3 yr 4 yr 5 yr 6 yr at 78 mo 98.1 98.1 98.1 98.1 98.1 98.1 98.1 130 98 90 82 77 65 50	ars After Implant 1 yr 2 yr 3 yr 4 yr 5 yr 6 yr at 78 mo 98.1 98.1 98.1 98.1 98.1 98.1 98.1 98.1 130 98 90 82 77 65 50 0	ars After Implant 1 yr 2 yr 3 yr 4 yr 5 yr 6 yr at 78 mo at 78 mo 98.1

#		1,907	1,180	1,074	968	863	752	617	485	336	238	181	119	59	46						
%		98.9	98.7	98.1	97.8	97.2	96.9	96.6	95.8	95.2	94.5	93.2	91.9	91.1	91.1						
		1 yr	2 yr	3 yr	4 yr	5 yr	бyr	7 yr	8 yr	9 yr	10 yr	11 yr	12 yr	13 yr	159 mo						
					1	1				1					at				1		
	-	s After	~ Impl:	0				, (· 1	- I		- I	5	15	10	17	.0		20	~ I
	0	1	2	3	4	т 5 б	5	7 8	3 9) 10	0 1	1 1	2 1	1 I 3 14	15	16	17	18	19	20	21
80																					
90																					
100																					
																			Overs	ensing	:
										Insula	tion (no	t furthe	r define	d) 1			Ext	tra Cardi	ac Stim	ulation	:
												Failure	e to Sen	se 11			Unsp	pecified	Clinical	Failure	
Ν	Number	of Lead	s Active	e in Stud	y		447				Co	nducto	r Fractu	re 2			Im	pedanc	e Out of	Range	
	Cumulat					124	,040						o Captu					Ir	sulatio	n (MIO)	:
Ν	Number	of Lead	s Enroll	ed in Stu	udy	2	2,413				Le	ad Dislo	dgeme	nt 8				Iı	nsulatio	n (ESC)	
	Longe		udy R	esults						Qualif	^f ying C	Compl	icatior	1S 66	Total						
sial D	lacen																			Other	1
A	Advisori	es				None	e S	teroid			Yes	5						Insu	lation	Breach	11
E	Estimate	d Active	e US Im	plants		36,000) P	olarity			Bip	olar						Crim	p/Welc	l/Bond	
F	Register	ed US In	nplants			124,200) T	ype and/	or Fixat	ion	Tra	nsveno	us, V or	A, Screw	-in					acture	4
ι	JS Mark	et Relea	se			Mar-96	5 S	erial Nur	nber Pre	efix	LCI	E					US Re	eturne	d Proc	luct An	alvsi

Ventricular Placement

	onge	, 50								20.011		· · · P	ications	42	Total						
Ν	lumber	of Lead	s Enrolle	ed in Stu	dy	1	,799					Failure	o Capture	21			lm	pedanc	e Out of	Range	
C	umulati	ve Mor	nths of F	ollow-Up	C	90),731				C	onducto	or Fracture	2			Unsp	pecified	Clinical	Failure	
Ν	lumber	of Lead	s Active	in Study	,		377					Failur	e to Sense	3			Ext	tra Cardi	ac Stim	ulation	
																			Overs	ensing	
100																					
90																					
80													I								
(0	1	2	3 4	4 !	5 (6	7	8	9 1	0	1 '	2 13	14	15	16	17	18	19	20	2
	Years	s After	r Impla	nt																	
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	11 yr	12 yr								
%		99.3	98.7	98.7	98.1	97.7	97.2	96.1	95.8	94.2	94.2	94.2	92.8								
#		1,428	950	863	764	676	576	446	295	179	106	71	51								
	Effectiv		ple Size																		

4073 CapSure Sense

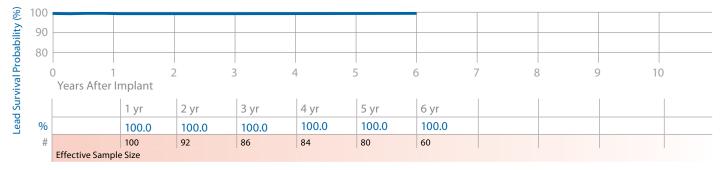
Product Characteristics

•				
US Market Release	Jun-02	Serial Number Prefix	BBF	US Returned Product Analysis
Registered US Implants	700	Type and/or Fixation	Transvenous, Vent., Tines	Conductor Fracture 0
Estimated Active US Implants	400	Polarity	Unipolar	Crimp/Weld/Bond 0
Advisories	None	Steroid	Yes	Insulation Breach 0 Other 0

System Longevity Study Results

Qualifying Complications 0 Total

Number of Leads Enrolled in Study102Cumulative Months of Follow-Up6,820Number of Leads Active in Study74



	US Market Release	Jun-02	Serial Num	ber Prefix	BBD		US Returne	ed Product Ana	alysi
	Registered US Implants	79,400	Type and/o	or Fixation	Transvenous, Vent.,	Tines	-	uctor Fracture	
	Estimated Active US Implants	52,200	Polarity		Bipolar			p/Weld/Bond	
	Advisories	None	Steroid		Yes		Insu	llation Breach Other	1
ial	al Placement								
ter	em Longevity Study Results			Qualifyi	ng Complication	5 2 Total			
	Number of Leads Enrolled in Study	2	14		Lead Dislodgemen	t 1			
	itaniber of Leads Enfonce in Stady	-	••		Lead Disloagemen				
	Cumulative Months of Follow-Up	13,16			Failure to Sense				
		13,16			-				
10	Cumulative Months of Follow-Up	13,16	66		-				
	Cumulative Months of Follow-Up Number of Leads Active in Study	13,16	66		-				
9	Cumulative Months of Follow-Up Number of Leads Active in Study	13,16	66		-				
9	Cumulative Months of Follow-Up Number of Leads Active in Study	13,16	66	5	-		8 9	10	
9	Cumulative Months of Follow-Up Number of Leads Active in Study	13,16	66 60	5	Failure to Sense	2 1 1	8 9	10	
9	Cumulative Months of Follow-Up Number of Leads Active in Study	13,16 16	66 60 4	-	Failure to Sense	2 1 1	8 9	10	
8	Cumulative Months of Follow-Up Number of Leads Active in Study	13,16 16 3 2 yr 5	66 60 4 3 yr	4 yr 5	Failure to Sense	2 1 1 7 1	89	10	

Ventricular Placement

ystem Longevity Study Results Qualifying Complications							3 Total				
C	Number of Leads Enrolled in Study Cumulative Months of Follow-Up Number of Leads Active in Study			606 24,280 482	4,280 Failure to Capture			1 1 1			
001 001 (%) 000 (%) 000 000 000 000 000 000 000 000 000 0											
80	0 1		2	3	4	5	6	7	8	9	10
	Years After	Implant									
; ;		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	at 81 mo			
%		99.6	99.3	99.3	99.3	99.3	99.3	99.3			
#		396	355	327	275	168	76	59			
	Effective Samp	ole Size									

	US Market Release	Feb-04	Serial Number Prefix	BBL			US Ret	urned Produ	ict Anal	lys
	Registered US Implants	322,200	Type and/or Fixation	Transvenous, V or A, S	crew-in		C	Conductor Frac	ture	1
	Estimated Active US Implants	255,300	Polarity	Bipolar				Crimp/Weld/B		
	Advisories	None	Steroid	Yes				Insulation Bre	each ther	1
	Placement n Longevity Study Results		Qu	alifying Complications	5 Tota	I				
	Number of Leads Enrolled in Study	1,658	3	Lead Dislodgement	3					
	Cumulative Months of Follow-Up	45,025	5	Failure to Capture	1					
	Cumulative Months of Follow-Up Number of Leads Active in Study	45,025 1,366		Failure to Capture Failure to Sense	1					
	Number of Leads Active in Study			•	•					
100	Number of Leads Active in Study			•	•					
10(9(Number of Leads Active in Study			•	•	8		9	10	
10(9(Number of Leads Active in Study	1,366	5	Failure to Sense	1	8		9	10	
10(9(Number of Leads Active in Study	1,366	4	Failure to Sense	1	8		9	10	
10(9(8(Number of Leads Active in Study	1,366	5 4 yr 4 yr	Failure to Sense	1	8		9	10	

Syst	em l	Longevity Stu	udy Results			Qı	ualifying Cor	nplications	2 Tota	al		
	C	Number of Leads Cumulative Mont Number of Leads	hs of Follow-U	Jp	1,225 38,151 976		Failt	ure to Capture	2			
Lead Survival Probability (%)	100							•				
	90)										
nan	80)										
-		0	1	2	3	4	5	б	7	8	9	10
2		Years After	Implant									
Inc			1 yr	2 yr	3 yr	4 yr	5 yr	at 69 mo				
בקסר	%		99.8	99.8	99.8	99.8	99.8	99.8				
	#		1,002	548	422	295	133	46				
		Effective Samp	le Size									

4092 CapSure SP Novus

Product Characteristics

	Capsure												
U	JS Market Rele	ease		Sep-98	Serial Number	Prefix	LEP				US Ret	urned Product Ana	alysis
R	legistered US	Implants		166,700	Type and/or Fi	xation	Transvenou	s, Vent., Tir	nes		C	Conductor Fracture	
E	stimated Act	ive US Implai	nts	82,600	Polarity		Bipolar					Crimp/Weld/Bond	
A	dvisories			None	Steroid		Yes					Insulation Breach Other	2
tem l	Longevity	Study Resi	ilts			Qualify	ing Complic	ations	18	Total			
	lumber of Lea	-		1,147	7	Quany	Lead Dislod		4	Iotai	Imp	edance Out of Range	1
	Cumulative Mo			64,009			Failure to	-	9		-	Cardiac Stimulation	1
	lumber of Lea			418			Conductor		3				
100													
100													
90													
90 80													
90 80	0	1	2	3	4		6		7		8	9 10	
90 80 (1 er Implant	2	3	4	5	6		7	1	8	9 10	
90 80 (1 er Implant	2 2 2 yr	3 3 yr	4 4 yr	5 yr	6 6 yr	7 yr	7	8 yr	8 9 yr	9 10 at 111 mo	
80			1	- I	1	I.		7 yr 97.9	7	I			

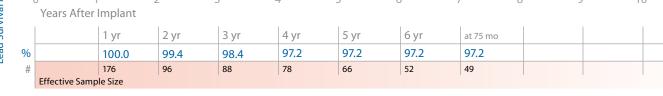
4523 CapSure SP

	Aug-9	Serial N	umber Prefix	ZE			US Retur	ned Product An	alysis
Registered US Implants	11,20) Type ar	d/or Fixation	Transvenous, Atrial-	J, Tines	;	Co	nductor Fracture	
Estimated Active US Implan	ts 2,70	D Polarity	,	Unipolar				rimp/Weld/Bond	
Advisories	Non	e Steroid		Yes			I	nsulation Breach Other	
stem Longevity Study Resu	llts		Qualif	ying Complications	4	Total			
Number of Leads Enrolled ir	n Study	121		Lead Dislodgement	2				
Cumulative Months of Follo	w-Up	5,819	h	mpedance Out of Range	1				
Number of Leads Active in S	Study	11		Oversensing	1				
100		1							
100									
90									
90 80									
90 80 Vears After Implant		3	4 5	6	7	8	9	10	
90 90 80 0 1 Years After Implant 1 yr		3 at 27 mo	4 5	6	7	8	9	10	
80 0 1 Years After Implant			4 5	6	7	8	9	10	

4524 CapSure SP **Product Characteristics** US Market Release Oct-91 Serial Number Prefix LAR **US Returned Product Analysis Registered US Implants** 101,800 Type and/or Fixation Transvenous, Atrial-J, Tines **Conductor Fracture** 1 Crimp/Weld/Bond 0 **Estimated Active US Implants** 27,800 Polarity Bipolar **Insulation Breach** 44 Advisories None Steroid Yes Other 13 System Longevity Study Results **Qualifying Complications** 6 Total Number of Leads Enrolled in Study 911 Lead Dislodgement 1 Cumulative Months of Follow-Up 27,302 Failure to Capture 3 Number of Leads Active in Study 44 Failure to Sense 2 Lead Survival Probability (%) 100 90 80 2 3 4 5 6 8 9 0 7 10 Years After Implant 3 yr 6 yr 7 yr 8 yr 2 yr 4 yr 9 yr 1 yr 5 yr at 114 mo % 99.6 99.2 99.2 98.4 98.4 98.4 98.4 98.4 98.4 98.4 # 682 138 124 112 99 89 81 73 62 51 Effective Sample Size

4533 CapSure Z

Product Characteristics US Market Release Not US Serial Number Prefix LCB **US Returned Product Analysis** released **Registered US Implants** NA Type and/or Fixation Transvenous, Atrial-J, Tines **Conductor Fracture** Estimated Active US Implants NA Polarity Unipolar Crimp/Weld/Bond Advisories None Steroid Yes Insulation Breach Other System Longevity Study Results **Qualifying Complications** 4 Total 206 Lead Dislodgement Oversensing Number of Leads Enrolled in Study 1 Cumulative Months of Follow-Up 10,116 Failure to Capture 1 Number of Leads Active in Study 14 Failure to Sense 1 100 Lead Survival Probability (%) 90 80 2 3 4 5 6 7 8 9 10 0



1

0

0

0

1

4558M Screw-In **Product Characteristics** US Market Release Nov-94 Serial Number Prefix LDC **US Returned Product Analysis Registered US Implants** 20,000 Type and/or Fixation Transvenous, Atrial-J, Screw-in **Conductor Fracture** 1 Estimated Active US Implants 4,800 Crimp/Weld/Bond Polarity Bipolar 1 Insulation Breach 19 Steroid Advisories None No Other 1 System Longevity Study Results **Qualifying Complications** 12 Total 539 Insulation (not further defined) 2 Number of Leads Enrolled in Study **Electrical Abandonment** 1 18,294 3 2 Cumulative Months of Follow-Up Failure to Capture Impedance Out of Range Number of Leads Active in Study 22 Failure to Sense 2 Oversensing 2 100 Lead Survival Probability (%) 90 80 2 3 5 6 7 8 9 10 0 4 Years After Implant 2 yr 3 yr 4 yr 5 yr 6 yr 7 yr 8 yr 9 yr 1 yr % 99.3 99.3 99.3 99.3 99.3 97.2 95.9 95.9 91.1 # 353 125 111 106 99 82 75 62 50 **Effective Sample Size**

4568 CapSureFix

I	US Market Release	Jan-97	Serial Number Prefix	LDD		US Ret	urned Product An	alysi
I	Registered US Implants	69,800	Type and/or Fixation	Transvenous, Atrial-J, S	crew-in	С	Conductor Fracture	
I	Estimated Active US Implants	26,100	Polarity	Bipolar			Crimp/Weld/Bond	
1	Advisories	None	Steroid	Yes			Insulation Breach Other	
em	Longevity Study Results		Qua	lifying Complications	33 Total			
I	Number of Leads Enrolled in Study	656	5	Lead Dislodgement	9	Impe	edance Out of Range	
	C 1.0. M .1. (C. II			Failure to Conture	18			
(Cumulative Months of Follow-Up	31,183	3	Failure to Capture	10		Medical Judgment	
	Cumulative Months of Follow-Up Number of Leads Active in Study	31,183 179		Failure to Capture	3		Medical Judgment	
100 90	Number of Leads Active in Study			•				
100	Number of Leads Active in Study			•		8	9 10	
100 90	Number of Leads Active in Study	175		Failure to Sense	3	8		
100 90	Number of Leads Active in Study	175	4	Failure to Sense	3	8 8 8 yr		
100 90	Number of Leads Active in Study	179 3 yr 3	4	Failure to Sense	3	_	9 10	

4574 CapSure Sense

Product Characteristics

135

US Market Release	Jun-02	Serial Number Prefix	BBE	US Returned Product Analysis
Registered US Implants	51,700	Type and/or Fixation	Transvenous, Atrial-J, Tines	Conductor Fracture 4
Estimated Active US Implants	36,600	Polarity	Bipolar	Crimp/Weld/Bond 0
Advisories	None	Steroid	Yes	Insulation Breach 2
	None	5101010		Other 0

System Longevity Study Results

Number of Leads Enrolled in Study

Qualifying Complications 0 Total

			у	120							
0	Survival estim	ate not availabl	e due to insuffic	ient sample siz	e						
80											
() .	1 2	2 3	3	4	5	6	7	8	9 1	0
	Years After	Implant									
	Years After	Implant									
%	Years After	Implant									

4592 CapSure SP Novus

	US	Market Releas	e	0	ct-98	Serial Numbe	er Prefix	LER			US R	Returned Prod	uct Analys
	Reg	gistered US Im	plants	8	1,300	Type and/or I	Fixation	Transvend	ous, Atrial-J, T	nes		Conductor Fra	cture
	Est				2,700	Polarity		Bipolar				Crimp/Weld/	
	Ad	lvisories		I	None	Steroid		Yes				Insulation B	reach Other
ster	m Lc	ongevity Stu	udy Results	;			Qualify	ing Compl	ications	5 Total			
	Nu	umber of Leads	Enrolled in St	tudy	283			Lead Dislo	odgement	2			
	Cu	imulative Mont	ths of Follow-	Up	14,023			Failure t	o Capture	2			
		n Longevity Study Results Number of Leads Enrolled in Study Cumulative Months of Follow-Up Number of Leads Active in Study											
	Nu	Cumulative Months of Follow-Up Number of Leads Active in Study			79			Failur	e to Sense	1			
10		umber of Leads	Active in Stu	dy	79			Failur	e to Sense	1			
10		umber of Leads	Active in Stu	dy	79			Failur	e to Sense	1	-		
10 9	00	umber of Leads	Active in Stu	dy	79			Failur	e to Sense	1			
10 9 8	00 90 -	umber of Leads	Active in Stu	dy	79	4	5		e to Sense	1	8	9	10
10 9 8	00 90 80 0	umber of Leads					5			1 7	8	9	10
10 9 8	00 90 80 0						5			7	8	9 at	10
10 9 8	00 90 80 0					4				1 7 7 yr	8 8 8 yr		10
8	00 90 80 0		I Implant	2	3	4 /r 4	yr 5	(5	7		at	10

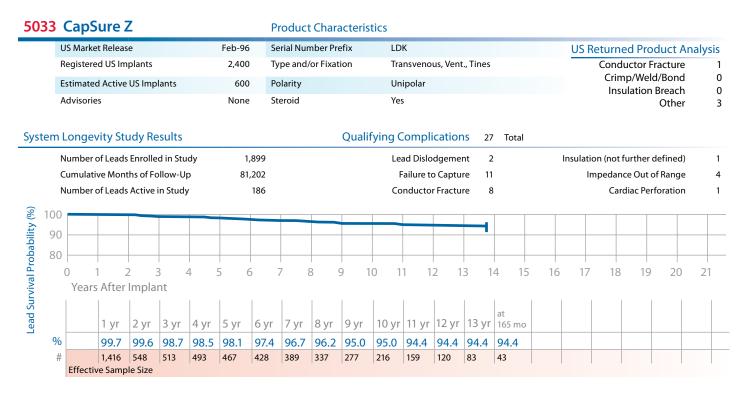
5023, 5023M CapSure SP

Product Characteristics

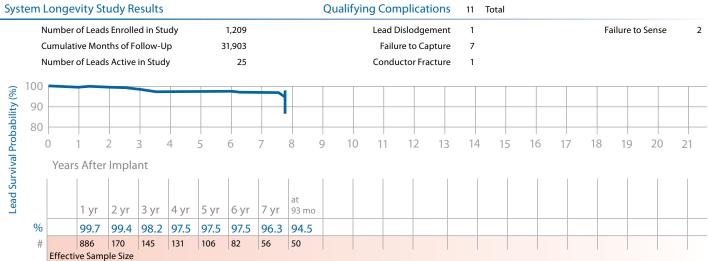
	US	5 Marke	t Releas	se			Nov-8	8 .	Serial Nu	ımber P	refix	SX	or LAS					US Re	turne	d Prod	uct Ar	nalysis
	Re	gistere	d US Im	plants			9,90	0 -	Type and	d/or Fixa	tion	Tra	insvenou	ıs, Vent., Ti	ines				Conduc			6
	Est	Longevity Study Results					2,30	0 1	Polarity			Un	ipolar							/Weld/		0
	Ad	Advisories				Non	e s	Steroid			Ye	5						Insula	ation B	reach Other	1 0	
		Longevity Study Results																	,	Julei	0	
ysten	n Lo	ongev	ity St	udy Re	esults						Qual	ifying C	Compli	cations	19	Total						
	Νu	umber c	of Leads	Enrolle	d in Stu	udy		1,354				F	ailure to	Capture	10			Ext	ra Cardi	ac Stimu	ulation	4
	Cu	Number of Leads Enrolled in Study Cumulative Months of Follow-Up			lp	7	9,518				Co	nductor	Fracture	3								
	Νu	umber c	of Leads	Active	in Stud	у		365				Impeda	nce Out	of Range	2							
<u>s</u> 10	0 -																					
<u>6</u> 9																						
8 8					-	4	-	_	-	-		10 1	1 17	12	1.4	15	1.0	17	10	10	20	
al P	0		After	z Impla	3 nt	4	5	6	/	8	9	10 1		2 13	14	15	16	17	18	19	20	21
2 Z	I	rears	/ liter			1	1	1	I	1	1	1	1		I	1	I	I				
Lead Survival Probability (%) 8 6 01			1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	11 yr	12 yr								
a	v <u> </u>		99.7	99.7	99.5	99.4	99.4	98.9	97.4	97.4	97.1	96.6	95.7	95.7								
ý Ľe																						
- '	#		1,077	818	760	698	617	545	423	331	230	151	88	43								

5024, 5024M CapSure SP

U	JS Marke	t Releas	se			Mar-90	S	erial Nur	nber Pr	efix	SY	or LAT					US	Retur	ned	Prod	uct An	alysis
R	legistere	d US Im	plants			201,600	Ty	ype and,	/or Fixat	tion	Tra	nsvenou	us, Vent	., Tines				Con	duct	or Fra	cture	52
E	stimated	d Active	US Imp	olants		49,200	P	olarity			Bip	olar								/Weld		10
A	dvisorie	S				None	S	teroid			Yes							In	isulat	ion Bi (reach Other	50 39
stem l	Longevity Study Results Number of Leads Enrolled in Stur Cumulative Months of Follow-Up								Qualif	ying C	ompli	cation	S 5-	4 Tota	I							
N	Number of Leads Enrolled in Stud Cumulative Months of Follow-Up			ıdy	8	,153				Lea	ad Dislo	dgemer	nt	5			Imped	dance	Out o	f Range	3	
C	Number of Leads Enrolled in Study Cumulative Months of Follow-Up Number of Leads Active in Study			р	330	,810				F	ailure to	o Captur	re 2	7		ι	Jnspeci	ified C	linical	Failure	1	
Ν	Number of Leads Enrolled in Study Cumulative Months of Follow-Up			у		452				Co	nductor	Fractur	e	3			Extra (Cardia	ic Stim	ulation	2	
												Failure	to Sens	e	2					Over	sensing	4
										Insula	tion (not	further	defined	d) (b	5						Other	1
												Insulat	ion (ESC	_)	1							
100																						
90																						
80																						
(0	1 2	2	3	4	5 6	5	7	8	9 1	0 1	1 12	2 1	3 1	4 15	5 16	5 17	7 1	8	19	20	21
	Years	After	Impla	int																		
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	11 yr	12 yr	13 yr	14 yr	15 yr	16 yr	17 yr				
%		99.6	99.5	99.3	99.2	99.1	99.0	98.8	98.7	98.5	98.4		98.2		98.0	97.1	97.1	95.7				
#		6,128	2,101	1,996		1,789	1,620		1,190	994	793	605	454	330	240	156	96	56				
	Effectiv	e Samp	ole Size																			







	US Market Relea	ise		lun-98	Serial N	umber Prefix	LEI	4			l	JS Reti	urned Produ	uct Anal	vsi
	Registered US In	nplants		92,000	Type an	d/or Fixation	Tra	nsvenous, Ve	nt., Tine	5	-		onductor Frac		
	Estimated Active	e US Implants		43,400	Polarity	,	Bip	olar					Crimp/Weld/E		
	Advisories			None	Steroid		Ye	5					Insulation Br	each Other	
	l Placement evity Study Res	sults				Οι	ualifving (Complicatio	ons	2 Total					
	Number of Lead		itudy	424	4			ad Dislodger		1					
	Cumulative Mor	nths of Follow-	Up	31,421	1			ailure to Cap		1					
	Cumulative Mor		•	31,421 185						1					
			•							1					
	Cumulative Mor Number of Lead		•							1					
10	Cumulative Mor Number of Lead		•							1		-			
10	Cumulative Mor Number of Lead		•							1					
10 9 8	Cumulative Mor Number of Lead		•							1					
9	Cumulative Mor Number of Lead	ls Active in Stu	•								8	9	10		
10 9 8	Cumulative Mor Number of Lead	ls Active in Stu	idy	185	5		F	ailure to Cap	ure		8	9	10		
10 9 8	Cumulative Mor Number of Lead	ls Active in Stu	idy	185	5		F	ailure to Cap	ure		8	9	10		
10 • 9 8	Cumulative Mor Number of Lead	ls Active in Stu	idy	3	5	4 yr	F	ailure to Cap	ure		8 8 8 yr	-	10 9 yr		
8	Cumulative Mor Number of Lead	s Active in Stu	dy	3	5		5	Failure to Cap	7			_			

mber of Leads En	rolled in Study									
mulative Months mber of Leads Ac	of Follow-Up	34,	967 ,109 125		Failure	slodgement e to Capture ure to Sense	1 6 1	Imp	edance Out of Range	
1 Years After Im ا	2 plant	3		4	5	6	7	8	9 10	
1	yr 2	2 yr	3 yr	4 yr	5 yr	бyr	7 yr	8 yr	9 yr	
9	9.5 9	99.4	99.4	99.0	99.0	97.6	97.6	97.6	97.6	
6	56 3	41	295	264	230	178	137	99	47	
	1 9 6	99.5 9	Years After Implant 1 yr 2 yr 99.5 99.4 656 341	Years After Implant 2 yr 3 yr 99.5 99.4 99.4 656 341 295	Years After Implant 1 yr 2 yr 3 yr 4 yr 99.5 99.4 99.0 99.0 656 341 295 264	Years After Implant 1 yr 2 yr 3 yr 4 yr 5 yr 99.5 99.4 99.4 99.0 99.0 656 341 295 264 230	Years After Implant 1 yr 2 yr 3 yr 4 yr 5 yr 6 yr 99.5 99.4 99.0 99.0 97.6 656 341 295 264 230 178	Years After Implant 1 yr 2 yr 3 yr 4 yr 5 yr 6 yr 7 yr 99.5 99.4 99.0 99.0 97.6 97.6 656 341 295 264 230 178 137	Years After Implant 1 yr 2 yr 3 yr 4 yr 5 yr 6 yr 7 yr 8 yr 99.5 99.4 99.0 99.0 97.6 97.6 97.6 656 341 295 264 230 178 137 99	Years After Implant 1 yr 2 yr 3 yr 4 yr 5 yr 6 yr 7 yr 8 yr 9 yr 99.5 99.4 99.0 99.0 97.6 97.6 97.6 97.6 656 341 295 264 230 178 137 99 47

	US Mark	ot Poloa	.0			Jan-9	7 0	Serial Nu	mbor Pr	ofix		DJ							d Due	J	a a la cati
													us Vor A	Coro	in		US R			duct A	
	Register		•	1		103,20		Type and	/or Fixa	tion			us, V or A	, Screw	-IN				uctor Fr		3
	Estimate		US Imp	biants		34,20		Polarity				ipolar							p/Weld lation		5
	Advisori	es				Non	e s	Steroid			Ye	es						mbe		Other	1
ial	Placer	nent																			
em	Longe	vity St	udy Re	esults						Qual	ifying	Compl	cations	7	Total						
	Number	of Lead	s Enrolle	ed in Stu	udy		967				L	ead Dislo	dgement	t 1			Im	pedanc	e Out o	f Range	
	Cumulat	ive Mon	ths of F	ollow-U	lp	3	0,149					Failure t	o Capture	2 2					Over	sensing	
	Number	of Lead	S Active	in Stud	у		46			Insula	ation (n	ot furthe	defined) 1							
10(1															
9(o ——— c										1										
8(o —— c																				
	0	1	2	3	4	5	6	7	8	9 1	0	11 1	2 13	14	15	16	17	18	19	20	21
	Year	s After	Impla	nt																	
												at									
			2.00	3 yr	4 yr	5 yr	бyr	7 yr	8 yr	9 yr	10 yr										
		1 yr	2 yr	0).	-																
9	6	1 yr 99.6	2 yr 99.6	99.6	99.1	99.1	99.1	99.1	97.4	97.4	97.4	97.4									

study Result	:S		Qi	ualifying Cor	nplications	5 Total			
ds Enrolled in S	Study	1,362		Lead	Dislodgement	1	Insulatio	n (not further d	efined)
onths of Follow	-Up	37,404		Faile	ure to Capture	2			
ds Active in Stu	ıdy	92		Cond	uctor Fracture	1			
									_
1	2	3	4	5	6	7	8	9	10
er Implant	1	1							1
1 yr	2 yr	3 yr	4 yr	5 yr	бyr	7 yr	8 yr	9 yr	10 yr
99.9	99.7	99.4	99.0	99.0	99.0	98.4	98.4	98.4	98.4
				219	189	155	134		54
1	ads Enrolled in Sonths of Follow ads Active in Stu- 1 er Implant 1 yr	1 yr 2 yr	ads Enrolled in Study 1,362 onths of Follow-Up 37,404 ads Active in Study 92 1 2 3 er Implant 1 yr 2 yr 3 yr	ads Enrolled in Study 1,362 onths of Follow-Up 37,404 ads Active in Study 92 1 2 3 4 er Implant 1 yr 2 yr 3 yr 4 yr	ads Enrolled in Study 1,362 Lead 1 and S Active in Study 92 Cond 1 2 3 4 5 er Implant 1 yr 2 yr 3 yr 4 yr 5 yr	ads Enrolled in Study 1,362 Lead Dislodgement ponths of Follow-Up 37,404 Failure to Capture ads Active in Study 92 Conductor Fracture 1 2 3 4 5 6 1 2 3 4 5 6 er Implant 1 1 2 3 4 5 7	ads Enrolled in Study 1,362 Lead Dislodgement 1 onths of Follow-Up 37,404 Failure to Capture 2 ads Active in Study 92 Conductor Fracture 1 1 2 3 4 5 6 7 1 1 2 3 4 5 6 7 er Implant 1 1 2 3 4 5 9	ads Enrolled in Study 1,362 Lead Dislodgement 1 Insulation onths of Follow-Up 37,404 Failure to Capture 2 ads Active in Study 92 Conductor Fracture 1 1 2 3 4 5 6 7 8 1 1 yr 2 yr 3 yr 4 yr 5 yr 6 yr 7 yr 8 yr	ads Enrolled in Study 1,362 Lead Dislodgement 1 Insulation (not further d Failure to Capture 2 Conductor Fracture 1 1 2 3 4 5 6 7 8 9 er Implant 1 yr 2 yr 3 yr 4 yr 5 yr 6 yr 7 yr 8 yr 9 yr



	US Market Rele	ase		Aug-00	Serial Num	nber Prefix	PJN				US Returned	Product An	alvsi
	Registered US	mplants		1,297,100	Type and/	or Fixation	Trans	venous, V or A,	Screw-in			or Fracture	25
	Estimated Acti	•	ants	860,900	Polarity		Bipol					Veld/Bond	25
	Advisories			None	Steroid		Yes				Insulat	ion Breach	26
												Other	17
ial	Placement												
tem	Longevity S	study Res	sults			Qua	lifying Co	mplications	17 1	Total			
	Number of Lea	ds Enrollec	l in Study	2,73	3		Lead	Dislodgement	4		Impedance C	out of Range	
	Cumulative Mc	onths of Fol	low-Up	126,012	2		Fail	ure to Capture	5		Extra Cardiac	Stimulation	
	Number of Lea	ds Active i	n Study	894	1		Cond	uctor Fracture	1		(Oversensing	
						Insu	lation (not fu	rther defined)	1		Cardiac	Perforation	
100)												
90													
50													
_)												
80	0	1	2	3	4		5	б	7	8	9	10	
80		r Imnlar	it										
80	Years Afte										at		
80						_			0.10	0.1/2	111 mo		
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	TIT mo		
80 %			2 yr 99.6	3 yr 99.4	4 yr 99.1	5 yr 99.1	6 yr 99.0	7 yr 99.0	99.0	9 yr 99.0	99.0		

ystern Lt	ongevity Stu					duniying co	mplications	10 Total				
Nu	umber of Leads	Enrolled in Stu	udy	1,536		Lead	l Dislodgement	2		Failure	to Sense	
Cu	umulative Mont	hs of Follow-L	Jp	63,799		Fa	ilure to Capture	3	I	mpedance Out o	of Range	
Nu	umber of Leads	Active in Stud	У	388		Con	ductor Fracture	1		Cardiac Per	foration	
§ 100 -												
90												
80 -												
0) 1		2	3	4	5	6	7	8	9	10	
VIVa	Years After I	mplant										
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	at 102 mo		
۳ %		99.6	99.4	99.3	99.0	99.0	99.0	99.0	99.0	99.0		
		1,084	853	723	601	473	363	222	123	62		

5092 CapSure SP Novus

Product Characteristics

US Market Release	Jun-98	Serial Number Prefix	LET	US Returned Product Analy	sis
Registered US Implants	124,100	Type and/or Fixation	Transvenous, Vent., Tines	Conductor Fracture	6
Estimated Active US Implants	61,400	Polarity	Bipolar	Crimp/Weld/Bond	0
Advisories	None	Steroid	Yes	Insulation Breach Other	35 12

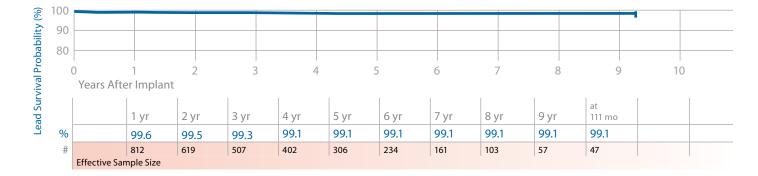
System Longevity Study Results

Qualifying Complications	7 Total
Lead Dislodgement	5

1

1

Number of Leads Enrolled in Study	1,172	Lead Dislodgement
Cumulative Months of Follow-Up	46,062	Failure to Capture
Number of Leads Active in Study	167	Extra Cardiac Stimulation



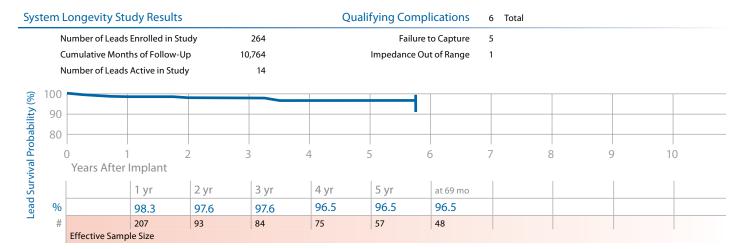
5524, 5524M CapSure SP

	US Mark	et Relea	se			Mar-9	0 9	Serial Nu	umber P	refix	Х	V or LA	V				ι	JS Ret	urne	d Pro	duct	Anal	ysi
I	Register	ed US In	nplants			60,60	0 -	Type and	d/or Fixa	ation	Т	ransver	nous, At	rial-J, Ti	nes			C	ondu	ctor Fi	racture	3	1
I	Estimate	d Active	e US Imp	olants		18,30	0 1	Polarity			B	lipolar						(•		l/Bong		
	Advisori	es				Non	e s	Steroid			Y	'es							Insul	ation	Breach Othe	-	1
stem	Longe	vity St	udy R	esults						Qual	ifying	Comp	licatio	ons :	37 Tot	al							
I	Number	of Lead	s Enrolle	ed in Sti	udy		4,497				L	ead Dis	lodgem	ent	3		Insu	ulation (not fu	irther o	definec)	
(Cumulat	ive Mor	nths of F	ollow-L	Jp	20	3,232					Failure	to Capt	ure 2	22			Impe	edance	e Out o	of Rang	e	1
I	Number	of Lead	s Active	in Stud	ly		404				C	onduct	or Fract	ure	1					Over	sensin	g	
												Failu	re to Se	nse	4						Othe	r	
100		_										1							1				
90				<u> </u>																			
80				<u> </u>																			
	0	1	2	3 .	4	5	6	7	8	9 1	0 1	, 1 1	2 1	3 1	4 1	5 1	61	7 1	8	19	20	21	
	Year	s After	r Impla	ant																			
	1		1	1	1	1	1	1	1	1							1	1					
					4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 vr	11 yr	12 vr	13 yr	14 yr	15 vr	at 189 mo						
		1 vr	2 vr	∣ ⊰ ∨r			, v , i	1	0 91														
100 90 80		1 yr	2 yr	3 yr	-	98.9	98.8	98 5	98.0	976	97.2	97.0	97.0	970	970	970	970						
%		1 yr 99.8 3,439	99.7	3 yr 99.3 1,375	99.0	98.9 1,183	98.8 1,059	98.5 912	98.0 775	97.6 653	97.2 525	97.0 400	97.0 304	97.0 219	97.0 144	97.0 81	97.0 48						

5534 CapSure Z

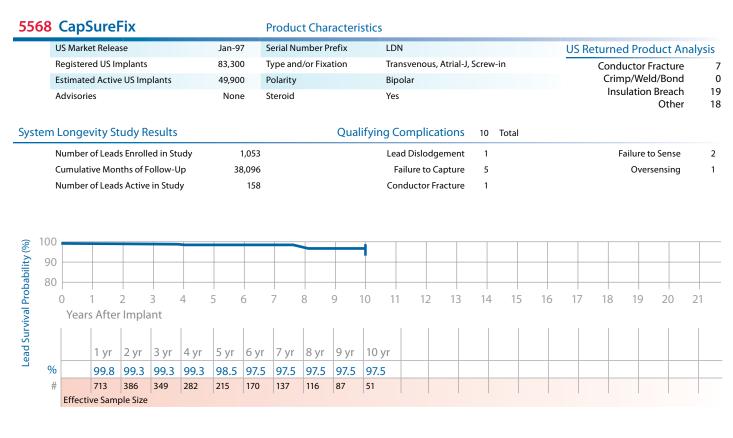
Product Characteristics

US Market Release	Feb-96	Serial Number Prefix	LDG	US Returned Product Analysis
Registered US Implants	26,100	Type and/or Fixation	Transvenous, Atrial-J, Tines	Conductor Fracture 3
Estimated Active US Implants	7,900	Polarity	Bipolar	Crimp/Weld/Bond 0
Advisories	None	Steroid	Yes	Insulation Breach 6
Advisories	None	Steroid	103	Other 5



	US Market Relea	ase		Jun-98	Serial Nur	mber Prefix	LEJ			ι	JS Returned	Product An	alysis
	Registered US I	mplants		59,400	Type and	/or Fixation	Transvenous,	, Atrial-J, Tir	es			or Fracture	
	Estimated Activ	e US Implants		30,800	Polarity		Bipolar				•	Weld/Bond	(
	Advisories			None	Steroid		Yes				Insulat	tion Breach Other	13 2
ster	m Longevity S	tudy Result	s			Qua	lifying Complica	ations	4 Total				
	Number of Lead	ds Enrolled in S	itudy	344	1		Lead Dislodg	jement	1			Oversensing	1
	Cumulative Mo	nths of Follow-	Un	10,597	7		Failure to C	anture	1				
	cumulative mo		·υμ	10,597			i anuic to c	apture					
	Number of Lead		•	43			Impedance Out of		1				
10			•						1				
10	Number of Lead		•						1				
10 9	Number of Lead		•						1				
10 9 8	Number of Lead 00		idy	43	3		Impedance Out of		- 1			10	
10 9 8	Number of Lead	ds Active in Stu	•		3	4			7	8	9	10	
10 9 8	Number of Lead	ds Active in Stu	idy	43	3	4 4 yr	Impedance Out of		7	8	9	10	
3	Number of Lead	ds Active in Stu	2	3	3	-	Impedance Out of		7	8	9	10	

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5592 CapSure SP Novus

	Number of Leads Enrolled in Study	67	n	Lead Dislodgement	ſ		
Syste	m Longevity Study Results		Quali	fying Complications	4 Total		
	Advisories	None	Steroid	Yes		Insulation Breach Other	3 0
	Estimated Active US Implants	18,700	Polarity	Bipolar		Crimp/Weld/Bond	0
	Registered US Implants	31,700	Type and/or Fixation	Transvenous, Atrial-J,	Tines	Conductor Fracture	2
	US Market Release	Jun-98	Serial Number Prefix	LEU		US Returned Product Analy	ysis

Cumulative	e Months of Follov	v-Up	29,718		Fail	ure to Capture	2			
Number of	Leads Active in St	udy	138							
0										
0										
0										
0	1	2	3	4	5	6	7	8	9	10
-	1 After Implant	2	3	4	5	6	7	8	9	10
-		2					7		9	10
-	After Implant	2 2 yr	3 3 3 yr	4 4 yr	5 5 5 yr	6 6 yr	7 7 7 yr	8 8 yr	9 at 99 mo	10
-		2 2 yr 99.3					7 7 yr 99.3			10

5594 CapSure SP Novus **Product Characteristics** US Market Release Serial Number Prefix LFD Jun-01 **US Returned Product Analysis** Registered US Implants Type and/or Fixation 13,800 Transvenous, Atrial-J, Tines **Conductor Fracture** 4 **Estimated Active US Implants** 9,600 Polarity Bipolar Crimp/Weld/Bond 0 Insulation Breach 5 Advisories None Steroid Yes Other 1 System Longevity Study Results **Qualifying Complications** 0 Total 21 Number of Leads Enrolled in Study Cumulative Months of Follow-Up 1,451

Number of Leads Active in Study 14 100 Survival estimate not available due to insufficient sample size

ity (90	Survivarestim	ate not available	e due to insuffici	ent sample size	<u> </u>					
lideo	80										
Prob		0	1 2	2 3	4	- 5	6	7	7 8	<u>ç</u>	10
vival		Years After I	mplant								
Sur											
ead	%										
	#										
		Effective Sample	e Size								

(%)

6940	Cap	Sure	Fix				I	Produc	t Cha	racteri	istics											
	US Mark	ket Relea	ise			Oct-9	8	Serial Nu	ımber P	refix	٦	ТСР						US R	leturne	d Prod	duct A	nalysis
	Register	red US Ir	nplants			25,50	0 1	Гуре and	d/or Fixa	ation	٦	Transver	ious, A	or V, S	crew-	in			Condu	ctor Fr	acture	11
	Estimate	ed Activ	e US Im	plants		8,50	0	Polarity			E	Bipolar							•	o/Weld		0
	Advisor	ies				Non	e s	Steroid			Y	Yes							Insu	lation E	Breach Other	15 4
Syster	n Longe	evity St	tudy R	esults						Qua	lifying	g Comp	olicati	ons	11	Total						
	Number	r of Lead	ls Enroll	ed in St	udy		816				I	Lead Dis	lodger	nent	1					Over	sensing	6
	Cumula	tive Mor	nths of F	ollow-U	Jp	4	1,330					Conduct	or Frac	ture	1							
	Number	r of Lead	ls Active	e in Stud	ly		112					Failu	ire to S	ense	3							
<u>ଛ</u> ା(00																					
lity	90																					
oabi	30										_											
Prof	0	1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	19	20	21
Lead Survival Probability (%)	Year	rs Aftei	r Impla	ant																		
d Sur												at										
-eac		1 yr	2 yr	3 yr	4 yr	5 yr	бyr	7 yr	8 yr	9 yr	10 yr	126 mo										
	%	99.7	99.6	98.3	98.0	98.0	98.0	98.0	98.0	98.0	98.0	98.0										

46

641

Effective Sample Size

#

506

413

331

277

237

196

149

116

84

evice Survival Probability (%)		4 yr 5 yr 6 yr 7 yr 8 yr 10 yr 12 yr 14 yr 16 yr 18 yr 20 yr	99.8 99.8 +0.2/-1 +0.2/-1	100.0	98.6 98.4 98.0 97.0 96.8 96.4 95.8 95.8 +0.6/-1.2 +0.7/-1.3 +0.8/-1.4 +1.2/-1.8 +1.2/-1.9 +1.3/-2.1 +1.6/-2.5 at 156 mo at 156 mo	998 99.8 99.8 99.8 99.8 99.8 99.8 98.0 +0.1/-0.7 +0.1/-0	97.5 96.8 96.0 94.8 93.3 +1.5/-3.5 +1.8/-3.9 +2.1/-4.4 +2.7/-5.5 +3.4/-6.7 at 105 mo at 105 mo at 105 mo at 105 mo	98.1 98.1 98.1 98.1 98.1 98.1 13/-3.9 +1.3/-3.9 +1.3/-3.9 +1.3/-3.9 at 78 mo	98.1 97.8 97.2 96.9 96.6 95.8 94.5 91.9 91.1 +0.5/-0.8 +0.6/-0.9 +0.8/-1 +0.9/-1.2 +1.1/-1.4 +1.4/-2 +2.4/-3.3 +2.7/-3.9at	98.7 98.1 97.7 97.2 97.2 96.1 95.8 94.2 92.8 94.2 92.8 +0.5/-0.8 +0.5/-1.2 +0.5/-1.3 +1.2/-1.6 +1.3/-1.7 +1.8/-2.6 +2.8/-4.4	100.0 100.0 100.0	991 991 991 991 991 991 991 991 991 +0.7/28 +0.7/28 10.7/28 10.7/28	99.3 99.3 99.3 99.3 99.3 99.3 99.3 10.5/-14 +0.5/-14 +0.5/-14 = 10.5/-14 at 81 mo	99.7 99.7 99.7 99.7 99.7 +0.2/-0.5 +0.2/-0.5 at 66 mo	998 99.8 99.8 99.8 99.8 10.2 ^{-0.5} +0.2 ^{-0.5} at 69.00 at	98.4 98.1 97.9 97.9 97.9 97.9 +0.6/-1.1 +0.8/-1.3 +0.8/-1.3 +0.8/-1.3 +0.8/-1.3 +0.8/-1.3
ے vpn32 ni c			12,367 99.8 +0.2/-1	9,721 100.0	69,632 99.8 +0.2/-0.6	30,182 99.9	22,610 99.4 +0.4/-1.4	10,425 98.1 +1.3/-3.9	124,040 98.9	90,731 99.3 +0.3/-0.6	6,820 100.0	13,166 99.1 +0.7/-2.8	24,280 99.6 +0.3/-1.2	45,025 99.8 +0.1/-0.5	38,151 99.8 +0.2/-0.5	64,009 98.9 +0.5/-0.8
su su		Inmu) Iqmo2	-	2	21 6	4 3	10 2	8	66 12	42 9	0	2 1	3 2	5	2 3	18
	βuiγ	†ilen O	500	281	262	19	33	48	447 0	377	74	160	482	66	976	418
λpnţς ui a			596 5(374 28	1,158 2(1,215	539	171			102	214 16	606 48	58 1,366		
		sbeəl							96 2,413	96 1,799				04 1,658	04 1,225	98 1,147
əssələ	rket R	₽W SU	Aug-05	Aug-05	Aug-91	Oct-91	Not US released	Jan-97	Mar-96	Mar-96	Jun-02	Jun-02	Jun-02	Feb-04	Feb-04	Sep-98
	Jêr	լառվշ	Atrial	Vent	Vent	Vent	Vent	Atrial	Atrial	Vent	Vent	Atrial	Vent	Atrial	Vent	Vent
	,	γlime٦	SelectSecure	SelectSecure	CapSure SP	CapSure SP	CapSure Z	CapSureFix	CapSureFix	CapSureFix	CapSure Sense	CapSure Sense	CapSure Sense	CapSureFix Novus	CapSureFix Novus	CapSure SP Novus
	θĽ	ləboM dmuN	3830	3830	4023	4024	4033	4067	4068	4068	4073	4074	4074	4076	4076	4092

Source: Medtronic Device Registration and Returned Product Analysis Data as of January 31, 2011

		20 yr														
		18 yr									95.7 +2.2/-4.6 at 204 mo					
		16 yr									97.1 +1.2/-1.8					
		14 yr									98.0 +0.7/-0.9	94.4 +1.9/-2.8 at 165 mo	98.8 +0.8/-1.9 at 150 mo			
		12 yr								95.7 +1.9/-3.1	98.2 +0.6/-0.7	94.4 +1.9/-2.8	98.8 +0.8/-1.9			
		10 yr		98.4 +1.1/-3.3 at 114 mo		91.1 +4.6/-9.3 at 108 mo	93.3 +2.1/-2.9 at 102 mo		97.4 +1.5/-3.9 at 102 mo	96.6 +1.4/-2.4	98,4 +0.5/-0.7	95.0 +1.7/-2.5	98.8 +0.8/-1.9		99.5 +0.4/-1.4 at 108 mo	97.6 +1.3/-2.7 at 108 mo
		8 yr		98.4 +1.1/-3.3		95.9 +2.5/-6.3	93.3 +2.1/-2.9		97.4 +1.5/-3.9	97.4 +1.1/-1.6	98.7 +0.4/-0.6	96.2 +1.4/-2.1	98.8 +0.8/-1.9	94.5 +3.1/-7.3 at 93 mo	99.5 +0.4/-1.4	97.6 +1.3/-2.7
		7 yr		98.4 +1.1/-3.3	97.2 +1.9/-6 at 75 mo	95.9 +2.5/-6.3	93.3 +2.1/-2.9		97.4 +1.5/-3.9	97.4 +1.1/-1.6	98.8 +0.4/-0.5	96.7 +1.3/-1.9	99.2 +0.5/-1.8	96.3 +2.1/-5	99.5 +0.4/-1.4	97.6 +1.3/-2.7
		6 yr		98.4 +1.1/-3.3	97.2 +1.9/-6	97.2 +1.8/-5.4	93.9 +1.9/-2.7		97.4 +1.5/-3.9	98.9 +0.5/-1.1	99.0 +0.3/-0.4	97.4 +1.1/-1.7	99.5 +0.4/-1.6	97.5 +1.4/-3.5	99.5 +0.4/-1.4	97.6 +1.3/-2.7
		5 yr		98.4 +1.1/-3.3	97.2 +1.9/-6	99.3 +0.5/-1.4	93.9 +1.9/-2.7		97.4 +1.5/-3.9	99.4 +0.3/-0.8	99.1 +0.3/-0.3	98.1 +0.8/-1.5	99.5 +0.4/-1.6	97.5 +1.4/-3.5	99.5 +0.4/-1.4	99.0 +0.6/-1.4
ity (%)		4 yr		98.4 +1.1/-3.3	97.2 +1.9/-6	99.3 +0.5/-1.4	94.6 +1.7/-2.5		98.2 +1.1/-3	99.4 +0.3/-0.8	99.2 +0.3/-0.4	98.5 +0.7/-1.3	99.5 +0.4/-1.6	97.5 +1.4/-3.5	99.5 +0.4/-1.4	99.0 +0.6/-1.4
Device Survival Probability (%)	ant	3 yr	98.1 +1.4/-5.3 at 27 mo	99.2 +0.5/-1.2	98.4 +1.2/-5.1	99.3 +0.5/-1.4	95.2 +1.5/-2.3		98.2 +1.1/-3	99.5 +0.3/-0.7	99.3 +0.2/-0.3	98.7 +0.6/-1.2	99.5 +0.4/-1.6	98.2 +1.1/-2.9	99.5 +0.4/-1.4	99.4 +0.3/-0.9
Survival	ears After Implant	2 yr	98.1 +1.4/-5.3	99.2 +0.5/-1.2	99.4 +0.5/-3.5	99.3 +0.5/-1.4	96.4 +1.3/-1.9		98.2 +1.1/-3	99.7 +0.2/-0.6	99.5 +0.2/-0.1	99.6 +0.2/-0.4	99.5 +0.4/-1.6	99.4 +0.3/-0.8	99.5 +0.4/-1.4	99.4 +0.3/-0.9
Device	Years A	1 yr	98.1 +1.4/-5.3	99.6 +0.3/-0.7	100.0	99.3 +0.5/-1.4	96.8 +1.2/-1.8	100.0 at 0 mo	98.2 +1.1/-3	99.7 +0.2/-0.5	99.6 +0.1/-0.2	99.7 +0.2/-0.4	99.5 +0.4/-1.6	99.7 +0.2/-0.6	99.5 +0.4/-1.4	99.5 +0.3/-0.8
sdtnoM γbut2 ni c			6,819	27,302	10,116	18,294	31,183	1,858	14,023	79,518	330,810	81,202	42,987	31,903	31,421	34,109
su		filenØ IqmoD	4	Q	4	12	33	0	2	19	54	27	4	11	2	6
γbut2 ni s	əvitəA	speəJ	1	44	14	22	179	120	79	365	452	186	147	25	185	125
pə	Enroll	speəj	121	911	206	539	656	135	283	1,354	8,153	1,899	386	1,209	424	967
əseələ	rket R	₽W SU	Aug-91	Oct-91	Not US released	Nov-94	Jan-97	Jun-02	Oct-98	Nov-88	Mar-90	Feb-96	Feb-96	Feb-96	Jun-98	Jun-98
	oer	լառվշ	Atrial	Atrial	Atrial	Atrial	Atrial	Atrial	Atrial	Vent	Vent	Vent	Atrial	Vent	Atrial	Vent
		γlime٦	CapSure SP	CapSure SP	CapSure Z	Screw-In	CapSureFix	CapSure Sense	CapSure SP Novus	CapSure SP	CapSure SP	CapSure Z	CapSure Z	CapSure Z	CapSure Z Novus	CapSure Z Novus
		ləboM dmuN	4523	4524	4533	4558M	4568	4574	4592	5023, 5023M	5024, 5024M	5033	5034	5034	5054	5054

continued

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Lead Survival Summary continued

		20 yr													
	_	18 yr 20													
	_														
	_	16 yr							97.0 +1/-1.3 at 189 mo						
		14 yr							97.0 +1/-1.3						
	_	12 yr	97.4 +1.6/-4.4 at 123 mo						97.0 +1/-1.3						98.0 +1/-1.6 at 126 mo
	_	10 yr	97.4 +1.6/-4.4	98.4 +1/-2.7	99.3 +0.5/-2.2 at 117 mo	99.0 +0.4/-0.6 at 111 mo	99 .0 +0.5/-0.9 at 102 mo	99.1 +0.5/-1.2 at 111 mo	97.2 +0.9/-1.2			97.5 +1.3/-2.8	99.3 +0.4/-1.3 at 99 mo		98.0 +1/-1.6
	_	8 yr	97.4 +1.6/-4.4	98,4 +1/-2.7	99.3 +0.5/-2.2	99.0 +0.4/-0.6	99.0 +0.5/-0.9	99.1 +0.5/-1.2	98.0 +0.6/-1			97.5 +1.3/-2.8	99.3 +0.4/-1.3		98.0 +1/-1.6
	_	7 yr	99.1 +0.6/-1.9	98.4 +1/-2.7	99.3 +0.5/-2.2	99.0 +0.4/-0.6	99.0 +0.5/-0.9	99.1 +0.5/-1.2	98.5 +0.6/-0.7			97.5 +1.3/-2.8	99.3 +0.4/-1.3		98.0 +1/-1.6
	_	6 yr	99.1 +0.6/-1.9	99.0 +0.7/-1.8	99.3 +0.5/-2.2	99.0 +0.4/-0.6	99.0 +0.5/-0.9	99.1 +0.5/-1.2	98.8 +0.5/-0.6	96.5 +2/-4.9 at 69 mo		97.5 +1.3/-2.8	99.3 +0.4/-1.3		98.0 +1/-1.6
		5 yr	99.1 +0.6/-1.9	99.0 +0.7/-1.8	99.3 +0.5/-2.2	99.1 +0.4/-0.5	99.0 +0.5/-0.9	99.1 +0.5/-1.2	98.9 +0.4/-0.6	96.5 +2/-4.9	96.8 +2.1/-5.9 at 54 mo	98.5 +0.9/-2	99.3 +0.4/-1.3		98.0 +1/-1.6
ity (%)		4 yr	99.1 +0.6/-1.9	99.0 +0.7/-1.8	99.3 +0.5/-2.2	99.1 +0.4/-0.5	99.0 +0.5/-0.9	99.1 +0.5/-1.2	99.0 +0.4/-0.6	96.5 +2/-4.9	96.8 +2.1/-5.9	99.3 +0.4/-1	99.3 +0.4/-1.3		98.0 +1/-1.6
Probabil	ant	3 yr	99.6 +0.3/-0.9	99.4 +0.4/-1.5	99.3 +0.5/-2.2	99.4 +0.3/-0.4	99.3 +0.4/-0.7	99.3 +0.4/-0.9	99.3 +0.3/-0.5	97.6 +1.4/-3.3	98.0 +1.4/-4.8	99.3 +0.4/-1	99.3 +0.4/-1.3		98.3 +0.8/-1.6
Device Survival Probability (%)	Years After Implant	2 yr	99.6 +0.3/-0.9	99.7 +0.2/-0.9	99.8 +0.2/-1.4	99.6 +0.2/-0.3	99.4 +0.3/-0.6	99.5 +0.3/-0.8	99.7 +0.2/-0.2	97.6 +1.4/-3.3	99.0 +0.8/-2.8	99.3 +0.4/-1	99.3 +0.4/-1.3		99.6 +0.3/-1
Device	Years A	1 yr	99.6 +0.3/-0.9	99.9 +0.1/-0.7	99.8 +0.2/-1.4	99.7 +0.1/-0.4	99.6 +0.2/-0.5	99.6 +0.2/-0.7	99.8 +0.1/-0.3	98.3 +1.1/-2.7	100.0	99.8 +0.1/-0.7	99.7 +0.2/-1.1	100 at 0 mo	99.7 +0.2/-0.8
sdtnoM Montbs			30,149	37,404	24,596	126,012	63,799	46,062	203,232	10,764	10,597	38,096	29,718	1,451	41,330
su	Pirog Picatio		2	ъ	7	17	10	7	37	Q	4	10	4	0	7
۸put2 ni ع			46	92	85	894	388	167	404	14	43	158	138	14	112
pə	iloın3 a	speəq	967	1,362	508	2,733	1,536	1,172	4,497	264	344	1,053	672	21	816
əssələ	arket R	W SU	Jan-97	Jan-97	Jun-98	Aug-00	Aug-00	Jun-98	Mar-90	Feb-96	Jun-98	Jan-97	Jun-98	Jun-01	Oct-98
	ıper	medD	Atrial	Vent	Atrial	Atrial	Vent	Vent	Atrial	Atrial	Atrial	Atrial	Atrial	Atrial	Atrial
	٨	limsA	CapSureFix	CapSureFix	SureFix	CapSureFix Novus	CapSureFix Novus	CapSure SP Novus	CapSure SP	CapSure Z	CapSure Z Novus	CapSureFix	CapSure SP Novus	CapSure SP Novus	CapSureFix
		amuN amuN	5068	5068	5072	5076	5076	5092	5524, 5524M	5534	5554	5568	5592	5594	6940

Lead Survival Summary continued

US Returned Product Analysis Summary

Model Number	Family	US Market Release	Estimated US Implants	Estimated US Active	Conductor Fracture	Crimp/Weld/ Bond	Insulation Breach	Other
3830	SelectSecure	Aug-05	18,800	15,500	2	0	6	5
4023	CapSure SP	Aug-91	41,200	8,500	17	0	4	8
4024	CapSure SP	Oct-91	222,300	48,500	28	0	148	41
4033	CapSure Z	Not US released	NA	NA	0	0	0	0
4067	CapSureFix	Jan-97	1,000	200	1	0	0	1
4068	CapSureFix	Mar-96	124,200	36,000	40	0	118	15
4073	CapSure Sense	Jun-02	700	400	0	0	0	0
4074	CapSure Sense	Jun-02	79,400	52,200	1	1	14	3
4076	CapSureFix Novus	Feb-04	322,200	255,300	14	1	12	23
4092	CapSure SP Novus	Sep-98	166,700	82,600	7	0	29	8
4523	CapSure SP	Aug-91	11,200	2,700	1	0	2	1
4524	CapSure SP	Oct-91	101,800	27,800	1	0	44	13
4533	CapSure Z	Not US released	NA	NA	1	0	0	0
4558M	Screw-in	Nov-94	20,000	4,600	1	1	19	1
4568	CapSureFix	Jan-97	69,800	26,100	3	0	37	6
4574	CapSure Sense	Jun-02	51,700	36,600	4	0	2	0
4592	CapSure SP Novus	Oct-98	81,300	42,700	5	0	11	1
5023, 5023M	CapSure SP	Nov-88	9,900	2,300	6	0	1	0
5024, 5024M	CapSure SP	Mar-90	201,600	49,200	52	10	50	39
5033	CapSure Z	Feb-96	2,400	600	1	0	0	3
5034	CapSure Z	Feb-96	56,100	14,400	14	1	16	13
5054	CapSure Z Novus	Jun-98	92,000	43,400	7	1	17	8
5068	CapSureFix	Jan-97	103,200	34,200	36	3	54	16
5072	SureFix	Jun-98	9,500	4,400	2	0	6	1
5076	CapSureFix Novus	Aug-00	1,297,100	860,900	259	0	261	170
5092	CapSure SP Novus	Jun-98	124,100	61,400	6	0	35	12
5524, 5524M	CapSure SP	Mar-90	60,600	18,300	11	2	13	9
5534	CapSure Z	Feb-96	26,100	7,900	3	0	6	5
5554	CapSure Z Novus	Jun-98	59,400	30,800	7	0	13	4
5568	CapSureFix	Jan-97	83,300	49,900	7	0	19	18
5592	CapSure SP Novus	Jun-98	31,700	18,700	2	0	3	0
5594	CapSure SP Novus	Jun-01	13,800	9,600	4	0	5	1
6940	CapSureFix	Oct-98	25,500	8,500	11	0	15	4

US Reports of Acute Lead Observations

Model Number	Family	Estimated US Implants	Cardiac Perforation	Conductor Fracture	Lead Dislodgement	Failure to Capture	Oversensing	Failure to Sense			Extracardiac Stimulation	Unspecified
3830	SelectSecure	18,800	7	0	23	8	2	2	1	0	0	0
4023	CapSure SP	41,200	0	1	3	4	1	0	3	0	1	0
4024	CapSure SP	222,300	16	11	53	110	0	15	2	10	2	16
4067	CapSure Fix	1,000	1	0	0	0	0	0	0	0	0	0
4068	CapSure Fix	124,200	5	3	33	29	1	5	1	2	1	1
4074	CapSure Sense	79,400	5	1	11	25	0	1	0	4	0	1
4076	CapSure Fix Novus	322,200	28	4	82	43	5	14	1	10	4	3
4092	CapSure SP Novus	166,700	2	5	19	24	0	0	0	4	0	2
4523	CapSure SP	11,200	0	0	2	2	0	1	0	0	0	0
4524	CapSure SP	101,800	0	3	23	17	0	5	2	1	0	10
4558M	Screw-in	20,000	2	0	4	4	0	1	0	2	1	0
4568	CapSure Fix	69,800	3	1	4	6	0	1	0	2	0	1
4574	CapSure Sense	51,700	0	1	17	10	1	4	0	0	0	3
4592	CapSure SP Novus	81,300	0	0	18	9	2	2	0	0	0	2
5023, 5023M	CapSure SP	9,900	0	1	2	0	1	0	0	0	0	1
5024, 5024M	CapSure SP	201,600	12	8	33	52	1	11	5	3	3	11
5033	CapSure Z	2,400	0	0	1	0	0	0	0	0	0	0
5034	CapSure Z	56,100	4	6	16	33	0	3	2	1	0	11
5054	CapSure Z Novus	92,000	1	1	11	21	0	2	2	1	0	10
5068	CapSure Fix	103,200	15	4	23	35	0	5	1	2	0	3
5072	SureFix	9,500	0	0	2	1	0	0	0	0	0	0
5076	CapSure Fix Novus	1,297,100	105	11	358	182	20	37	6	23	12	18
5092	CapSure SP Novus	124,100	4	1	32	25	1	7	3	2	3	8
5524, 5524M	CapSure SP	60,600	1	4	20	14	0	9	2	0	0	8
5534	CapSure Z	26,100	0	0	5	5	0	1	0	0	2	4
5554	CapSure Z Novus	59,400	0	1	27	19	0	1	0	0	0	3
5568	CapSure Fix	83,300	5	0	25	15	2	3	1	2	2	1
5592	CapSure SP Novus	31,700	0	0	18	3	0	1	0	0	0	1
5594	CapSure SP Novus	13,800	0	1	5	0	0	0	0	0	0	2
6940	CapSure Fix	25,500	0	1	6	1	0	0	0	0	0	1

Report Cutoff Date: January 31, 2011

Reference Chart

Model Number	Family	Туре	Insulation	Conductor Material	Tip Electrode	Connector Type
3830	SelectSecure	Transvenous V or A Screw-In	Polyurethane/Silicone (55D,4719)	MP35N 5 Filars/ Cable	1.8 mm Helix/Steroid	IS-1 BI
4023	CapSure SP	Transvenous Ventricular Tines	Polyurethane (55D)	MP35N 4 Filars	Porous Platinized/ Steroid	IS-1 UNI
4024	CapSure SP	Transvenous Ventricular Tines	Polyurethane (55D)	MP35N 4/5 Filars	Porous Platinized/ Steroid	IS-1 BI
4033	CapSure Z	Transvenous Ventricular Tines	Polyurethane (55D)	MP35N 2 Filars	CapSure Z Platinized/Steroid	IS-1 UNI
4067	CapSureFix	Transvenous V or A Screw-In	Polyurethane (80A)	MP35N 3 Filars	1.8 mm Helix/Steroid	IS-1 UNI
4068	CapSureFix	Transvenous V or A Screw-In	Polyurethane (80A/55D)	MP35N 4/3 Filars	1.8 mm Helix/Steroid	IS-1 BI
4073	CapSure Sense	Transvenous Ventricular Tines	Polyurethane (55D)	MP35N 5 Filars	TiN Coated Platinum Iridium/Steroid	IS-1 UNI
4074	CapSure Sense	Transvenous Ventricular Tines	Polyurethane/Silicone (55D, 4719)	MP35N 5/5 Filars	TiN Coated Platinum Iridium/ Steroid	IS-1 BI
4076	CapSureFix Novus	Transvenous V or A Screw-In	Polyurethane/Silicone (55D, 4719)	MP35N 4/6 Filars	TiN Coated Platinum Alloy/Steroid	IS-1 BI
4092	CapSure SP Novus	Transvenous Ventricular Tines	Polyurethane/Silicone (55D/4719)	MP35N 6/4 Filars	Porous Platinized/ Steroid	IS-1 BI
4523	CapSure SP	Transvenous Atrial-J Tines	Polyurethane (55D)	MP35N 2 Filars	Porous Platinized/ Steroid	IS-1 UNI
4524	CapSure SP	Transvenous Atrial-J Tines	Polyurethane (55D)	MP35N 4/5 Filars	Porous Platinized/ Steroid	IS-1 BI
4533	CapSure Z	Transvenous Atrial-J Tines	Polyurethane (55D)	MP35N 2 Filars	CapSure Z Platinized/Steroid	IS-1 UNI
4558M	Screw-In	Transvenous Atrial-J Screw-In	Polyurethane (80A/55D)	MP35N 6/3 Filars	1.8 mm Helix/Steroid	IS-1 BI
4568	CapSureFix	Transvenous Atrial-J Screw-In	Polyurethane (80A/55D)	MP35N 6/3 Filars	1.8 mm Helix/Steroid	IS-1 BI
4574	CapSure Sense	Transvenous Atrial -J Tines	Polyurethane/Silicone (55D,4719)	MP35N 5/5 Filars	TiN Coated Platinum Iridium	IS-1 BI
4592	CapSure SP Novus	Transvenous Atrial-J Tines	Polyurethane/Silicone (55D/4719)	MP35N 6/3 Filars	Porous Platinized/ Steroid	IS-1 BI
5023, 5023M	CapSure SP	Transvenous Ventricular Tines	Silicone	MP35N 4 Filars	Porous Platinized/ Steroid	5 mm (5023) IS-1 UNI (5023M)
5024, 5024M	CapSure SP	Transvenous Ventricular Tines	Silicone	MP35N 4/5 Filars	Porous Platinized/ Steroid	3.2 mm Low Profile (5024) IS-1 BI (5024M)
5033	CapSure Z	Transvenous Ventricular Tines	Silicone	MP35N 4 Filars	CapSure Z Platinized/Steroid	IS-1 UNI
5034	CapSure Z	Transvenous Ventricular Tines	Silicone	MP35N 4/5 Filars	CapSure Z Platinized/Steroid	IS-1 BI
5054	CapSure Z Novus	Transvenous Ventricular Tines	Silicone (4719)	MP35N 5/5 Filars	CapSure Z Porous/Platinized/ Steroid	IS-1 BI
5068	CapSureFix	Transvenous V or A Screw-In	Silicone	MP35N 4/3 Filars	1.8 mm Helix/Steroid	IS-1 BI
5072	SureFix	Transvenous V or A Screw-In	Silicone	MP35N 4/5 Filars	1.8 mm Helix/Steroid	IS-1 BI
5076	CapSureFix Novus	Transvenous V or A Screw-In	Silicone (4719)	MP35N 4/6 Filars	Porous Platinized/ Steroid	IS-1 BI
5092	CapSure SP Novus	Transvenous Ventricular Tines	Silicone (4719)	MP35N 5/5 Filars	Porous Platinized/ Steroid	IS-1 BI
5524, 5524M	CapSure SP	Transvenous Atrial-J Tines	Silicone	MP35N 6/5 Filars	Porous Platinized/ Steroid	3.2 mm Low Profile (5524) IS-1 Bl (5524M)
5534	CapSure Z	Transvenous	Silicone	MP35N	CapSure Z	IS-1 BI

continued

Reference Chart continued

Model Number	Family	Туре	Insulation	Conductor Material	Tip Electrode	Connector Type
5554	CapSure Z Novus	Transvenous Atrial-J Tines	Silicone (4719)	MP35N 6/5 Filars	CapSure Z Porous Platinized/ Steroid	IS-1 BI
5568	CapSureFix	Transvenous Atrial-J Screw-In	Silicone	MP35N 6/3 Filars	1.8 mm Helix/Steroid	IS-1 BI
5592	CapSure SP Novus	Transvenous Atrial-J Tines	Silicone (4719)	MP35N 6/5 Filars	Porous Platinized/ Steroid	IS-1 BI
5594	CapSure SP Novus	Transvenous Atrial-J Tines	Silicone (4719)	MP35N 6/5 Filars	Platinized Platinum/ Steroid	IS-1 BI
6940	CapSureFix	Transvenous A or V Screw-In	Silicone	MP35N 3/6 Filars	Platinum Alloy	IS-1 BI

Epi/Myocardial Pacing Leads

4951, 4951M Spectraflex

51,	4951M S	pectrafie	K	Produc	t Characteris	stics						
	US Market Releas	se	Oct-81	Serial Nu	mber Prefix	TF or LBJ				US Retu	rned Product An	alysis
	Registered US Im	plants	23,200	Type and	l/or Fixation	Myocardia	al Stab-in, V	or A, Peds	5	Co	nductor Fracture	57
	Estimated Active	US Implants	3,000	Polarity		Unipolar					imp/Weld/Bond	0
	Advisories		None	Steroid		No				I	nsulation Breach Other	39 29
em	Longevity St	udy Results			Quali	fying Compl	ications	14 To	tal			
	Number of Lead	s Enrolled in Stu	dy 1	179		Failure t	o Capture	7		Insulation (n	ot further defined)	1
	Cumulative Mon	ths of Follow-U	p 4,5	557		Conducto	r Fracture	1			Insulation (ESC)	1
	Number of Lead	s Active in Study	/	4		Failur	e to Sense	3		Impec	lance Out of Range	1
100)	1				1						
90												
80												
0(-					
	0 Years After	l Implant	2 3		4	5 6)	7	8	(9 10	
					1	1			I			
		1 yr	2 yr									
%		97.7	96.5									
1	#	89	50			l						
	Effective Sam	Die Size										

	US Market Release	e	Se	p-96	Serial Num	ber Prefix	LBT			US Return	ned Product An	alysis
	Registered US Imp	olants	20	,300	Type and/o	or Fixation	Epicardial Suture-	On V or A	Ą	Conc	ductor Fracture	127
	Estimated Active	US Implants	9	,700	Polarity		Unipolar				np/Weld/Bond	1
	Advisories		Ν	lone	Steroid		Yes			Ins	ulation Breach Other	31 2
stem	n Longevity Stu	idy Results	5			Quali	fying Complication	<mark>s</mark> 8	Total			
	Number of Leads	Enrolled in S	tudy	218			Failure to Captur	e 2			Oversensing	2
	Cumulative Month	hs of Follow-	Up	6,504			Conductor Fractu	e 3				
	Number of Leads	Active in Stu	dy	35			Failure to Sens	e 1				
10	Number of Leads	Active in Stu	dy	35			Failure to Sens	e 1				
10	0	Active in Stu	dy	35	4		Failure to Sens	e 1				
	0	Active in Stu	dy	35	7		Failure to Sens	e 1				
100 90 80	0 0 0	Active in Stu			7			e 1			10	
	0		dy	35	4			e 1	8	9	10	
10 9 8					4	1		e 1	8	9	10	
10 9 8 9		Implant	2	3		-		e 1	8	9	10	

Epi/Myocardial Pacing Leads continued

	CapSure	Ері			Product Charac	teristics					
ι	JS Market Relea	se	S	ep-99	Serial Number Prefix	< LEN			US R	eturned Product Ana	alysi
F	Registered US In	nplants	:	21,800	Type and/or Fixation	n Epica	rdial Suture-On	V or A		Conductor Fracture	1
E	stimated Active	e US Implants		13,900	Polarity	Bipola	ar			Crimp/Weld/Bond	
A	Advisories			None	Steroid	Yes				Insulation Breach Other	
em l	Longevity St	udy Result	S		Q	ualifying Cor	nplications	32 Total			
Ν	Number of Lead	s Enrolled in S	tudy	703		Fail	ure to Capture	13	Insulatio	on (not further defined)	
C	Cumulative Mor	ths of Follow-	Up	33,274		Cond	uctor Fracture	6	Im	pedance Out of Range	
Ν	Number of Leads Active in Study			395		Fa	ailure to Sense	3		Oversensing	
100											
	Number of Leads Active in Study										
90											
80											
	0	1	2	3	4	5	6	7	8	9 10	
	Years After	⁻ Implant									
	1	1 yr	2 yr	З у	r 4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	
						05.0	94.5	93.7	93.7	01.2	
%		99.8	98.1	97.	1 96.2	95.0	94.5	95.7	95./	91.3	

				Product Charac	.teristies						
US Market Release	2	Dec	-92	Serial Number Prefi	ix LAQ				US Retu	rned Product Ana	alysis
Registered US Imp	olants	40,1	100	Type and/or Fixatio	n Myo	ardial Screw-in	Vent.				10
Estimated Active	US Implants	15,0	000	Polarity	Unip	olar				•	0
Advisories		No	one S	Steroid	No					Insulation Breach Other	2 5
Longevity Stu	idy Results			C	Qualifying Co	mplications	11	Total			
Number of Leads	Enrolled in Stud	ly	259		Fai	lure to Capture	9				
Cumulative Mont	hs of Follow-Up		6,000			Oversensing	2				
Number of Leads	Active in Study		49								
		-									
			2	1		6	7	0		 0 10	
Years After			J	+	5	0	/	0		2 10	
	1 yr	2 yr	at 27	mo							
	97.4	94.6	94.6	5							
	132	52	49								
	Registered US Imp Estimated Active I Advisories Longevity Stu Number of Leads Cumulative Monti Number of Leads 0 1 Years After I	Longevity Study Results Number of Leads Enrolled in Stud Cumulative Months of Follow-Up Number of Leads Active in Study 0 1 2 Years After Implant 1 yr 97.4 132	Registered US Implants 40,7 Estimated Active US Implants 15,0 Advisories Nor Longevity Study Results Nor Number of Leads Enrolled in Study Cumulative Months of Follow-Up Number of Leads Active in Study 1 0 1 2 Years After Implant 1 yr 97,4 94,6	Registered US Implants 40,100 1 Estimated Active US Implants 15,000 1 Advisories None 1 Longevity Study Results 259 Number of Leads Enrolled in Study 259 Cumulative Months of Follow-Up 6,000 Number of Leads Active in Study 49 0 1 2 3 Years After Implant 1 yr 2 3 132 52 49	Registered US Implants 40,100 Type and/or Fixation Estimated Active US Implants 15,000 Polarity Advisories None Steroid Longevity Study Results Cumulative Months of Follow-Up 6,000 Number of Leads Active in Study 49 O 1 2 3 4 Years After Implant 1 yr 2 yr at 27 mo 97.4 94.6 94.6 132 52 49	Registered US Implants 40,100 Type and/or Fixation Myod Estimated Active US Implants 15,000 Polarity Unip Advisories None Steroid No Longevity Study Results Qualifying Co Number of Leads Enrolled in Study 259 Fai Cumulative Months of Follow-Up 6,000 Number of Leads Active in Study 49 0 1 2 3 4 5 Years After Implant 1 yr 2 yr at 27 mo	Registered US Implants 40,100 Type and/or Fixation Myocardial Screw-in Estimated Active US Implants 15,000 Polarity Unipolar Advisories None Steroid No Longevity Study Results Qualifying Complications Number of Leads Enrolled in Study 259 Failure to Capture Cumulative Months of Follow-Up 6,000 Oversensing Number of Leads Active in Study 49 49 0 1 2 3 4 5 6 Years After Implant 1 <td< td=""><td>Registered US Implants 40,100 Type and/or Fixation Myocardial Screw-in Vent. Estimated Active US Implants 15,000 Polarity Unipolar Advisories None Steroid No Longevity Study Results Qualifying Complications 11 Number of Leads Enrolled in Study 259 Failure to Capture 9 Cumulative Months of Follow-Up 6,000 Oversensing 2 Number of Leads Active in Study 49 49 49 0 1 2 3 4 5 6 7 Years After Implant 1 yr 2 yr at 27 mo 1 1 132 52 49 0 1 0 1 0</td><td>Registered US Implants 40,100 Type and/or Fixation Myocardial Screw-in Vent. Estimated Active US Implants 15,000 Polarity Unipolar Advisories None Steroid No Longevity Study Results Qualifying Complications 11 Number of Leads Enrolled in Study 259 Failure to Capture 9 Cumulative Months of Follow-Up 6,000 Oversensing 2 Number of Leads Active in Study 49 0 0 0 1 2 3 4 5 6 7 8 Years After Implant 1 yr 2 yr at 27 mo 1 1 1 1 1</td><td>Registered US Implants 40,100 Type and/or Fixation Myocardial Screw-in Vent. Estimated Active US Implants 15,000 Polarity Unipolar Advisories None Steroid No Longevity Study Results Qualifying Complications 11 Total Number of Leads Enrolled in Study 259 Failure to Capture 9 Cumulative Months of Follow-Up 6,000 Oversensing 2 Number of Leads Active in Study 49 O 1 2 3 44 5 6 7 8 Years After Implant 1 yr 2 yr 1 yr 2 yr 1 yr 2 yr 1 32 52</td><td>Registered US Implants 40,100 Type and/or Fixation Myocardial Screw-in Vent. Conductor Fracture Crimp/Weld/Bond Insulation Breach Other Stimated Active US Implants 15,000 Polarity Unipolar Conductor Fracture Crimp/Weld/Bond Insulation Breach Other Advisories None Steroid No No Conductor Fracture Crimp/Weld/Bond Insulation Breach Other Longevity Study Results 259 Failure to Capture 9 Cumulative Months of Follow-Up 6,000 Oversensing 2 Number of Leads Enrolled in Study 259 Failure to Capture 9 Cumulative Months of Follow-Up 6,000 Oversensing 2 Number of Leads Active in Study 49 49 10 Oracle Active in Study 49 49 10 Image: Active in Study 49 40 10</td></td<>	Registered US Implants 40,100 Type and/or Fixation Myocardial Screw-in Vent. Estimated Active US Implants 15,000 Polarity Unipolar Advisories None Steroid No Longevity Study Results Qualifying Complications 11 Number of Leads Enrolled in Study 259 Failure to Capture 9 Cumulative Months of Follow-Up 6,000 Oversensing 2 Number of Leads Active in Study 49 49 49 0 1 2 3 4 5 6 7 Years After Implant 1 yr 2 yr at 27 mo 1 1 132 52 49 0 1 0 1 0	Registered US Implants 40,100 Type and/or Fixation Myocardial Screw-in Vent. Estimated Active US Implants 15,000 Polarity Unipolar Advisories None Steroid No Longevity Study Results Qualifying Complications 11 Number of Leads Enrolled in Study 259 Failure to Capture 9 Cumulative Months of Follow-Up 6,000 Oversensing 2 Number of Leads Active in Study 49 0 0 0 1 2 3 4 5 6 7 8 Years After Implant 1 yr 2 yr at 27 mo 1 1 1 1 1	Registered US Implants 40,100 Type and/or Fixation Myocardial Screw-in Vent. Estimated Active US Implants 15,000 Polarity Unipolar Advisories None Steroid No Longevity Study Results Qualifying Complications 11 Total Number of Leads Enrolled in Study 259 Failure to Capture 9 Cumulative Months of Follow-Up 6,000 Oversensing 2 Number of Leads Active in Study 49 O 1 2 3 44 5 6 7 8 Years After Implant 1 yr 2 yr 1 yr 2 yr 1 yr 2 yr 1 32 52	Registered US Implants 40,100 Type and/or Fixation Myocardial Screw-in Vent. Conductor Fracture Crimp/Weld/Bond Insulation Breach Other Stimated Active US Implants 15,000 Polarity Unipolar Conductor Fracture Crimp/Weld/Bond Insulation Breach Other Advisories None Steroid No No Conductor Fracture Crimp/Weld/Bond Insulation Breach Other Longevity Study Results 259 Failure to Capture 9 Cumulative Months of Follow-Up 6,000 Oversensing 2 Number of Leads Enrolled in Study 259 Failure to Capture 9 Cumulative Months of Follow-Up 6,000 Oversensing 2 Number of Leads Active in Study 49 49 10 Oracle Active in Study 49 49 10 Image: Active in Study 49 40 10

Leads

Epi/Myocardial Pacing Leads continued

(95% Confidence Interval)
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Sep- 96 OC US Market Rele 23 139 Leads Enrolled 23 179 Leads Active in 34 34 Market Rele	չքողչ sղդս												
20 Oct. <	юW	Device S	urvival P	Device Survival Probability (%)	ty (%)								
Sep-96 Ct-81 Leads Cualification Ct-81 Cualifi	oiteoil evite	Years Aft	ears After Implant/	nt									
Oct-81 179 4 Sep-96 218 35	וחשחכ וdwoכ	1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	10 yr	12 yr	14 yr	16 yr
Sep-96 218 35	14 4,557	97.7 +1.6/-4.8	96.5 +2.2/-5.8										
	8 6,504	99.0 +0.7/-3.1	98.0 +1.4/-4.3	96.8 +2.1/-5.9	92.3 +4.1/-8.6 at 45 mo								
CapSure Epi Sep-99 703 395	32 30,274	99.8 +0.2/-0.9	98.1 +0.9/-1.7	97.1 +1.2/-2	96.2 +1.4/-2.3	95.0 +1.8/-2.7	94.5 +2/-3.1	93.7 +2.3/-3.6	93.7 +2.3/-3.6	91.3 +3.4/-5.6 at 108 mo			
(No brand Dec-92 259 49 name)	11 6,000	97.4 +1.5/-3.6	94.6 +2.8/-5.6	94.6 +2.8/-5.6 at 27 mo									

Epi/Myocardial Pacing Leads continued

US Returned Product Analysis Summary

Model Number	Family	US Market Release	Estimated US Implants	Estimated US Active	Conductor Fracture	Crimp/Weld/ Bond	Insulation Breach	Other
4951, 4951M	Spectraflex	Oct-81	23,200	3,000	57	0	39	29
4965	CapSure Epi	Sep-96	20,300	9,700	127	1	31	2
4968	CapSure Epi	Sep-99	21,800	13,900	17	0	6	1
5071	Screw-in	Dec-92	40,100	15,000	10	0	2	5

Source: Returned Product Analysis Data as of January 31, 2011

US Reports of Acute Lead Observations

Model Number	Family	Estimated US Implants	Cardiac Perforation	Conductor Fracture	Lead Dislodgement	Failure to Capture	Oversensing	Extracardiac Stimulation	Impedance Abnormal	Extracardiac Stimulation	Unspecified
4951, 4951M	Spectraflex	23,200	1	1	0	13	0	0	0	0	2
4965	CapSure Epi	20,300	0	1	1	4	0	1	3	0	0
4968	CapSure Epi	21,800	1	0	3	8	1	0	2	0	0
5071	Screw-in	40,100	1	0	0	25	0	1	3	1	1

Report Cutoff Date: January 31, 2011

Reference Chart

Model Number	Family	Туре	Insulation	Conductor Material	Tip Electrode	Connector Type
4951, 4951M	Spectraflex	Myocardial Stab-In V or A/Peds	Polyurethane (80A)	MP35N 4 Filars	Barb	5 mm (4951) IS-1 UNI (4951M)
4965	CapSure Epi	Epicardial Suture-On V or A	Silicone	MP35N 5 Filars	Porous Platinized/ Steroid	IS-1 UNI
4968	CapSure Epi	Epicardial Suture V or A	Silicone	MP35N 5 Filars	Porous Platinized/ Steroid	IS-1 B1
5069	(No brand name)	Myocardial Screw-In	Silicone	MP35N Multifilars	3-Turn Helix	IS-1 UNI
5071	(No brand name)	Myocardial Screw-In Ventricular	Silicone	MP35N Multifilars	2-Turn Helix	IS-1 UNI

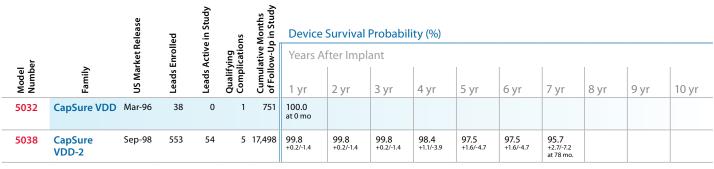
VDD Single Pass Pacing Leads

US Marke	et Release	Mar-96	Serial Number Prefix	LCL, LCN,	ICM		LIS Rotu	rned Product A	nalv
	ed US Implants	5,400	Type and/or Fixation		ous, Atr-Vent.,T	ines		nductor Fracture	anary
-	d Active US Implants	1,400	Polarity	Quadripo	lar		Cr	rimp/Weld/Bond	
Advisorie	25	None	Steroid	Yes			lı	nsulation Breach Other	
tem Longe	vity Study Results		Q	ualifying Comp	lications	1 Total			
Number	of Leads Enrolled in Study	38	8	Failur	re to Sense	1			
Number	or Leads Enroned in Stady	50							
	ive Months of Follow-Up	751							
Cumulati	-								
Cumulati Number	ive Months of Follow-Up	751							
Cumulati Number 100 Survi	ive Months of Follow-Up	751)						
Cumulati Number 100 90	ive Months of Follow-Up of Leads Active in Study	751)						
Cumulati Number 100 90 80	ive Months of Follow-Up of Leads Active in Study	751 0 ue to insufficie) ent sample size						
Cumulati Number 100 90 80 0	val estimate not available du	751)	5	6	7	8	9	10
Cumulati Number 100 90 80 0	ive Months of Follow-Up of Leads Active in Study	751 0 ue to insufficie) ent sample size	5	6	7	8	9	10
Cumulati Number 100 90 80 0	val estimate not available du	751 0 ue to insufficie) ent sample size	5	6	7	8	9	10
Cumulati Number 100 90 80 0	val estimate not available du	751 0 ue to insufficie) ent sample size	5	6	7	8	9	10

5038	B CapSure	VDD-2		Product	t Characte	ristics						
	US Market Relea	se	Sep-98	Serial Nur	nber Prefix	LEE, LI	EG, or LEF			US Retu	ned Product	t Analysis
	Registered US In	nplants	8,700	Type and	or Fixation	Transv	venous, Atr-Vent.	"Tines		Cor	ductor Fractu	re 3
	Estimated Active	e US Implants	3,700	Polarity		Quadı	ipolar				imp/Weld/Bor	
	Advisories		None	Steroid		Yes				Ir	nsulation Bread Oth	
Syster	m Longevity St	udy Results	;		Qu	alifying Cor	nplications	5 Tota	I			
	Number of Lead	s Enrolled in S	tudy 5	53		Failu	ire to Capture	1				
	Cumulative Mon	ths of Follow-	Up 17,4	98		Cond	uctor Fracture	2				
	Number of Lead	s Active in Stu	dy	54		Fa	ilure to Sense	2				
8 10	00											
lity	90											
obabi	30											
Lead Survival Probability (%)	0 Years After	1 Implant	2 3	2	1	5	6	7	8	ç	10)
d Su		1 yr	2 yr 3	8 yr	4 yr	5 yr	бyr	at 78 r	no			
Lea	%	99.8	99.8	9.8	98.4	97.5	97.5	95.7				
	#	419	172 1	50	121	99	63	51				
	Effective Sam	ple Size										

VDD Single Pass Pacing Leads continued

Lead Survival Summary (95% Confidence Interval)



Source: System Longevity Study

Data as of January 31, 2011

US Returned Product Analysis Summary

Model Number	Family	US Market Release	Estimated US Implants	Estimated US Active	Conductor Fracture	Crimp/Weld/ Bond	Insulation Breach	Other
5032	CapSure VDD	Mar-96	5,400	1,400	6	0	7	0
5038	CapSure VDD-2	Sep-98	8,700	3,700	3	1	1	1

Source: Returned Product Analysis Data as of January 31, 2011

US Reports of Acute Lead Observations

Model Number	Family	Estimated US Implants	Lead Dislodgement	Failure to Capture	Failure to Sense	Extracardiac Stimulation
5032	CapSure VDD	5,400	1	4	1	0
5038	CapSure VDD-2	8,700	1	1	0	1

Report Cutoff Date: January 31, 2011

Reference Chart

Model Number	Family	Туре	Insulation	Conductor Material	Tip Electrode	Connector Type
5032	CapSure VDD	Transvenous V and A Tines	Silicone	MP35N 5/6/1 Filars	Porous Platinized/ Steroid	Atr. IS-1 BI, Vent. IS-1 BI
5038	CapSure VDD-2	Transvenous Ventricular Tines	Silicone	MP35N	Porous Platinized/ Steroid	Atr. IS-1 Bl, Vent. IS-1 Bl

ICD and CRT-D Charge Time Performance

Medtronic continues its commitment to providing updated information on charge time performance.

Introduction

Information on charge time performance of Medtronic products is presented in this section of the CRDM Product Performance Report. Medtronic implemented the collection of charge time data on July 1, 1999. The data are collected via our ongoing active clinical study of long-term system performance called the System Longevity Study. The study protocol requests device data be routinely taken and sent to Medtronic at no more than 6-month intervals.

In our analysis performed for this report, only charge times resulting from full energy charges are considered. To ensure consistent reporting across devices, the charge time reported at implant represents the last charge time available from date of implant. When more than one charge time is available in a 6-month interval, a conservative approach has been adopted whereby only the maximum charge time in each 6-month interval is reported. As charge time is directly proportional to the time elapsed since the last capacitor reformation, charges occurring within 15 days of a previous charge are excluded. This precludes the reporting of overly optimistic results.

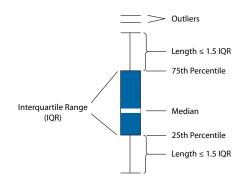
Data from over 20,000 devices contribute to the charge time data in this report. By tracking and reporting this charge time data, Medtronic is able to ascertain the actual performance of its charging circuitry. The insight gained through this information is applied to Medtronic's ongoing efforts to provide charge times that are short and consistent over the life of the product.

Data Presentation

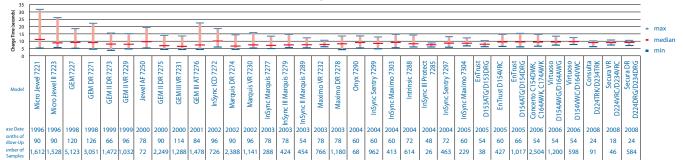
Charge time data for ICD and CRT-D models are presented using boxplots at 6-month intervals. The shaded box on the plots represents the middle half of the data – the Interquartile Range (IQR). The white line in the middle of each box is the median charge time. The top of the box representing the IQR is the third quartile or the 75th percentile (i.e., 75% of all charge times fall below this line), whereas the bottom of the box represents the first quartile or the 25th percentile. Vertical lines are drawn from the quartiles to the farthest value not more than 1.5 times the interquartile range. Any values more extreme than the vertical lines are considered outliers.

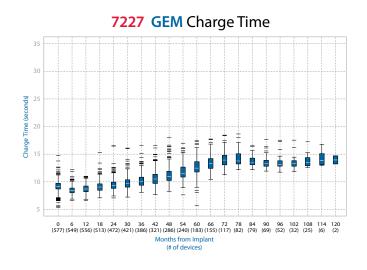
Results

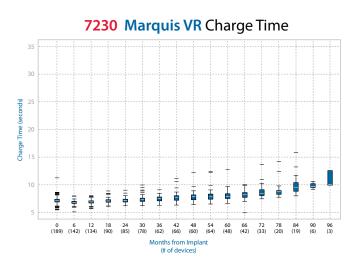
The graph below shows the overall maximums, minimums, and medians for Medtronic ICD and CRT-D products, beginning with the 7221 Micro Jewel.



Medtronic CRT-D and ICD Charge Time Performance

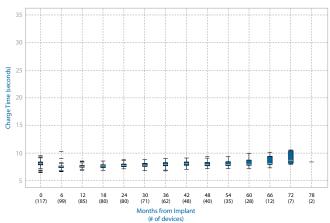




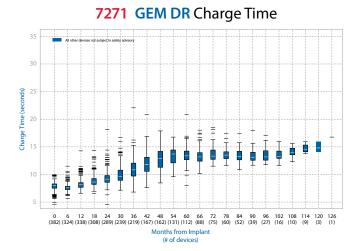


7231 GEM III VR Charge Time (spuc Charge Time (s İ İ ŧ Ì É Ī ţ Ē Ē İ Ē ¢ Months from Implant (# of devices)

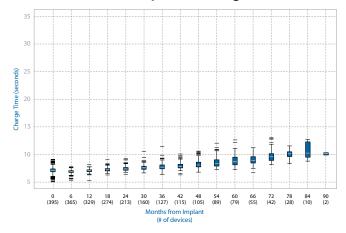
7232 Maximo VR Charge Time



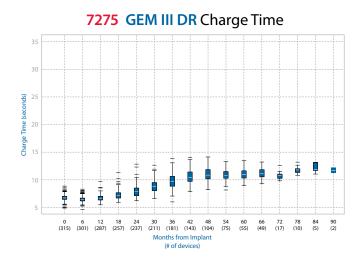
ICD Charge Times

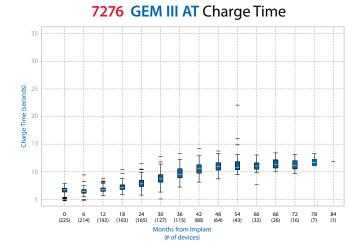


7274 Marquis DR Charge Time



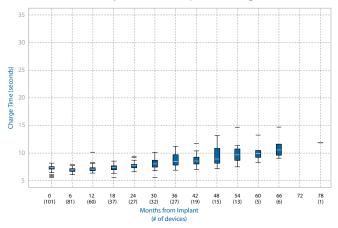
Source: System Longevity Study Data as of January 31, 2011

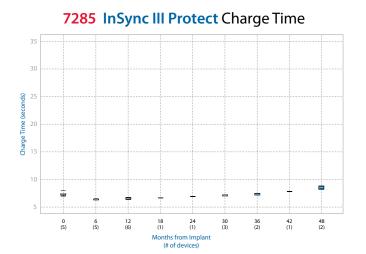




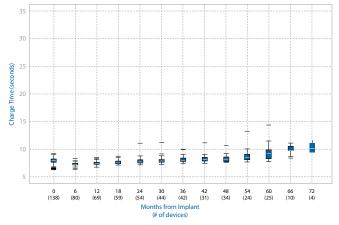
7278 Maximo DR Charge Time

7279 InSync III Marquis Charge Time

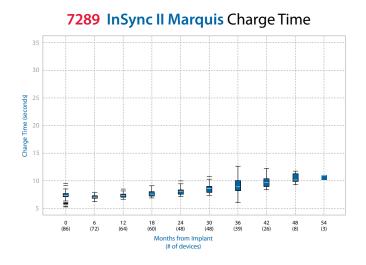


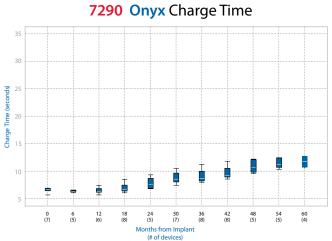


7288 Intrinsic Charge Time



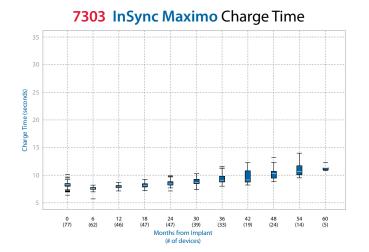
134 Medtronic CRDM Product Performance Report www.medtronic.com/CRDMProductPerformance Source: System Longevity Study Data as of January 31, 2011



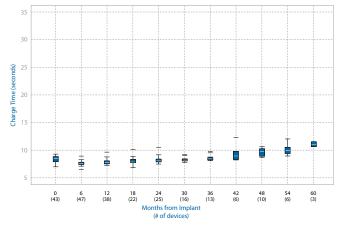


7297 InSync Sentry Charge Time 30 conds) Charge Time (see ₫ É 主 12 (48) 18 (46) 24 (55) 30 (35) 42 (36) 48 (31) 72 (1) 0 (84) 6 (61) 36 (37) 54 (16) 60 (9) 66 (4) Months from Implant (# of devices)

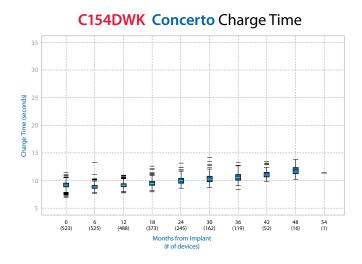
7299 InSync Sentry Charge Time (sp Charge Time (Ę ≣ 18 42 (60) 0 (170) 6 (128) 12 (132) 24 (116) 30 36 (90) 48 (42) 54 (9) 60 (1) (122) (92) Months from Implant (# of devices)

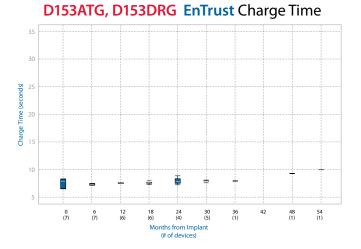


7304 InSync Maximo Charge Time



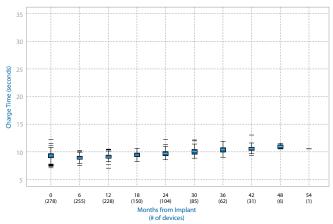
7200 Open Chame

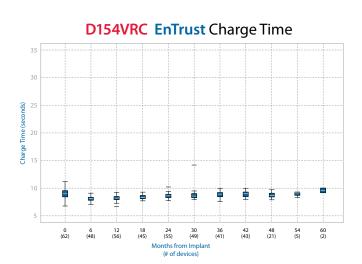




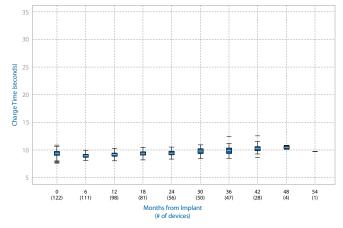
D154ATG, D154DRG EnTrust Charge Time Charge Time (seconds) 1 Ţ ŧ Ê Ŧ İ Ŧ ₹ ¢ ₫ 48 (49) 12 (132) 18 (125) 24 (101) 30 (99) 36 (95) 42 (76) 54 (30) 60 (6) 66 (3) 0 (175) 6 (126) Months from Implant (# of devices)

D154AWG Virtuoso Charge Time

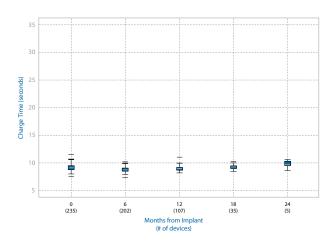


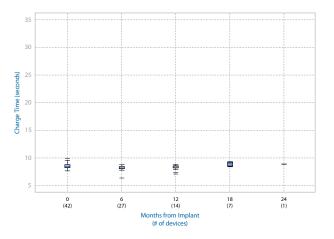


D154VWC Virtuoso Charge Time



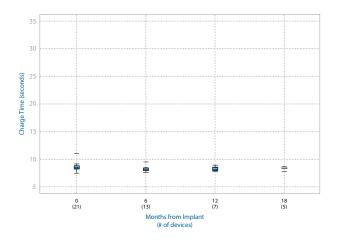
D224DRG, D234DRG Secura DR Charge Time





D234TRK Consulta Charge Time

D234VRC Secura VR Charge Time



Advisories

EnRhythm Pacemakers Original Date of Advisory: February 2010

Low Battery Voltage Displayed at Device Interrogation

Product

All EnRhythm pacemakers.

Advisory

Two specific battery issues with EnRhythm pacemakers have been identified and both are addressed by a Medtronic software update.

First Issue

As of February 2010, Medtronic had received 62 reports (out of approximately 110,000 devices worldwide) indicating that the battery voltage at device interrogation was lower than the battery voltage that is tracked by the device to provide data for the elective replacement indicator (ERI) notification. The lower voltage measurement has caused confusion and occasionally has resulted in unnecessary explants.

Medtronic's investigation has shown that none of these reports have resulted in loss of therapy. Importantly, the ERI notification, which uses the nightly battery measurement, is unaffected and accurate. Medtronic has identified the root cause as higher than expected battery resistance.

Medtronic's internal testing has shown that there is no current risk for compromised therapy delivery. If the software update referenced above is not implemented, there will be a potential risk of loss of device functionality in a small percent (less than 0.08% 6 years post-implant) of devices. The software update will eliminate this risk.

Patient Management Recommendations

Medtronic recommends physicians continue to use the ERI notification to determine time for device replacement. At this time, no other action, reprogramming, or change in the frequency of follow-up is recommended.

Second Issue

Through internal accelerated testing, Medtronic has identified a second issue that projects battery voltage could decrease sooner than expected due to a slightly increased rate of lithium depletion. This issue has not been clinically observed and is not expected to occur until approximately 9 years post-implant. If the software update referenced above is not implemented, there may be a potential risk for loss of therapy at or near ERI in a small number of devices. The software eliminate's this issue by changing ERI criteria.

Summary

The software update eliminate's any potential future risk of the two battery issues described above by changing the ERI criteria. This update will reduce longevity of these devices by approximately 10-15%, but the expected average longevity will still be 8.5 to 10.5 years depending on device settings.¹ At this time, no other action, reprogramming, or change in the frequency of patient follow-up is recommended.

Status Update

As of April 1, 2011, 326 devices out of approximately 140,000 devices worldwide have been confirmed as having exhibited an advisory related event. Approximately 107,000 remain implanted.

 1 The 8.5 year estimate represents a high use scenario (DDD, 100% pacing in atrium and ventricle with 3.0 V output in both chambers). The 10.5 year estimate represents a typical use scenario for a sinus node dysfunction patient with the MVP function ON (AAI(R) <=> DDD(R), 50% pacing in atrium and 5% pacing in ventricle with 3.0 V output in both chambers).

Initial Affected Population	Number of Confirmed Advisory Related Events	Estimated Remaining Active Population	Current Malfunction Rate (Confirmed Malfunctions over total population)	The software update eliminates any potential future risk of the two battery issues described above by changing the ERI criteria.
All EnRhythm pacemakers (140,000 Worldwide).	326 Worldwide	107,000 Worldwide	0.23%	

Potential Reduced Device Longevity

Product

A subset of Concerto CRT-D and Virtuoso ICD devices may not meet expected device longevity. Go to <u>www.medtronic.</u> <u>com/CRDMProductPerformance</u> to determine if a specific device is affected.

Advisory

A subset of Concerto CRT-D and Virtuoso ICD devices may not meet expected device longevity due to gradually increasing current drain caused by low voltage capacitor degradation. This issue may present in the affected devices as reaching the Recommended Replacement Time (RRT) earlier than projected. This issue does not compromise device functionality or affect therapy delivery.

Based on information from returned devices, Medtronic expects that affected devices will continue to provide at least 3 months of normal device function between RRT and End of Service (EOS) as described in device labeling.

A total of 8,900 devices worldwide are affected by this advisory. An estimated 6,300 of these devices were active at the time of the original advisory communication.

Concerto and Virtuoso devices in the affected subset were manufactured primarily in 2006 and can be traced to a specific subset of low voltage capacitors.

Patient Management Recommendations

After consultation with Medtronic's Independent Physician Quality Panel, Medtronic offers the following recommendations for patients with devices in the affected subset:

Physicians should continue routine follow-up sessions at least every 3 months in accordance with product labeling. Physicians should verify that the Low Battery Voltage RRT alert is programmed to "On-High." This provides an audible, alternating tone when the device reaches RRT. These devices are shipped with this alert programmed nominally to "On-High."

Physicians may consider monitoring patients through CareLink. The CareLink home monitor can be used to automatically notify the clinician when the device reaches RRT.

Status Update

As of April 1, 2011, 3,352 devices out of approximately 8,900 devices in this subset worldwide have been confirmed as having exhibited this capacitor degradation. Out of the initial advisory population of 8,900 worldwide, approximately 300 remain implanted. Approximately 200 of these are in the United States.

Initial Affected Population	Number of Confirmed Advisory Related Events	Estimated Remaining Active Population	Current Malfunction Rate (Confirmed Malfunctions over total population)
8,900 Implanted Worldwide (7,000 United States)	3,352 Worldwide (2,880 United States)	300 Worldwide (200 United States)	38% Worldwide (40% United States)

Concerto CRT-D and Virtuoso ICD Original Date of Advisory: September 2009

Kappa 600/700/900 Pacemakers Sigma 100/200/300 Pacemakers Original Date of Advisory: May 2009

Potential Separation of Interconnect Wires

Product

A specific subset of Kappa and Sigma series pacemakers may fail due to separation of interconnect wires from the hybrid circuit. Go to <u>www.medtronic.com/CRDMProductPerformance</u> to determine if a specific device is affected.

Advisory Population

Specific subsets of Kappa and Sigma series pacemakers may fail at a higher than expected rate due to separation of wires that connect the electronic circuit to other pacemaker components (e.g., battery, connector). This may present clinically as loss of rate response, premature battery depletion, loss of telemetry, or no output.

Some patients, whose devices experience a wire separation resulting in a loss of pacing output, will experience a return of bradycardia symptoms (e.g., fainting or lightheadedness). In rare cases involving pacemaker dependent patients, loss of pacing output may result in death or serious injury.

Since 1997, there have been over 1.7 million Kappa and Sigma devices implanted worldwide. . At the time of the original advisory communication, an estimated 15,200 Kappa and 6,100 Sigma devices affected by the advisory remained implanted and active. These devices were manufactured primarily between November 2000 and November 2002. Most of these devices have been implanted in patients for five years or longer and may be nearing normal elective replacement time.

There is no provocative testing that can predict which specific devices may fail, and no device programming can mitigate this issue if it occurs.

Patient Management Recommendations

We realize that each patient requires unique clinical consideration and we support your judgment in caring for your patients. After consultation with Medtronic's Independent Physician Quality Panel, Medtronic offers the following recommendations for patients:

- Physicians should advise their patients to seek medical attention immediately if they experience symptoms (e.g., fainting or lightheadedness).
- Physicians should consider device replacement for patients who are both pacemaker dependent and who have been implanted with a device in the affected subsets. Medtronic will offer a supplemental device warranty if the device is not already at elective replacement time.
- Physicians should continue routine follow-up in accordance with standard practice for those patients who are not pacemaker dependent.

Status Update

Advisory Population

Patient management recommendations remain

unchanged. As of April 1, 2011, Medtronic has observed 454 Kappa devices and 261 Sigma devices with this failure mechanism from the Kappa and new Sigma device subsets. This represents 0.78% (Kappa) and 1.75% (Sigma) of the original affected implant population.

Four hundred seventeen (417) of the Kappa devices (0.72%) and 199 of the Sigma devices (1.34%) were returned with information indicating a problem with the patient's pacing system prior to explant. The remaining 37 Kappa devices (0.06%) and 62 Sigma devices (0.42%) were returned with no information indicating a potential malfunction while implanted or with insufficient information to determine the state of the device at explant. Lacking definite information indicating proper operation until explant, these remaining devices are conservatively categorized as having experienced interconnect wire separation while implanted.

As of May 2009, our modeling predicts failure rates due to this issue of 1.1% (Kappa) and 4.8% (Sigma) over the remaining lifetime of those pacemakers still in service at that time.

Out of the initial advisory population of 58,300 Kappa devices and 14,900 Sigma devices worldwide, approximately 4,700 Kappa devices and 3,200 Sigma devices remain implanted. Of these, approximately 1,400 Kappa and 800 Sigma devices are in the United States.

Continued Vigilance

Included in the advisory communication was information about an additional subset of Kappa devices where we have observed a much lower rate of occurrence of this issue. Approximately 44,000 devices of this subset remain active. We have observed a failure rate of approximately 0.085% in this subset and our May 2009 modeling predicts a failure rate of 0.12% over the remaining device life of those pacemakers still in service at that time. After review with our Independent Physician Quality Panel, we do not recommend any specific actions for this group of devices. We will continue to monitor performance and inform you if any specific patient management recommendations are warranted.

continued

Kappa 600/700/900 Pacemakers

Sigma 100/200/300 Pacemakers Original Date of Advisory: May 2009

Potential Separation of Interconnect Wires, continued

Initial Affected Population	Number of Confirmed Advisory Related Events	Estimated Remaining Active Population	Current Malfunction Rate (Confirmed Malfunctions over total population)	Predicted Malfunction Rate Over the Remaining Life of the Devices Still Implanted Population
Kappa Pacemakers				
58,300 Implanted Worldwide (est.) (17,600 United States)	417 Worldwide (220 United States) with information indicating a clinical presentation. An additional 37 worldwide (25 US) without information indicating a clinical presentation or with insufficient information to determine the state of the device at explant.	4,700 Worldwide (1,400 United States)	0.78% Worldwide 1.39% (United States)	1.1%
Sigma Pacemakers				
14,900 Implanted Worldwide (est.) (3,700 United States)	199 Worldwide (41 United States) with information indicating a clinical presentation. An additional 62 worldwide (15 US) without information indicating a clinical presentation or with insufficient information to determine the state of the device at explant.	3,200 Worldwide (800 United States)	1.75% Worldwide 1.51% (United States)	4.8%

6930, 6931, 6948, 6949 Sprint Fidelis Defibrillation Leads

Original Date of Advisory: October 2007

Potential Conductor Wire Fracture

Product

All Model 6930, 6931, 6948, and 6949 implantable defibrillation leads

Advisory

There are two primary locations where chronic conductor fractures have occurred on Sprint Fidelis leads: 1) the distal portion of the lead, affecting the anode (ring electrode) and 2) near the anchoring sleeve tie-down, predominantly affecting the cathode (helix tip electrode), and occasionally the high voltage conductor. These two locations account for approximately 90% of the chronic fractures identified in Returned Product Analysis (RPA). The remaining 10% of chronic fractures occurred in the DF-1 connector leg and the proximal portion of the RV coil. High voltage conductor fractures could result in the inability to deliver defibrillation therapy. Anode or cathode conductor fractures (at either location) may present clinically as increased impedance, oversensing, increased interval counts, multiple inappropriate shocks, and/or loss of pacing output.

Patient Management Recommendations (Updated April 2011)

The Lead Integrity Alert (LIA) provides three days advance notice prior to inappropriate therapy to 76% of patients with lead fractures.¹ As a result, we strongly recommend that all Sprint Fidelis patients who have the ability to upgrade to Lead Integrity Alert do so promptly. Also ensure that high voltage lead impedance alerts (maximum of 100 ohms) are programmed. When a lead fracture is suspected or confirmed, immediate patient attention is strongly recommended. Physicians should inform their patients to seek medical attention without delay if they experience unexpected shocks.

- If a Fidelis lead fracture of any type has occurred, we recommend implanting a new high voltage lead with or without extraction of the Fidelis lead.
- In patients with normal device function and no manifestation of lead fracture, no action is recommended. The risk of prophylactic intervention appears to be greater than serious injury resulting from lead fracture even for pacemaker dependent patients, except in select individual patient circumstances as determined by the physician.
- In the event of a device change-out or upgrade procedure, with no manifestation of lead fracture, consider the patient age and lead model data above, as well as patient life expectancy, comorbidities, ease of extraction related to implant time, patient preference, etc., for the following options:
 - Leave a properly performing lead intact
 - Implant a new ICD lead without extraction of the existing lead

- Carefully consider all factors before prophylactic placement of a pace-sense lead. Data shows an increased risk of high voltage conductor fracture if a pace-sense conductor fracture has previously occurred. This data is available at www.medtronic.com/fidelis.
- Individual patient circumstances may warrant extracting and implanting a new ICD lead. If warranted, Medtronic's Independent Physician Quality Panel recommends the lead extraction procedure be performed by a physician with extensive lead extraction experience.²

Status Update

As of April 1, 2011, of the initial implant population of 205,600 in the United States, approximately 114,000 remain implanted. According to System Longevity Study results, Model 6949 lead survival is estimated to be 91.3% (+2.7/-3.8%) at 66 months. As the implanted population ages and the sample size increases for each time interval, the accuracy of the estimated survival probability will increase as shown by tighter confidence intervals.

- ¹ Swerdlow CD, Gunderson, BD, Ousdigian KT, et al. Downloadable algorithm to reduce inappropriate shocks caused by fractures of implantable cardioverter-defibrillator leads. *Circulation*. November 18, 2008;118(21):2122-2129.
- ² Wilkoff BL, Love CJ, Byrd CL, et al. Transvenous lead extraction: Heart Rhythm Society expert consensus on facilities, training, indications, and patient management. *Heart Rhythm*. July 2009;6(7):1085-1104.

continued

Advisories continued

6930, 6931, 6948, 6949 Sprint Fidelis Defibrillation Leads Original Date of Advisory: October 2007

Potential Conductor Wire Fracture, continued

Keeping Physicians Informed

The most recent Sprint Fidelis lead performance information, including survival curves, physician letters, and subpopulation data, can be found at www. medtronic.com/fidelis and will be updated semi-annually. Medtronic's website also has a selected list of peerreviewed publications related to Fidelis lead performance and extraction. Medtronic is committed to answering your questions and keeping you informed. If you have any questions or concerns, please contact your Medtronic Representative or Medtronic Technical Services at 1 (800) 723-4636 (US).

Initial Affected Population	Number of Confirmed Advisory Related Events	Estimated Remaining Active Population	Additional information about the Sprint Fidelis lead is available at: www.medtronic.com/fidelis.
205,600	4,293 (United	114,000 (United	
(United States)	States)	States)	

Sigma Implantable Pulse Generators

Original Date of Advisory: November 2005

Potential Separation of Interconnect Wires

Product

A specific subset of Sigma series pacemakers may fail due to separation of interconnect wires from the hybrid circuit. Go to <u>www.medtronic.com/CRDMProductPerformance</u> to determine if a specific device is affected.

Advisory

This subset of Sigma series pacemakers that may fail due to separation of interconnect wires from the hybrid circuit may present clinically as loss of rate response, premature battery depletion, intermittent or total loss of telemetry, or no output.

Separation of redundant interconnect wires has been observed on hybrid terminal blocks. Device failure occurs only where both interconnect wires separate from a hybrid terminal block. In October 2005, testing and analysis identified the root cause of these failures and the affected population. Hybrid circuits used in this subset of devices were cleaned during manufacturing with a particular cleaning solvent that could potentially reduce the strength of the interconnect wire bond over time.

No provocative testing can predict which devices may fail.

Patient Management Recommendations

Recommendation for the management of patients who have pacemakers affected by this advisory were changed in May 2009. Current recommendations are:

We realize that each patient requires unique clinical consideration and we support your judgment in caring for your patients. After consultation with Medtronic's Independent Physician Quality Panel, Medtronic offers the following recommendations for patients in the 2005 Sigma advisory:

• Physicians should advise their patients to seek medical attention immediately if they experience symptoms (e.g., fainting or lightheadedness).

- Physicians should consider device replacement for patients who are both pacemaker dependent and who have been implanted with a device in the affected subsets. Medtronic will offer a supplemental device warranty if the device is not already at elective replacement time.
- Physicians should continue routine follow-up in accordance with standard practice for those patients who are not pacemaker dependent.

Status Update

Patient management recommendations remain unchanged. As of April 1, 2011, 670 devices out of approximately 40,000 devices worldwide have been confirmed as having experienced interconnect wire separation.

Three hundred twenty-four (324) of the Sigma devices (0.81%) were returned with information indicating a problem with the patient's pacing system prior to explant. The remaining 346 Sigma devices (0.87%) were returned with no information indicating a potential malfunction while implanted or with insufficient information to determine the state of the device at explant. Lacking definite information indicating proper operation until explant, these remaining devices are conservatively categorized as having experienced interconnect wire separation while implanted.

Our original modeling predicted a failure rate from 0.17% to 0.30% over the remaining lifetime of these pacemakers. However, as of May 2009 updated updated modeling now predicts a failure rate of 3.9% over the remaining device life of those devices still in service at that time.

Out of the initial advisory population of 40,000 worldwide, approximately 9,600 remain implanted. Approximately 2,200 of these are in the United States.

fainting or lighthea	dedness).			
Initial Affected Population	Number of Confirmed Advisory Related Events	Estimated Remaining Active Population	Current Malfunction Rate (Confirmed Malfunctions over total population)	Predicted Malfunction Rate Over the Remaining Life of the Devices Still in Service as of May 2009
40,000 Implanted Worldwide (est.) (9,900 United States)	324 Worldwide (67 United States) with information indicating a clinical presentation.An additional 346 Worldwide (62 US) without information indicating a clinical presentation or with insufficient information to determine the state of the device at explant.	9,600 Worldwide (2,200 United States)	1.68% Worldwide 1.30% (United States)	3.9%

7274 Marguis DR 7278 Maximo DR 7230 Marguis VR

7232 Maximo VR

7277 InSync Marquis 7289 InSync II Marquis 7279 InSync III Marquis 7285 InSync III Protect

Original Date of Advisory: February 2005

Potential Premature Battery Depletion Due to Battery Short

Product

The specific subset of Marquis family ICD and CRT-D devices having batteries manufactured prior to December 2003 is affected. Devices manufactured with batteries produced after December 2003 are not affected. Go to www.medtronic.com/CRDMProductPerformance to determine if a specific device is affected.

Advisory

Medtronic Marquis family of ICD and CRT-D devices having batteries manufactured prior to December 2003 may experience rapid battery depletion due to a specific internal battery short mechanism. Battery design changes were implemented in December 2003 that eliminate the possibility of this internal shorting mechanism.

Highly accelerated bench testing indicated the rate of this shorting mechanism may increase as the battery is depleted. As of February 2005, the rate of shorting was approximately 1 in 10,000 (0.01%); bench test data indicated the rate may increase to between 0.2% and 1.5% over the second half of device life.

No provocative testing can predict which of these devices will experience this issue. Once a short occurs, battery depletion can take place within a few hours to a few days. After depletion the device ceases to function. It is also possible that as the battery depletes quickly, patients may experience temporary warmth in the area surrounding the ICD.

Patient Management Recommendations

We recommend you consider the following patient management options:

Conduct quarterly (i.e., every 3 months) follow-up procedures

- Inform patients that should they experience warmth in the area surrounding the ICD to seek follow-up care promptly
- Program Low Battery Voltage ERI Patient Alert to "On-High." This will result in an audible, alternating tone in the limited circumstances where a battery depletes slowly over a number of days. Data indicates most shorts will occur rapidly and will not be detected by this feature.
- · Provide a hand-held magnet to patients to check device status and program the Low Battery Voltage ERI Patient Alert to "On-High." Device operation may be monitored periodically (e.g., daily) by patients placing the magnet over the device for 1-2 seconds. If the device is functional, a steady tone will sound for approximately 20 seconds. If no tone is heard, follow-up care should be sought promptly.

Status Update

The Marquis Family device performance related to the battery shorting mechanism continues to be within Medtronic's engineering projections. As of April 1, 2011, 187 Marquis Family devices have been confirmed as having this internal battery shorting mechanism. One hundred ten (113) of these devices were returned from the United States.

Out of the initial advisory population of 87,000 worldwide, approximately 11,000 remain implanted. Approximately 9,600 of these are in the United States.

The Patient Management Recommendations set forth in the advisory remain unchanged.

Initial Affected Population	Number of Confirmed Advisory Related Events	Estimated Remaining Active Population	Current Malfunction Rate (Confirmed Malfunctions over total population)	Predicted Malfunction Rate Over the Remaining Life of the Devices Still Implanted Population
87,000 Implanted Worldwide (76,000 United States)	187 Worldwide (113 United States)	11,000 Worldwide (9,600 United States)	0.22% Worldwide (0.15% United States)	Consistent with Medtronic projections, the observed rate of shorting may increase to between 0.2% and 1.5% over the second half of device life.

Kappa 600, 700 Dual Chamber (D, DR, and VDD) IPGs

Original Date of Advisory: March 15, 2002

Potential Fractured Power Supply Wires

Product

A specific subset of Kappa 700/600 dual chamber (D, DR, and VDD) implantable pulse generators has been identified by serial numbers. Hospitals and Physicians were notified. Go to <u>www.medtronic.com/</u> <u>CRDMProductPerformance</u> to determine if a specific device is affected.

Advisory

As of March 15, 2002, Medtronic observed 53 related failures (0.02%) in over 255,000 Kappa 700/600 dual chamber (D, DR, and VDD) series devices sold worldwide. Medtronic voluntarily communicated this information to physicians because these failures had been observed in patients having submuscular implants.

These devices have presented with an electrical reset, intermittent output, or no output. Our investigation identified the root cause as fractured wires supplying power to the pacemaker. This has been directly correlated to submuscular placement of these devices. Submuscular implant locations (e.g., subpectoral, abdominal, etc.) can result in additional stress and repetitive flexing on the implanted device causing excessive fatigue on these wires. Of the estimated 4,000 devices implanted submuscular, approximately 200 (5%) may experience this failure. These stresses on the implanted device are unique to submuscular implant sites and do not exist with subcutaneous implants.

Patient Management Recommendations

While there is no provocative testing or time dependency that will predict which submuscular placed device will fail, certain electrical resets may be an indicator that a wire fracture has occurred. Normal electrical resets can occur as a result of electrosurgical procedures such as cautery and ablation or from defibrillation therapy. If none of the normal causes of electrical reset can be confirmed, or if a device serial number presents as "000000" following an electrical reset, this may be an indicator of a wire fracture.

For patients who have submuscular implants of devices within the designated serial number range and who are pacemaker dependent with no underlying rhythm, replacement of the device should be considered. Medtronic will provide the replacement device free of charge under the terms of its warranty program if a device is replaced in these patients.

For patients having subcutaneous implants, no change to your current patient care and follow-up is advised.

Status Update

Patient management recommendations remain

unchanged. As of April 1, 2011, 321 out of approximately 180,000 distributed (0.18% incidence) Kappa family devices worldwide have been confirmed as having fractured power supply wires. One hundred sixty-nine (169) of these devices were returned from the United States. Out of the initial implant population of 121,000 in the United States, less than 500 remain implanted.

Initial Affected Population	Number of Confirmed Advisory Related Events	Estimated Remaining Active Population	Current Malfunction Rate (Confirmed Malfunctions over total population)	Predicted Malfunction Rate Over the Remaining Life of the Devices Still Implanted Population
180,000 Active Worldwide at time of advisory (121,000 United States)	321 Worldwide (169 United States)	< 500 Worldwide (< 500 United States)	0.18% Worldwide (0.14% United States)	0.03%

Minix and Minix ST IPGs

Original Date of Advisory: May 6, 1991

Potential Delayed Restoration of Permanent Settings

Product

All Models of the Minix and Minix ST families of implantable pulse generators

Advisory

Possibility of delayed restoration of permanent pacing mode and parameters, after the magnet or programming head is removed under certain conditions.

Patient Management Recommendations

To eliminate any potential risk associated with temporary programming, depress the INTERROGATE key and verify successful interrogation before moving the programming head away from the pulse generator. The delay condition can also be terminated by repositioning the programming head and depressing the EMERGENCY VVI key.

Status Update

Device performance related to this advisory continues to be within Medtronic's engineering projections. Patient management recommendations remain unchanged. Out of the initial implant population of 65,000 in the United States, approximately 3,000 remain implanted. The devices affected by this advisory are nearing the end of their expected longevity.

Initial Affected Population	Estimated Remaining Active Population	To eliminate any potential risk associated with temporary programming, depress the INTERROGATE key and verify successful interrogation before moving the programming head
All Minix and Minix ST implantable pulse generators	3,000	away from the pulse generator.

Performance Notes

Dual Chamber Pacemakers with Measurement Lock-up ERI Kappa 600, 700, 800, 900, EnPulse, Adapta, Versa, Sensia, Relia, and Vitatron Models E50A1, E60A1, and G70A1

Purpose of this Information

This Performance Note describes a rare measurement lock-up issue that impacts the Medtronic Dual Chamber pacemakers listed above. If this measurement lock-up occurs, the device will trigger a false Elective Replacement Indicator (ERI). A reset is available to clear this condition and there is no need to explant the device. This issue does not impact battery longevity.

Background

If this rare measurement lock-up occurs in the pacemaker, it causes the device to read a value of zero for battery voltage. After four measurements of zero, the device will trigger ERI and revert to a VVI pacing mode at 65 bpm. There is no loss of ventricular pacing and the output voltage will remain the same.

The issue can be uniquely identified using the programmer or via CareLink transmission; the battery voltage measurements and remaining longevity will appear as blank values. Medtronic has developed a method for clearing the ERI condition through the use of a specially configured programmer. There is no impact to the device functionality or longevity after this reset is complete.

Example

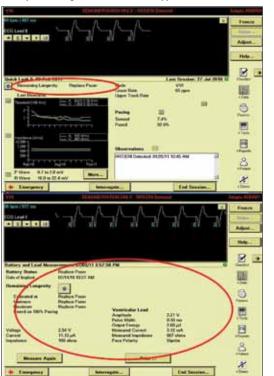
Two examples of images from the Medtronic 2090 Programmer are shown below. Example 1 shows what a normal ERI condition looks like. Example 2 shows what will be displayed if the ERI is triggered due to the measurement lock-up condition.

A device that has experienced a measurement lock-up ERI will present ALL of the following symptoms:

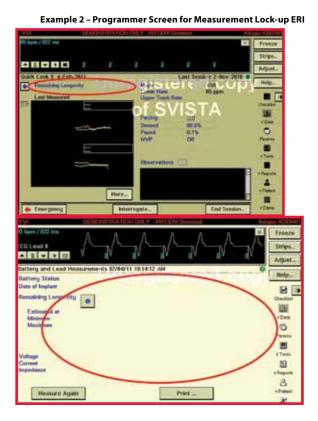
- Device declaring ERI/RRT
- Remaining Longevity = <Blank> on the programmer (and CareLink where available)
- Battery Voltage = <Blank> on the programmer (and CareLink where available)
- If the user attempts to take a Battery and Lead Measurement, a pop-up window will indicate that it cannot estimate remaining battery life.

Recommendation

This condition can be reset and does not require device explant. If this measurement lock-up occurs, obtain a saveto-disk file and contact Medtronic Brady Technical Services at 1 (800) 505-4636 for assistance. Reset devices are no more likely to experience a recurrence of this issue.



Example 1 – Programmer Screen for Typical Pacemaker at ERI



Helix Retraction of the Sprint Quattro Secure S 6935 and **Sprint Quattro Secure 6947**

Purpose of this Information

This performance note is intended to provide guidance regarding retraction of the helix of Sprint Quattro Model 6935 or 6947 leads.

Background

In certain cases, over-retraction of the helix, during initial implant or subsequent repositioning, may result in the inability to extend the helix. This does not impact acute or chronic performance of successfully implanted leads.

The root cause is over-retraction of the helix mechanism beyond the retraction stop, resulting in the inability to extend the helix in a subsequent attempt.

Recommendations

Consistent with the Technical Manual, the following steps can be used to mitigate this issue.

- Fluoroscopy should be used to confirm when the helix is fully retracted.
- Rotation of fixation tool should be stopped once full helix retraction is visually verified.
- If helix is unable to extend, replace with a new lead and report the issue to Medtronic.

Fully Retracted – Stop Rotation





Potential Malfunction of CRT, ICD, and IPG Products due to Anomalies in MOSFET Integrated Circuit Technology

Medtronic has detected a specific pattern of MOSFET IC malfunctions in its Concerto, Virtuoso and EnRhythm family of devices. As of July 2009, Medtronic has confirmed twenty-eight (28) malfunctions related to this pattern out of 115,000 EnRhythm and 233,000 Concerto/Virtuoso products distributed worldwide. Reliability analysis of this pattern shows the probability of occurrence decreases with time and, to date over 90% of the malfunctions related to the pattern have occurred within the first twelve months after implant. With process improvements in place, Medtronic expects few, if any, additional malfunctions related to this pattern.

The pattern involves metal-oxide-semiconductor fieldeffect transistors (MOSFET). A MOSFET is an electronic circuit used to amplify or switch electronic signals. MOSFETs have been used in the electronics industries for decades and MOSFET technology is the most widely used type of integrated circuit. Medtronic uses this technology in the circuitry of its CRT, ICD, and IPG products. Each product contains thousands of MOSFETs in its electronic circuitry.

Each MOSFET depends on a layer of insulating material to electrically isolate its components. The integrity of this insulating layer is important to the operation of the MOSFET. Variation in the thickness of the insulating layer can cause the MOSFET to operate in an undesirable manner. Process variations for electronic circuits can affect the integrity of the insulating material, and can lead to MOSFET malfunction. Medtronic's quality system strives to control process variation and detect undesired anomalies that are characteristic of all MOSFET manufacturing. In addition, Medtronic's post-market vigilance activities monitor malfunctions and may implement screening and testing improvements when a pattern of related malfunctions is identified. The pattern with the Concerto, Virtuoso and EnRhythm models has presented clinically as high lead impedance, sensing difficulty, loss of pacing therapy and/or early battery depletion due to higher than normal battery drain. The degree of battery drain varies case by case, such that the time from the onset to battery depletion has ranged from several days to several months. If not detected by normal patient follow-up procedures, the use of patient alerts or CareLink remote monitoring, the battery will fully deplete, leaving the patient without therapy.

As of March 2009, Medtronic has implemented additional electrical screening and stress tests to address this specific pattern for products being sold.

Since these rates of malfunction are low and the probability of occurrence decreases with time, Medtronic recommends physicians continue following patients in accordance with standard practice.

Clinical Management of VCM near Elective Replacement

Background

Medtronic Technical Services has received reports of devices going to ERI or end of life (EOL) sooner than expected after a normal follow-up in which the device longevity was projected to be approximately 18 months. It has been noted that these cases typically involve Kappa 700 devices where Ventricular Capture Management set the ventricular lead to high output (5 V, 1 ms), which occurs by device design when a high threshold is measured. It is important for physicians and allied professionals to understand VCM behavior as it relates to longevity so that they can, in turn, understand how this affects management of the device and follow-up visits as VCM equipped IPGs near the end of their expected longevity.

Device Longevity and VCM Behavior

Ventricular Capture Management is a feature that uses evoked response sensing to determine the stimulation threshold needed to capture the ventricular chamber. Proper detection of the evoked response is crucial to the VCM algorithm determining an accurate capture threshold. There are rare conditions, however, during which the VCM algorithm will not be able to measure the evoked response accurately.¹ When this occurs, for safety reasons the VCM algorithm will reprogram the output to 5 V, 1 ms until the subsequent VCM measurement.

If the device has considerable remaining longevity, these occasional excursions to high output do not substantially affect remaining longevity. However, if the device has less than approximately 18 months remaining longevity, there is the possibility that the high output condition caused by the 5 V, 1 ms output will drain the battery and trigger ERI.

When ERI is declared by the device, VCM is disabled and the outputs are left at 5 V, 1 ms until the device is reprogrammed at an in-office follow-up. This increased current drain of a high output condition will speed depletion of the device, possibly resulting in the device getting to the EOL (battery voltage ≤ 2.15 V).

Please note that the following parameter changes occur when the device goes to ERI:

Table: IPG T	herapy Paramete	er Changes at ERI

Parameter	Value
Pacing Mode	VVI
Lower Rate	65 bpm
Single Chamber Hysteresis	OFF
Sleep Function	OFF
Ventricular Capture Management	OFF
Atrial Sensing Assurance	OFF
Ventricular Sensing Assurance	OFF

Kappa 700 is Medtronic's first-generation VCM algorithm, which has a relatively higher incidence of evoked response undersensing compared to subsequent algorithms, resulting in more frequent high output conditions. Therefore, Kappa 700 products are the primary focus of this note. It should be noted that IPGs equipped with the second-generation VCM algorithm (Kappa 900, EnPulse, Adapta/Versa/Sensia, and Relia) have not been observed with evoked response undersensing in the general population, though the items listed in "Follow-Up Considerations" may also be used on these devices.

Follow-Up Considerations

- Estimated longevity in the event the device goes to high output can be determined by the following steps. This allows the clinician to determine follow-up frequency if he or she is concerned the device may go to ERI due to high output.
 - Program the ventricular channel to 5 V, 1 ms
 - Navigate to Data/Battery and Lead Measurements
 - When the message stating "Warning Old Data" is displayed, select "Yes" to measure battery voltage and lead impedance at the new ventricular outputs
 - An updated remaining longevity estimate will be calculated on the elevated outputs. Note the "Minimum Remaining Longevity." Clinical decisions can be based on this value.
 - Program the Amplitude and Pulse Widths back to their original values before leaving the session
- If the capture trends and lead impedance trends are stable, VCM can be programmed to "Monitor Only" for the remaining device life. This should be considered only if remaining longevity is 18 months or less.
- Follow-up frequency can be increased for those patients who do not have stable capture or lead impedance trends. This can be done via a CareLink Home Monitor, or in-office.

¹ Medtronic, Inc. (2001). Medtronic Kappa 700/600 Series Pacemaker Reference Guide (Chapter 4, p. 27). Can be retrieved from http://manuals.medtronic.com.

Ensuring the Accuracy of Battery Longevity Estimates

Purpose of This Information

This article is intended to help the clinician understand how Medtronic estimates CRT-D, ICD, and IPG device longevity and Medtronic's performance against these estimates.

Device Longevity and Battery Depletion

The device service life ends when the usable battery capacity is depleted. The time to battery depletion depends on three factors:

- The amount of electrical energy expended in providing therapy to the patient
- The amount of energy consumed by the electronic circuitry to perform the functions of the device (e.g., operating the microprocessor, telemetry, memory, and charging component)
- The energy capacity of the battery

Medtronic has developed a statistical model for device longevity that accounts for each of these factors, and has validated the model with real time clinical performance. During the development of its products, Medtronic engineers characterize device longevity using this model. Testing begins during development and continues after market release to ensure the accuracy of device longevity estimates.

Using Survival Curves to Assess Longevity

The survival curves in the Product Performance Report represent the composite experience of thousands of devices over a wide range of programming options and patient use conditions. While the curves are useful for understanding the overall performance of a population of devices, they cannot be used to accurately predict the longevity of a specific device in a specific patient. To get a longevity prediction for a specific device, the longevity model must be used. The model is available by contacting Medtronic's Technical Services Department.

Because the survival curves are an aggregate result, the Reference pages in the Product Performance Report include several longevity estimates for a range of use conditions. These longevity estimates are mean values calculated for the parameters given. This range of longevity estimates can be compared to the survival curve including normal battery depletion to assess the overall clinical performance of a device model against the original longevity estimates.

If most of a device model's population is being used at nominal parameters and conditions, the time at which the survival curve including normal battery depletion equals 50% should approximate the midpoint in the range of longevity estimates.

If devices tend to be used at conditions that consume more or less energy than nominal, then the time at which the survival curve equals 50% should tend toward the lower or higher end of the range of longevity estimates, respectively.

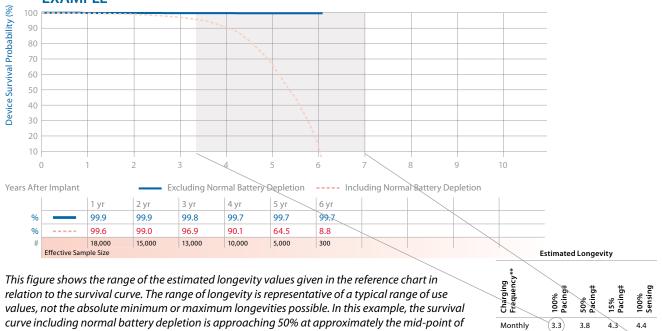
Quarterly

Semiannual

4.2

4.5

5.0



EXAMPLE

the range of longevity values.

6.3 (7.0

5.8

6.5

Interactions between Cardiac Pacing and Ventricular Arrhythmia Initiation

Purpose of This Information

This article is intended to provide information for consideration when programming pacemaker operation in ICDs and pacemakers.

Background

Right ventricular pacing has been associated with increased risk of appropriate therapy for ventricular tachycardia (VT) and ventricular fibrillation (VF) in ICD patients.¹ Abrupt changes in ventricular cycle lengths (short-long-short, S-L-S) may precede initiation of VT/VF in some instances. S-L-S sequences may be permitted in all forms of cardiac pacing. The pause lengths depend upon pacing mode and lower rate programming.²⁻⁴ Because pauses may be associated with VT/VF initiation, pause suppression algorithms have been developed in ICDs. Although pause suppression may have utility in specific patients with repolarization abnormalities and pause dependent VT, it has not been shown to reduce arrhythmia incidence in the general ICD population.⁵ Conversely, S-L-S sequences may occur with ventricular pacing in a variety of ways, including atrial tracking of premature atrial contractions (PACs) or by terminating pauses with ventricular paced beats.⁶ In some patients, the ectopic depolarization pattern of a ventricular paced beat may be pro-arrhythmic, independent of pause timing. These observations have further enforced the desire to reduce unnecessary ventricular pacing.

Clinical Trial Observations

Medtronic-sponsored clinical trials were retrospectively analyzed to further understand pause-mediated (i.e., S-L-S) scenarios prior to VT/VF. S-L-S onset scenarios were observed in a minority of patients in all pacing modes. Pacemaker interactions prior to VT/VF are dependent on patient conditions, as well as the technical aspects of pacing operation (i.e., pacing mode, lower rate, and AV interval). Because a very low frequency of ventricular pacing is observed during Managed Ventricular Pacing (MVP)⁷⁻⁹ or VVI 40 pacing modes,¹⁰ the long interval tended to terminate with a ventricular sense. In DDD mode, the long interval tended to be terminated by a ventricular pace. Long intervals of > 1,000 ms prior to VT/VF were rare in MVP mode. In these analyses, only an association between cardiac pacing and VT/VF initiation can be observed, causality cannot be established. The ongoing MVP (Managed Ventricular Pacing vs. VVI 40 Pacing) Trial, a 2-year, 1,000-patient prospective, randomized trial in ICD patients may offer more insight into the frequency of VT/ VF across pacing modes.¹¹

Pacemaker Patients

In pacemaker patients, ventricular pacing has been associated with higher incidence of AT/AF and heart failure hospitalization.^{12,13} MVP provides atrial rate support while dramatically reducing ventricular pacing in patients with sinus node dysfunction and transient AV block.⁹ However, as stated in Medtronic reference manuals, depending upon the patient's intrinsic rhythm and conduction, MVP may allow ventricular cycle variation and occasional pauses of up to twice the lower rate. DDD pacing with long AV intervals may reduce ventricular pacing and may decrease the potential length of pauses compared to MVP. However, DDD with long AV interval programming does not appear to be as effective as AAI-based pacing modes at reducing ventricular pacing,^{13,14} may lead to endless loop tachycardia,^{14,15} and does not completely eliminate pauses. Also, in DDD mode, a higher programmed lower rate or activation of rate response can lead to an increase in AV conduction times and a higher percentage of ventricular pacing. The potential benefits of reducing ventricular pacing must be weighed against the potential for longer ventricular pacemaker mode and lower rate programming, particularly in the setting of frequent AV block and repolarization abnormalities due to congenital Long QT, electrolyte imbalances, and some medications that prolong QT.

Conclusion

Pacemaker operation may interact with VT/VF initiation in a variety of ways. The patient's heart failure status, arrhythmia substrate, medications, and the relative importance of maintaining ventricular synchrony versus ensuring ventricular rate support must be weighed when choosing optimal hardware (ICD vs. pacemaker) and pacemaker programming (pacing mode, lower rate, etc.).

References

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AT500 Pacing System Follow-Up Protocol

Purpose of This Information

This article is intended to provide clinical guidance regarding follow-up practice and patient management when the AT500 battery voltage approaches the Elective Replacement Indicator (ERI) level of 2.6 volts.

Background

Many AT500 pacing systems are now reaching their ERI voltage level (2.6 volts). This is expected since the battery used has an approximate longevity of 5-6 years under normal conditions (100% DDD pacing, 3 volts, 0.4 ms).

Technical Services has received reports of battery voltage levels below end of life (EOL of 2.2 volts) where EGM prestorage is programmed ON, or higher outputs and/or pacing rates are necessary. It is important for physicians and allied professionals to understand battery depletion characteristics between ERI and EOL so that they, in turn, can understand how this affects management of follow-up visits for the AT500 as this device nears the end of its expected longevity.

AT500 Battery and Longevity Information

In contrast to other IPGs, the AT500 does not change its mode, stimulation rate, or any other parameter when the battery voltage drops below the ERI level of 2.6 volts (with or without magnet applied). The Threshold Margin Test (TMT) is also not available.

Therefore, it is not possible to perform transtelephonic assessment of AT500 battery status. This must be done during an in-clinic follow-up session. A warning will be displayed on the Quick Look screen at the beginning of a programmer (follow-up) session when the ERI battery level occurs. The measured battery voltage will also appear on the programmer display and on printouts.

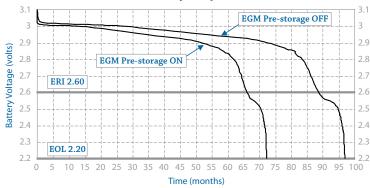
Battery depletion curves are shown in Figure 1, with special focus on device longevity when programming EGM prestorage ON or OFF.

Medtronic's review of ongoing AT500 battery life test data matches our original longevity modeling and so meets our expectations. However, when using longer durations between follow-up periods (> 3 months), clinicians should consider the following in setting their remaining longevity expectations.

- Enabling the "EGM Pre-storage On" capability will increase current and reduce device longevity by approximately
 9 days for each month pre-storage is ON
- Longevity decreases with an increase in pacing rate, an increase in pacing amplitude or pulse width, a decrease in pacing impedance, a higher ratio of paced to sensed events, or extended use of the Atrial Preference Pacing, EGM prestorage, or Holter Telemetry features

Recommendations

Follow-up frequency should always be accelerated as devices reach ERI voltage levels to ensure device explant/replacement occurs prior to end of life voltage levels. With the wide variety of follow-up schedules being used, Medtronic recommends a 3-month follow-up frequency for the AT500 pacing systems. This is particularly important for patients in whom EGM prestorage is programmed ON, or higher outputs and/or pacing rates are necessary.



AT500 Battery Depletion Curve

Figure 1

AT500 battery depletion curve for common parameter settings of DDDR, LR 70 ppm, UR 120 ppm, 100% pacing, Atrial – 2 V, 0.4 ms, 600 ohms, Ventricle – 2 V, 0.6 ms, 900 ohms, and EGM Pre-storage ON versus OFF.

Insertion of the Lead into the Device

The implantable system consists of a pulse generator and at least one lead. The system operation depends on proper electrical and mechanical operation. With the advent of internationally recognized connector standards, the challenge of ensuring proper mechanical fit between the lead and device connectors has been simplified, although the international connector standard does not address all aspects of the procedure for connecting a lead to the device.

If the lead connector is not fully installed, oversensing may result as described in the connector problems section of the performance note, "Clinical Management of High Voltage Lead System Oversensing."

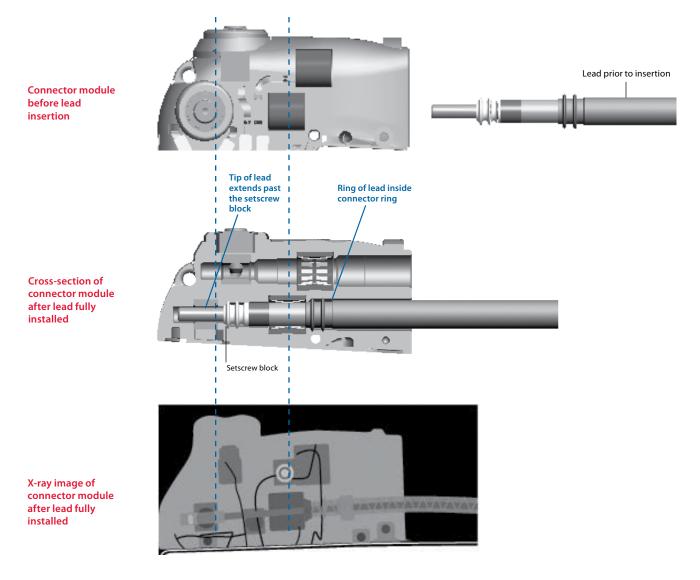
Performing the following steps can be used for each lead connection during the implant procedure:

1 Insert the torque wrench into the appropriate setscrew. For easier lead insertion, insert the lead closest to the device first.

- 2 Look down the connector port to verify that the port is not obstructed. If the port is obstructed, retract the setscrew to clear the bore. Take care not to disengage the setscrew from the connector block.
- **3** Push the lead into the connector port until the lead pin is clearly visible beyond the setscrew block.
- 4 Hold the lead in position while tightening the setscrew until the torque wrench clicks.
- 5 Tug gently on the lead to confirm a secure fit.

Current publications may provide additional information on implant procedures used by others, e.g., radiographic evaluation of the terminal pin beyond the terminal post.¹

¹ Pickett RA III, Saavedra P, Ali MF, Darbar D, Rottman JN. Implantable cardioverter-defibrillator malfunction due to mechanical failure of the header connection. *J Cardiovasc Electrophysiol*. September 2004;15(9):1095-1099.



GEM II DR/VR and GEM III DR/VR/AT ICD Battery Discharge Behavior

Medtronic manufactured and utilized a unique lithium/ silver vanadium oxide battery in the GEM II/III family of ICDs. This battery has a distinctive voltage discharge with two regions of constant voltage at 3.2 volts and 2.6 volts.

The battery discharge curve (see curve below) is characterized by a significant decrease in the battery voltage approaching middle of life (MOL), followed by a plateau (MOL to ERI) where the battery voltage remains around 2.6 volts. The transition to the plateau could be easily misinterpreted as the battery rapidly approaches ERI, which occurs at 2.55 volts, when the battery may in fact have several years remaining

until ERI.

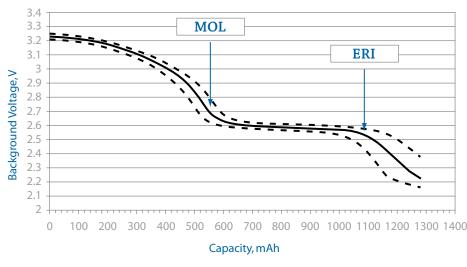
It is important to understand that this battery voltage decrease in the GEM II/III family of ICDs is a normal

characteristic of the battery function in these devices and should not create a need for additional follow-up or monitoring.

As a general rule of thumb, the longevity from implant to MOL = MOL to ERI.

The design of the battery in subsequently released models has been modified to present a more linear battery discharge curve.

If you are concerned about early ERI in your patient's device, you can utilize the battery trend measurements stored in the save-to-disk file, which can be accessed and interpreted through the Medtronic Technical Services at 1 (800) 723-4636.



GEM II/III Battery Discharge Curve

General Follow-Up and Replacement of ICD Leads

Implanted leads operate in the challenging biochemical environment of the human body and the body's response to foreign objects. Implanted leads are also subject to mechanical stresses associated with heart motion, body motion, and patient anatomy.

In this environment, pacemaker and defibrillation leads cannot be expected to last forever. Unlike implantable cardioverter defibrillators (ICDs), a lead's longevity cannot be predicted nor are there simple indicators that a lead is approaching the end of its service life. The determination that a lead may be approaching end of service life requires follow-up of the chronically implanted lead and thorough evaluation of lead integrity at ICD replacement.

Follow-Up of Chronically Implanted Leads

The frequency of follow-up for ICD patients will depend on a number of factors including the patient's medical condition, ICD system implant time, hospital/clinic follow-up practice, and Medicare guidelines. In all cases, it is important to assess the functionality of the ICD system and the integrity. For newly implanted leads, it is beneficial to establish a baseline of chronic performance parameters once the lead has stabilized, generally within 6 to 12 months after implant. These performance parameters should include pacing and sensing thresholds and impedance. During routine patient follow-up, these procedures can be used to evaluate lead integrity.

- Measure pacing and sensing threshold and compare to the chronic baseline. Significant increases or decreases may be indicative of lead failure, dislodgement, perforation, exit block, etc.
- Measure pacing impedance where possible and compare to the chronic baseline. Decreases of 30% or more or pacing impedances below 200-250 ohms may be indicative of insulation failure. Sudden and significant increases in pacing impedance may be indicative of conductor fracture.
- High voltage lead circuit impedance should be between 10-75 ohms at system implant. Chronic measurements below 10 and above 200 ohms may be indicative of high voltage lead circuit failure.
- Carefully review ECGs or the nonsustained detection log on Medtronic ICDs for indications of pacing and/or sensing abnormalities such as oversensing, undersensing, and loss of capture
- Elicit and investigate any patient complaints/symptoms that may be suggestive of potential lead failure

Where routine follow-up indicates, additional tools should be used to further evaluate performance. Tools include radiographic data, ICD electrograms, ICD Patient Alert and performance information from the System Longevity Study (SLS).

The final decision on the functional integrity and continued use of an implanted lead must be a matter of medical judgment based on these factors as well as specific patient conditions.

General Criteria for Lead Replacement

The evaluation of a chronically implanted lead is an important part of the decision to continue to use the lead with a new ICD. However, these results alone do not necessarily predict the future integrity of that lead. With the expected longevity of today's ICDs varying between approximately 5 and 10 years, a physician replacing a device should consider a number of factors, including those listed below.

Factors that should be considered in a decision to replace or continue to use include:

- Pacing and sensing thresholds should be evaluated for the potential to maintain acceptable levels
- Pacing impedance should be measured. Bear in mind that pacing impedance below 250 ohms results in excessive battery current drain, which may seriously compromise ICD longevity, regardless of lead integrity.
- The physical appearance of the lead should be examined for insulation cracks, breaches, or other indications of lead wear or degradation
- Medtronic System Longevity Study data should be referenced. Actuarial survival of the lead and the observed lead failure mechanisms are specific factors to consider. Use of a new lead should be considered if failure mechanisms suggest an increased time dependency as suggested in the shape of performance curve for the specific lead model.
- Current publications may provide additional information on the clinical management of leads.¹⁻³ Ultimately, the decision to replace an implanted lead involves medical judgment.
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Performance Notes

Clinical Management of High-Voltage Lead System Oversensing

Appropriate sensing by an ICD system refers to the sensing of cardiac events that may or may not require therapy delivery. ICD systems must sense relatively large QRS complexes while avoiding sensing of smaller T waves, yet continue to sense often small variable amplitude ventricular fibrillation. Thus, ICD systems attempt to dynamically adjust sensing of electrical events and discriminate between them based on detection algorithms and programmed settings.

Inappropriate sensing can occur when an ICD system classifies events of non-cardiac origin as QRS/VF events, or senses and counts T and far-field P waves as ventricular depolarizations. This is often referred to as "oversensing," and may result in delivery of inappropriate high-voltage therapies. This is due, in part, to the desire to err on the side of delivering lifesaving high voltage therapy rather than withholding it. Thus, an ICD system that is experiencing oversensing issues will continue to deliver therapeutic shocks as required, but may also subject the patient to unnecessary shocks.

Oversensing can be difficult to manage, in that the precipitating cause of the oversensing can be problematic to isolate. Oversensing can be caused by many factors, including myopotentials/farfield sensing, electromagnetic interference, T wave sensing, connector issues, incomplete or complete conductor fractures, and insulation breaches. While the individual physician must exercise medical judgment in determination of appropriate clinical management of ICD systems, the chart below may assist in the process of causal factor differentiation and possible intervention.

Phenomenon	Causal Factors	Characteristics	Management/Comments
Myopotentials/ Far-field sensing	Diaphragmatic muscle potentials in breathing, wide tip-to-ring (coil on integrated bipolar leads) spacing	Nonphysiological sensed event on EGM, which may confuse detection potentially resulting in false positive shocks	Check R waves for deterioration. Reprogram sensitivity. Try repositioning lead. Consider change-out to true bipolar lead, or if true bipolar lead in use, one with closer tip-to-ring spacing than current lead.
EMI (Electro-Magnetic Interference)	Arc welders, electrical generators, store walk-through security scanners, poorly insulated electrical equipment	Multiple and consecutive short intervals (< 140 ms) independent of underlying sinus beats. Associated with proximity to the EMI source.	Avoid EMI areas. True bipolar leads less susceptible.
T-wave sensing	Drugs, ischemic tissue, exercise, Long QT syndrome, electrolyte imbalance	Sense markers seen on EGM related to T wave. False positive detection.	Check for R wave deterioration and characteristics. If R wave > 3.0 mV, reprogram sensitivity. If R wave < 3.0 mV, reposition/replace lead. Address causal factor (e.g., drugs [if appropriate/medically viable]).
Connector problems	Loose setscrew, cross-threaded setscrew, incomplete lead insertion into header	This is an acute phenomenon seen within 6 months of implant (usually sooner)	Requires invasive check of connections. May be reproducible with pocket manipulation.
Incomplete conductor fracture	One or more filars of a multifilar conductor fracturing while leaving enough filars intact to provide a conduction circuit	Characterized by chaotic oversensing related to motion of the fracture site	Check EGMs and x-rays. Manipulate lead at suspected fracture site if possible as a provocative test. If confirmed, replace lead.
Lead insulation breach	Cuts, tears, metal ion oxidization, abrasion, cold flow, environmental stress cracking	Characterized by cyclical and/or erratic, intermittent, spontaneous oversensing; often post-pace or post-shock can cause false positives	Replace lead. If acute, usually secondary to implant damage/replacement damage. If late, material characteristic.
Oversensing during interrogation with programming head (not wireless telemetry) with complete lead fracture	Interrogation with a programming head in combination with complete lead fracture that creates an open circuit can induce noise on the sensing circuitry inside the ICD can	Nonphysiologic sensed event on EGM. If detection is enabled during interrogation, oversensing may result in inappropriate therapy.	Quickly remove the programming head. CANCEL the interrupted interrogation and manually load the software for the specific device model. Reposition the programmer head over the device and immediately select SUSPEND. Device will resume detection when programming head is removed, or when RESUME is selected. Replace lead.

Technical Services is available at all times to advise clinicians in the troubleshooting and management of Medtronic products. For assistance in the United States, please call 1 (800) 723-4636. In other countries, please contact your local Medtronic representative.

Tests and Observations for Clinical Assessment of Chronic Pacing Leads

Test/Observation	Possible Insulation Failure	Possible Conductor Failure	Possible Other System Failure	Effect on Test/ Observation
Pacing Impedance (Telemetered or Measured Invasively)	Sudden and Significant Decrease	Sudden and Significant Increase	Dislodgement Perforation Electrolyte Imbalance Improper IPG/Lead Connection	Decrease Increase or Decrease Increase or Decrease Increase or Decrease
Pacing Thresholds (Telemetered/Programmed or Measured Invasively)	Sudden and Significant Increase, Especially in Bipolar System	Sudden and Significant Increase	Dislodgement Exit Block Infarct at Electrode Site Perforation Improper IPG/Lead Connection	Increase Increase Increase Increase Increase
Electrograms (Telemetered or Measured Invasively)	Sudden and Significant Decrease in Amplitudes and/ or Slew Rates for P and/or R Waves	Sudden and Significant Decrease or Disappearance of Amplitudes and/or Slew Rates for P and/or R Waves	Dislodgement Perforation Infarct at Electrode Site Electrolyte Imbalance Improper IPG/Lead Connection	Decrease Decrease Decrease Decrease Decrease
Waveform Analysis (Oscillographs of Pacer Artifact from ECG Electrodes)	Sudden Increase in Ratios of Leading-Edge Voltages to Trailing-Edge Voltages (i.e., over 25% increase)	Intermittent or No Pacer Artifacts (Even in Asynchronous Mode)	Improper IPG/Lead Connection	Intermittent or No Pacer Artifacts (Even in Asynchronous Mode)
Radiographs (Post-Implant, Recent, Current)	Not Discernible	Visual Observation of Conductor/Connector/ Electrode Fracture (Sometimes Discernible)	Dislodgement or Perforation. Improper IPG/Lead Connection.	Sometimes Discernible
Visual Inspection (Invasive)	Insulation Breach and/or Degradation, or Ligature Cut-Through	Not Easily Discernible	Connector Defect or Connector Pulled Apart. Improper IPG/ Lead Connection.	Sometimes Discernible
Pectoral Muscle Stimulation	Sudden Onset, Especially in Bipolar System		Connector Defect in Bipolar or Unipolar. Hypersensitivity to Unipolar Pulse Generator Can. Anti-Stim Coating or Protection Deficient.	
Phrenic Nerve/ Diaphragmatic Stimulation	Sudden Onset in Bipolar or Unipolar Systems		Perforation or Displacement of Atrial Lead (Phrenic Nerve)	
Pacemaker ECG Stimulus Artifact Size and Morphology Change (May Not Be Possible with Digital ECG)	Sudden Onset and Significant Change, Especially in Bipolar System (Increase in Size)	Sudden Changes, Usually a Decrease in Size	Perforation or Dislodgement. Connector Defect. Improper IPG/Lead Connection.	Sometimes Discernible
Oversensing (Intermittent or Continuous)	Sudden Onset, Especially in Bipolar Systems		Physical Contact between the Electrode(s) on the Lead and that of Another Lead. Inappropriate IPG Parameter Setting. Improper IPG/ Lead Connection.	Sometimes Discernible
Undersensing (Intermittent or Continuous)	Sudden Onset in Either Unipolar or Bipolar Systems	Sudden Onset in Either Unipolar or Bipolar Systems	Dislodgement or Perforation. Infarct at Electrode Site. Electrolyte Imbalance. Inappropriate IPG Parameter Setting. Improper IPG/Lead Connection.	
Loss of Capture	See "Pacing Thresholds" Above	See "Pacing Thresholds" Above	See "Pacing Thresholds" Above	

Mailer Kits Available for Returning Product

Medtronic urges all physicians to return explanted products and to notify Medtronic when a product is no longer in use, regardless of reason for explant or removal from use. The procedures for returning products vary by geographic location.

Mailer kits with prepaid US postage are available for use within the United States to send CRT, ICD, IPG, and leads to Medtronic's CRDM Returned Product Analysis Lab. These mailers are sized to accommodate the devices and leads from a single patient or clinical event and are designed to meet US postal regulations for mailing biohazard materials.

If the product being returned is located outside the United States, please contact your local Medtronic representative for instructions.

Medtronic also requests the return of devices from non-clinical sources, such as funeral homes, and will assume responsibility for storage and disposal of the product once received.

Mailer kits can be obtained by contacting the Returned Product Lab.

CRDM Returned Product Analysis Laboratory Phone: 1 (800) 328-2518, ext. 44800 Email: crdm.returnedproduct@medtronic.com



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